Radiation Report

TPS7H5005-SEP and TPS7H5001-SP QMLP Neutron Displacement Damage (NDD) Characterization Report

ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the TPS7H5005-SEP and TPS7H5001-SP QMLP PWM controller. Both the TPS7H5005-SEP and TPS7H5001-SP QMLP showed a strong degree of hardness to neutron irradiation up to fluence level 1 × 10^{13} n/cm^2.

The neutron irradiation test is a destructive test. Test procedure follows MIL-STD-883 method 1017 as guidance. The purpose of this test is to determine the device susceptibility to non-ionizing energy loss (NIEL) degradation. Objectives of the test are, to detect and measure the degradation of critical device parameters as a function of neutron fluence and to determine if these parameters are within specified limits after exposure to a specified level of neutron fluence.

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1 Device Information

1.1 Product Description

The TPS7H5005-SEP and TPS7H5001-SP QMLP are 4-V to 14-V, current mode, dual output, high speed PWM controller optimized for DC-DC converters. The high switching frequency capability of the TPS7H5005-SEP and TPS7H5001-SP QMLP, small footprint, and low-current consumption makes the device ideal for fully exploiting the area reduction and high-efficiency benefits of DC-DC converters. The TPS7H5005-SEP and TPS7H5001-SP

QMLP feature integrated synchronous rectifier control outputs and dead-time programmability in order to target high-efficiency and high-performance topologies. In addition, these devices, single-ended converter topologies by providing the user the flexibility to control the maximum duty cycle.

The TPS7H5005-SEP and TPS7H5001-SP QMLP can be driven using an external clock through the SYNC pin or run using its internal oscillator at a frequency programmed by the user. Other programmable features include the UVLO threshold, soft start, and slope compensation. The TPS7H5005-SEP and TPS7H5001-SP QMLP are packaged in a very small 24-pin TSSOP (thin-shrink small outline package) package. As the TPS7H5001-SP QMLP uses the same material set, the results are applicable to both devices.

1.2 Device Details

Device and Exposure Details lists the device information and test conditions used in the NDD characterization.

Table 1-1. Device and Exposure Details

NDD Exposure Details	
TI Devices	TPS7H5005-SEP
TI Part Name	TPS7H5005MPWTSEP
Device Function	PWM controller
Package	24-pin TSSOP
Technology	LBC7
Lot Number / Lot Trace Code	02326747 / 24CF0HK
Sample Quantity	9 + 1 control unit
Exposure Facility	Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor (UMLRR)
Neutron Fluence (1-MeV equivalent) Level	1×10^{12}, 5×10^{12}, 1×10^{13} n/cm^2
Irradiation Temperature	25°C

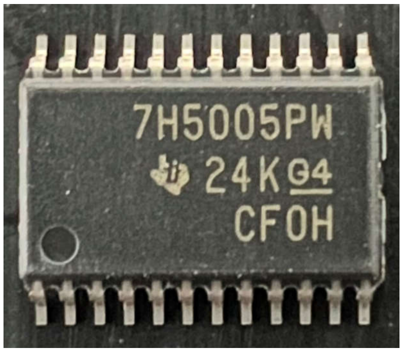


Figure 1-1. TPS7H5005-SEP Device

2 Total Dose Test Setup

2.1 Test Overview

General test procedures adhere to MIL-STD-883, Method 1017 as a guide for neutron irradiation. The TPS7H5005-SEP was electrically tested using the production automated test equipment (ATE) program at an ambient room temperature of 25°C before and after neutron irradiation.

2.2 Test Facility

The utilized test facility is the Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor. The neutron fluence for this irradiation was measured utilizing ASTM E-265 “Measuring Reaction Rates and Fast Neutron Fluence by Radioactivation of Sulfur-32” and correlated to the measured reactor power level. All irradiation conditions required under ASTM 722 were met, this includes: neutron fluence, distribution and uncertainty. The Average Integrated Neutron Fluence, 1-MeV(Si) equivalent, reflects these factors.

Detailed information of the radiation facility is available at the following link:

https://www.uml.edu/docs/FNI%20Brochure_tcm18-90375.pdf

2.3 Test Setup Details

Devices were irradiated at three fluence levels in unbiased conditions: 1.0×10^{12} n/cm^2, 5.0×10^{12} n/cm^2 and 1.0×10^{13} n/cm^2.

Table 2-1. Neutron Irradiation Conditions

GROUP	SAMPLE QTY	NEUTRON FLUENCE (n/cm^2)	BIAS
A	3	1.0×10^{12}	Unbias
B	3	5.0×10^{12}	Unbias
C	3	1.0×10^{13}	Unbias
Control Unit	1	N/A	N/A

3 Test Results

3.1 NDD Characterization Summary

The results show that all devices were fully functional and within specification limits. A sample size of nine units was exposed for neutron irradiation and an additional unirradiated control unit was used as correlation.

Overall, the TPS7H5005-SEP showed a strong degree of hardness to Neutron irradiation up to fluence level 1×10^{13} n/cm^2. As the TPS7H5001-SP QMLP uses the same material set, the results are applicable to this orderable as well. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each fluence level. The parameters that showed a greater degree of change between pre- and post- irradiation were still within the Electrical Performance Characteristics specified in the Data Sheet Electrical Parameters table. See Table 3-1 for the Data Sheet Electrical Parameters and Associated Tests.

Electrical testing is done for pre- and post- neutron irradiation by ATE. ATE electrical test is done at an ambient room temperature of 25°C. Parameters not listed in the Table 3-1 are omitted either because there is no parametric data or because verification was done through bench testing.

See Appendix A for NDD report up to 1.0×10^{13} n/cm^2.

3.2 Data Sheet Electrical Parameters and Associated Tests

Table 3-1. TPS7H5005-SEP and TPS7H5001-SP QMLP Electrical Parameters Table

PARAMETER	TEST CONDITION	TPS7H5005-SEP and TPS7H5001-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
SUPPLY VOLTAGES AND CURRENTS						
IDD Operating supply current	f_{SW} = 500 kHz, No load for OUTA, OUTB, SRA, and SRB		6.25	8	mA	5.24 __IDD_ACT_500K_NOLOAD_4V, 5.25 __IDD_ACT_500K_NOLOAD_5V, 5.26 __IDD_ACT_500K_NOLOAD_12V, 5.27 __IDD_ACT_500K_NOLOAD_14V
	f_{SW} = 1 MHz, No load for OUTA, OUTB, SRA, and SRB		6.75	9.5	mA	5.28 __IDD_ACT_1M_NOLOAD_4V, 5.29 __IDD_ACT_1M_NOLOAD_5V, 5.30 __IDD_ACT_1M_NOLOAD_12V, 5.31 __IDD_ACT_1M_NOLOAD_14V
	f_{SW} = 2 MHz, No load for OUTA, OUTB, SRA, and SRB		8.5	13.5	mA	5.36 __IDD_ACT_2M_NOLOAD_4V, 5.37 __IDD_ACT_2M_NOLOAD_5V, 5.38 __IDD_ACT_2M_NOLOAD_12V, 5.39 __IDD_ACT_2M_NOLOAD_14V
	f_{SW} = 500 kHz, C_{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		7.5	9.5	mA	5.48 __IDD_ACT_500K_4V, 5.49 __IDD_ACT_500K_5V, 5.50 __IDD_ACT_500K_12V, 5.51 __IDD_ACT_500K_14V
	f_{SW} = 1 MHz, C_{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		9	12	mA	5.52 __IDD_ACT_1M_4V, 5.53 __IDD_ACT_1M_5V, 5.54 __IDD_ACT_1M_12V, 5.55 __IDD_ACT_1M_14V
	f_{SW} = 2 MHz, C_{LOAD} = 100pF for OUTA, OUTB, SRA, and SRB		14	19.5	mA	5.60 __IDD_ACT_2M_4V, 5.61 __IDD_ACT_2M_5V, 5.62 __IDD_ACT_2M_12V, 5.63 __IDD_ACT_2M_14V
$I_{DD(dis)}$ Standby current	EN = 0 V			3	mA	5.1 __IDD_DIS_4V, 5.2 __IDD_DIS_5V, 5.3 __IDD_DIS_12V 5.4 __IDD_DIS_14V
VLDO Internal linear regulator output voltage	5 V ≤VIN ≤ 14 V, fsw ≤ 1 MHz	4.75	5	5.2	V	5.65 __V_LDO_100K_5V, 5.66 __V_LDO_100K_12V, 5.67 __V_LDO_100K_14V, 5.69 __V_LDO_200K_5V, 5.70 __V_LDO_200K_12V, 5.71 __V_LDO_200K_14V, 5.73 __V_LDO_500K_5V, 5.74 __V_LDO_500K_12V, 5.75 __V_LDO_500K_14V, 5.77 __V_LDO_1M_5V, 5.78 __V_LDO_1M_12V, 5.79 __V_LDO_1M_14V
	5 V ≤ VIN ≤ 14 V, fsw = 2 MHz	4.65	5	5.2	V	5.85 __V_LDO_2M_5V, 5.86 __V_LDO_2M_12V, 5.87 __V_LDO_2M_14V
ENABLE AND UNDERVOLTAGE LOCKOUT						
V_{ENR} EN threshold rising		0.57	0.6	0.65	V	6.5 __V_EN_RISE_4V, 6.8 __V_EN_RISE_5V, 6.11 __V_EN_RISE_12V, 6.14 __V_EN_RISE_14V
V_{ENF} EN threshold falling		0.47	0.5	0.55	V	6.6 __V_EN_FALL_4V, 6.9 __V_EN_FALL_5V, 6.12 __V_EN_FALL_12V, 6.15 __V_EN_FALL_14V
V_{ENH} EN hysteresis voltage		85	95	105	mV	6.7 __V_EN_HYS_4V, 6.10 __V_EN_HYS_5V, 6.13 __V_EN_HYS_12V, 6.16 __V_EN_HYS_14V
I_{EN} EN pin input leakage current	VIN = 14 V, EN = 5V		5	50	nA	6.1 __I_EN_LEAK_4V, 6.2 __I_EN_LEAK_5V, 6.3 __I_EN_LEAK_12V, 6.4 __I_EN_LEAK_14V
$VLDO_{UVLOR}$ VLDO UVLO rising		3.44	3.55	3.66	V	6.34 __UVLO_VLDO_RISE_1MHz, 6.37 __UVLO_VLDO_RISE_100kHz, 6.40 __UVLO_VLDO_RISE_200kHz, 6.43 __UVLO_VLDO_RISE_500kHz, 6.46 __UVLO_VLDO_RISE_2MHz
$VLDO_{UVLOF}$ VLDO UVLO falling		3.29	3.4	3.51	V	6.35 __UVLO_VLDO_FALL_1MHz, 6.38 __UVLO_VLDO_FALL_100kHz, 6.41 __UVLO_VLDO_FALL_200kHz, 6.44 __UVLO_VLDO_FALL_500kHz, 6.47 __UVLO_VLDO_FALL_2MHz
$VLDO_{UVLOH}$ VLDO UVLO hysteresis		115	135	160	mV	6.36 __UVLO_VLDO_HYS_1MHz, 6.39 __UVLO_VLDO_HYS_100kHz, 6.42 __UVLO_VLDO_HYS_200kHz, 6.45 __UVLO_VLDO_HYS_500kHz, 6.48 __UVLO_VLDO_HYS_2MHz
SOFT START						
I_{SS} Soft-start current	SS = 0.3 V	1.98	2.7	3.32	µA	7.1 __I_SS_4V, 7.3 __I_SS_5V, 7.5 __I_SS_12V, 7.7 __I_SS_14V
ERROR AMPLIFIER						
EA_{gm} Transconductance	–2 µA < I_{COMP} < 2 µA, $V_{(COMP)}$ = 1 V	1150	1800	2500	µA/V	8.9 __EA_GM_4V, 8.10 __EA_GM_5V, 8.11 __EA_GM_12V, 8.12 __EA_GM_14V

Table 3-1. TPS7H5005-SEP and TPS7H5001-SP QMLP Electrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5005-SEP and TPS7H5001-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
EA_{ISRC} Error amplifier source current	$V_{(COMP)}$ = 1 V, 100-mV input overdrive	100		190	µA	8.13 __EA_I_SOURCE_4V, 8.14 __EA_I_SOURCE_5V, 8.15 __EA_I_SOURCE_12V, 8.16 __EA_I_SOURCE_14V
EA_{ISNK} Error amplifier sink current	$V_{(COMP)}$ = 1 V, 100-mV input overdrive	100		190	µA	8.17 __EA_I_SINK_4V, 8.18 __EA_I_SINK_5V, 8.19 __EA_I_SINK_12V, 8.20 __EA_I_SINK_14V
EA_{OS} Error amplifier offset voltage		–2		2	mV	8.5 __EA_OS_4V, 8.6 __EA_OS_5V, 8.7 __EA_OS_12V, 8.8 __EA_OS_14V
OSCILLATOR						
$SYNC_{RT}$ SYNC out low-to-high rise time (10%/90%)	C_{LOAD} = 25 pF		6	15	ns	9.1 __T_SYNC_RISE_100kHz_4V, 9.5 __T_SYNC_RISE_200kHz_4V, 9.9 __T_SYNC_RISE_500kHz_4V, 9.13 __T_SYNC_RISE_1MHz_4V, 9.17 __T_SYNC_RISE_1p5MHz_4V, 9.21 __T_SYNC_RISE_2MHz_4V, 9.25 __T_SYNC_RISE_100kHz_5V, 9.29 __T_SYNC_RISE_200kHz_5V, 9.33 __T_SYNC_RISE_500kHz_5V, 9.37 __T_SYNC_RISE_1MHz_5V, 9.41 __T_SYNC_RISE_1p5MHz_5V, 9.45 __T_SYNC_RISE_2MHz_5V, 9.49 __T_SYNC_RISE_100kHz_12V, 9.53 __T_SYNC_RISE_200kHz_12V, 9.57 __T_SYNC_RISE_500kHz_12V, 9.61 __T_SYNC_RISE_1MHz_12V, 9.65 __T_SYNC_RISE_1p5MHz_12V, 9.69 __T_SYNC_RISE_2MHz_12V, 9.73 __T_SYNC_RISE_100kHz_14V, 9.77 __T_SYNC_RISE_200kHz_14V, 9.81 __T_SYNC_RISE_500kHz_14V, 9.85 __T_SYNC_RISE_1MHz_14V, 9.89 __T_SYNC_RISE_1p5MHz_14V, 9.93 __T_SYNC_RISE_2MHz_14V
$SYNC_{FT}$ SYNC out high-to-low fall time (10%/90%)	C_{LOAD} = 25 pF		6	17	ns	9.2 __T_SYNC_FALL_100kHz_4V, 9.14 __T_SYNC_FALL_1MHz_4V, 9.22 __T_SYNC_FALL_2MHz_4V, 9.26 __T_SYNC_FALL_100kHz_5V, 9.38 __T_SYNC_FALL_1MHz_5V, 9.46 __T_SYNC_FALL_2MHz_5V, 9.74 __T_SYNC_FALL_100kHz_14V, 9.86 __T_SYNC_FALL_1MHz_14V, 9.94 __T_SYNC_FALL_2MHz_14V
$SYNC_{OL}$ SYNC out low level	I_{OL}= 10 mA			500	mV	9.186__SYNC_VOL_4V, 9.187__SYNC_VOL_5V, 9.188__SYNC_VOL_12V, 9.189__SYNC_VOL_14V
EXT_{DT} Externally set frequency detection time	RT = Open, f = 200 kHz			20	µs	9.185__T_SYNC_DETECT
FSW_{EXT} Externally set frequency	RT = 1.07 MΩ	95	105	115	kHz	9.4 __FSW_EXT_RT_100kHz_4V, 9.28 __FSW_EXT_RT_100kHz_5V, 9.52 __FSW_EXT_RT_100kHz_12V, 9.76 __FSW_EXT_RT_100kHz_14V
	RT = 511 kΩ	190	210	230	kHz	9.8 __FSW_EXT_RT_200kHz_4V, 9.32 __FSW_EXT_RT_200kHz_5V, 9.56 __FSW_EXT_RT_200kHz_12V, 9.80 __FSW_EXT_RT_200kHz_14V
	RT =90.9 kΩ	900	1000	1100	kHz	9.16 __FSW_EXT_RT_1MHz_4V, 9.40 __FSW_EXT_RT_1MHz_5V, 9.64 __FSW_EXT_RT_1MHz_12V, 9.88 __FSW_EXT_RT_1MHz_14V
	RT = 34.8 kΩ	1700	2000	2300	kHz	9.24 __FSW_EXT_RT_2MHz_4V, 9.48 __FSW_EXT_RT_2MHz_5V, 9.72 __FSW_EXT_RT_2MHz_12V, 9.96 __FSW_EXT_RT_2MHz_14V
VOLTAGE REFERENCE						
VREF Internal voltage reference initial tolerance	Measured at COMP, 25°C	0.609	0.613	0.615	V	8.1 __VREF_4V, 8.2 __VREF_5V, 8.3 __VREF_12V, 8.4 __VREF_14V

Table 3-1. TPS7H5005-SEP and TPS7H5001-SP QMLP Electrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5005-SEP and TPS7H5001-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
REFCAP REFCAP voltage	REFCAP = 470 nF	1.213	1.225	1.237	V	5.88 __V_REFCAP_100K_4V, 5.89 __V_REFCAP_100K_5V, 5.90 __V_REFCAP_100K_12V, 5.91 __V_REFCAP_100K_14V, 5.92 __V_REFCAP_200K_4V, 5.93 __V_REFCAP_200K_5V, 5.94 __V_REFCAP_200K_12V, 5.95 __V_REFCAP_200K_14V, 5.96 __V_REFCAP_500K_4V, 5.97 __V_REFCAP_500K_5V, 5.98 __V_REFCAP_500K_12V, 5.99 __V_REFCAP_500K_14V, 5.100__V_REFCAP_1M_4V, 5.101__V_REFCAP_1M_5V, 5.102__V_REFCAP_1M_12V, 5.103__V_REFCAP_1M_14V, 5.104__V_REFCAP_1P5M_4V, 5.105__V_REFCAP_1P5M_5V, 5.106__V_REFCAP_1P5M_12V, 5.107__V_REFCAP_1P5M_14V, 5.108__V_REFCAP_2M_4V, 5.109__V_REFCAP_2M_5V, 5.110__V_REFCAP_2M_12V, 5.111__V_REFCAP_2M_14V
CURRENT SENSE, CURRENT LIMIT, AND HICCUP						
CCSR	COMP to CS_ILIM ratio	2.00	2.06	2.12		10.49 __CCSR_Ratio
V_{CS_ILIM} Current limit (over-current) threshold			1.05	1.09	V	10.1 __V_CS_ILIM_OC_Rise_4V, 10.3 __V_CS_ILIM_OC_Rise_5V, 10.5 __V_CS_ILIM_OC_Rise_12V, 10.7 __V_CS_ILIM_OC_Rise_14V
FAULT						
V_{FLTR} FLT threshold rising		0.57	0.6	0.65	V	12.1 __V_FAULT_RISE_4V, 12.4 __V_FAULT_RISE_5V, 12.7 __V_FAULT_RISE_12V, 12.10 __V_FAULT_RISE_14V
V_{FLTF} FLT threshold falling		0.47	0.5	0.55	V	12.2 __V_FAULT_FALL_4V, 12.5 __V_FAULT_FALL_5V, 12.8 __V_FAULT_FALL_12V, 12.11 __V_FAULT_FALL_14V
V_{FLTH} FLT hysteresis voltage		90	100	110	mV	12.3 __V_FAULT_HYS_4V, 12.6 __V_FAULT_HYS_5V, 12.9 __V_FAULT_HYS_12V, 12.12 __V_FAULT_HYS_14V
T_{FLT} FLT minimum pulse width	V_{FLT} = 1 V	0.4		1.4	µs	12.14 __T_FAULT_MIN
t_{DFLT} FLT delay duration	f_{sw} = 100 kHz	140	152	169	µs	12.15 __T_FAULT_DELAY_100kHz
	f_{sw} = 200 kHz	66	78	86	µs	12.17 __T_FAULT_DELAY_200kHz
	f_{sw} = 1 MHz	14	17	21	µs	12.21 __T_FAULT_DELAY_1MHz
	f_{sw} = 2 MHz	7	11	14	µs	12.23 __T_FAULT_DELAY_2MHz
PRIMARY AND SYNCHRONOUS RECTIFIER OUTPUTS						
Rise/fall time	R_{LOAD} = 50 kΩ, C_{LOAD} = 100 pF, 10% to 90%		10	17	ns	13.1 __OUTA_RISE_1MHz_4V, 13.9 __OUTA_RISE_1MHz_5V, 13.17 __OUTA_RISE_1MHz_12V, 13.25 __OUTA_RISE_1MHz_14V, 13.3 __OUTA_FALL_1MHz_4V, 13.11 __OUTA_FALL_1MHz_5V, 13.19 __OUTA_FALL_1MHz_12V, 13.27 __OUTA_FALL_1MHz_14V, 13.2 __OUTB_RISE_1MHz_4V, 13.10 __OUTB_RISE_1MHz_5V, 13.18 __OUTB_RISE_1MHz_12V, 13.26 __OUTB_RISE_1MHz_14V, 13.4 __OUTB_FALL_1MHz_4V, 13.12 __OUTB_FALL_1MHz_5V, 13.20 __OUTB_FALL_1MHz_12V, 13.28 __OUTB_FALL_1MHz_14V
t_{MIN} Minimum on-time LEB = 10 kΩ	LEB = 10 kΩ, 5 V ≤ VIN ≤ 14 V			85	ns	13.145__OUT_T_ON_MIN

Table 3-1. TPS7H5005-SEP and TPS7H5001-SP QMLP Electrical Parameters Table (continued)

PARAMETER	TEST CONDITION	TPS7H5005-SEP and TPS7H5001-SP QMLP DATA SHEET				TEST #
		MIN	TYP	MAX	UNIT	
TD_{PS} Primary off to secondary on dead time	PS = floating, 5 V ≤ VIN ≤ 14 V, 90% of OUTx falling edge to 10% of SRx rising edge with OUTx and SRx floating	5	8	11	ns	13.37 __PSA_DT_0ns_1M_5V, 13.38 __PSB_DT_0ns_1M_5V, 13.41 __PSA_DT_0ns_1M_12V, 13.42 __PSB_DT_0ns_1M_12V, 13.45 __PSA_DT_0ns_1M_14V, 13.46 __PSB_DT_0ns_1M_14V
	PS = 49.9 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of OUTx falling edge to 10% of SRx rising edge with OUTx and SRx floating	43	50	55	ns	13.53 __PSA_DT_50ns_1M_5V, 13.54 __PSB_DT_50ns_1M_5V, 13.57 __PSA_DT_50ns_1M_12V, 13.58 __PSB_DT_50ns_1M_12V, 13.61 __PSA_DT_50ns_1M_14V, 13.62 __PSB_DT_50ns_1M_14V
	PS = 107 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of OUTx falling edge to 10% of SRx rising edge with OUTx and SRx floating	85	100	110	ns	13.69 __PSA_DT_100ns_1M_5V, 13.70 __PSB_DT_100ns_1M_5V, 13.73 __PSA_DT_100ns_1M_12V, 13.74 __PSB_DT_100ns_1M_12V, 13.77 __PSA_DT_100ns_1M_14V, 13.78 __PSB_DT_100ns_1M_14V
TD_{SP} Secondary off to primary on dead time	SP = floating, 5 V ≤ VIN ≤ 14 V, 90% of SRx falling edge to 10% of OUTx rising edge with OUTx and SRx floating	5	8	11	ns	13.39 __SPA_DT_0ns_1M_5V, 13.40 __SPB_DT_0ns_1M_5V, 13.43 __SPA_DT_0ns_1M_12V, 13.44 __SPB_DT_0ns_1M_12V, 13.47 __SPA_DT_0ns_1M_14V, 13.48 __SPB_DT_0ns_1M_14V
	SP = 49.9 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of SRx falling edge to 10% of OUTx rising edge with OUTx and SRx floating	43	50	55	ns	13.55 __SPA_DT_50ns_1M_5V, 13.56 __SPB_DT_50ns_1M_5V, 13.59 __SPA_DT_50ns_1M_12V, 13.60 __SPB_DT_50ns_1M_12V, 13.63 __SPA_DT_50ns_1M_14V, 13.64 __SPB_DT_50ns_1M_14V
	SP = 100 kΩ, 5 V ≤ VIN ≤ 14 V, 90% of SRx falling edge to 10% of OUTx rising edge with OUTx and SRx floating	85	100	110	ns	13.71 __SPA_DT_100ns_1M_5V, 13.72 __SPB_DT_100ns_1M_5V, 13.75 __SPA_DT_100ns_1M_12V, 13.76 __SPB_DT_100ns_1M_12V, 13.79 __SPA_DT_100ns_1M_14V, 13.80 __SPB_DT_100ns_1M_14V
DUTY CYCLE						
D_{MAX} Maximum duty cycle	DCL = AVSS	45	48	50	%	13.160__MAX_DC_DCL_AVSS
	DCL = floating	70	75	80	%	13.163__MAX_DC_DCL_OPEN
	DCL =VLDO			100	%	13.166__MAX_DC_DCL_VLDO

4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H5005-SEP Radiation-Hardness-Assured Si and GaN Dual Output Controller* data sheet (SLVSGG1)
- Texas Instruments, TPS7H500x-SP Radiation-Hardness-Assured 2-MHz Current Mode PWM Controllers
- Texas Instruments, *TPS7H500x-SEP Evaluation Module (EVM)* user's guide
- Texas Instruments, *TPS7H500x-SEP Single-Event Effects (SEE)* Radiation Report

4.2 Reference Documents

Texas Instruments neutron irradiation test follow the guideline from MIL-STD-883 TM 1017. The document is available in Defense Logistic Agency's website.

A Appendix: NDD Report Data

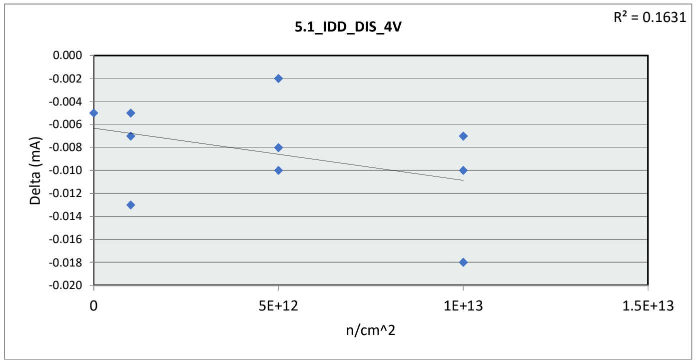
This appendix contains the NDD report data.

NDD Characterization Report
TPS7H5005-SEP

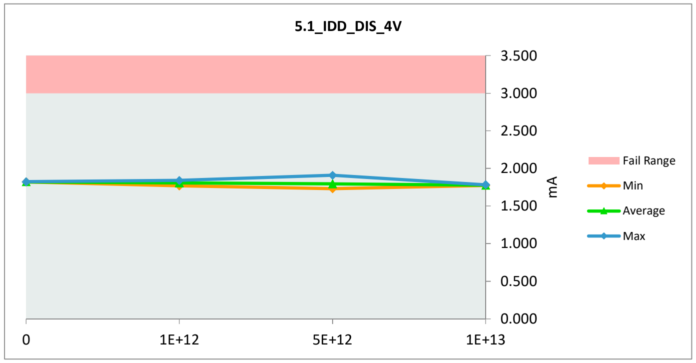
NDD Characterization Report
TPS7H5005-SEP

	5.1_IDD_DIS_4V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	3	3
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.827	1.822	-0.005
1E+12	1	1.826	1.813	-0.013
1E+12	2	1.774	1.769	-0.005
1E+12	3	1.847	1.840	-0.007
5E+12	4	1.741	1.731	-0.010
5E+12	5	1.916	1.908	-0.008
5E+12	6	1.745	1.743	-0.002
1E+13	7	1.784	1.774	-0.010
1E+13	8	1.794	1.776	-0.018
1E+13	9	1.790	1.783	-0.007
	Max	1.916	1.908	-0.002
	Average	1.804	1.796	-0.009
	Min	1.741	1.731	-0.018
	Std Dev	0.052	0.052	0.005

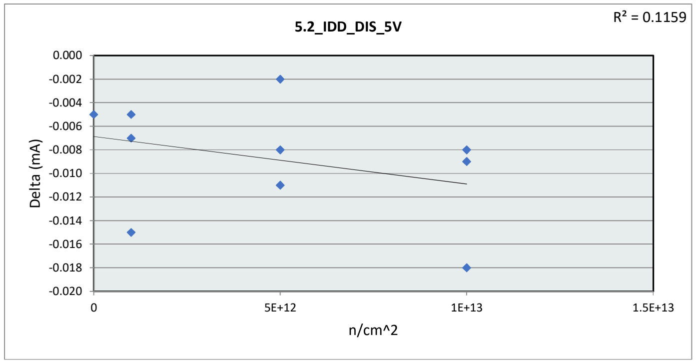


	5.1_IDD_DIS_4V			
Test Site				
Tester				
Test Number				
Max Limit	3	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.822	1.769	1.731	1.774
Average	1.822	1.807	1.794	1.778
Max	1.822	1.840	1.908	1.783
UL	3.000	3.000	3.000	3.000

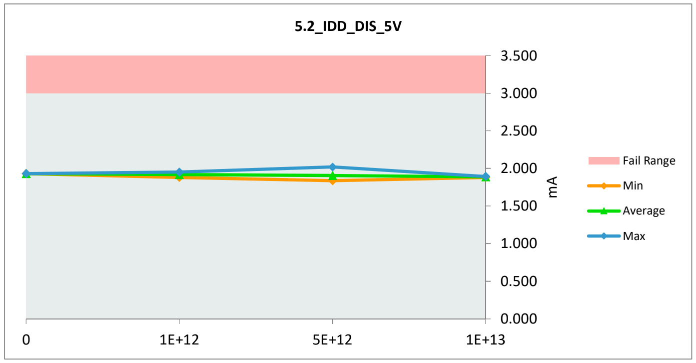


NDD Characterization Report
TPS7H5005-SEP

		5.2_IDD_DIS_5V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		3	3	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.937	1.932	-0.005
1E+12	1	1.937	1.922	-0.015
1E+12	2	1.885	1.880	-0.005
1E+12	3	1.959	1.952	-0.007
5E+12	4	1.849	1.838	-0.011
5E+12	5	2.027	2.019	-0.008
5E+12	6	1.855	1.853	-0.002
1E+13	7	1.890	1.881	-0.009
1E+13	8	1.903	1.885	-0.018
1E+13	9	1.902	1.894	-0.008
	Max	2.027	2.019	-0.002
	Average	1.914	1.906	-0.009
	Min	1.849	1.838	-0.018
	Std Dev	0.053	0.053	0.005



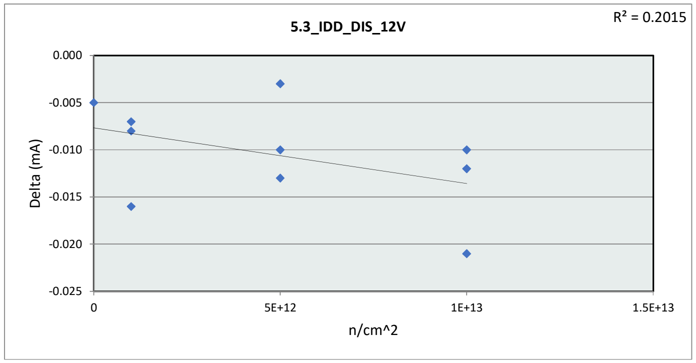
	5.2_IDD_DIS_5V			
Test Site				
Tester				
Test Number				
Max Limit	3	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.932	1.880	1.838	1.881
Average	1.932	1.918	1.903	1.887
Max	1.932	1.952	2.019	1.894
UL	3.000	3.000	3.000	3.000



NDD Characterization Report
TPS7H5005-SEP

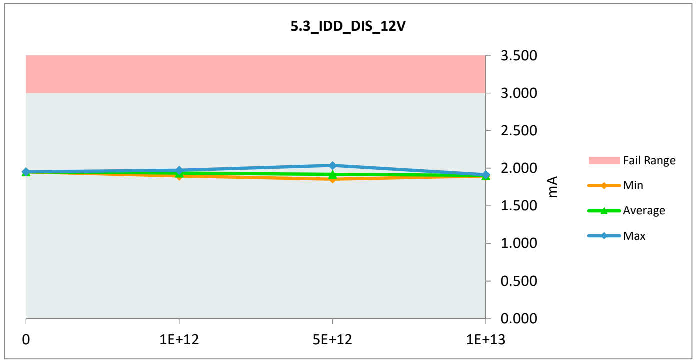
	5.3_IDD_DIS_12V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	3	3
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.957	1.952	-0.005
1E+12	1	1.956	1.940	-0.016
1E+12	2	1.903	1.896	-0.007
1E+12	3	1.980	1.972	-0.008
5E+12	4	1.868	1.855	-0.013
5E+12	5	2.045	2.035	-0.010
5E+12	6	1.872	1.869	-0.003
1E+13	7	1.908	1.896	-0.012
1E+13	8	1.923	1.902	-0.021
1E+13	9	1.924	1.914	-0.010
	Max	2.045	2.035	-0.003
	Average	1.934	1.923	-0.010
	Min	1.868	1.855	-0.021
	Std Dev	0.053	0.053	0.005



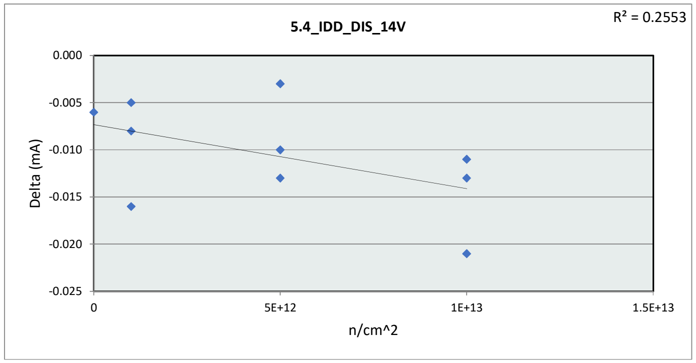
	5.3_IDD_DIS_12V	
Test Site		
Tester		
Test Number		
Max Limit	3	mA
Min Limit		mA

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.952	1.896	1.855	1.896
Average	1.952	1.936	1.920	1.904
Max	1.952	1.972	2.035	1.914
UL	3.000	3.000	3.000	3.000

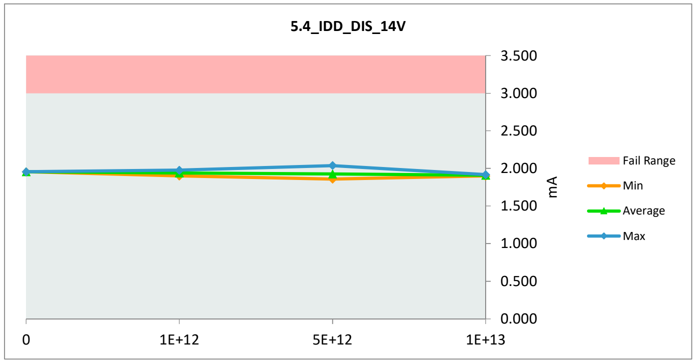


NDD Characterization Report
TPS7H5005-SEP

		5.4_IDD_DIS_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		3	3	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.962	1.956	-0.006
1E+12	1	1.961	1.945	-0.016
1E+12	2	1.906	1.901	-0.005
1E+12	3	1.984	1.976	-0.008
5E+12	4	1.872	1.859	-0.013
5E+12	5	2.049	2.039	-0.010
5E+12	6	1.876	1.873	-0.003
1E+13	7	1.913	1.900	-0.013
1E+13	8	1.927	1.906	-0.021
1E+13	9	1.929	1.918	-0.011
	Max	2.049	2.039	-0.003
	Average	1.938	1.927	-0.011
	Min	1.872	1.859	-0.021
	Std Dev	0.053	0.053	0.005

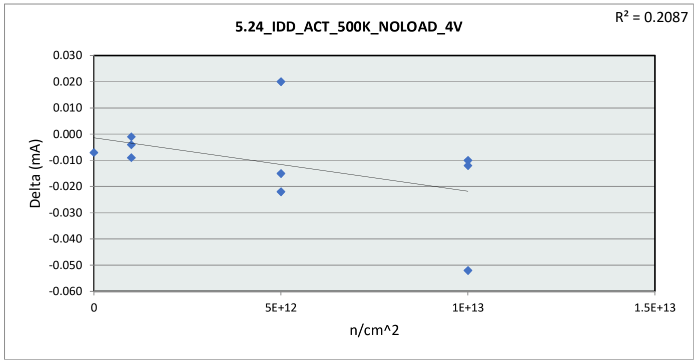


	5.4_IDD_DIS_14V			
Test Site				
Tester				
Test Number				
Max Limit	3	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.956	1.901	1.859	1.900
Average	1.956	1.941	1.924	1.908
Max	1.956	1.976	2.039	1.918
UL	3.000	3.000	3.000	3.000

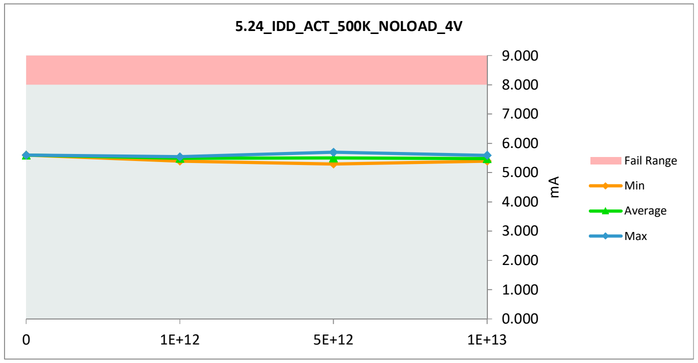


NDD Characterization Report
TPS7H5005-SEP

		5.24_IDD_ACT_500K_NOLOAD_4V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		8	8	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.605	5.598	-0.007
1E+12	1	5.543	5.542	-0.001
1E+12	2	5.401	5.397	-0.004
1E+12	3	5.546	5.537	-0.009
5E+12	4	5.320	5.298	-0.022
5E+12	5	5.714	5.699	-0.015
5E+12	6	5.487	5.507	0.020
1E+13	7	5.404	5.392	-0.012
1E+13	8	5.509	5.457	-0.052
1E+13	9	5.602	5.592	-0.010
	Max	5.714	5.699	0.020
	Average	5.513	5.502	-0.011
	Min	5.320	5.298	-0.052
	Std Dev	0.116	0.118	0.018

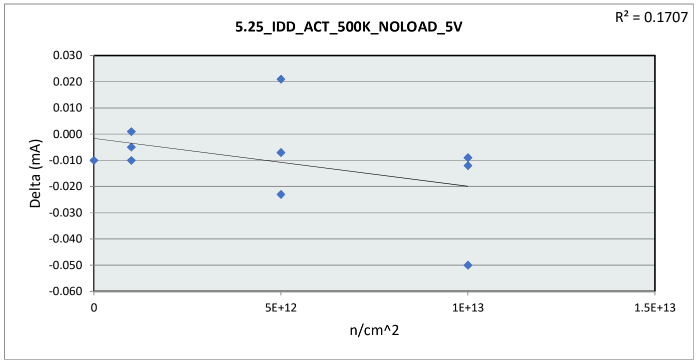


	5.24_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	5.598	5.397	5.298	5.392
Average	5.598	5.492	5.501	5.480
Max	5.598	5.542	5.699	5.592
UL	8.000	8.000	8.000	8.000

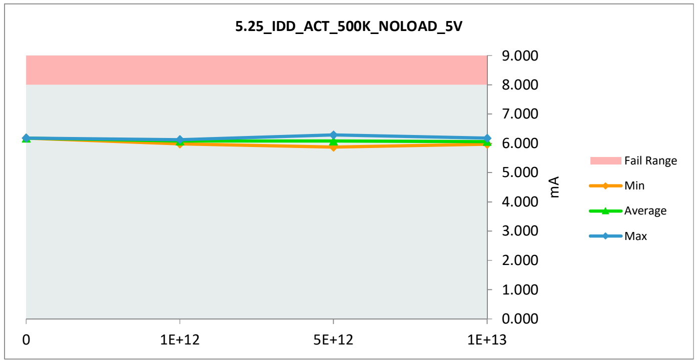


NDD Characterization Report
TPS7H5005-SEP

		5.25_IDD_ACT_500K_NOLOAD_5V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		8	8	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.190	6.180	-0.010
1E+12	1	6.126	6.127	0.001
1E+12	2	5.983	5.978	-0.005
1E+12	3	6.128	6.118	-0.010
5E+12	4	5.895	5.872	-0.023
5E+12	5	6.293	6.286	-0.007
5E+12	6	6.070	6.091	0.021
1E+13	7	5.982	5.970	-0.012
1E+13	8	6.091	6.041	-0.050
1E+13	9	6.188	6.179	-0.009
	Max	6.293	6.286	0.021
	Average	6.095	6.084	-0.010
	Min	5.895	5.872	-0.050
	Std Dev	0.118	0.122	0.018



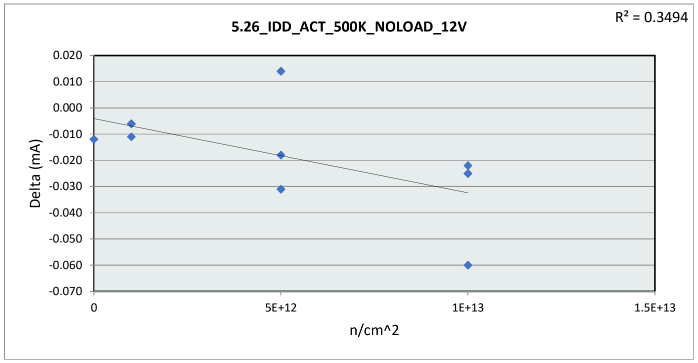
	5.25_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.180	5.978	5.872	5.970
Average	6.180	6.074	6.083	6.063
Max	6.180	6.127	6.286	6.179
UL	8.000	8.000	8.000	8.000



NDD Characterization Report
TPS7H5005-SEP

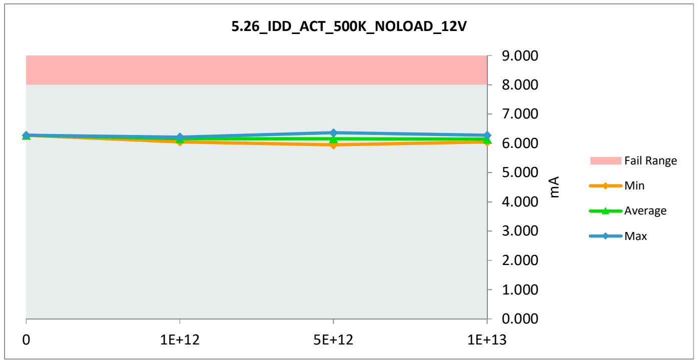
	5.26_IDD_ACT_500K_NOLOAD_12V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	8	8
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.287	6.275	-0.012
1E+12	1	6.215	6.209	-0.006
1E+12	2	6.059	6.053	-0.006
1E+12	3	6.224	6.213	-0.011
5E+12	4	5.979	5.948	-0.031
5E+12	5	6.378	6.360	-0.018
5E+12	6	6.151	6.165	0.014
1E+13	7	6.068	6.043	-0.025
1E+13	8	6.179	6.119	-0.060
1E+13	9	6.295	6.273	-0.022
	Max	6.378	6.360	0.014
	Average	6.184	6.166	-0.018
	Min	5.979	5.948	-0.060
	Std Dev	0.123	0.126	0.019



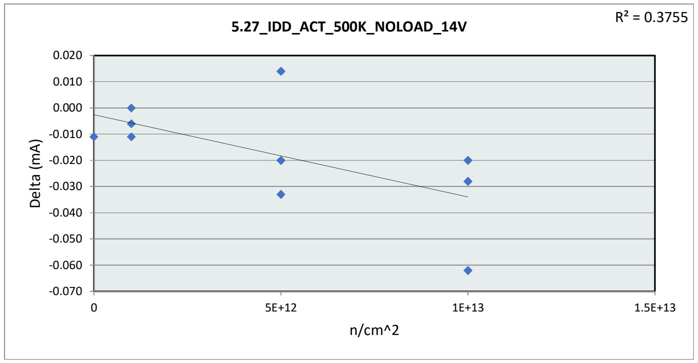
	5.26_IDD_ACT_500K_NOLOAD	
Test Site		
Tester		
Test Number		
Max Limit	8	mA
Min Limit		mA

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.275	6.053	5.948	6.043
Average	6.275	6.158	6.158	6.145
Max	6.275	6.213	6.360	6.273
UL	8.000	8.000	8.000	8.000

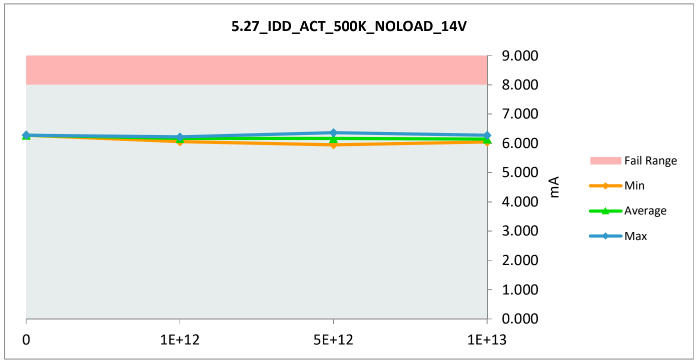


NDD Characterization Report
TPS7H5005-SEP

		5.27_IDD_ACT_500K_NOLOAD_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		8	8	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.290	6.279	-0.011
1E+12	1	6.216	6.216	0.000
1E+12	2	6.064	6.058	-0.006
1E+12	3	6.229	6.218	-0.011
5E+12	4	5.984	5.951	-0.033
5E+12	5	6.385	6.365	-0.020
5E+12	6	6.154	6.168	0.014
1E+13	7	6.075	6.047	-0.028
1E+13	8	6.186	6.124	-0.062
1E+13	9	6.296	6.276	-0.020
	Max	6.385	6.365	0.014
	Average	6.188	6.170	-0.018
	Min	5.984	5.951	-0.062
	Std Dev	0.122	0.126	0.021



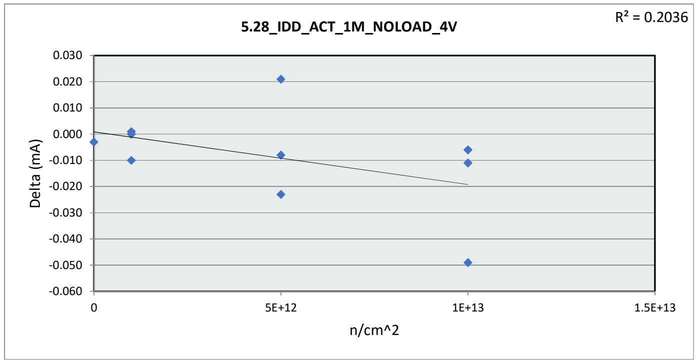
	5.27_IDD_ACT_500K_NOLOAD			
Test Site				
Tester				
Test Number				
Max Limit	8	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.279	6.058	5.951	6.047
Average	6.279	6.164	6.161	6.149
Max	6.279	6.218	6.365	6.276
UL	8.000	8.000	8.000	8.000



NDD Characterization Report
TPS7H5005-SEP

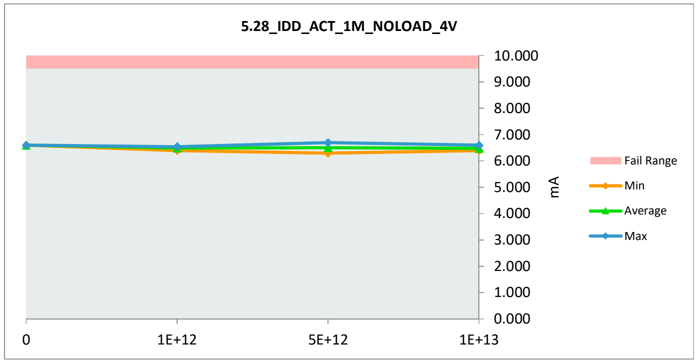
	5.28_IDD_ACT_1M_NOLOAD_4V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	9.5	9.5
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.598	6.595	-0.003
1E+12	1	6.537	6.538	0.001
1E+12	2	6.394	6.394	0.000
1E+12	3	6.536	6.526	-0.010
5E+12	4	6.315	6.292	-0.023
5E+12	5	6.700	6.692	-0.008
5E+12	6	6.488	6.509	0.021
1E+13	7	6.402	6.391	-0.011
1E+13	8	6.499	6.450	-0.049
1E+13	9	6.600	6.594	-0.006
	Max	6.700	6.692	0.021
	Average	6.507	6.498	-0.009
	Min	6.315	6.292	-0.049
	Std Dev	0.114	0.118	0.018



	5.28_IDD_ACT_1M_NOLOAD_	
Test Site		
Tester		
Test Number		
Max Limit	9.5	mA
Min Limit		mA

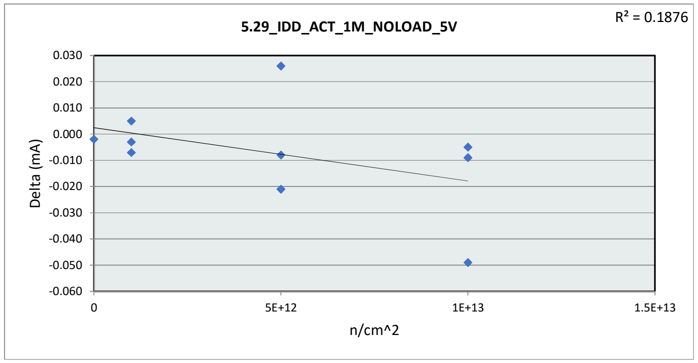
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.595	6.394	6.292	6.391
Average	6.595	6.486	6.498	6.478
Max	6.595	6.538	6.692	6.594
UL	9.500	9.500	9.500	9.500



NDD Characterization Report
TPS7H5005-SEP

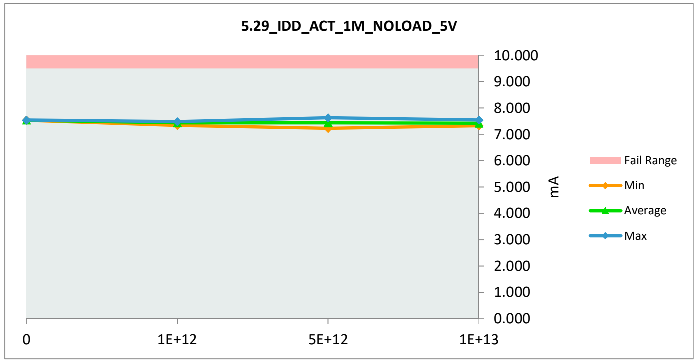
	5.29_IDD_ACT_1M_NOLOAD_5V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	9.5	9.5
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.541	7.539	-0.002
1E+12	1	7.476	7.481	0.005
1E+12	2	7.337	7.334	-0.003
1E+12	3	7.473	7.466	-0.007
5E+12	4	7.247	7.226	-0.021
5E+12	5	7.639	7.631	-0.008
5E+12	6	7.429	7.455	0.026
1E+13	7	7.341	7.332	-0.009
1E+13	8	7.439	7.390	-0.049
1E+13	9	7.548	7.543	-0.005
	Max	7.639	7.631	0.026
	Average	7.447	7.440	-0.007
	Min	7.247	7.226	-0.049
	Std Dev	0.116	0.120	0.019



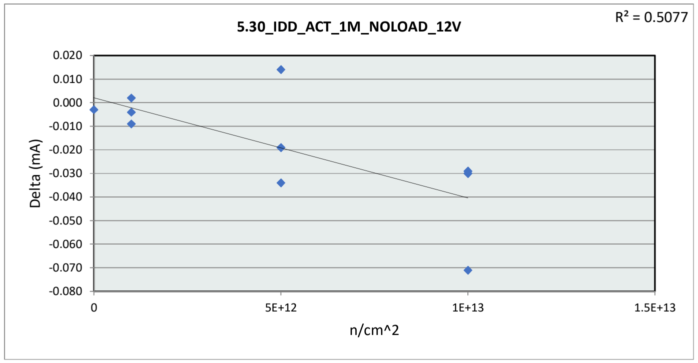
	5.29_IDD_ACT_1M_NOLOAD_5	
Test Site		
Tester		
Test Number		
Max Limit	9.5	mA
Min Limit		mA

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.539	7.334	7.226	7.332
Average	7.539	7.427	7.437	7.422
Max	7.539	7.481	7.631	7.543
UL	9.500	9.500	9.500	9.500

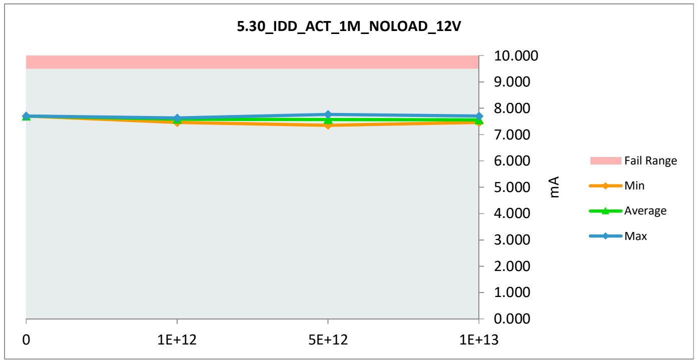


NDD Characterization Report
TPS7H5005-SEP

		5.30_IDD_ACT_1M_NOLOAD_12V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.5	9.5	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.703	7.700	-0.003
1E+12	1	7.625	7.627	0.002
1E+12	2	7.466	7.462	-0.004
1E+12	3	7.639	7.630	-0.009
5E+12	4	7.389	7.355	-0.034
5E+12	5	7.786	7.767	-0.019
5E+12	6	7.571	7.585	0.014
1E+13	7	7.491	7.462	-0.029
1E+13	8	7.596	7.525	-0.071
1E+13	9	7.729	7.699	-0.030
	Max	7.786	7.767	0.014
	Average	7.600	7.581	-0.018
	Min	7.389	7.355	-0.071
	Std Dev	0.124	0.129	0.024

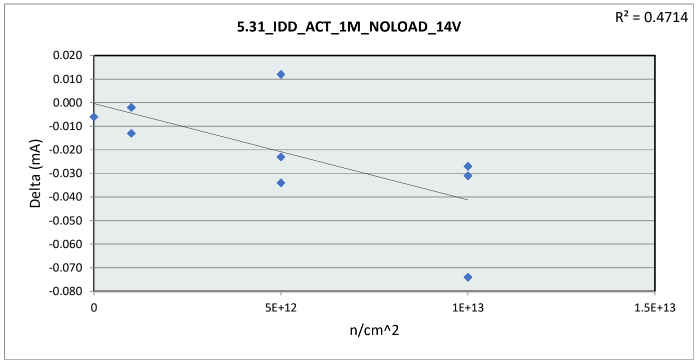


	5.30_IDD_ACT_1M_NOLOAD_1			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.700	7.462	7.355	7.462
Average	7.700	7.573	7.569	7.562
Max	7.700	7.630	7.767	7.699
UL	9.500	9.500	9.500	9.500

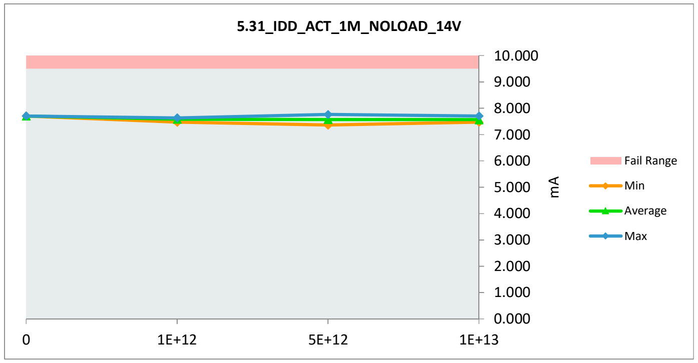


NDD Characterization Report
TPS7H5005-SEP

		5.31_IDD_ACT_1M_NOLOAD_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.5	9.5	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.711	7.705	-0.006
1E+12	1	7.632	7.630	-0.002
1E+12	2	7.470	7.468	-0.002
1E+12	3	7.645	7.632	-0.013
5E+12	4	7.394	7.360	-0.034
5E+12	5	7.792	7.769	-0.023
5E+12	6	7.577	7.589	0.012
1E+13	7	7.495	7.464	-0.031
1E+13	8	7.601	7.527	-0.074
1E+13	9	7.732	7.705	-0.027
	Max	7.792	7.769	0.012
	Average	7.605	7.585	-0.020
	Min	7.394	7.360	-0.074
	Std Dev	0.125	0.129	0.024

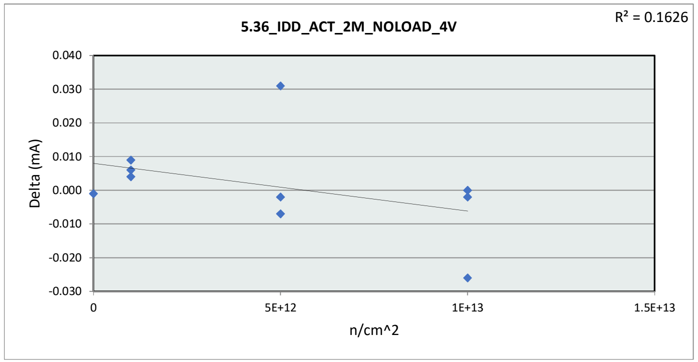


	5.31_IDD_ACT_1M_NOLOAD_1			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.705	7.468	7.360	7.464
Average	7.705	7.577	7.573	7.565
Max	7.705	7.632	7.769	7.705
UL	9.500	9.500	9.500	9.500

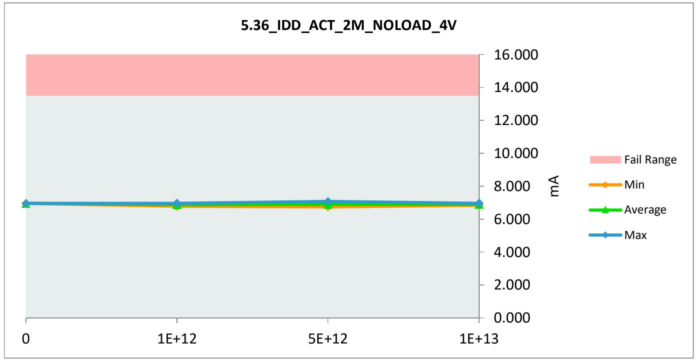


NDD Characterization Report
TPS7H5005-SEP

		5.36_IDD_ACT_2M_NOLOAD_4V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		13.5	13.5	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.960	6.959	-0.001
1E+12	1	6.906	6.915	0.009
1E+12	2	6.774	6.780	0.006
1E+12	3	6.958	6.962	0.004
5E+12	4	6.759	6.752	-0.007
5E+12	5	7.069	7.067	-0.002
5E+12	6	6.886	6.917	0.031
1E+13	7	6.855	6.853	-0.002
1E+13	8	6.885	6.859	-0.026
1E+13	9	6.961	6.961	0.000
	Max	7.069	7.067	0.031
	Average	6.901	6.903	0.001
	Min	6.759	6.752	-0.026
	Std Dev	0.093	0.094	0.014

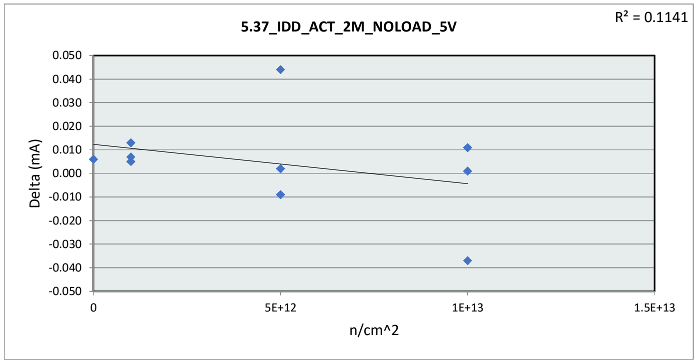


	5.36_IDD_ACT_2M_NOLOAD_			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.959	6.780	6.752	6.853
Average	6.959	6.886	6.912	6.891
Max	6.959	6.962	7.067	6.961
UL	13.500	13.500	13.500	13.500

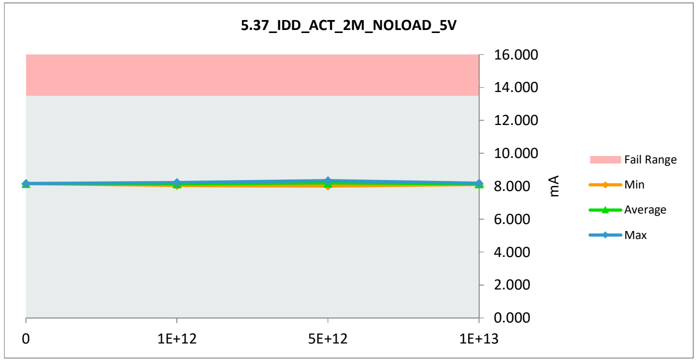


NDD Characterization Report
TPS7H5005-SEP

		5.37_IDD_ACT_2M_NOLOAD_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	13.5	13.5	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.150	8.156	0.006
1E+12	1	8.147	8.154	0.007
1E+12	2	8.032	8.045	0.013
1E+12	3	8.217	8.222	0.005
5E+12	4	8.022	8.013	-0.009
5E+12	5	8.335	8.337	0.002
5E+12	6	8.192	8.236	0.044
1E+13	7	8.110	8.111	0.001
1E+13	8	8.178	8.141	-0.037
1E+13	9	8.166	8.177	0.011
	Max	8.335	8.337	0.044
	Average	8.155	8.159	0.004
	Min	8.022	8.013	-0.037
	Std Dev	0.090	0.094	0.020

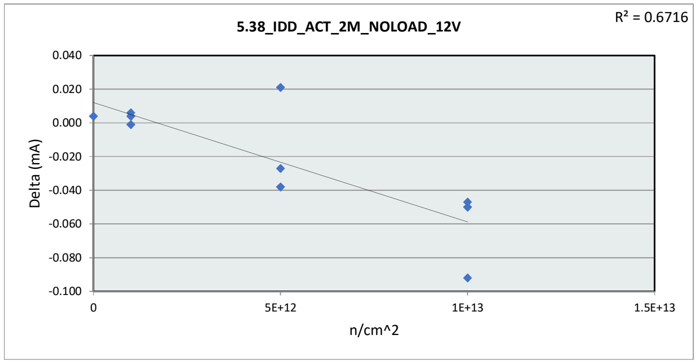


	5.37_IDD_ACT_2M_NOLOAD_5			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.156	8.045	8.013	8.111
Average	8.156	8.140	8.195	8.143
Max	8.156	8.222	8.337	8.177
UL	13.500	13.500	13.500	13.500

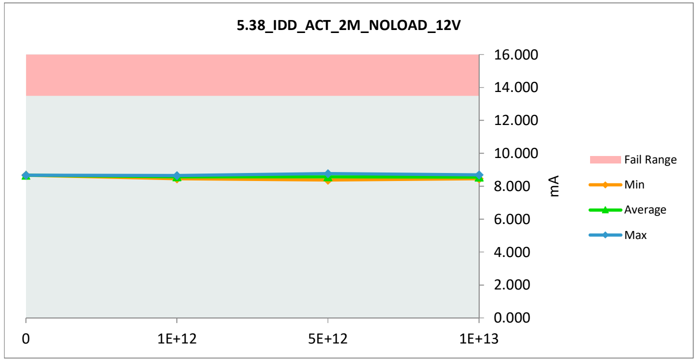


NDD Characterization Report
TPS7H5005-SEP

		5.38_IDD_ACT_2M_NOLOAD_12V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		13.5	13.5	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.671	8.675	0.004
1E+12	1	8.625	8.631	0.006
1E+12	2	8.457	8.461	0.004
1E+12	3	8.651	8.650	-0.001
5E+12	4	8.409	8.371	-0.038
5E+12	5	8.788	8.761	-0.027
5E+12	6	8.580	8.601	0.021
1E+13	7	8.512	8.465	-0.047
1E+13	8	8.585	8.493	-0.092
1E+13	9	8.748	8.698	-0.050
	Max	8.788	8.761	0.021
	Average	8.603	8.581	-0.022
	Min	8.409	8.371	-0.092
	Std Dev	0.121	0.126	0.035



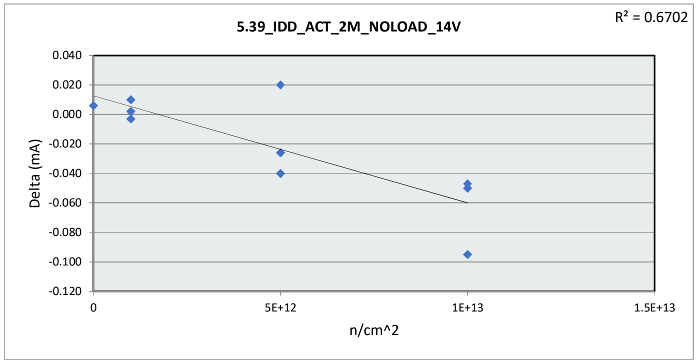
	5.38_IDD_ACT_2M_NOLOAD_			
Test Site				
Tester				
Test Number				
Max Limit	13.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.675	8.461	8.371	8.465
Average	8.675	8.581	8.578	8.552
Max	8.675	8.650	8.761	8.698
UL	13.500	13.500	13.500	13.500



NDD Characterization Report
TPS7H5005-SEP

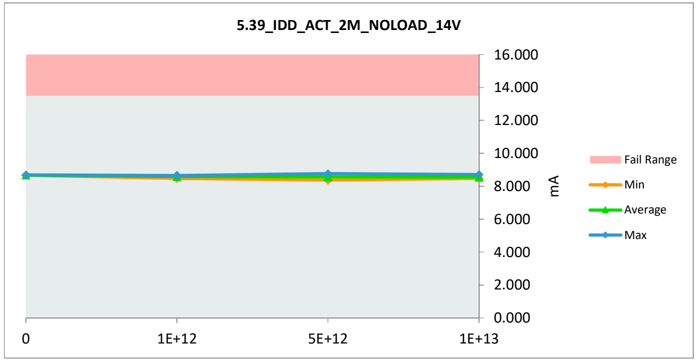
	5.39_IDD_ACT_2M_NOLOAD_14V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	13.5	13.5
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.672	8.678	0.006
1E+12	1	8.630	8.640	0.010
1E+12	2	8.465	8.467	0.002
1E+12	3	8.656	8.653	-0.003
5E+12	4	8.412	8.372	-0.040
5E+12	5	8.792	8.766	-0.026
5E+12	6	8.585	8.605	0.020
1E+13	7	8.516	8.469	-0.047
1E+13	8	8.592	8.497	-0.095
1E+13	9	8.753	8.703	-0.050
	Max	8.792	8.766	0.020
	Average	8.607	8.585	-0.022
	Min	8.412	8.372	-0.095
	Std Dev	0.120	0.126	0.036



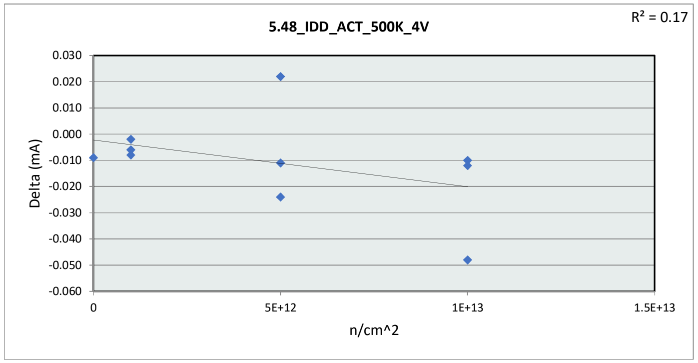
	5.39_IDD_ACT_2M_NOLOAD_1	
Test Site		
Tester		
Test Number		
Max Limit	13.5	mA
Min Limit		mA

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.678	8.467	8.372	8.469
Average	8.678	8.587	8.581	8.556
Max	8.678	8.653	8.766	8.703
UL	13.500	13.500	13.500	13.500

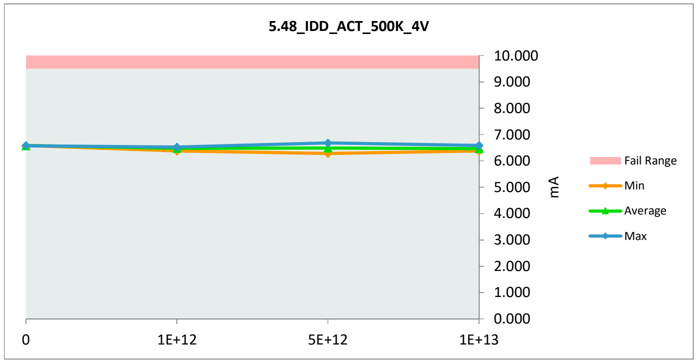


NDD Characterization Report
TPS7H5005-SEP

		5.48_IDD_ACT_500K_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	9.5	9.5	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.590	6.581	-0.009
1E+12	1	6.525	6.523	-0.002
1E+12	2	6.386	6.380	-0.006
1E+12	3	6.530	6.522	-0.008
5E+12	4	6.306	6.282	-0.024
5E+12	5	6.693	6.682	-0.011
5E+12	6	6.470	6.492	0.022
1E+13	7	6.392	6.380	-0.012
1E+13	8	6.488	6.440	-0.048
1E+13	9	6.592	6.582	-0.010
	Max	6.693	6.682	0.022
	Average	6.497	6.486	-0.011
	Min	6.306	6.282	-0.048
	Std Dev	0.115	0.118	0.017



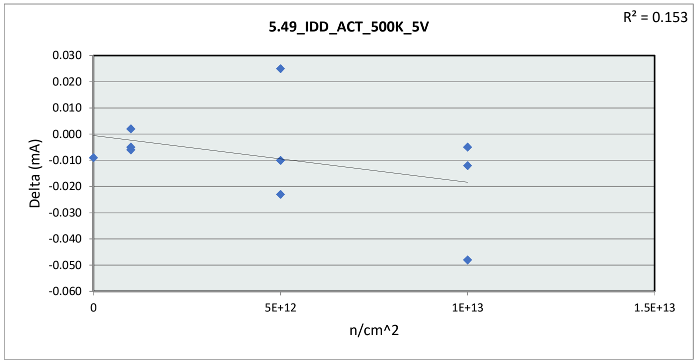
	5.48_IDD_ACT_500K_4V			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	6.581	6.380	6.282	6.380
Average	6.581	6.475	6.485	6.467
Max	6.581	6.523	6.682	6.582
UL	9.500	9.500	9.500	9.500



NDD Characterization Report
TPS7H5005-SEP

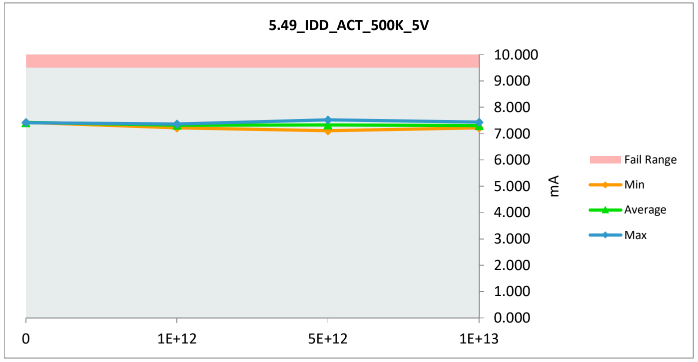
	5.49_IDD_ACT_500K_5V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	9.5	9.5
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.428	7.419	-0.009
1E+12	1	7.364	7.366	0.002
1E+12	2	7.224	7.218	-0.006
1E+12	3	7.367	7.362	-0.005
5E+12	4	7.135	7.112	-0.023
5E+12	5	7.530	7.520	-0.010
5E+12	6	7.307	7.332	0.025
1E+13	7	7.230	7.218	-0.012
1E+13	8	7.324	7.276	-0.048
1E+13	9	7.436	7.431	-0.005
	Max	7.530	7.520	0.025
	Average	7.335	7.325	-0.009
	Min	7.135	7.112	-0.048
	Std Dev	0.117	0.121	0.018



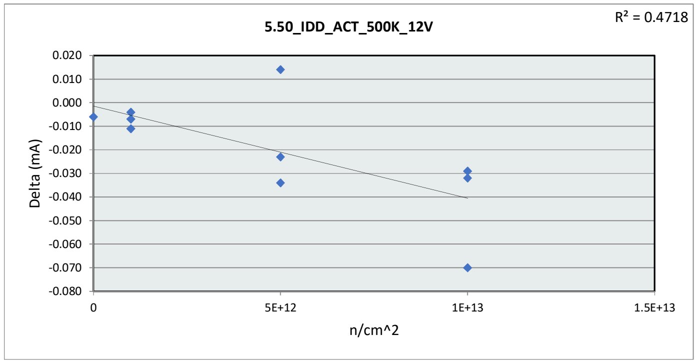
	5.49_IDD_ACT_500K_5V	
Test Site		
Tester		
Test Number		
Max Limit	9.5	mA
Min Limit		mA

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.419	7.218	7.112	7.218
Average	7.419	7.315	7.321	7.308
Max	7.419	7.366	7.520	7.431
UL	9.500	9.500	9.500	9.500

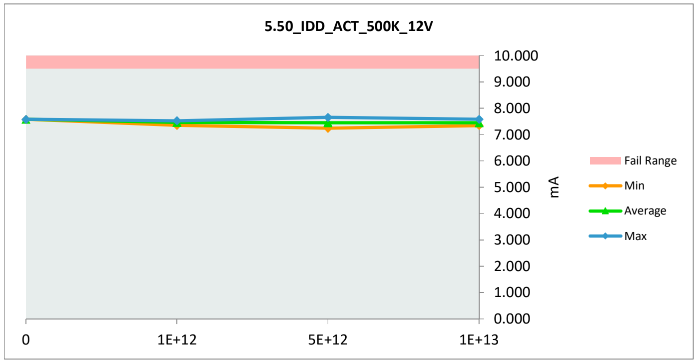


NDD Characterization Report
TPS7H5005-SEP

		5.50_IDD_ACT_500K_12V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.5	9.5	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.586	7.580	-0.006
1E+12	1	7.513	7.509	-0.004
1E+12	2	7.355	7.348	-0.007
1E+12	3	7.536	7.525	-0.011
5E+12	4	7.277	7.243	-0.034
5E+12	5	7.677	7.654	-0.023
5E+12	6	7.445	7.459	0.014
1E+13	7	7.377	7.345	-0.032
1E+13	8	7.479	7.409	-0.070
1E+13	9	7.615	7.586	-0.029
	Max	7.677	7.654	0.014
	Average	7.486	7.466	-0.020
	Min	7.277	7.243	-0.070
	Std Dev	0.125	0.129	0.023

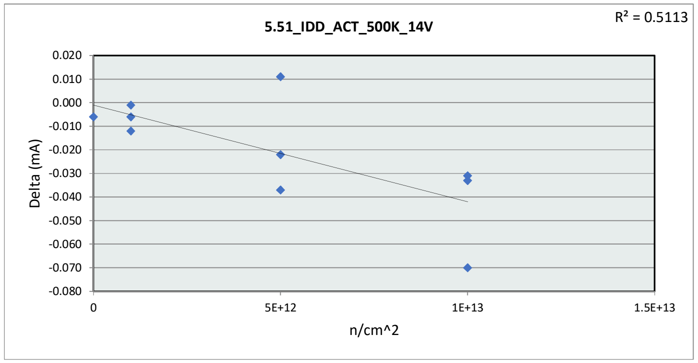


	5.50_IDD_ACT_500K_12V			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.580	7.348	7.243	7.345
Average	7.580	7.461	7.452	7.447
Max	7.580	7.525	7.654	7.586
UL	9.500	9.500	9.500	9.500

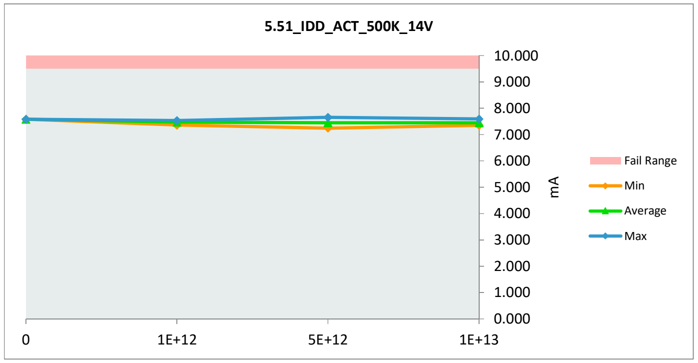


NDD Characterization Report
TPS7H5005-SEP

		5.51_IDD_ACT_500K_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		9.5	9.5	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.590	7.584	-0.006
1E+12	1	7.516	7.515	-0.001
1E+12	2	7.361	7.355	-0.006
1E+12	3	7.542	7.530	-0.012
5E+12	4	7.283	7.246	-0.037
5E+12	5	7.681	7.659	-0.022
5E+12	6	7.452	7.463	0.011
1E+13	7	7.382	7.349	-0.033
1E+13	8	7.486	7.416	-0.070
1E+13	9	7.620	7.589	-0.031
	Max	7.681	7.659	0.011
	Average	7.491	7.471	-0.021
	Min	7.283	7.246	-0.070
	Std Dev	0.124	0.129	0.023



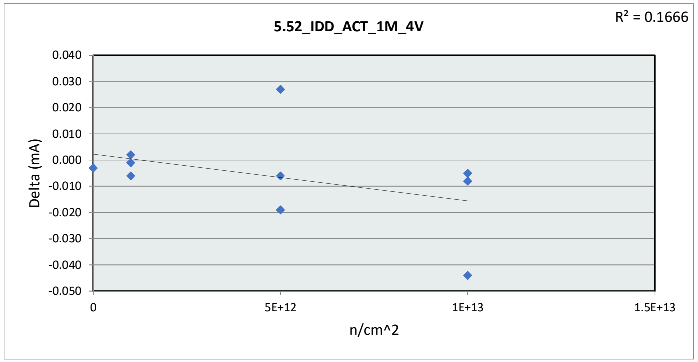
	5.51_IDD_ACT_500K_14V			
Test Site				
Tester				
Test Number				
Max Limit	9.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.584	7.355	7.246	7.349
Average	7.584	7.467	7.456	7.451
Max	7.584	7.530	7.659	7.589
UL	9.500	9.500	9.500	9.500



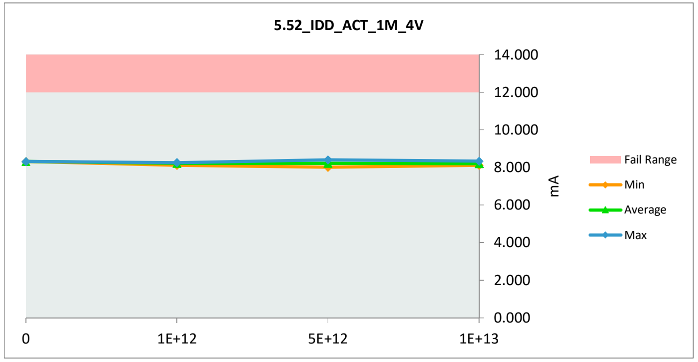
NDD Characterization Report
TPS7H5005-SEP

	5.52_IDD_ACT_1M_4V	
Test Site		
Tester		
Test Number		
Unit	mA	mA
Max Limit	12	12
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.317	8.314	-0.003
1E+12	1	8.253	8.255	0.002
1E+12	2	8.115	8.114	-0.001
1E+12	3	8.257	8.251	-0.006
5E+12	4	8.031	8.012	-0.019
5E+12	5	8.411	8.405	-0.006
5E+12	6	8.208	8.235	0.027
1E+13	7	8.129	8.121	-0.008
1E+13	8	8.206	8.162	-0.044
1E+13	9	8.332	8.327	-0.005
	Max	8.411	8.405	0.027
	Average	8.226	8.220	-0.006
	Min	8.031	8.012	-0.044
	Std Dev	0.113	0.118	0.018

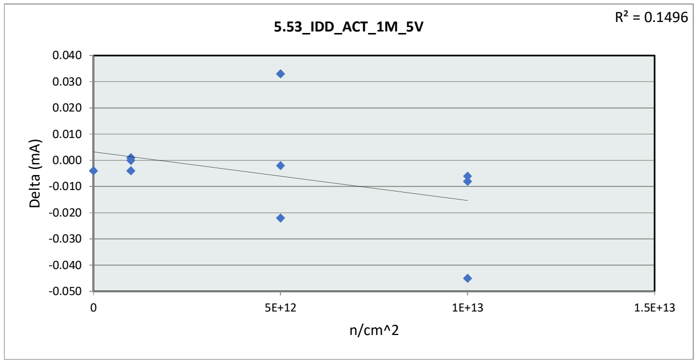


	5.52_IDD_ACT_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.314	8.114	8.012	8.121
Average	8.314	8.207	8.217	8.203
Max	8.314	8.255	8.405	8.327
UL	12.000	12.000	12.000	12.000

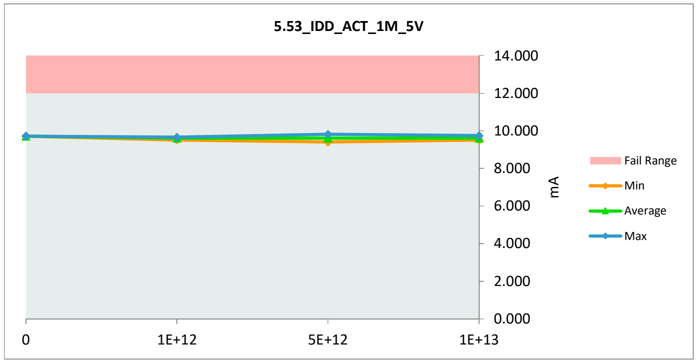


NDD Characterization Report
TPS7H5005-SEP

n/cm^2		5.53_IDD_ACT_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	12	12	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	9.724	9.720	-0.004
1E+12	1	9.653	9.654	0.001
1E+12	2	9.513	9.513	0.000
1E+12	3	9.649	9.645	-0.004
5E+12	4	9.423	9.401	-0.022
5E+12	5	9.810	9.808	-0.002
5E+12	6	9.606	9.639	0.033
1E+13	7	9.524	9.516	-0.008
1E+13	8	9.601	9.556	-0.045
1E+13	9	9.745	9.739	-0.006
	Max	9.810	9.808	0.033
	Average	9.625	9.619	-0.006
	Min	9.423	9.401	-0.045
	Std Dev	0.118	0.123	0.019

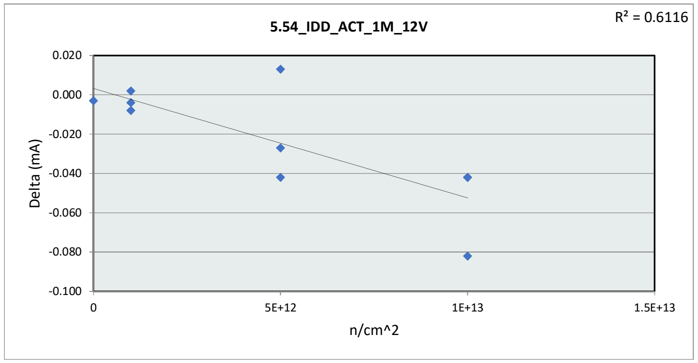


	5.53_IDD_ACT_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	9.720	9.513	9.401	9.516
Average	9.720	9.604	9.616	9.604
Max	9.720	9.654	9.808	9.739
UL	12.000	12.000	12.000	12.000

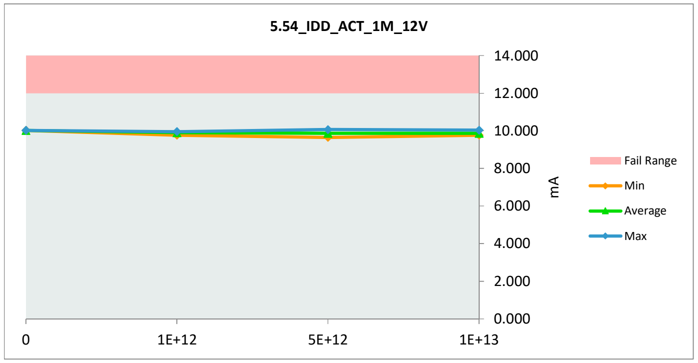


NDD Characterization Report
TPS7H5005-SEP

		5.54_IDD_ACT_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	12	12	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	10.029	10.026	-0.003
1E+12	1	9.937	9.939	0.002
1E+12	2	9.776	9.772	-0.004
1E+12	3	9.968	9.960	-0.008
5E+12	4	9.695	9.653	-0.042
5E+12	5	10.094	10.067	-0.027
5E+12	6	9.876	9.889	0.013
1E+13	7	9.809	9.767	-0.042
1E+13	8	9.899	9.817	-0.082
1E+13	9	10.078	10.036	-0.042
	Max	10.094	10.067	0.013
	Average	9.916	9.893	-0.023
	Min	9.695	9.653	-0.082
	Std Dev	0.131	0.137	0.029

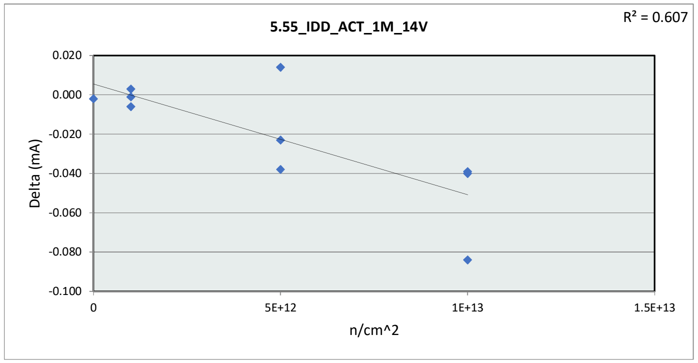


	5.54_IDD_ACT_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	10.026	9.772	9.653	9.767
Average	10.026	9.890	9.870	9.873
Max	10.026	9.960	10.067	10.036
UL	12.000	12.000	12.000	12.000

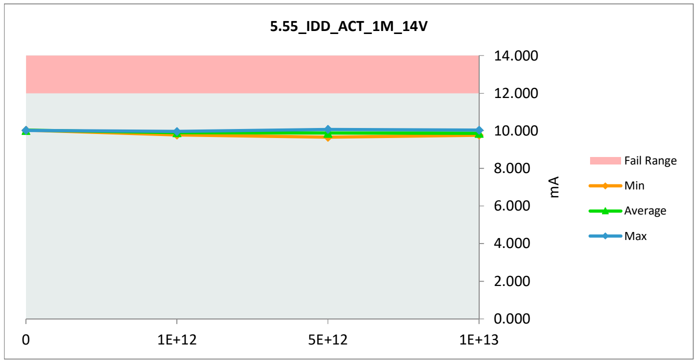


NDD Characterization Report
TPS7H5005-SEP

		5.55_IDD_ACT_1M_14V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		12	12	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	10.032	10.030	-0.002
1E+12	1	9.940	9.943	0.003
1E+12	2	9.778	9.777	-0.001
1E+12	3	9.972	9.966	-0.006
5E+12	4	9.698	9.660	-0.038
5E+12	5	10.095	10.072	-0.023
5E+12	6	9.881	9.895	0.014
1E+13	7	9.811	9.772	-0.039
1E+13	8	9.903	9.819	-0.084
1E+13	9	10.080	10.040	-0.040
	Max	10.095	10.072	0.014
	Average	9.919	9.897	-0.022
	Min	9.698	9.660	-0.084
	Std Dev	0.131	0.137	0.029

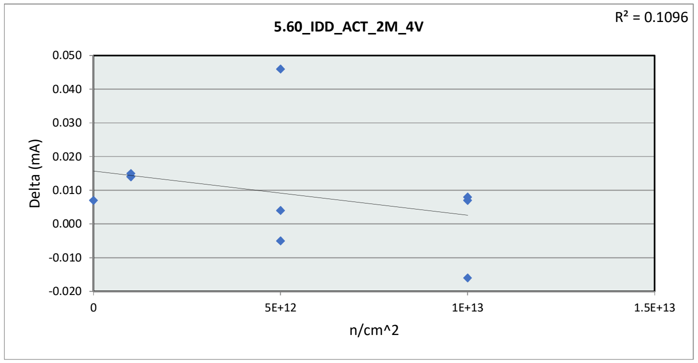


	5.55_IDD_ACT_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	12	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	10.030	9.777	9.660	9.772
Average	10.030	9.895	9.876	9.877
Max	10.030	9.966	10.072	10.040
UL	12.000	12.000	12.000	12.000

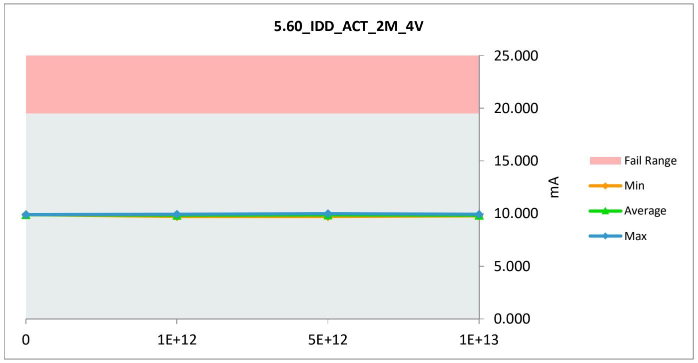


NDD Characterization Report
TPS7H5005-SEP

		5.60_IDD_ACT_2M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	19.5	19.5	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	9.892	9.899	0.007
1E+12	1	9.832	9.846	0.014
1E+12	2	9.710	9.725	0.015
1E+12	3	9.921	9.935	0.014
5E+12	4	9.721	9.716	-0.005
5E+12	5	9.994	9.998	0.004
5E+12	6	9.825	9.871	0.046
1E+13	7	9.820	9.827	0.007
1E+13	8	9.795	9.779	-0.016
1E+13	9	9.908	9.916	0.008
	Max	9.994	9.998	0.046
	Average	9.842	9.851	0.009
	Min	9.710	9.716	-0.016
	Std Dev	0.089	0.092	0.016

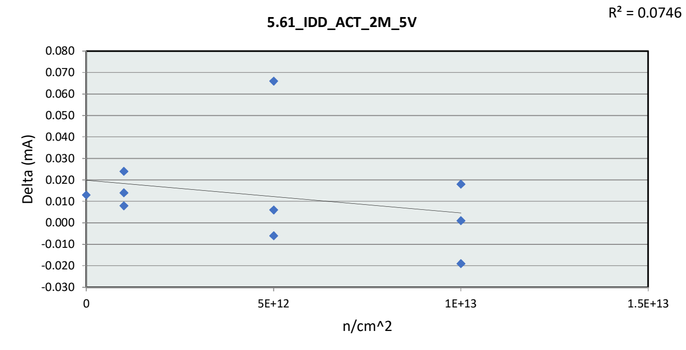


	5.60_IDD_ACT_2M_4V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	9.899	9.725	9.716	9.779
Average	9.899	9.835	9.862	9.841
Max	9.899	9.935	9.998	9.916
UL	19.500	19.500	19.500	19.500

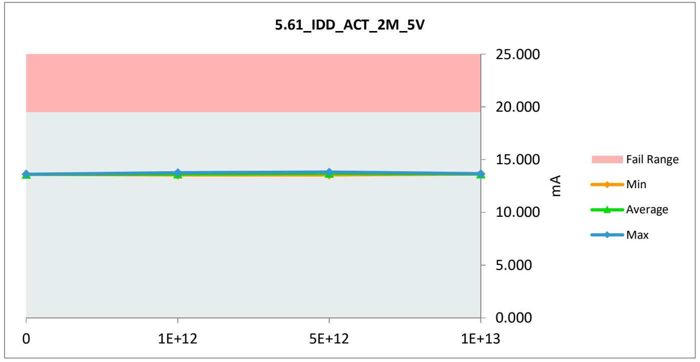


NDD Characterization Report
TPS7H5005-SEP

		5.61_IDD_ACT_2M_5V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		19.5	19.5	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	13.597	13.610	0.013
1E+12	1	13.599	13.613	0.014
1E+12	2	13.522	13.546	0.024
1E+12	3	13.754	13.762	0.008
5E+12	4	13.542	13.536	-0.006
5E+12	5	13.814	13.820	0.006
5E+12	6	13.694	13.760	0.066
1E+13	7	13.645	13.646	0.001
1E+13	8	13.650	13.631	-0.019
1E+13	9	13.635	13.653	0.018
	Max	13.814	13.820	0.066
	Average	13.645	13.658	0.012
	Min	13.522	13.536	-0.019
	Std Dev	0.090	0.094	0.023

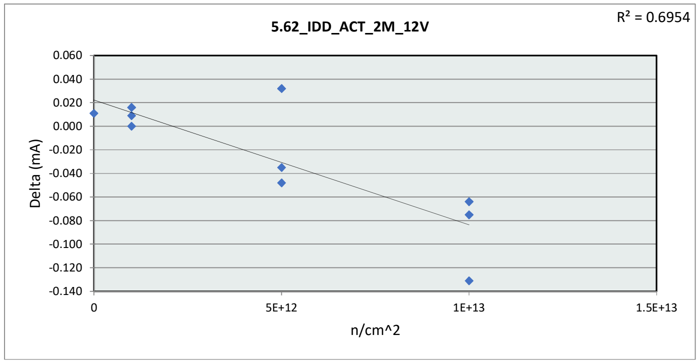


	5.61_IDD_ACT_2M_5V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	13.610	13.546	13.536	13.631
Average	13.610	13.640	13.705	13.643
Max	13.610	13.762	13.820	13.653
UL	19.500	19.500	19.500	19.500

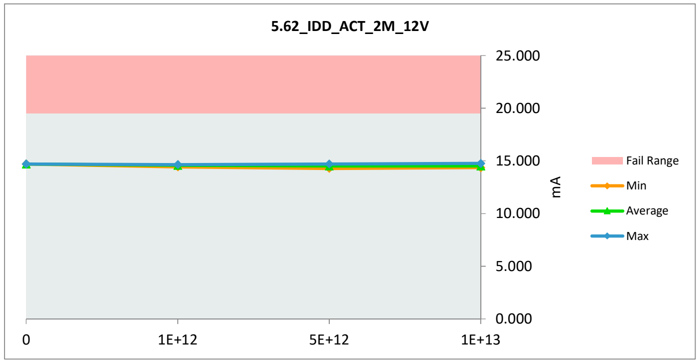


NDD Characterization Report
TPS7H5005-SEP

		5.62_IDD_ACT_2M_12V		
Test Site				
Tester				
Test Number				
Unit		mA	mA	
Max Limit		19.5	19.5	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	14.696	14.707	0.011
1E+12	1	14.582	14.598	0.016
1E+12	2	14.434	14.443	0.009
1E+12	3	14.649	14.649	0.000
5E+12	4	14.340	14.292	-0.048
5E+12	5	14.750	14.715	-0.035
5E+12	6	14.524	14.556	0.032
1E+13	7	14.465	14.401	-0.064
1E+13	8	14.502	14.371	-0.131
1E+13	9	14.837	14.762	-0.075
	Max	14.837	14.762	0.032
	Average	14.578	14.549	-0.029
	Min	14.340	14.292	-0.131
	Std Dev	0.154	0.164	0.051

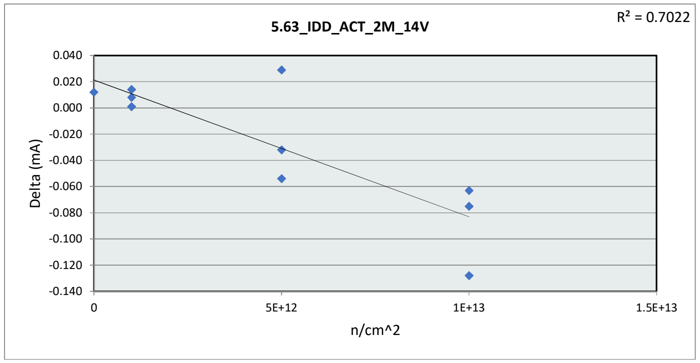


	5.62_IDD_ACT_2M_12V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	14.707	14.443	14.292	14.371
Average	14.707	14.563	14.521	14.511
Max	14.707	14.649	14.715	14.762
UL	19.500	19.500	19.500	19.500

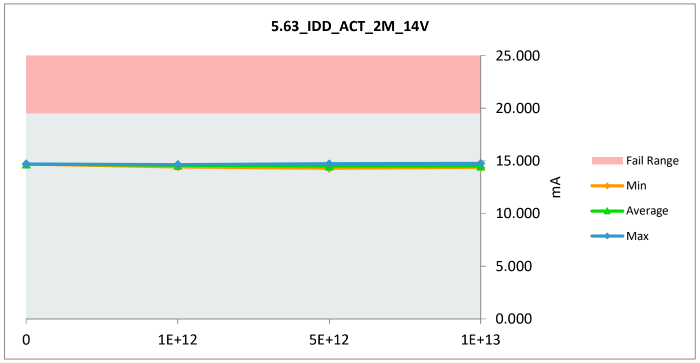


NDD Characterization Report
TPS7H5005-SEP

		5.63_IDD_ACT_2M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	mA	mA	
	Max Limit	19.5	19.5	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	14.700	14.712	0.012
1E+12	1	14.589	14.603	0.014
1E+12	2	14.439	14.447	0.008
1E+12	3	14.653	14.654	0.001
5E+12	4	14.347	14.293	-0.054
5E+12	5	14.755	14.723	-0.032
5E+12	6	14.529	14.558	0.029
1E+13	7	14.469	14.406	-0.063
1E+13	8	14.506	14.378	-0.128
1E+13	9	14.842	14.767	-0.075
	Max	14.842	14.767	0.029
	Average	14.583	14.554	-0.029
	Min	14.347	14.293	-0.128
	Std Dev	0.154	0.165	0.050

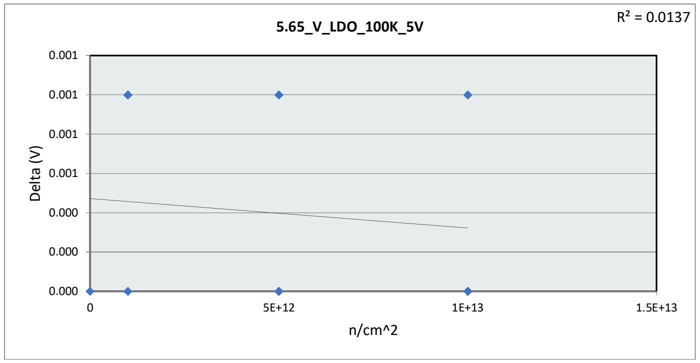


	5.63_IDD_ACT_2M_14V			
Test Site				
Tester				
Test Number				
Max Limit	19.5	mA		
Min Limit		mA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	14.712	14.447	14.293	14.378
Average	14.712	14.568	14.525	14.517
Max	14.712	14.654	14.723	14.767
UL	19.500	19.500	19.500	19.500

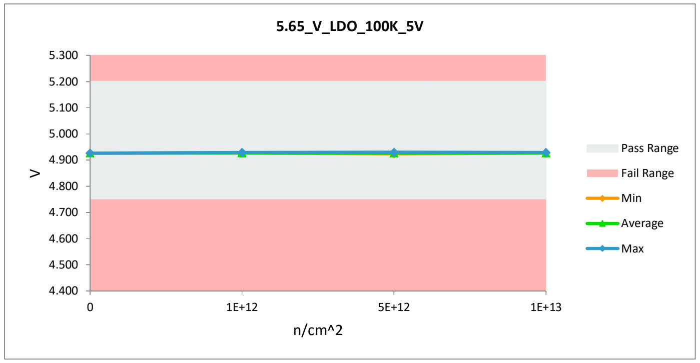


NDD Characterization Report
TPS7H5005-SEP

		5.65_V_LDO_100K_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.2	5.2	
Min Limit		4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	4.927	4.927	0.000
1E+12	1	4.927	4.927	0.000
1E+12	2	4.928	4.929	0.001
1E+12	3	4.927	4.928	0.001
5E+12	4	4.929	4.930	0.001
5E+12	5	4.924	4.924	0.000
5E+12	6	4.927	4.927	0.000
1E+13	7	4.929	4.929	0.000
1E+13	8	4.926	4.927	0.001
1E+13	9	4.926	4.926	0.000
	Max	4.929	4.930	0.001
	Average	4.927	4.927	0.000
	Min	4.924	4.924	0.000
	Std Dev	0.001	0.002	0.001

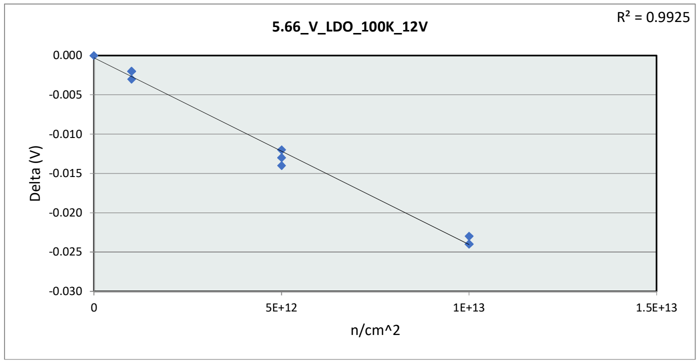


	5.65_V_LDO_100K_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.927	4.927	4.924	4.926
Average	4.927	4.928	4.927	4.927
Max	4.927	4.929	4.930	4.929
UL	5.200	5.200	5.200	5.200

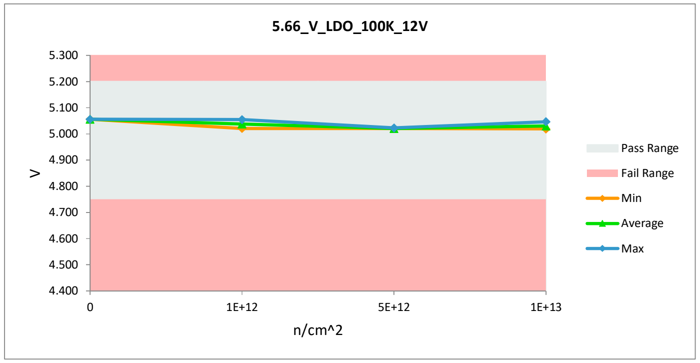


NDD Characterization Report
TPS7H5005-SEP

		5.66_V_LDO_100K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.2	5.2	
	Min Limit	4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.056	5.056	0.000
1E+12	1	5.039	5.037	-0.002
1E+12	2	5.023	5.021	-0.002
1E+12	3	5.058	5.055	-0.003
5E+12	4	5.036	5.023	-0.013
5E+12	5	5.034	5.020	-0.014
5E+12	6	5.032	5.020	-0.012
1E+13	7	5.043	5.019	-0.024
1E+13	8	5.047	5.023	-0.024
1E+13	9	5.070	5.047	-0.023
	Max	5.070	5.056	0.000
	Average	5.044	5.032	-0.012
	Min	5.023	5.019	-0.024
	Std Dev	0.014	0.015	0.010

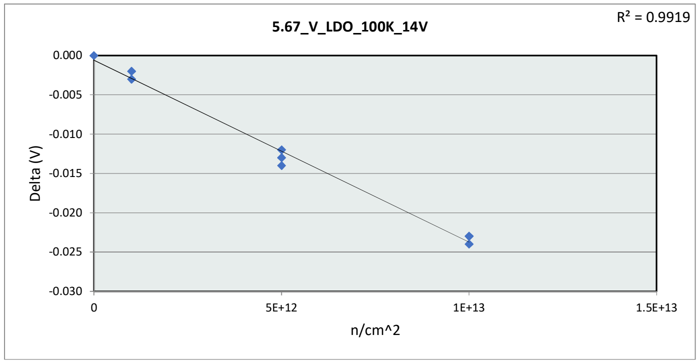


	5.66_V_LDO_100K_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.056	5.021	5.020	5.019
Average	5.056	5.038	5.021	5.030
Max	5.056	5.055	5.023	5.047
UL	5.200	5.200	5.200	5.200

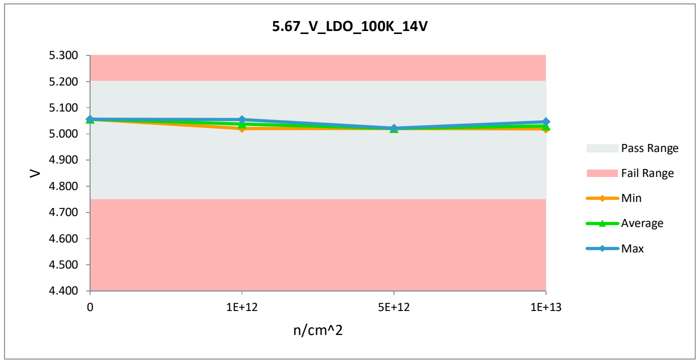


NDD Characterization Report
TPS7H5005-SEP

		5.67_V_LDO_100K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.2	5.2	
	Min Limit	4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.056	5.056	0.000
1E+12	1	5.039	5.036	-0.003
1E+12	2	5.023	5.021	-0.002
1E+12	3	5.058	5.055	-0.003
5E+12	4	5.036	5.022	-0.014
5E+12	5	5.033	5.020	-0.013
5E+12	6	5.032	5.020	-0.012
1E+13	7	5.042	5.019	-0.023
1E+13	8	5.047	5.023	-0.024
1E+13	9	5.070	5.047	-0.023
	Max	5.070	5.056	0.000
	Average	5.044	5.032	-0.012
	Min	5.023	5.019	-0.024
	Std Dev	0.014	0.015	0.009

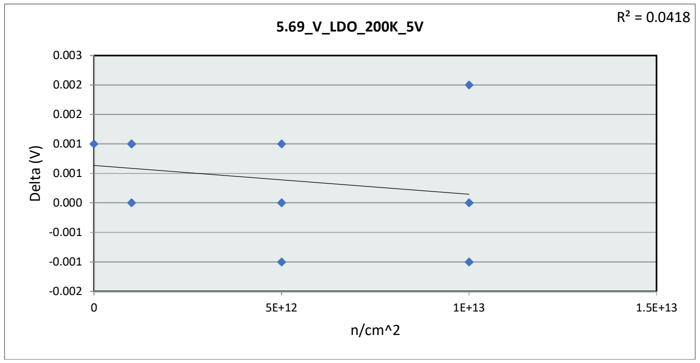


	5.67_V_LDO_100K_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.056	5.021	5.020	5.019
Average	5.056	5.037	5.021	5.030
Max	5.056	5.055	5.022	5.047
UL	5.200	5.200	5.200	5.200

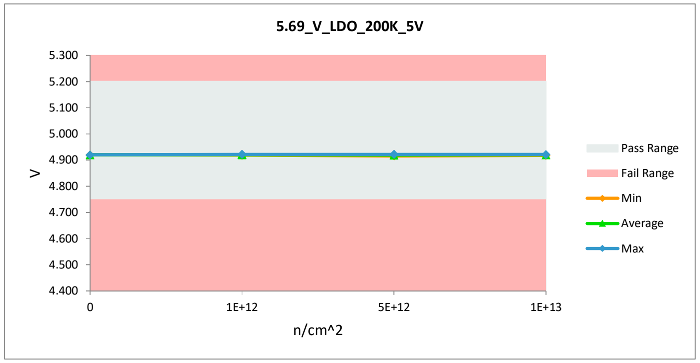


NDD Characterization Report
TPS7H5005-SEP

		5.69_V_LDO_200K_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.2	5.2	
Min Limit		4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	4.919	4.920	0.001
1E+12	1	4.919	4.919	0.000
1E+12	2	4.921	4.922	0.001
1E+12	3	4.920	4.921	0.001
5E+12	4	4.921	4.922	0.001
5E+12	5	4.916	4.916	0.000
5E+12	6	4.919	4.918	-0.001
1E+13	7	4.922	4.921	-0.001
1E+13	8	4.918	4.920	0.002
1E+13	9	4.918	4.918	0.000
	Max	4.922	4.922	0.002
	Average	4.919	4.920	0.000
	Min	4.916	4.916	-0.001
	Std Dev	0.002	0.002	0.001

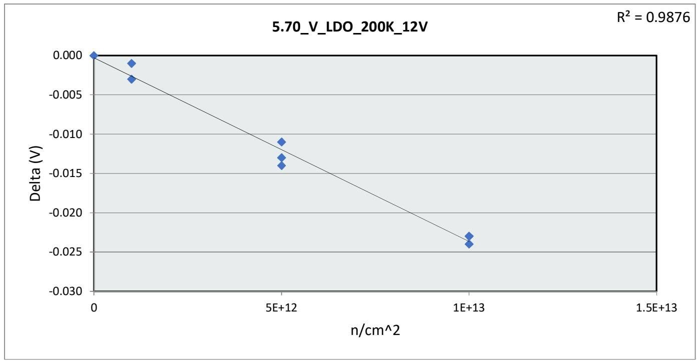


	5.69_V_LDO_200K_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.920	4.919	4.916	4.918
Average	4.920	4.921	4.919	4.920
Max	4.920	4.922	4.922	4.921
UL	5.200	5.200	5.200	5.200

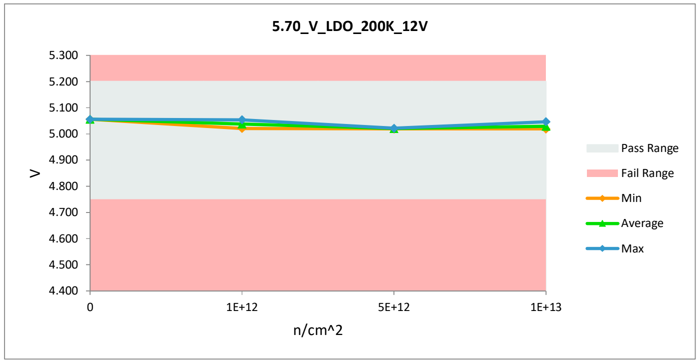


NDD Characterization Report
TPS7H5005-SEP

		5.70_V_LDO_200K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.2	5.2	
	Min Limit	4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.056	5.056	0.000
1E+12	1	5.039	5.036	-0.003
1E+12	2	5.022	5.021	-0.001
1E+12	3	5.057	5.054	-0.003
5E+12	4	5.035	5.022	-0.013
5E+12	5	5.033	5.019	-0.014
5E+12	6	5.031	5.020	-0.011
1E+13	7	5.042	5.019	-0.023
1E+13	8	5.046	5.022	-0.024
1E+13	9	5.070	5.047	-0.023
	Max	5.070	5.056	0.000
	Average	5.043	5.032	-0.012
	Min	5.022	5.019	-0.024
	Std Dev	0.014	0.015	0.010

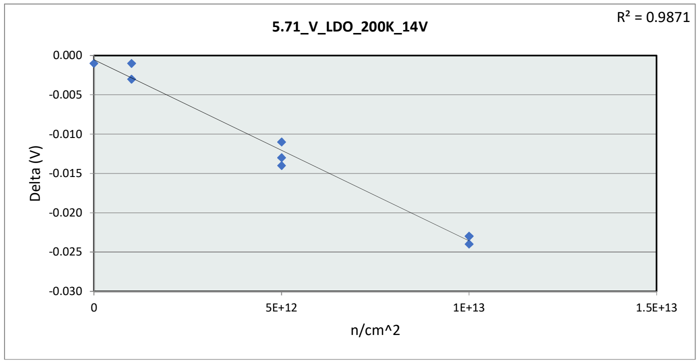


	5.70_V_LDO_200K_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.056	5.021	5.019	5.019
Average	5.056	5.037	5.020	5.029
Max	5.056	5.054	5.022	5.047
UL	5.200	5.200	5.200	5.200

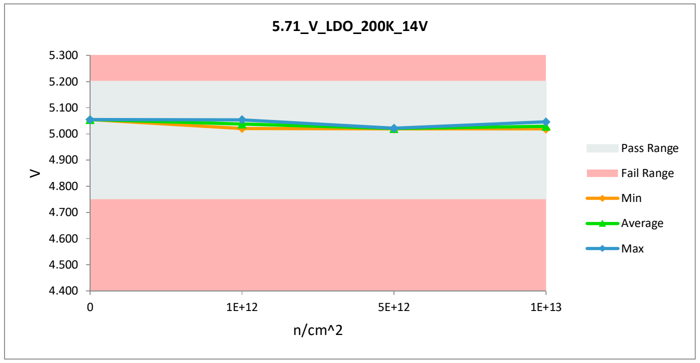


NDD Characterization Report
TPS7H5005-SEP

		5.71_V_LDO_200K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.2	5.2	
	Min Limit	4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.056	5.055	-0.001
1E+12	1	5.039	5.036	-0.003
1E+12	2	5.022	5.021	-0.001
1E+12	3	5.057	5.054	-0.003
5E+12	4	5.035	5.022	-0.013
5E+12	5	5.033	5.019	-0.014
5E+12	6	5.031	5.020	-0.011
1E+13	7	5.042	5.019	-0.023
1E+13	8	5.046	5.022	-0.024
1E+13	9	5.069	5.046	-0.023
	Max	5.069	5.055	-0.001
	Average	5.043	5.031	-0.012
	Min	5.022	5.019	-0.024
	Std Dev	0.014	0.015	0.009

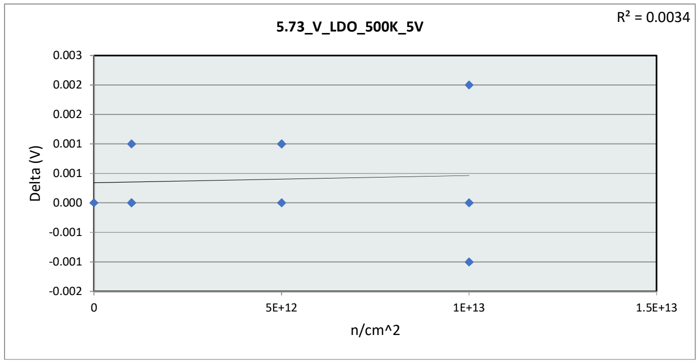


	5.71_V_LDO_200K_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.055	5.021	5.019	5.019
Average	5.055	5.037	5.020	5.029
Max	5.055	5.054	5.022	5.046
UL	5.200	5.200	5.200	5.200

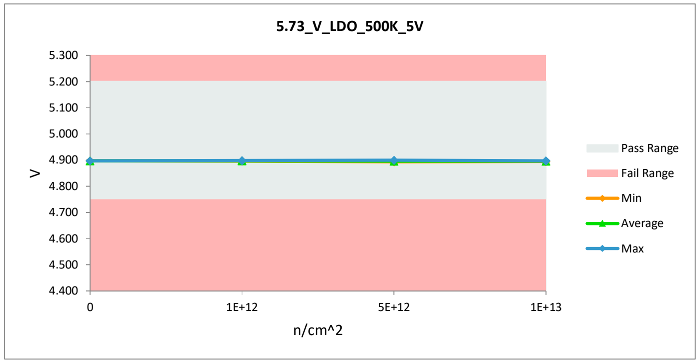


NDD Characterization Report
TPS7H5005-SEP

		5.73_V_LDO_500K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.2	5.2	
	Min Limit	4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	4.897	4.897	0.000
1E+12	1	4.896	4.896	0.000
1E+12	2	4.898	4.898	0.000
1E+12	3	4.896	4.897	0.001
5E+12	4	4.898	4.899	0.001
5E+12	5	4.893	4.893	0.000
5E+12	6	4.895	4.896	0.001
1E+13	7	4.898	4.897	-0.001
1E+13	8	4.894	4.896	0.002
1E+13	9	4.895	4.895	0.000
	Max	4.898	4.899	0.002
	Average	4.896	4.896	0.000
	Min	4.893	4.893	-0.001
	Std Dev	0.002	0.002	0.001



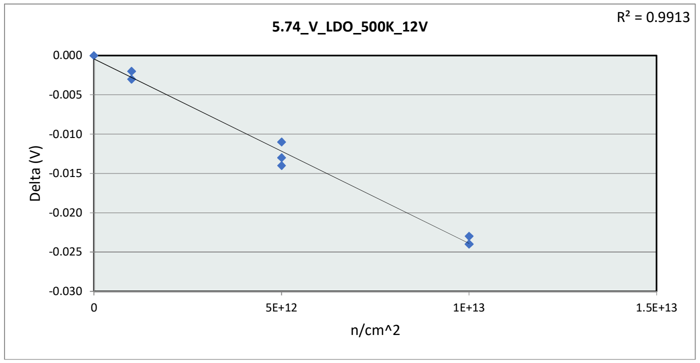
	5.73_V_LDO_500K_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.897	4.896	4.893	4.895
Average	4.897	4.897	4.896	4.896
Max	4.897	4.898	4.899	4.897
UL	5.200	5.200	5.200	5.200



NDD Characterization Report
TPS7H5005-SEP

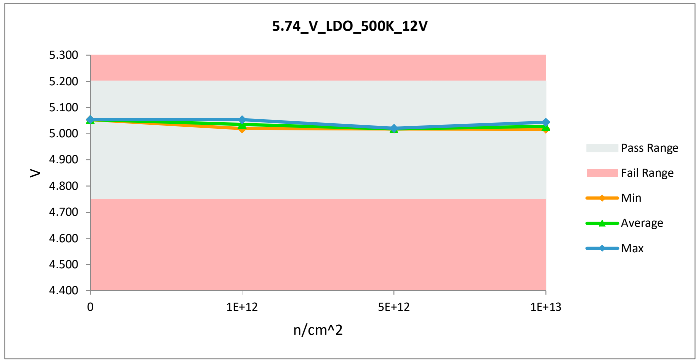
	5.74_V_LDO_500K_12V	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	5.2	5.2
Min Limit	4.75	4.75

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.054	5.054	0.000
1E+12	1	5.037	5.034	-0.003
1E+12	2	5.021	5.019	-0.002
1E+12	3	5.056	5.053	-0.003
5E+12	4	5.033	5.020	-0.013
5E+12	5	5.032	5.018	-0.014
5E+12	6	5.029	5.018	-0.011
1E+13	7	5.041	5.017	-0.024
1E+13	8	5.045	5.021	-0.024
1E+13	9	5.067	5.044	-0.023
	Max	5.067	5.054	0.000
	Average	5.041	5.030	-0.012
	Min	5.021	5.017	-0.024
	Std Dev	0.014	0.015	0.010



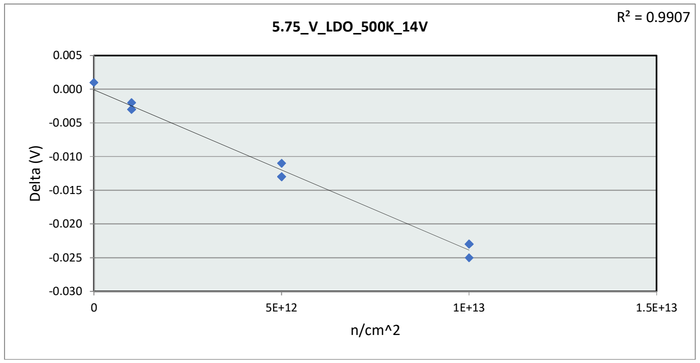
	5.74_V_LDO_500K_12V	
Test Site		
Tester		
Test Number		
Max Limit	5.2	V
Min Limit	4.75	V

n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.054	5.019	5.018	5.017
Average	5.054	5.035	5.019	5.027
Max	5.054	5.053	5.020	5.044
UL	5.200	5.200	5.200	5.200

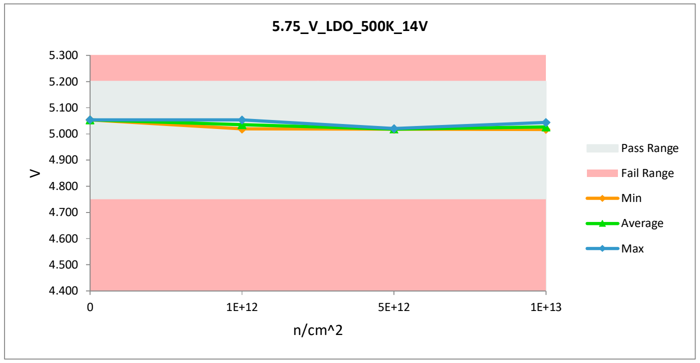


NDD Characterization Report
TPS7H5005-SEP

		5.75_V_LDO_500K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.2	5.2	
	Min Limit	4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.053	5.054	0.001
1E+12	1	5.037	5.034	-0.003
1E+12	2	5.021	5.019	-0.002
1E+12	3	5.056	5.053	-0.003
5E+12	4	5.033	5.020	-0.013
5E+12	5	5.031	5.018	-0.013
5E+12	6	5.029	5.018	-0.011
1E+13	7	5.040	5.017	-0.023
1E+13	8	5.045	5.020	-0.025
1E+13	9	5.067	5.044	-0.023
	Max	5.067	5.054	0.001
	Average	5.041	5.030	-0.011
	Min	5.021	5.017	-0.025
	Std Dev	0.014	0.015	0.010

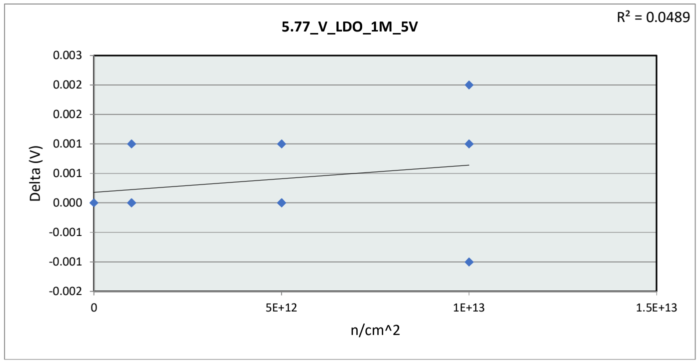


	5.75_V_LDO_500K_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.054	5.019	5.018	5.017
Average	5.054	5.035	5.019	5.027
Max	5.054	5.053	5.020	5.044
UL	5.200	5.200	5.200	5.200

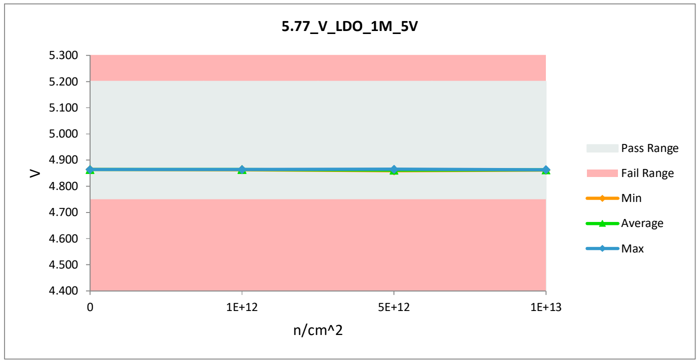


NDD Characterization Report
TPS7H5005-SEP

		5.77_V_LDO_1M_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.2	5.2	
Min Limit		4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	4.864	4.864	0.000
1E+12	1	4.863	4.863	0.000
1E+12	2	4.864	4.864	0.000
1E+12	3	4.863	4.864	0.001
5E+12	4	4.864	4.865	0.001
5E+12	5	4.859	4.859	0.000
5E+12	6	4.862	4.862	0.000
1E+13	7	4.864	4.863	-0.001
1E+13	8	4.861	4.863	0.002
1E+13	9	4.861	4.862	0.001
	Max	4.864	4.865	0.002
	Average	4.862	4.863	0.000
	Min	4.859	4.859	-0.001
	Std Dev	0.002	0.002	0.001

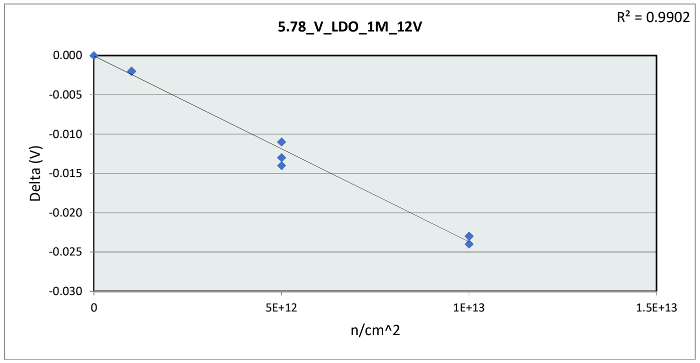


	5.77_V_LDO_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	4.864	4.863	4.859	4.862
Average	4.864	4.864	4.862	4.863
Max	4.864	4.864	4.865	4.863
UL	5.200	5.200	5.200	5.200

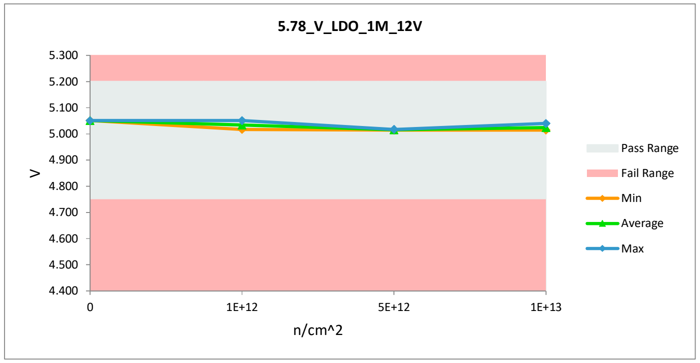


NDD Characterization Report
TPS7H5005-SEP

		5.78_V_LDO_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.2	5.2	
	Min Limit	4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.051	5.051	0.000
1E+12	1	5.034	5.032	-0.002
1E+12	2	5.019	5.017	-0.002
1E+12	3	5.053	5.051	-0.002
5E+12	4	5.031	5.017	-0.014
5E+12	5	5.029	5.016	-0.013
5E+12	6	5.026	5.015	-0.011
1E+13	7	5.038	5.015	-0.023
1E+13	8	5.042	5.018	-0.024
1E+13	9	5.063	5.040	-0.023
	Max	5.063	5.051	0.000
	Average	5.039	5.027	-0.011
	Min	5.019	5.015	-0.024
	Std Dev	0.014	0.015	0.010

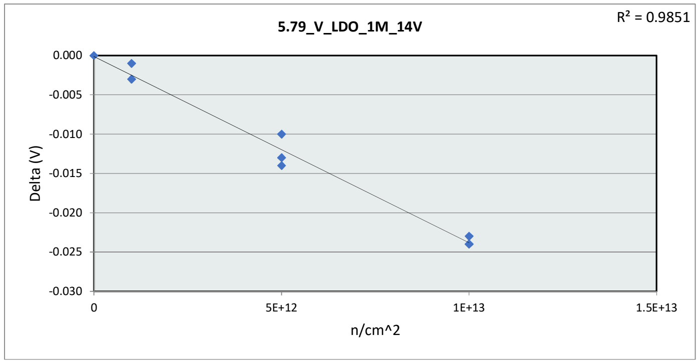


	5.78_V_LDO_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.051	5.017	5.015	5.015
Average	5.051	5.033	5.016	5.024
Max	5.051	5.051	5.017	5.040
UL	5.200	5.200	5.200	5.200

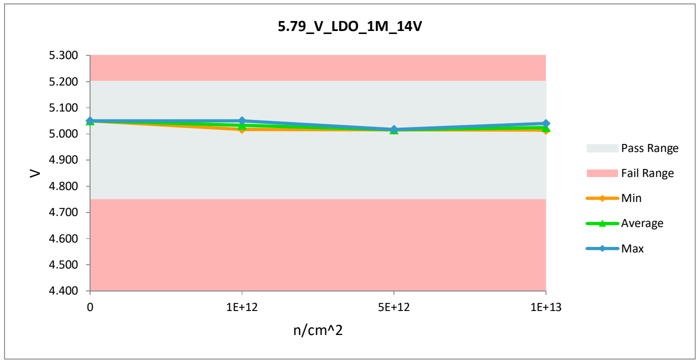


NDD Characterization Report
TPS7H5005-SEP

		5.79_V_LDO_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.2	5.2	
	Min Limit	4.75	4.75	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.050	5.050	0.000
1E+12	1	5.034	5.031	-0.003
1E+12	2	5.018	5.017	-0.001
1E+12	3	5.053	5.050	-0.003
5E+12	4	5.030	5.017	-0.013
5E+12	5	5.029	5.015	-0.014
5E+12	6	5.025	5.015	-0.010
1E+13	7	5.038	5.014	-0.024
1E+13	8	5.042	5.018	-0.024
1E+13	9	5.063	5.040	-0.023
	Max	5.063	5.050	0.000
	Average	5.038	5.027	-0.011
	Min	5.018	5.014	-0.024
	Std Dev	0.014	0.015	0.010

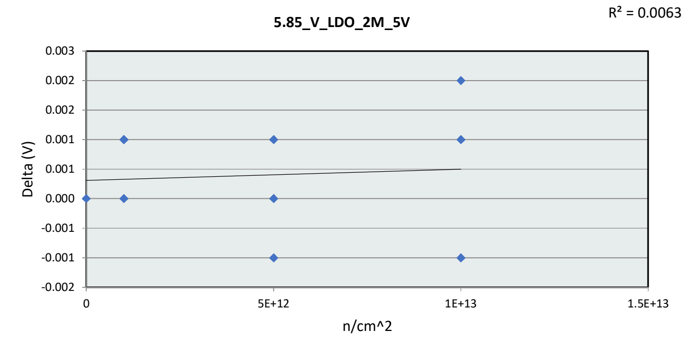


5.79_V_LDO_1M_14V				
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.75	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.750	4.750	4.750	4.750
Min	5.050	5.017	5.015	5.014
Average	5.050	5.033	5.016	5.024
Max	5.050	5.050	5.017	5.040
UL	5.200	5.200	5.200	5.200

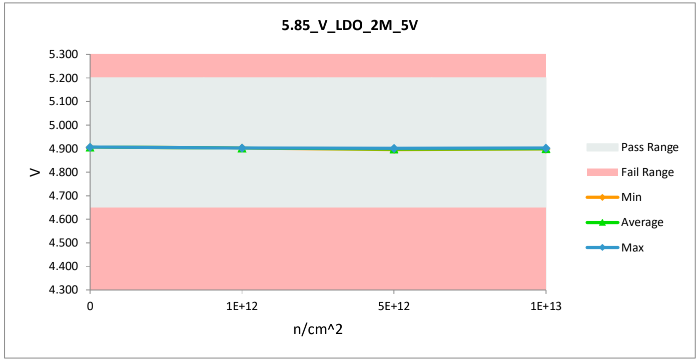


NDD Characterization Report
TPS7H5005-SEP

		5.85_V_LDO_2M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.2	5.2	
	Min Limit	4.65	4.65	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	4.906	4.906	0.000
1E+12	1	4.902	4.902	0.000
1E+12	2	4.902	4.903	0.001
1E+12	3	4.901	4.902	0.001
5E+12	4	4.900	4.901	0.001
5E+12	5	4.897	4.896	-0.001
5E+12	6	4.898	4.898	0.000
1E+13	7	4.901	4.900	-0.001
1E+13	8	4.897	4.899	0.002
1E+13	9	4.901	4.902	0.001
	Max	4.906	4.906	0.002
	Average	4.900	4.901	0.000
	Min	4.897	4.896	-0.001
	Std Dev	0.003	0.003	0.001

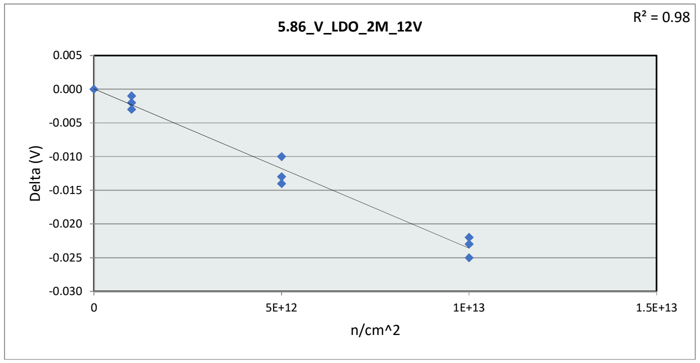


	5.85_V_LDO_2M_5V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	4.906	4.902	4.896	4.899
Average	4.906	4.902	4.898	4.900
Max	4.906	4.903	4.901	4.902
UL	5.200	5.200	5.200	5.200

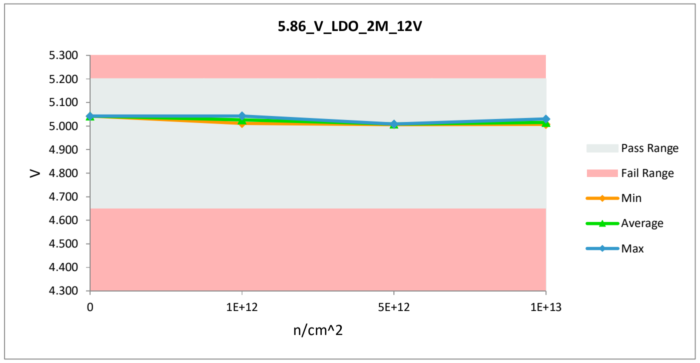


NDD Characterization Report
TPS7H5005-SEP

		5.86_V_LDO_2M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	5.2	5.2	
	Min Limit	4.65	4.65	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.042	5.042	0.000
1E+12	1	5.026	5.024	-0.002
1E+12	2	5.012	5.011	-0.001
1E+12	3	5.046	5.043	-0.003
5E+12	4	5.022	5.009	-0.013
5E+12	5	5.023	5.009	-0.014
5E+12	6	5.016	5.006	-0.010
1E+13	7	5.030	5.007	-0.023
1E+13	8	5.035	5.010	-0.025
1E+13	9	5.052	5.030	-0.022
	Max	5.052	5.043	0.000
	Average	5.030	5.019	-0.011
	Min	5.012	5.006	-0.025
	Std Dev	0.013	0.015	0.010

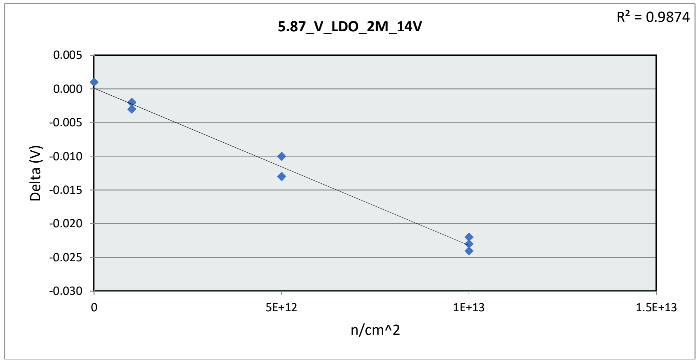


	5.86_V_LDO_2M_12V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	5.042	5.011	5.006	5.007
Average	5.042	5.026	5.008	5.016
Max	5.042	5.043	5.009	5.030
UL	5.200	5.200	5.200	5.200

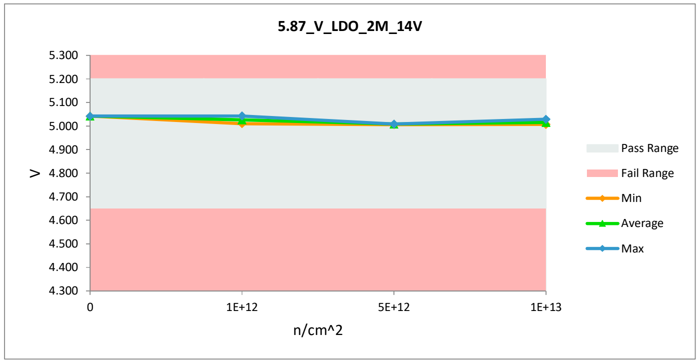


NDD Characterization Report
TPS7H5005-SEP

		5.87_V_LDO_2M_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		5.2	5.2	
Min Limit		4.65	4.65	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.041	5.042	0.001
1E+12	1	5.026	5.024	-0.002
1E+12	2	5.012	5.010	-0.002
1E+12	3	5.046	5.043	-0.003
5E+12	4	5.022	5.009	-0.013
5E+12	5	5.022	5.009	-0.013
5E+12	6	5.016	5.006	-0.010
1E+13	7	5.029	5.007	-0.022
1E+13	8	5.034	5.010	-0.024
1E+13	9	5.052	5.029	-0.023
	Max	5.052	5.043	0.001
	Average	5.030	5.019	-0.011
	Min	5.012	5.006	-0.024
	Std Dev	0.013	0.015	0.010

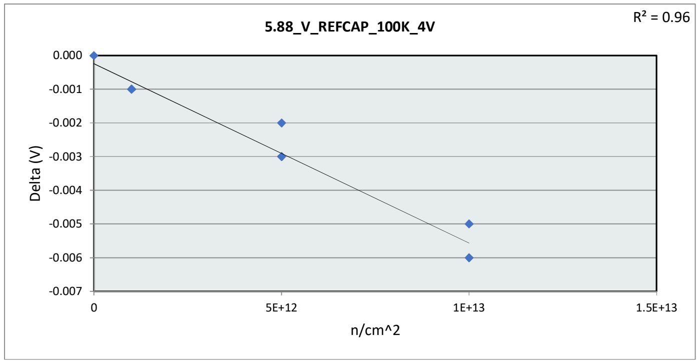


	5.87_V_LDO_2M_14V			
Test Site				
Tester				
Test Number				
Max Limit	5.2	V		
Min Limit	4.65	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	4.650	4.650	4.650	4.650
Min	5.042	5.010	5.006	5.007
Average	5.042	5.026	5.008	5.015
Max	5.042	5.043	5.009	5.029
UL	5.200	5.200	5.200	5.200

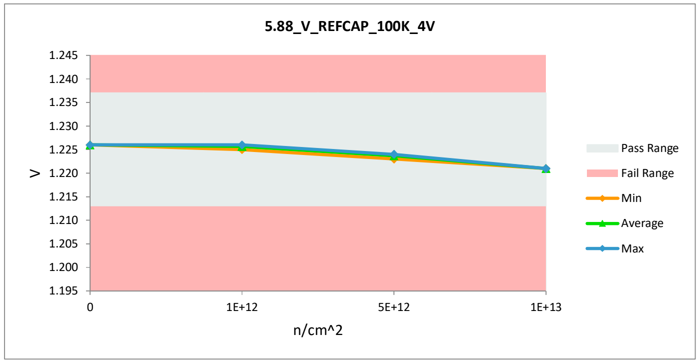


NDD Characterization Report
TPS7H5005-SEP

		5.88_V_REFCAP_100K_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.226	-0.001
1E+12	2	1.226	1.225	-0.001
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.226	1.223	-0.003
5E+12	6	1.226	1.224	-0.002
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.226	1.221	-0.005
	Max	1.227	1.226	0.000
	Average	1.226	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

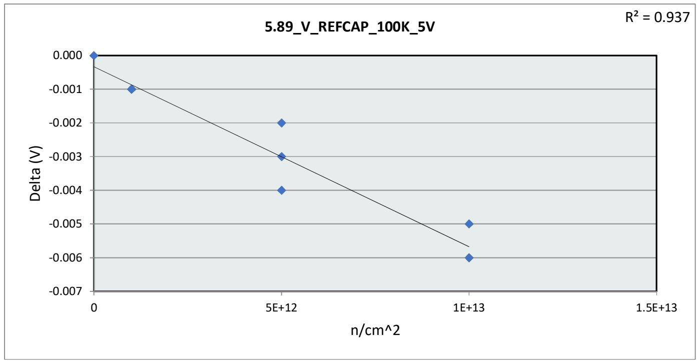


	5.88_V_REFCAP_100K_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.225	1.223	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.226	1.224	1.221
UL	1.237	1.237	1.237	1.237

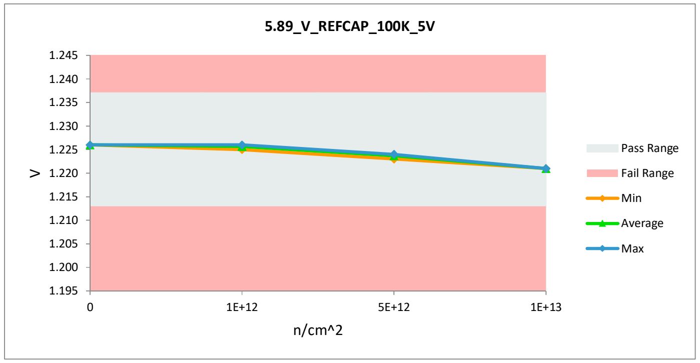


NDD Characterization Report
TPS7H5005-SEP

		5.89_V_REFCAP_100K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.226	-0.001
1E+12	2	1.226	1.225	-0.001
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.227	1.223	-0.004
5E+12	6	1.226	1.224	-0.002
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.226	1.221	-0.005
	Max	1.227	1.226	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

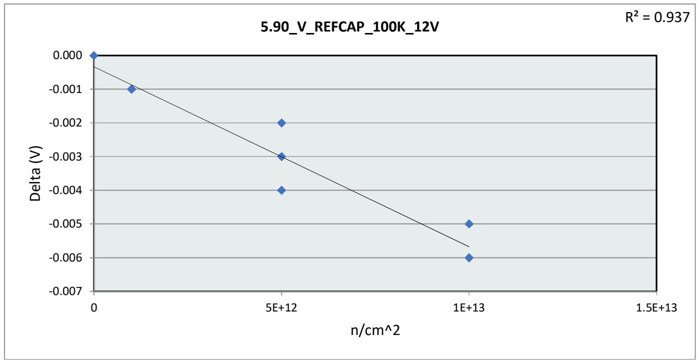


	5.89_V_REFCAP_100K_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.225	1.223	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.226	1.224	1.221
UL	1.237	1.237	1.237	1.237

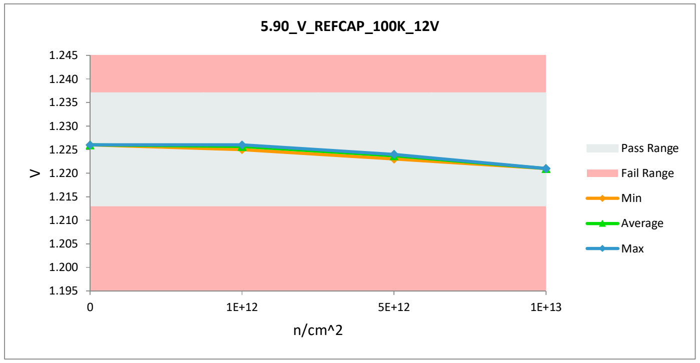


NDD Characterization Report
TPS7H5005-SEP

		5.90_V_REFCAP_100K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.226	-0.001
1E+12	2	1.226	1.225	-0.001
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.227	1.223	-0.004
5E+12	6	1.226	1.224	-0.002
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.226	1.221	-0.005
	Max	1.227	1.226	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

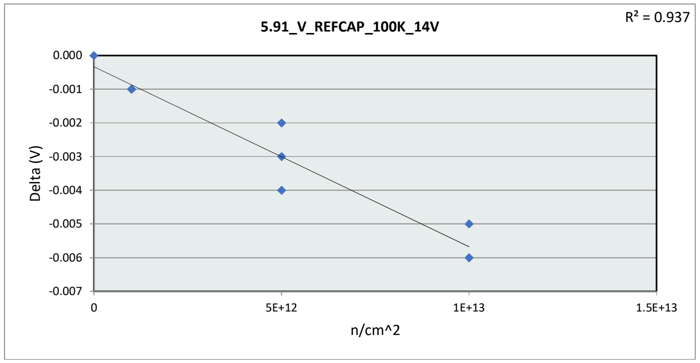


	5.90_V_REFCAP_100K_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.225	1.223	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.226	1.224	1.221
UL	1.237	1.237	1.237	1.237

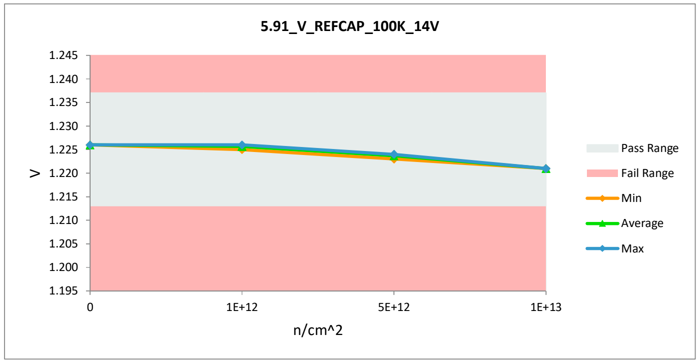


NDD Characterization Report
TPS7H5005-SEP

		5.91_V_REFCAP_100K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.226	-0.001
1E+12	2	1.226	1.225	-0.001
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.227	1.223	-0.004
5E+12	6	1.226	1.224	-0.002
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.226	1.221	-0.005
	Max	1.227	1.226	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

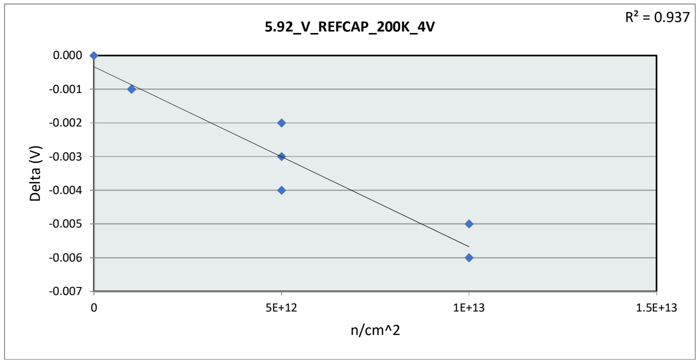


	5.91_V_REFCAP_100K_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.225	1.223	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.226	1.224	1.221
UL	1.237	1.237	1.237	1.237

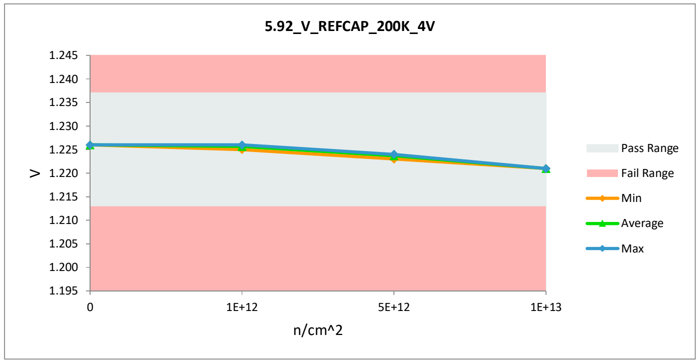


NDD Characterization Report
TPS7H5005-SEP

		5.92_V_REFCAP_200K_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.226	-0.001
1E+12	2	1.226	1.225	-0.001
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.227	1.223	-0.004
5E+12	6	1.226	1.224	-0.002
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.226	1.221	-0.005
	Max	1.227	1.226	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

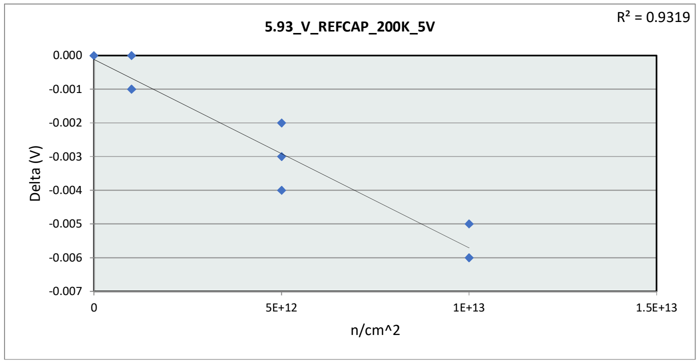


	5.92_V_REFCAP_200K_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.225	1.223	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.226	1.224	1.221
UL	1.237	1.237	1.237	1.237

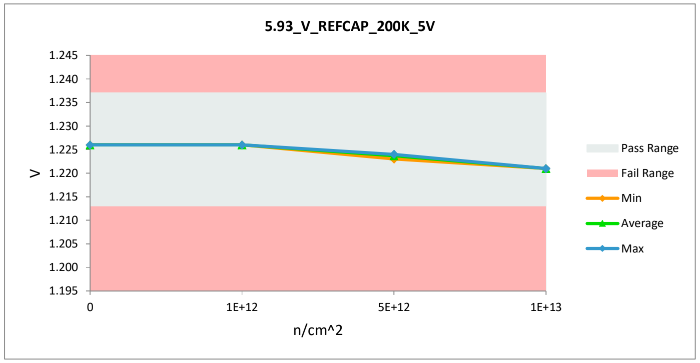


NDD Characterization Report
TPS7H5005-SEP

		5.93_V_REFCAP_200K_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.226	-0.001
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.227	1.223	-0.004
5E+12	6	1.226	1.224	-0.002
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.226	1.221	-0.005
	Max	1.227	1.226	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

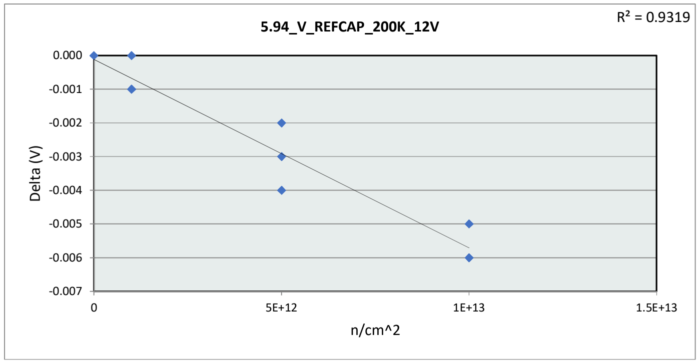


	5.93_V_REFCAP_200K_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.226	1.224	1.221
UL	1.237	1.237	1.237	1.237

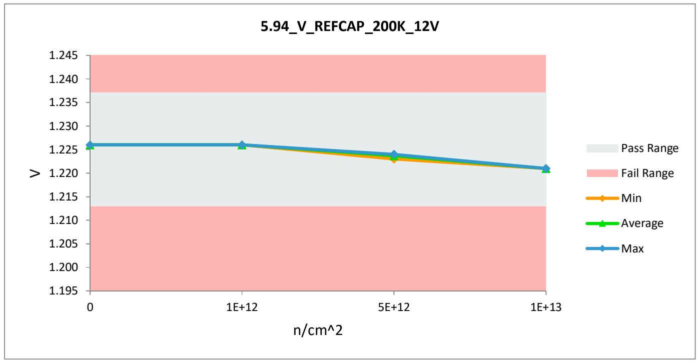


NDD Characterization Report
TPS7H5005-SEP

		5.94_V_REFCAP_200K_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.226	-0.001
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.227	1.223	-0.004
5E+12	6	1.226	1.224	-0.002
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.226	1.221	-0.005
	Max	1.227	1.226	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

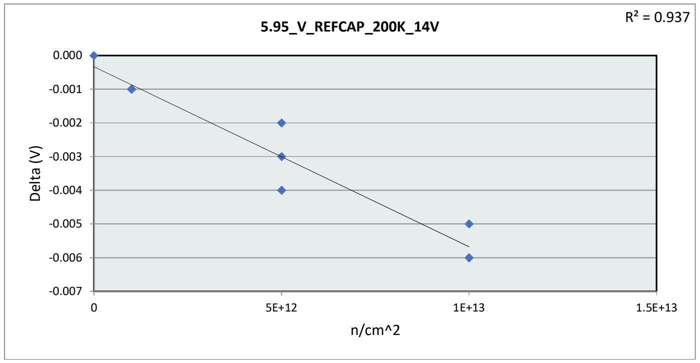


	5.94_V_REFCAP_200K_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.226	1.224	1.221
UL	1.237	1.237	1.237	1.237

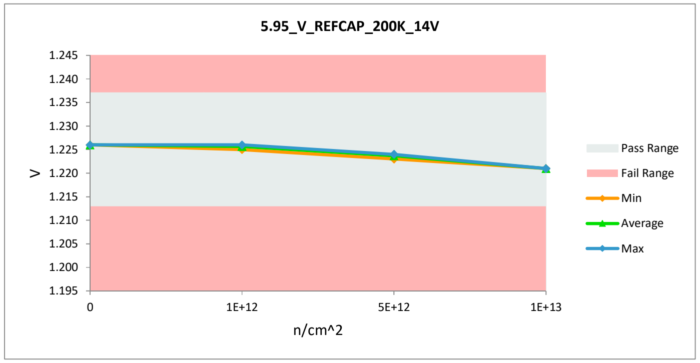


NDD Characterization Report
TPS7H5005-SEP

		5.95_V_REFCAP_200K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.226	-0.001
1E+12	2	1.226	1.225	-0.001
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.227	1.223	-0.004
5E+12	6	1.226	1.224	-0.002
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.226	1.221	-0.005
	Max	1.227	1.226	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

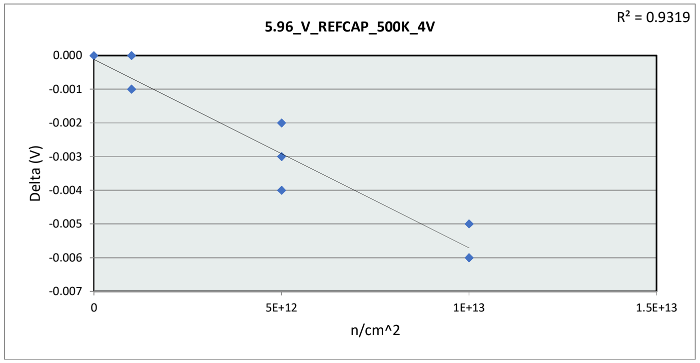


	5.95_V_REFCAP_200K_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.225	1.223	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.226	1.224	1.221
UL	1.237	1.237	1.237	1.237

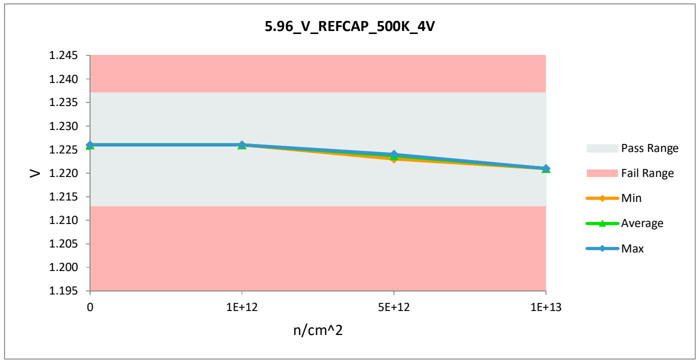


NDD Characterization Report
TPS7H5005-SEP

		5.96_V_REFCAP_500K_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.226	-0.001
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.227	1.223	-0.004
5E+12	6	1.226	1.224	-0.002
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.226	1.221	-0.005
	Max	1.227	1.226	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

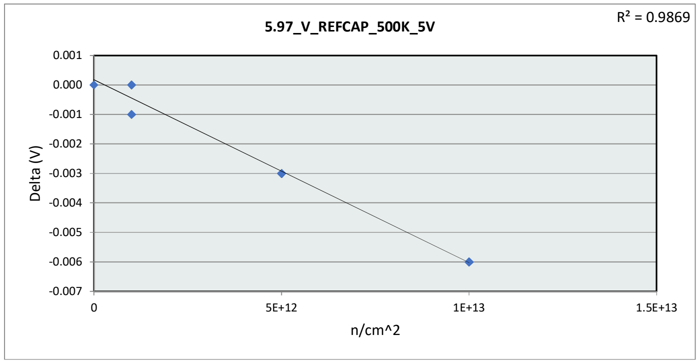


5.96_V_REFCAP_500K_4V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.223	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.226	1.224	1.221
UL	1.237	1.237	1.237	1.237

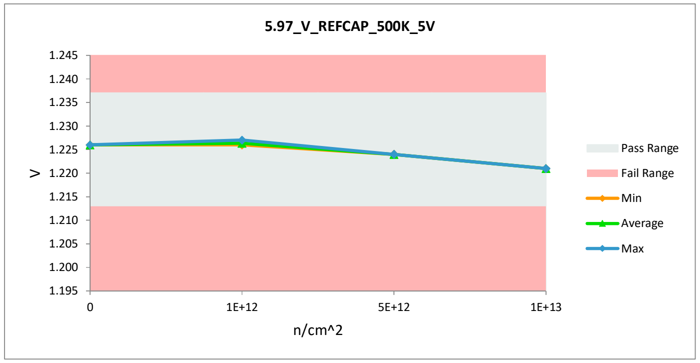


NDD Characterization Report
TPS7H5005-SEP

		5.97_V_REFCAP_500K_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.227	0.000
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.227	1.224	-0.003
5E+12	6	1.227	1.224	-0.003
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.227	1.221	-0.006
	Max	1.227	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.000	0.002	0.003

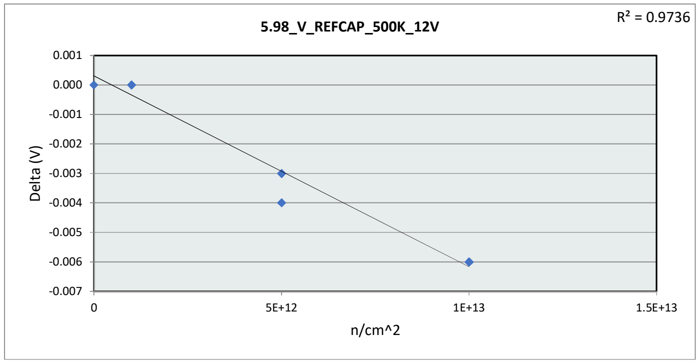


	5.97_V_REFCAP_500K_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.224	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

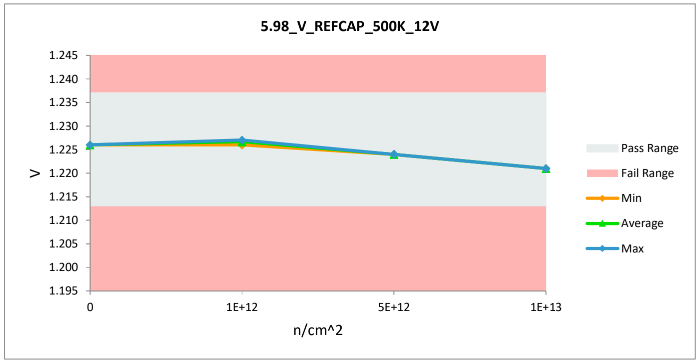


NDD Characterization Report
TPS7H5005-SEP

		5.98_V_REFCAP_500K_12V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.227	0.000
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.227	0.000
5E+12	4	1.228	1.224	-0.004
5E+12	5	1.227	1.224	-0.003
5E+12	6	1.227	1.224	-0.003
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.003

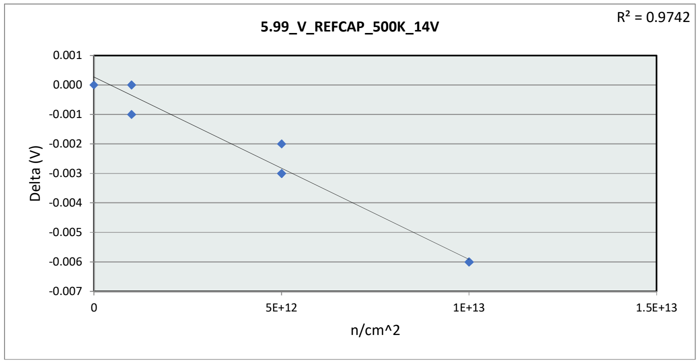


	5.98_V_REFCAP_500K_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.224	1.221
Average	1.226	1.227	1.224	1.221
Max	1.226	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

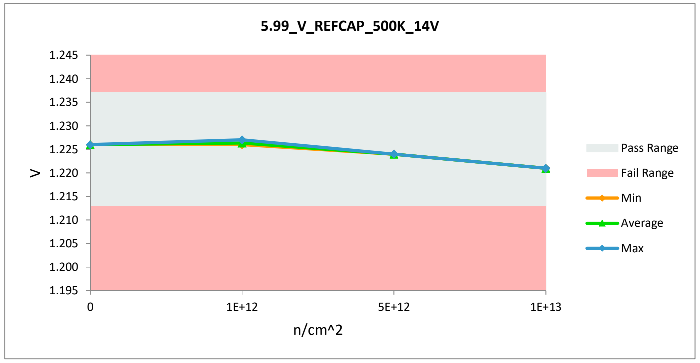


NDD Characterization Report
TPS7H5005-SEP

		5.99_V_REFCAP_500K_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.227	0.000
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.227	1.224	-0.003
5E+12	5	1.227	1.224	-0.003
5E+12	6	1.226	1.224	-0.002
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.227	1.221	-0.006
	Max	1.227	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.000	0.002	0.003

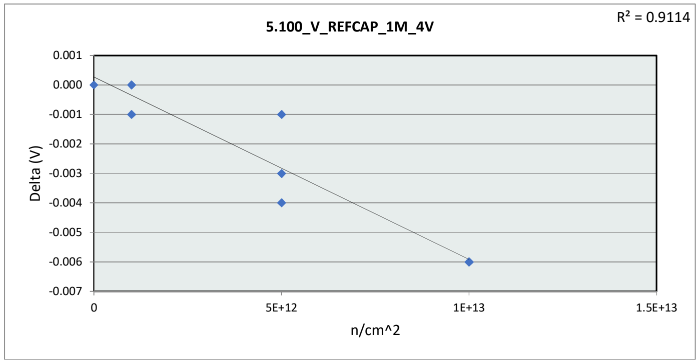


	5.99_V_REFCAP_500K_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.224	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.227	1.224	1.221
UL	1.237	1.237	1.237	1.237

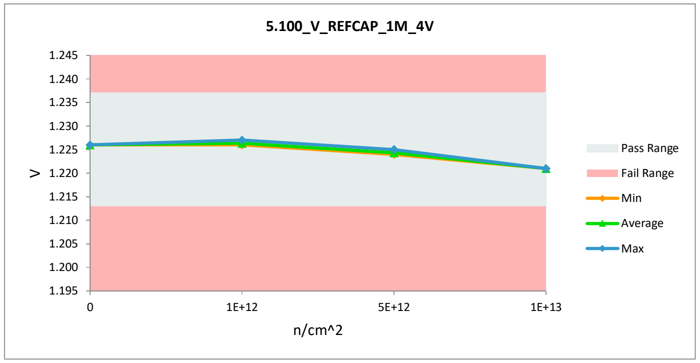


NDD Characterization Report
TPS7H5005-SEP

		5.100_V_REFCAP_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.227	0.000
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.226	-0.001
5E+12	4	1.228	1.224	-0.004
5E+12	5	1.227	1.224	-0.003
5E+12	6	1.226	1.225	-0.001
1E+13	7	1.227	1.221	-0.006
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.003

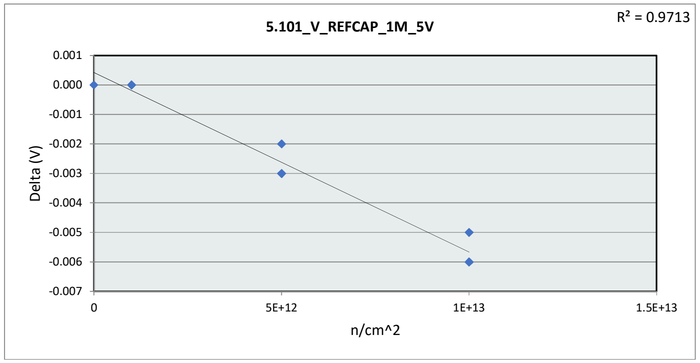


	5.100_V_REFCAP_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.224	1.221
Average	1.226	1.226	1.224	1.221
Max	1.226	1.227	1.225	1.221
UL	1.237	1.237	1.237	1.237

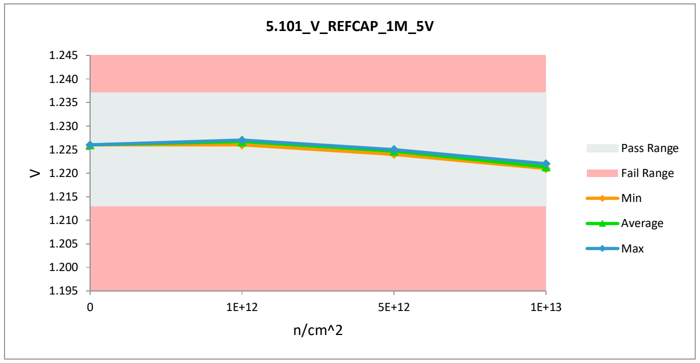


NDD Characterization Report
TPS7H5005-SEP

		5.101_V_REFCAP_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.227	0.000
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.227	0.000
5E+12	4	1.228	1.225	-0.003
5E+12	5	1.227	1.224	-0.003
5E+12	6	1.227	1.225	-0.002
1E+13	7	1.227	1.222	-0.005
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.003

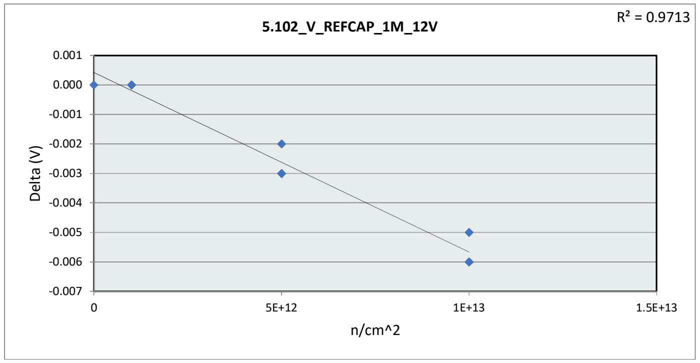


	5.101_V_REFCAP_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.224	1.221
Average	1.226	1.227	1.225	1.221
Max	1.226	1.227	1.225	1.222
UL	1.237	1.237	1.237	1.237

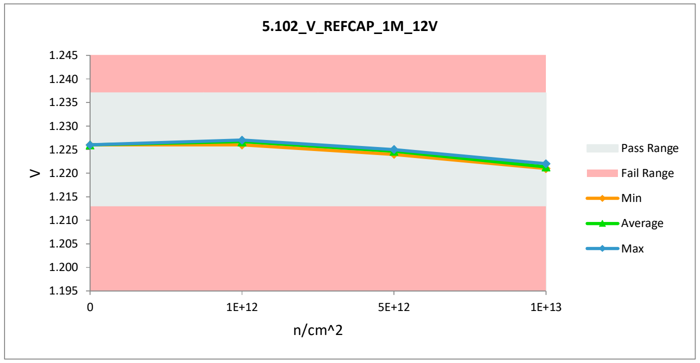


NDD Characterization Report
TPS7H5005-SEP

		5.102_V_REFCAP_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.227	0.000
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.227	0.000
5E+12	4	1.228	1.225	-0.003
5E+12	5	1.227	1.224	-0.003
5E+12	6	1.227	1.225	-0.002
1E+13	7	1.227	1.222	-0.005
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.003

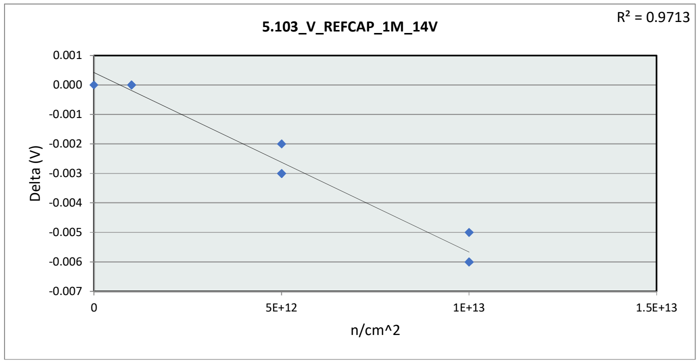


	5.102_V_REFCAP_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.224	1.221
Average	1.226	1.227	1.225	1.221
Max	1.226	1.227	1.225	1.222
UL	1.237	1.237	1.237	1.237

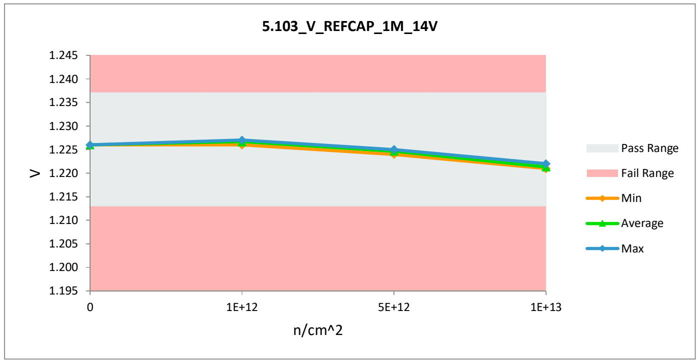


NDD Characterization Report
TPS7H5005-SEP

		5.103_V_REFCAP_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.227	0.000
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.227	0.000
5E+12	4	1.228	1.225	-0.003
5E+12	5	1.227	1.224	-0.003
5E+12	6	1.227	1.225	-0.002
1E+13	7	1.227	1.222	-0.005
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.003

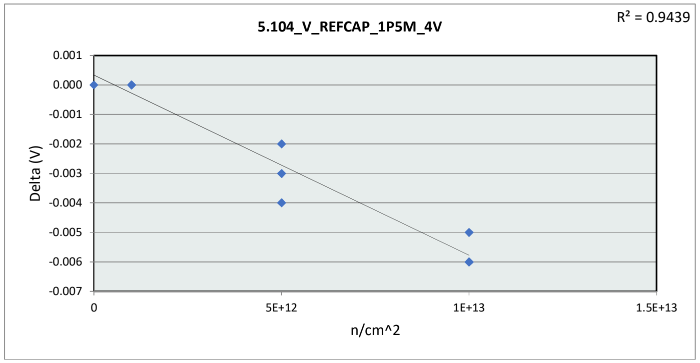


	5.103_V_REFCAP_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.224	1.221
Average	1.226	1.227	1.225	1.221
Max	1.226	1.227	1.225	1.222
UL	1.237	1.237	1.237	1.237

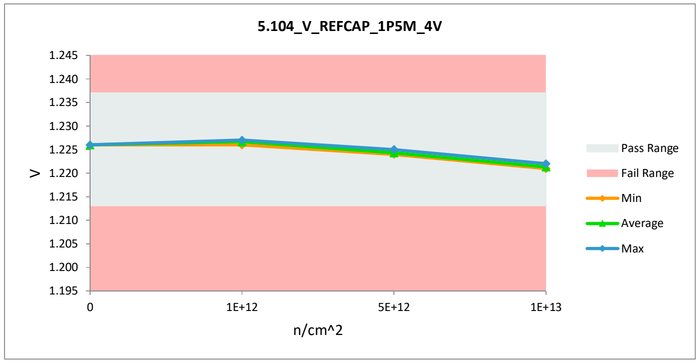


NDD Characterization Report
TPS7H5005-SEP

		5.104_V_REFCAP_1P5M_4V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.237	1.237	
Min Limit		1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.227	0.000
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.227	0.000
5E+12	4	1.228	1.224	-0.004
5E+12	5	1.227	1.224	-0.003
5E+12	6	1.227	1.225	-0.002
1E+13	7	1.227	1.222	-0.005
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.003

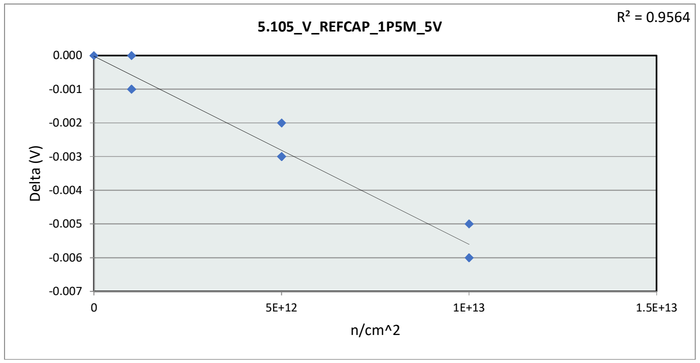


5.104_V_REFCAP_1P5M_4V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.224	1.221
Average	1.226	1.227	1.224	1.221
Max	1.226	1.227	1.225	1.222
UL	1.237	1.237	1.237	1.237

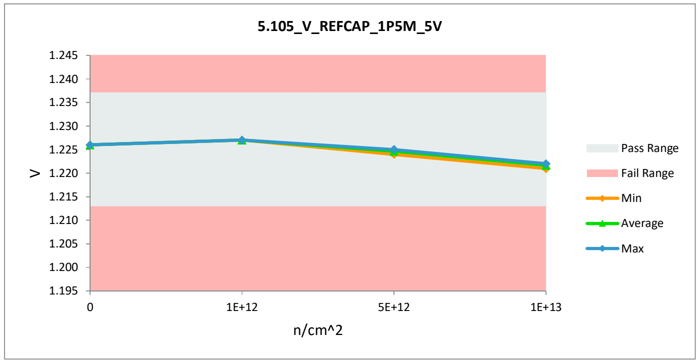


NDD Characterization Report
TPS7H5005-SEP

		5.105_V_REFCAP_1P5M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.228	1.227	-0.001
1E+12	2	1.227	1.227	0.000
1E+12	3	1.228	1.227	-0.001
5E+12	4	1.228	1.225	-0.003
5E+12	5	1.227	1.224	-0.003
5E+12	6	1.227	1.225	-0.002
1E+13	7	1.228	1.222	-0.006
1E+13	8	1.227	1.222	-0.005
1E+13	9	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.225	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

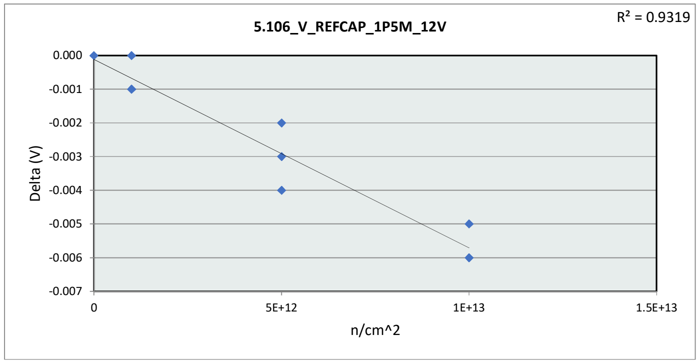


	5.105_V_REFCAP_1P5M_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.227	1.224	1.221
Average	1.226	1.227	1.225	1.222
Max	1.226	1.227	1.225	1.222
UL	1.237	1.237	1.237	1.237

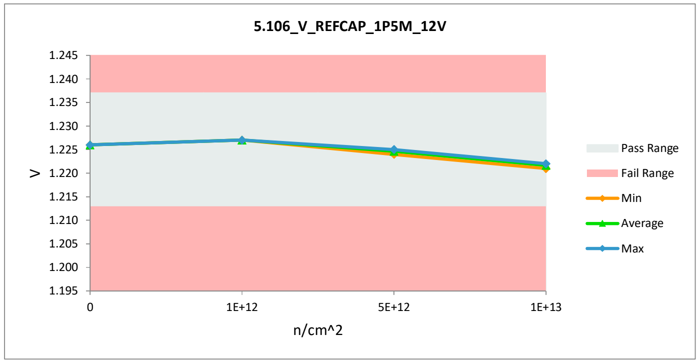


NDD Characterization Report
TPS7H5005-SEP

		5.106_V_REFCAP_1P5M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.228	1.227	-0.001
1E+12	2	1.227	1.227	0.000
1E+12	3	1.228	1.227	-0.001
5E+12	4	1.228	1.225	-0.003
5E+12	5	1.228	1.224	-0.004
5E+12	6	1.227	1.225	-0.002
1E+13	7	1.228	1.222	-0.006
1E+13	8	1.227	1.222	-0.005
1E+13	9	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.225	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

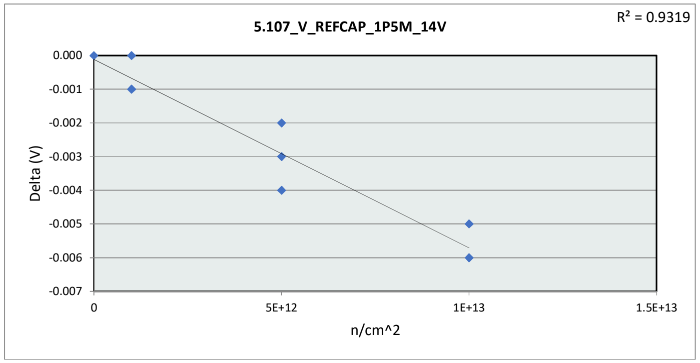


	5.106_V_REFCAP_1P5M_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.227	1.224	1.221
Average	1.226	1.227	1.225	1.222
Max	1.226	1.227	1.225	1.222
UL	1.237	1.237	1.237	1.237

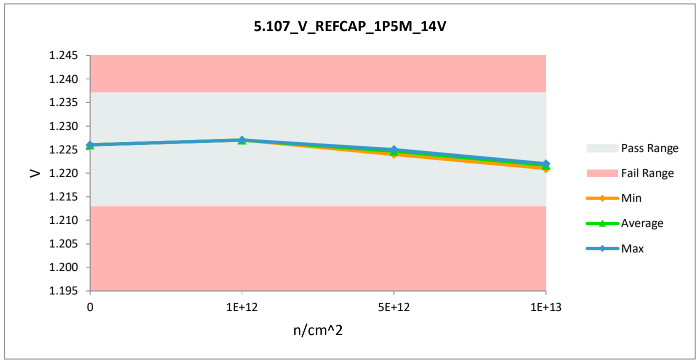


NDD Characterization Report
TPS7H5005-SEP

		5.107_V_REFCAP_1P5M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.228	1.227	-0.001
1E+12	2	1.227	1.227	0.000
1E+12	3	1.228	1.227	-0.001
5E+12	4	1.228	1.225	-0.003
5E+12	5	1.228	1.224	-0.004
5E+12	6	1.227	1.225	-0.002
1E+13	7	1.228	1.222	-0.006
1E+13	8	1.227	1.222	-0.005
1E+13	9	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.225	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.002

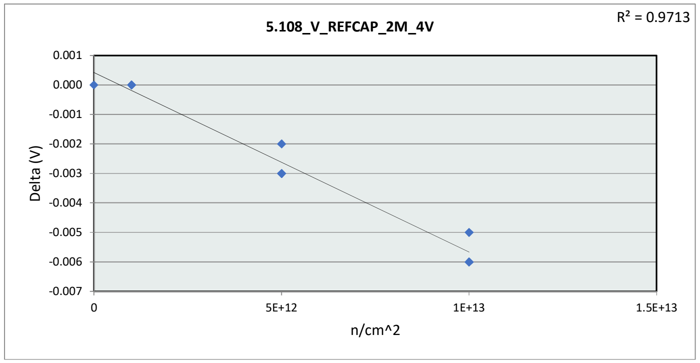


5.107_V_REFCAP_1P5M_14V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.227	1.224	1.221
Average	1.226	1.227	1.225	1.222
Max	1.226	1.227	1.225	1.222
UL	1.237	1.237	1.237	1.237

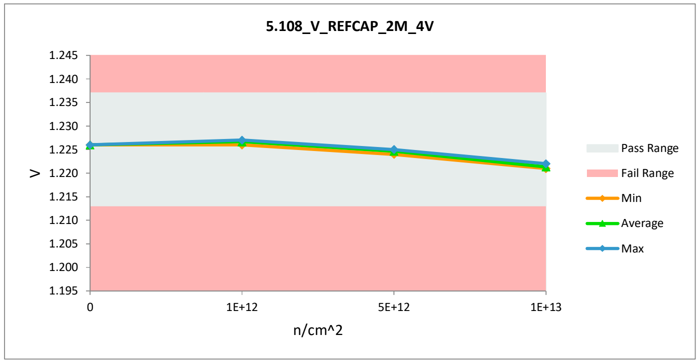


NDD Characterization Report
TPS7H5005-SEP

		5.108_V_REFCAP_2M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.226	1.226	0.000
1E+12	1	1.227	1.227	0.000
1E+12	2	1.226	1.226	0.000
1E+12	3	1.227	1.227	0.000
5E+12	4	1.228	1.225	-0.003
5E+12	5	1.227	1.224	-0.003
5E+12	6	1.227	1.225	-0.002
1E+13	7	1.227	1.222	-0.005
1E+13	8	1.227	1.221	-0.006
1E+13	9	1.227	1.221	-0.006
	Max	1.228	1.227	0.000
	Average	1.227	1.224	-0.003
	Min	1.226	1.221	-0.006
	Std Dev	0.001	0.002	0.003

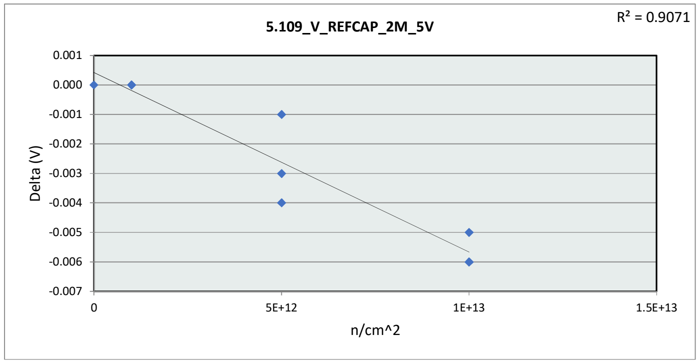


	5.108_V_REFCAP_2M_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.226	1.226	1.224	1.221
Average	1.226	1.227	1.225	1.221
Max	1.226	1.227	1.225	1.222
UL	1.237	1.237	1.237	1.237

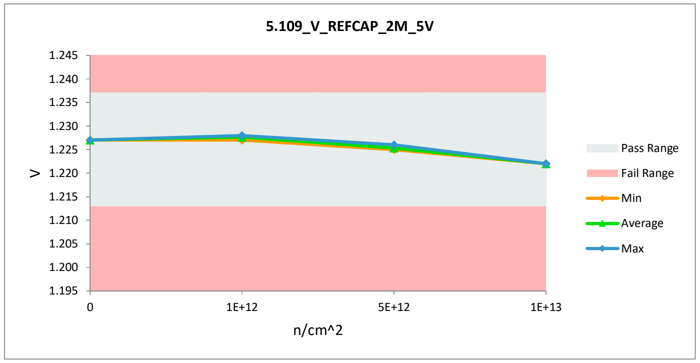


NDD Characterization Report
TPS7H5005-SEP

		5.109_V_REFCAP_2M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.227	1.227	0.000
1E+12	1	1.228	1.228	0.000
1E+12	2	1.227	1.227	0.000
1E+12	3	1.228	1.228	0.000
5E+12	4	1.229	1.225	-0.004
5E+12	5	1.228	1.225	-0.003
5E+12	6	1.227	1.226	-0.001
1E+13	7	1.228	1.222	-0.006
1E+13	8	1.228	1.222	-0.006
1E+13	9	1.227	1.222	-0.005
	Max	1.229	1.228	0.000
	Average	1.228	1.225	-0.003
	Min	1.227	1.222	-0.006
	Std Dev	0.001	0.002	0.003

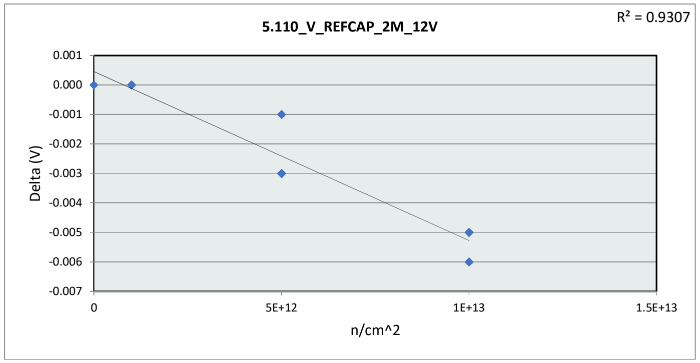


	5.109_V_REFCAP_2M_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.227	1.225	1.222
Average	1.227	1.228	1.225	1.222
Max	1.227	1.228	1.226	1.222
UL	1.237	1.237	1.237	1.237

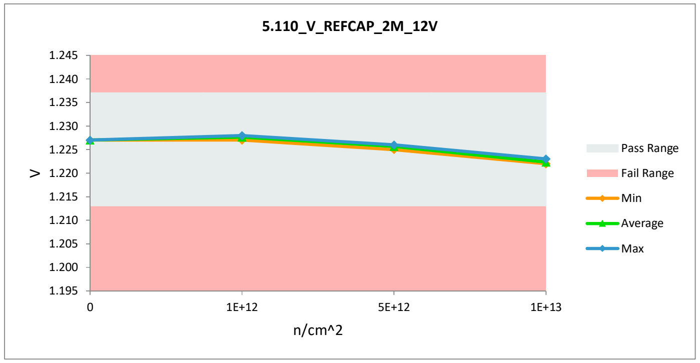


NDD Characterization Report
TPS7H5005-SEP

		5.110_V_REFCAP_2M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.227	1.227	0.000
1E+12	1	1.228	1.228	0.000
1E+12	2	1.227	1.227	0.000
1E+12	3	1.228	1.228	0.000
5E+12	4	1.229	1.226	-0.003
5E+12	5	1.228	1.225	-0.003
5E+12	6	1.227	1.226	-0.001
1E+13	7	1.228	1.223	-0.005
1E+13	8	1.228	1.222	-0.006
1E+13	9	1.227	1.222	-0.005
	Max	1.229	1.228	0.000
	Average	1.228	1.225	-0.002
	Min	1.227	1.222	-0.006
	Std Dev	0.001	0.002	0.002

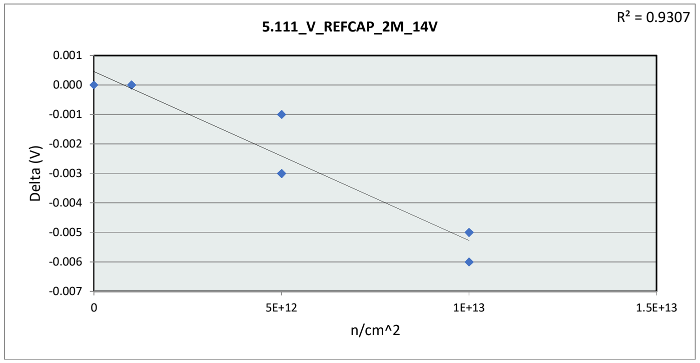


	5.110_V_REFCAP_2M_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.227	1.225	1.222
Average	1.227	1.228	1.226	1.222
Max	1.227	1.228	1.226	1.223
UL	1.237	1.237	1.237	1.237

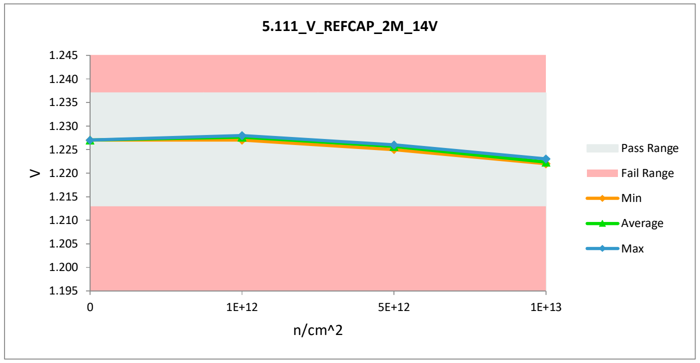


NDD Characterization Report
TPS7H5005-SEP

		5.111_V_REFCAP_2M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.237	1.237	
	Min Limit	1.213	1.213	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.227	1.227	0.000
1E+12	1	1.228	1.228	0.000
1E+12	2	1.227	1.227	0.000
1E+12	3	1.228	1.228	0.000
5E+12	4	1.229	1.226	-0.003
5E+12	5	1.228	1.225	-0.003
5E+12	6	1.227	1.226	-0.001
1E+13	7	1.228	1.223	-0.005
1E+13	8	1.228	1.222	-0.006
1E+13	9	1.227	1.222	-0.005
	Max	1.229	1.228	0.000
	Average	1.228	1.225	-0.002
	Min	1.227	1.222	-0.006
	Std Dev	0.001	0.002	0.002



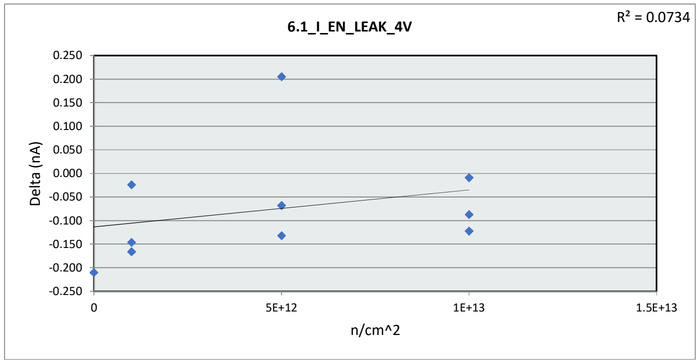
5.111_V_REFCAP_2M_14V				
Test Site				
Tester				
Test Number				
Max Limit	1.237	V		
Min Limit	1.213	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.213	1.213	1.213	1.213
Min	1.227	1.227	1.225	1.222
Average	1.227	1.228	1.226	1.222
Max	1.227	1.228	1.226	1.223
UL	1.237	1.237	1.237	1.237



NDD Characterization Report
TPS7H5005-SEP

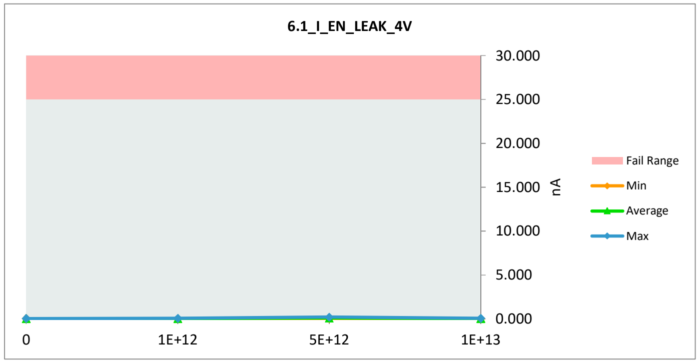
	6.1_I_EN_LEAK_4V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	25	25
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.256	0.046	-0.210
1E+12	1	0.178	0.032	-0.146
1E+12	2	0.227	0.061	-0.166
1E+12	3	0.056	0.032	-0.024
5E+12	4	0.105	0.037	-0.068
5E+12	5	0.002	0.207	0.205
5E+12	6	0.178	0.046	-0.132
1E+13	7	0.041	0.032	-0.009
1E+13	8	0.159	0.037	-0.122
1E+13	9	0.168	0.081	-0.087
	Max	0.256	0.207	0.205
	Average	0.137	0.061	-0.076
	Min	0.002	0.032	-0.210
	Std Dev	0.083	0.054	0.117



	6.1_I_EN_LEAK_4V	
Test Site		
Tester		
Test Number		
Max Limit	25	nA
Min Limit		nA

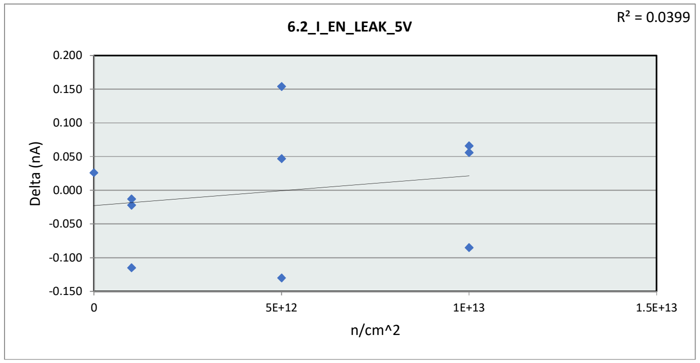
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.046	0.032	0.037	0.032
Average	0.046	0.042	0.097	0.050
Max	0.046	0.061	0.207	0.081
UL	25.000	25.000	25.000	25.000



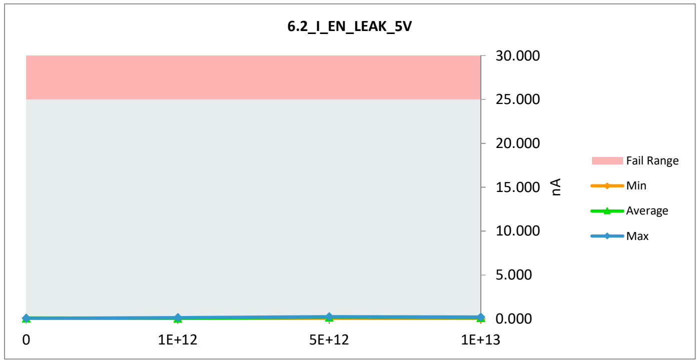
NDD Characterization Report
TPS7H5005-SEP

	6.2_I_EN_LEAK_5V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	25	25
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.059	0.085	0.026
1E+12	1	0.156	0.041	-0.115
1E+12	2	0.059	0.037	-0.022
1E+12	3	0.176	0.163	-0.013
5E+12	4	0.107	0.261	0.154
5E+12	5	0.195	0.242	0.047
5E+12	6	0.215	0.085	-0.130
1E+13	7	0.068	0.124	0.056
1E+13	8	0.166	0.232	0.066
1E+13	9	0.107	0.022	-0.085
	Max	0.215	0.261	0.154
	Average	0.131	0.129	-0.002
	Min	0.059	0.022	-0.130
	Std Dev	0.058	0.090	0.089

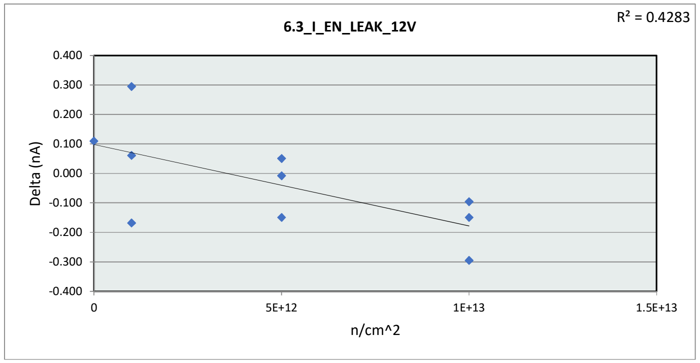


	6.2_I_EN_LEAK_5V			
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit		nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.085	0.037	0.085	0.022
Average	0.085	0.080	0.196	0.126
Max	0.085	0.163	0.261	0.232
UL	25.000	25.000	25.000	25.000

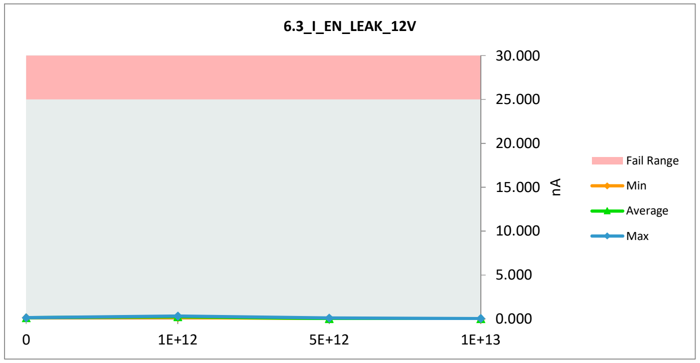


NDD Characterization Report
TPS7H5005-SEP

		6.3_I_EN_LEAK_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	nA	nA	
	Max Limit	25	25	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.029	0.139	0.110
1E+12	1	0.322	0.154	-0.168
1E+12	2	0.039	0.334	0.295
1E+12	3	0.254	0.315	0.061
5E+12	4	0.059	0.110	0.051
5E+12	5	0.166	0.017	-0.149
5E+12	6	0.059	0.051	-0.008
1E+13	7	0.322	0.027	-0.295
1E+13	8	0.156	0.007	-0.149
1E+13	9	0.137	0.041	-0.096
	Max	0.322	0.334	0.295
	Average	0.154	0.119	-0.035
	Min	0.029	0.007	-0.295
	Std Dev	0.112	0.119	0.171



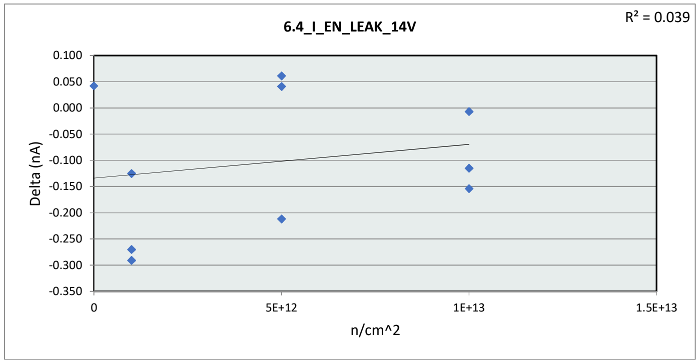
	6.3_I_EN_LEAK_12V			
Test Site				
Tester				
Test Number				
Max Limit	25	nA		
Min Limit		nA		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.139	0.154	0.017	0.007
Average	0.139	0.268	0.059	0.025
Max	0.139	0.334	0.110	0.041
UL	25.000	25.000	25.000	25.000



NDD Characterization Report
TPS7H5005-SEP

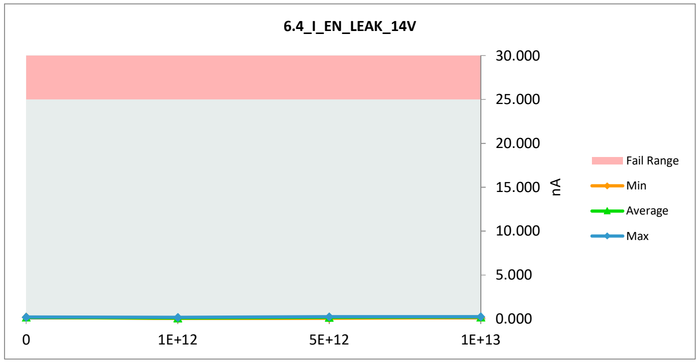
	6.4_I_EN_LEAK_14V	
Test Site		
Tester		
Test Number		
Unit	nA	nA
Max Limit	25	25
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.156	0.198	0.042
1E+12	1	0.293	0.168	-0.125
1E+12	2	0.390	0.120	-0.270
1E+12	3	0.332	0.041	-0.291
5E+12	4	0.146	0.207	0.061
5E+12	5	0.293	0.081	-0.212
5E+12	6	0.215	0.256	0.041
1E+13	7	0.371	0.256	-0.115
1E+13	8	0.185	0.178	-0.007
1E+13	9	0.303	0.149	-0.154
	Max	0.390	0.256	0.061
	Average	0.268	0.165	-0.103
	Min	0.146	0.041	-0.291
	Std Dev	0.088	0.070	0.132



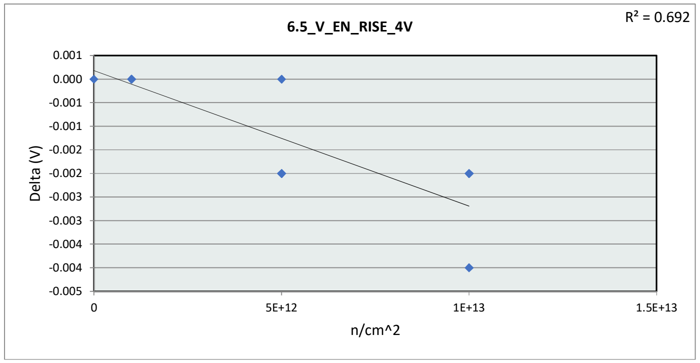
	6.4_I_EN_LEAK_14V	
Test Site		
Tester		
Test Number		
Max Limit	25	nA
Min Limit		nA

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.198	0.041	0.081	0.149
Average	0.198	0.110	0.181	0.194
Max	0.198	0.168	0.256	0.256
UL	25.000	25.000	25.000	25.000

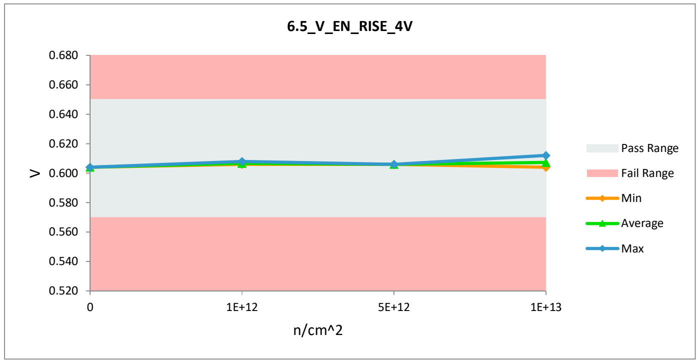


NDD Characterization Report
TPS7H5005-SEP

		6.5_V_EN_RISE_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.65	0.65	
	Min Limit	0.57	0.57	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.604	0.604	0.000
1E+12	1	0.606	0.606	0.000
1E+12	2	0.608	0.608	0.000
1E+12	3	0.606	0.606	0.000
5E+12	4	0.608	0.606	-0.002
5E+12	5	0.608	0.606	-0.002
5E+12	6	0.606	0.606	0.000
1E+13	7	0.606	0.604	-0.002
1E+13	8	0.616	0.612	-0.004
1E+13	9	0.608	0.606	-0.002
	Max	0.616	0.612	0.000
	Average	0.608	0.606	-0.001
	Min	0.604	0.604	-0.004
	Std Dev	0.003	0.002	0.001

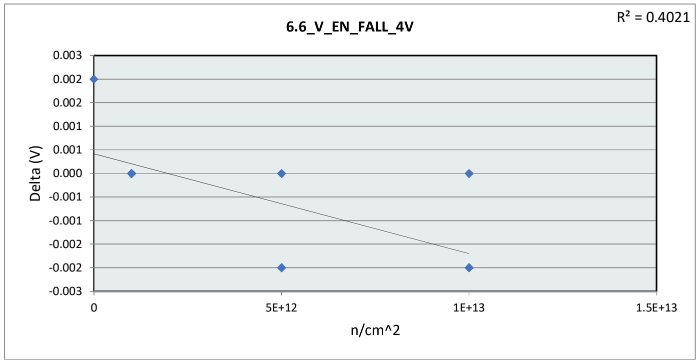


	6.5_V_EN_RISE_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.65	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.604	0.606	0.606	0.604
Average	0.604	0.607	0.606	0.607
Max	0.604	0.608	0.606	0.612
UL	0.650	0.650	0.650	0.650

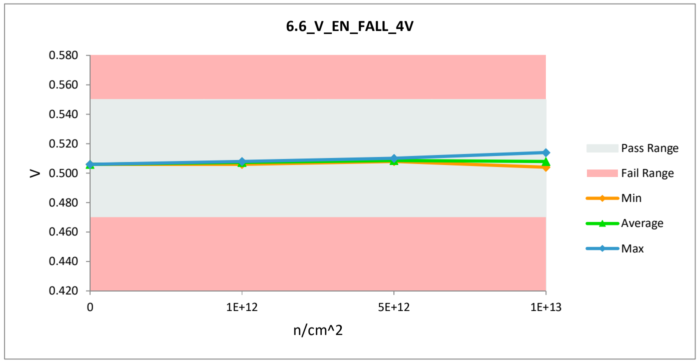


NDD Characterization Report
TPS7H5005-SEP

		6.6_V_EN_FALL_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.55	0.55	
	Min Limit	0.47	0.47	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.504	0.506	0.002
1E+12	1	0.506	0.506	0.000
1E+12	2	0.508	0.508	0.000
1E+12	3	0.508	0.508	0.000
5E+12	4	0.512	0.510	-0.002
5E+12	5	0.510	0.508	-0.002
5E+12	6	0.508	0.508	0.000
1E+13	7	0.506	0.504	-0.002
1E+13	8	0.514	0.514	0.000
1E+13	9	0.508	0.506	-0.002
	Max	0.514	0.514	0.002
	Average	0.508	0.508	-0.001
	Min	0.504	0.504	-0.002
	Std Dev	0.003	0.003	0.001

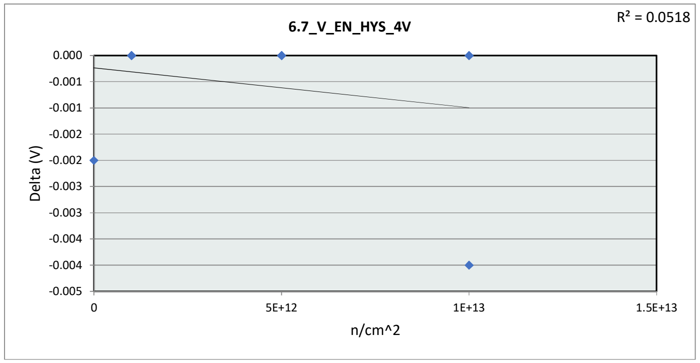


	6.6_V_EN_FALL_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.55	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.506	0.508	0.504
Average	0.506	0.507	0.509	0.508
Max	0.506	0.508	0.510	0.514
UL	0.550	0.550	0.550	0.550

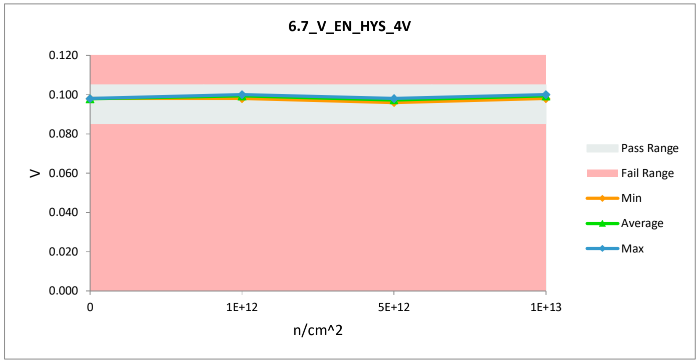


NDD Characterization Report
TPS7H5005-SEP

		6.7_V_EN_HYS_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.100	0.098	-0.002
1E+12	1	0.100	0.100	0.000
1E+12	2	0.100	0.100	0.000
1E+12	3	0.098	0.098	0.000
5E+12	4	0.096	0.096	0.000
5E+12	5	0.098	0.098	0.000
5E+12	6	0.098	0.098	0.000
1E+13	7	0.100	0.100	0.000
1E+13	8	0.102	0.098	-0.004
1E+13	9	0.100	0.100	0.000
	Max	0.102	0.100	0.000
	Average	0.099	0.099	-0.001
	Min	0.096	0.096	-0.004
	Std Dev	0.002	0.001	0.001

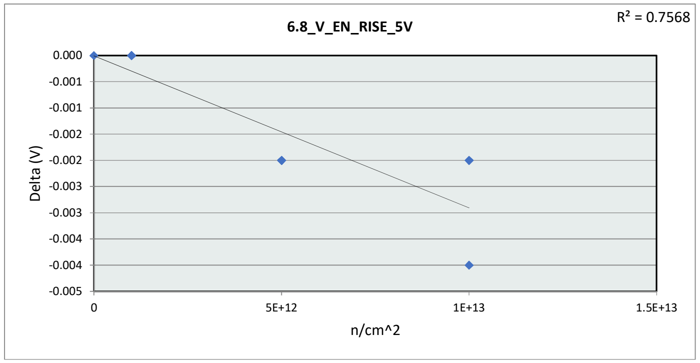


	6.7_V_EN_HYS_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.098	0.098	0.096	0.098
Average	0.098	0.099	0.097	0.099
Max	0.098	0.100	0.098	0.100
UL	0.105	0.105	0.105	0.105

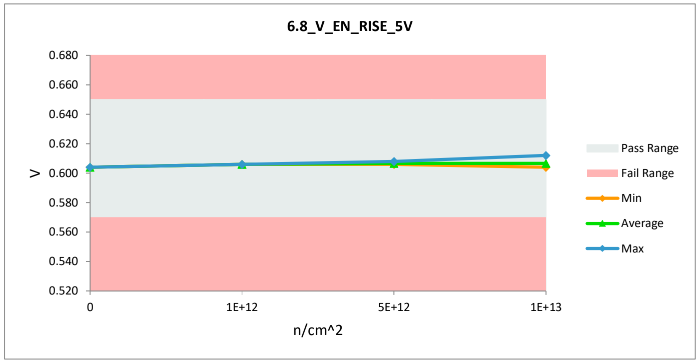


NDD Characterization Report
TPS7H5005-SEP

		6.8_V_EN_RISE_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.65	0.65	
	Min Limit	0.57	0.57	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.604	0.604	0.000
1E+12	1	0.606	0.606	0.000
1E+12	2	0.606	0.606	0.000
1E+12	3	0.606	0.606	0.000
5E+12	4	0.610	0.608	-0.002
5E+12	5	0.608	0.606	-0.002
5E+12	6	0.608	0.606	-0.002
1E+13	7	0.606	0.604	-0.002
1E+13	8	0.616	0.612	-0.004
1E+13	9	0.606	0.604	-0.002
	Max	0.616	0.612	0.000
	Average	0.608	0.606	-0.001
	Min	0.604	0.604	-0.004
	Std Dev	0.003	0.002	0.001

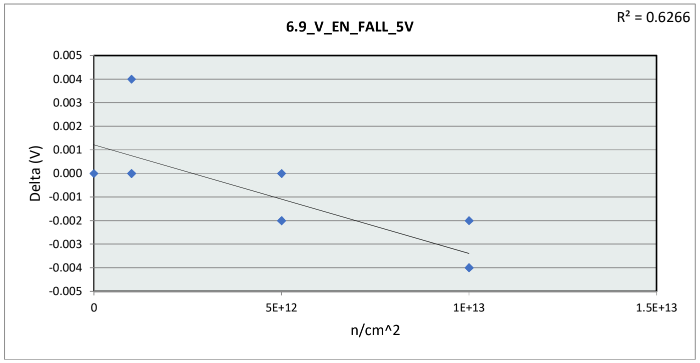


	6.8_V_EN_RISE_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.65	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.604	0.606	0.606	0.604
Average	0.604	0.606	0.607	0.607
Max	0.604	0.606	0.608	0.612
UL	0.650	0.650	0.650	0.650

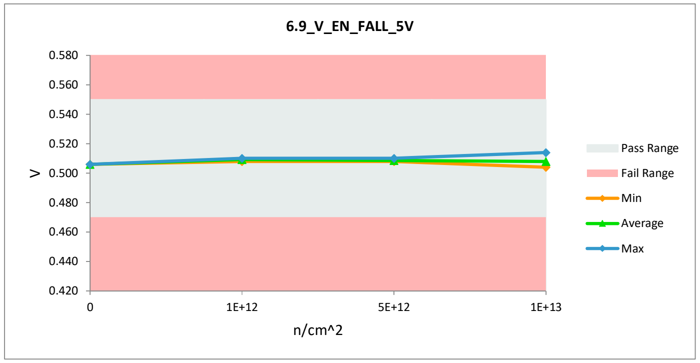


NDD Characterization Report
TPS7H5005-SEP

		6.9_V_EN_FALL_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.55	0.55	
	Min Limit	0.47	0.47	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.506	0.506	0.000
1E+12	1	0.506	0.510	0.004
1E+12	2	0.510	0.510	0.000
1E+12	3	0.508	0.508	0.000
5E+12	4	0.512	0.510	-0.002
5E+12	5	0.510	0.508	-0.002
5E+12	6	0.508	0.508	0.000
1E+13	7	0.506	0.504	-0.002
1E+13	8	0.518	0.514	-0.004
1E+13	9	0.510	0.506	-0.004
	Max	0.518	0.514	0.004
	Average	0.509	0.508	-0.001
	Min	0.506	0.504	-0.004
	Std Dev	0.004	0.003	0.002

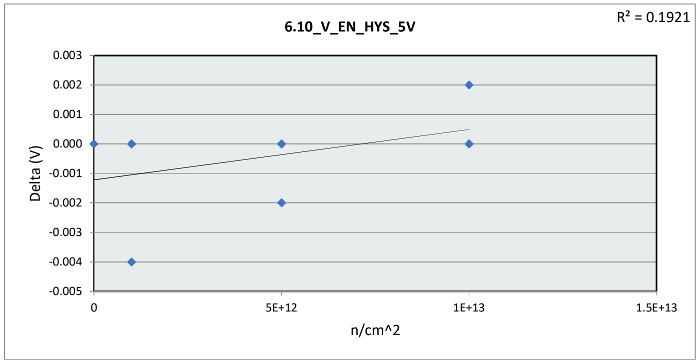


	6.9_V_EN_FALL_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.55	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.504
Average	0.506	0.509	0.509	0.508
Max	0.506	0.510	0.510	0.514
UL	0.550	0.550	0.550	0.550

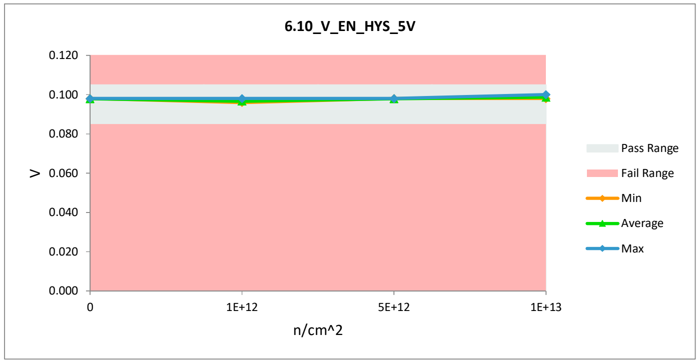


NDD Characterization Report
TPS7H5005-SEP

		6.10_V_EN_HYS_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.098	0.098	0.000
1E+12	1	0.100	0.096	-0.004
1E+12	2	0.096	0.096	0.000
1E+12	3	0.098	0.098	0.000
5E+12	4	0.098	0.098	0.000
5E+12	5	0.098	0.098	0.000
5E+12	6	0.100	0.098	-0.002
1E+13	7	0.100	0.100	0.000
1E+13	8	0.098	0.098	0.000
1E+13	9	0.096	0.098	0.002
	Max	0.100	0.100	0.002
	Average	0.098	0.098	0.000
	Min	0.096	0.096	-0.004
	Std Dev	0.001	0.001	0.002

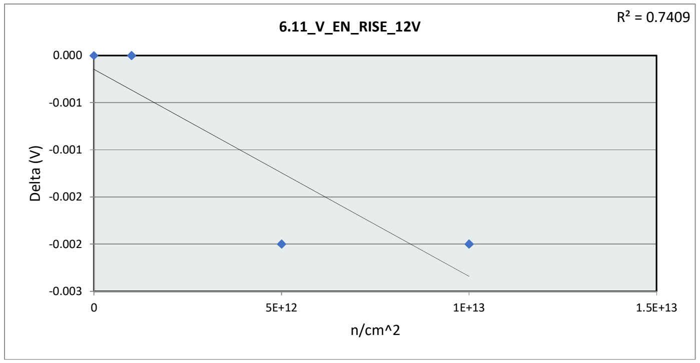


6.10_V_EN_HYS_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.098	0.096	0.098	0.098
Average	0.098	0.097	0.098	0.099
Max	0.098	0.098	0.098	0.100
UL	0.105	0.105	0.105	0.105

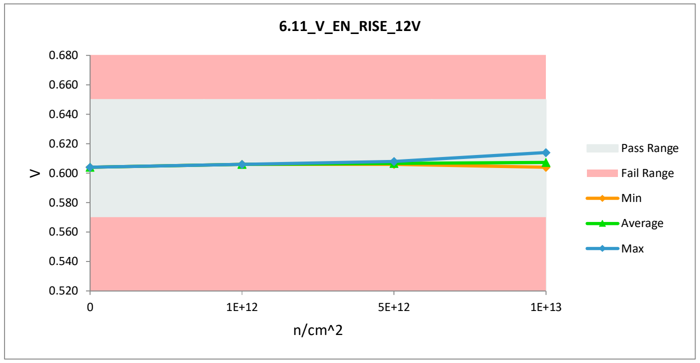


NDD Characterization Report
TPS7H5005-SEP

		6.11_V_EN_RISE_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.65	0.65	
	Min Limit	0.57	0.57	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.604	0.604	0.000
1E+12	1	0.606	0.606	0.000
1E+12	2	0.606	0.606	0.000
1E+12	3	0.606	0.606	0.000
5E+12	4	0.610	0.608	-0.002
5E+12	5	0.608	0.606	-0.002
5E+12	6	0.608	0.606	-0.002
1E+13	7	0.606	0.604	-0.002
1E+13	8	0.616	0.614	-0.002
1E+13	9	0.606	0.604	-0.002
	Max	0.616	0.614	0.000
	Average	0.608	0.606	-0.001
	Min	0.604	0.604	-0.002
	Std Dev	0.003	0.003	0.001

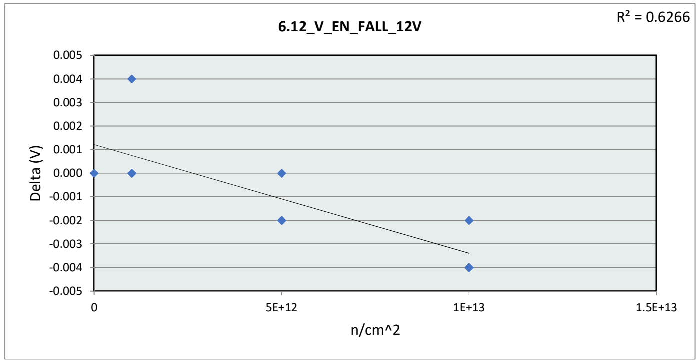


	6.11_V_EN_RISE_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.65	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.604	0.606	0.606	0.604
Average	0.604	0.606	0.607	0.607
Max	0.604	0.606	0.608	0.614
UL	0.650	0.650	0.650	0.650

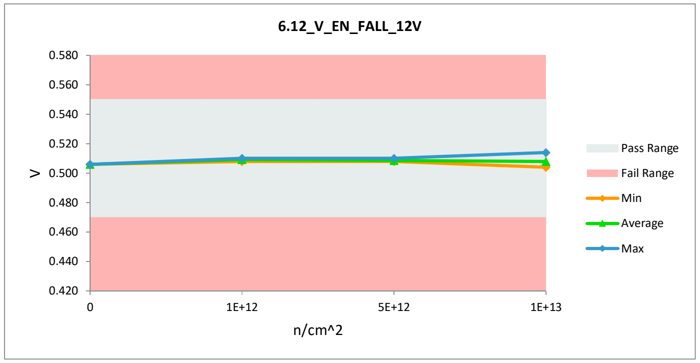


NDD Characterization Report
TPS7H5005-SEP

		6.12_V_EN_FALL_12V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.55	0.55	
Min Limit		0.47	0.47	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.506	0.506	0.000
1E+12	1	0.506	0.510	0.004
1E+12	2	0.510	0.510	0.000
1E+12	3	0.508	0.508	0.000
5E+12	4	0.512	0.510	-0.002
5E+12	5	0.510	0.508	-0.002
5E+12	6	0.508	0.508	0.000
1E+13	7	0.506	0.504	-0.002
1E+13	8	0.518	0.514	-0.004
1E+13	9	0.510	0.506	-0.004
	Max	0.518	0.514	0.004
	Average	0.509	0.508	-0.001
	Min	0.506	0.504	-0.004
	Std Dev	0.004	0.003	0.002

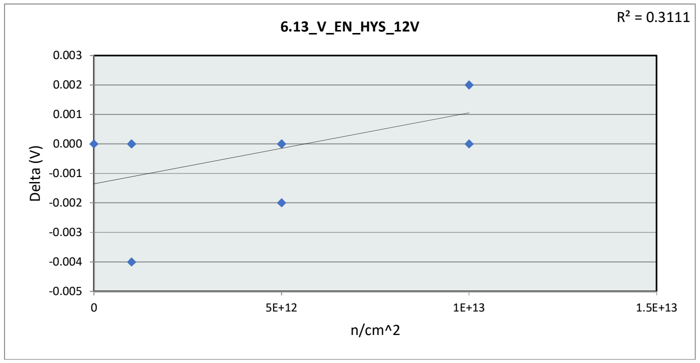


	6.12_V_EN_FALL_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.55	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.504
Average	0.506	0.509	0.509	0.508
Max	0.506	0.510	0.510	0.514
UL	0.550	0.550	0.550	0.550

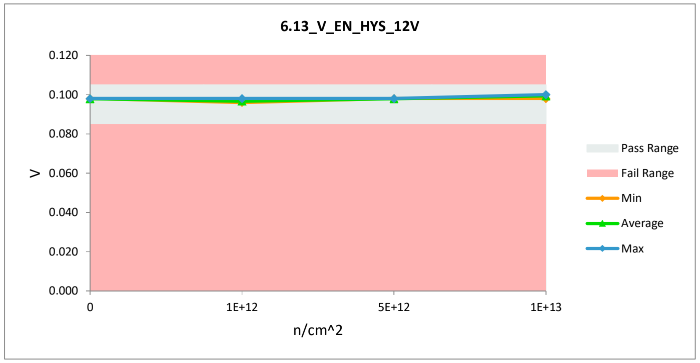


NDD Characterization Report
TPS7H5005-SEP

		6.13_V_EN_HYS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.098	0.098	0.000
1E+12	1	0.100	0.096	-0.004
1E+12	2	0.096	0.096	0.000
1E+12	3	0.098	0.098	0.000
5E+12	4	0.098	0.098	0.000
5E+12	5	0.098	0.098	0.000
5E+12	6	0.100	0.098	-0.002
1E+13	7	0.100	0.100	0.000
1E+13	8	0.098	0.100	0.002
1E+13	9	0.096	0.098	0.002
	Max	0.100	0.100	0.002
	Average	0.098	0.098	0.000
	Min	0.096	0.096	-0.004
	Std Dev	0.001	0.001	0.002

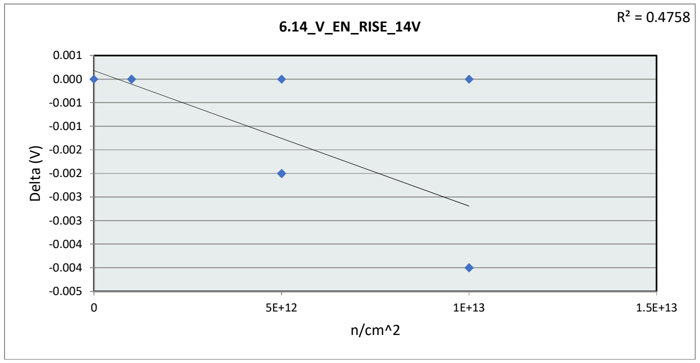


	6.13_V_EN_HYS_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.098	0.096	0.098	0.098
Average	0.098	0.097	0.098	0.099
Max	0.098	0.098	0.098	0.100
UL	0.105	0.105	0.105	0.105

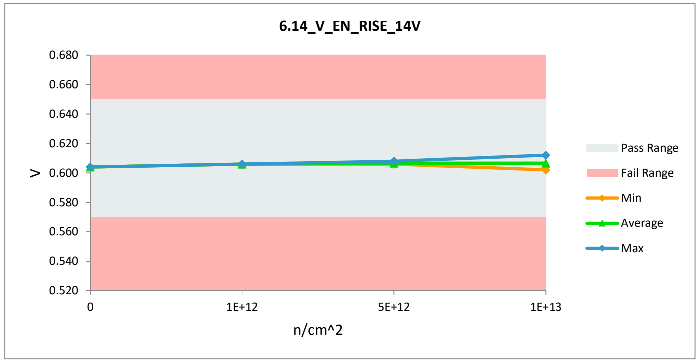


NDD Characterization Report
TPS7H5005-SEP

		6.14_V_EN_RISE_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.65	0.65	
	Min Limit	0.57	0.57	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.604	0.604	0.000
1E+12	1	0.606	0.606	0.000
1E+12	2	0.606	0.606	0.000
1E+12	3	0.606	0.606	0.000
5E+12	4	0.608	0.608	0.000
5E+12	5	0.608	0.606	-0.002
5E+12	6	0.608	0.606	-0.002
1E+13	7	0.606	0.602	-0.004
1E+13	8	0.616	0.612	-0.004
1E+13	9	0.606	0.606	0.000
	Max	0.616	0.612	0.000
	Average	0.607	0.606	-0.001
	Min	0.604	0.602	-0.004
	Std Dev	0.003	0.003	0.002

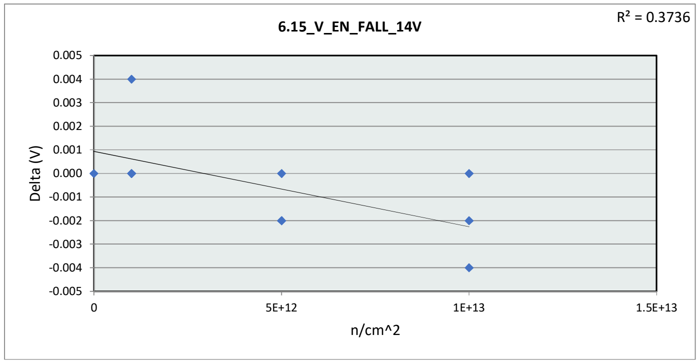


	6.14_V_EN_RISE_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.65	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.604	0.606	0.606	0.602
Average	0.604	0.606	0.607	0.607
Max	0.604	0.606	0.608	0.612
UL	0.650	0.650	0.650	0.650

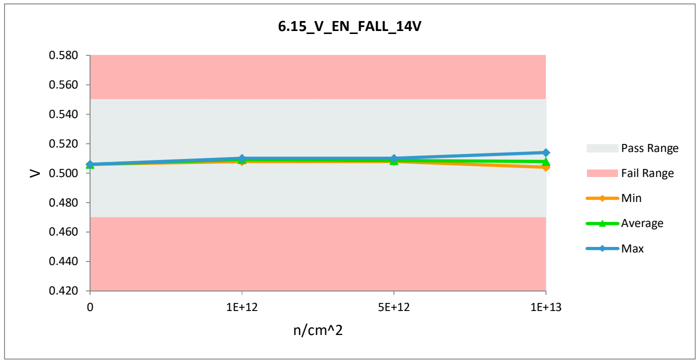


NDD Characterization Report
TPS7H5005-SEP

		6.15_V_EN_FALL_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.55	0.55	
Min Limit		0.47	0.47	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.506	0.506	0.000
1E+12	1	0.506	0.510	0.004
1E+12	2	0.510	0.510	0.000
1E+12	3	0.508	0.508	0.000
5E+12	4	0.512	0.510	-0.002
5E+12	5	0.510	0.508	-0.002
5E+12	6	0.508	0.508	0.000
1E+13	7	0.506	0.504	-0.002
1E+13	8	0.514	0.514	0.000
1E+13	9	0.510	0.506	-0.004
	Max	0.514	0.514	0.004
	Average	0.509	0.508	-0.001
	Min	0.506	0.504	-0.004
	Std Dev	0.003	0.003	0.002

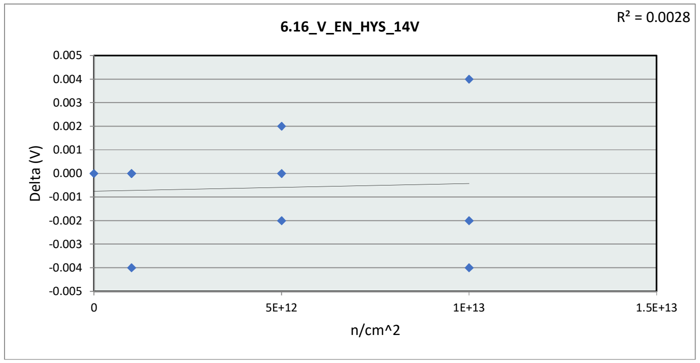


	6.15_V_EN_FALL_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.55	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.506	0.508	0.508	0.504
Average	0.506	0.509	0.509	0.508
Max	0.506	0.510	0.510	0.514
UL	0.550	0.550	0.550	0.550

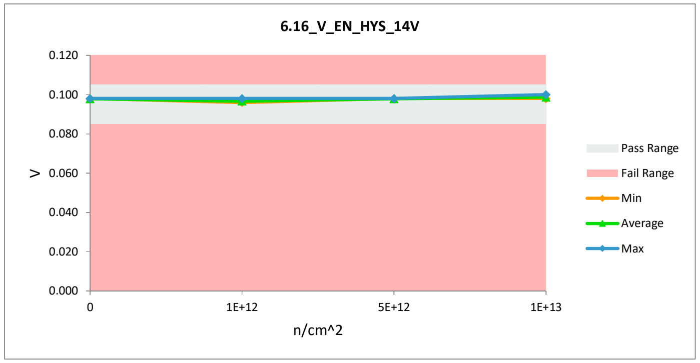


NDD Characterization Report
TPS7H5005-SEP

		6.16_V_EN_HYS_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.105	0.105	
	Min Limit	0.085	0.085	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.098	0.098	0.000
1E+12	1	0.100	0.096	-0.004
1E+12	2	0.096	0.096	0.000
1E+12	3	0.098	0.098	0.000
5E+12	4	0.096	0.098	0.002
5E+12	5	0.098	0.098	0.000
5E+12	6	0.100	0.098	-0.002
1E+13	7	0.100	0.098	-0.002
1E+13	8	0.102	0.098	-0.004
1E+13	9	0.096	0.100	0.004
	Max	0.102	0.100	0.004
	Average	0.098	0.098	-0.001
	Min	0.096	0.096	-0.004
	Std Dev	0.002	0.001	0.003

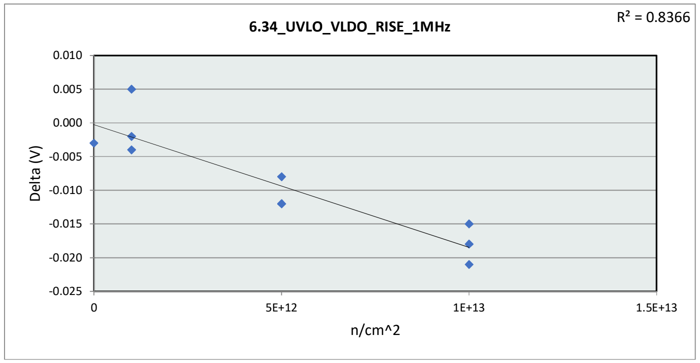


6.16_V_EN_HYS_14V				
Test Site				
Tester				
Test Number				
Max Limit	0.105	V		
Min Limit	0.085	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.085	0.085	0.085	0.085
Min	0.098	0.096	0.098	0.098
Average	0.098	0.097	0.098	0.099
Max	0.098	0.098	0.098	0.100
UL	0.105	0.105	0.105	0.105

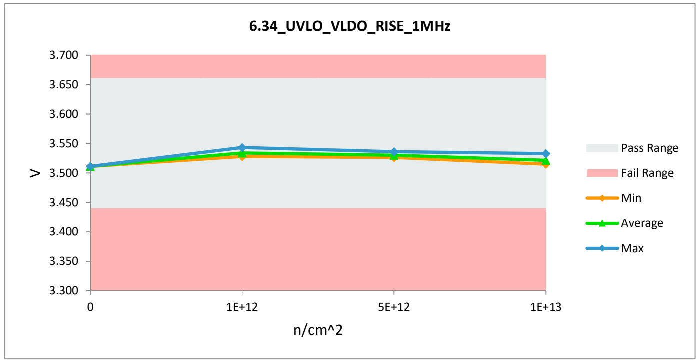


NDD Characterization Report
TPS7H5005-SEP

		6.34_UVLO_VLDO_RISE_1MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.66	3.66	
	Min Limit	3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	3.514	3.511	-0.003
1E+12	1	3.535	3.531	-0.004
1E+12	2	3.538	3.543	0.005
1E+12	3	3.530	3.528	-0.002
5E+12	4	3.548	3.536	-0.012
5E+12	5	3.538	3.526	-0.012
5E+12	6	3.536	3.528	-0.008
1E+13	7	3.533	3.515	-0.018
1E+13	8	3.554	3.533	-0.021
1E+13	9	3.532	3.517	-0.015
	Max	3.554	3.543	0.005
	Average	3.536	3.527	-0.009
	Min	3.514	3.511	-0.021
	Std Dev	0.011	0.010	0.008

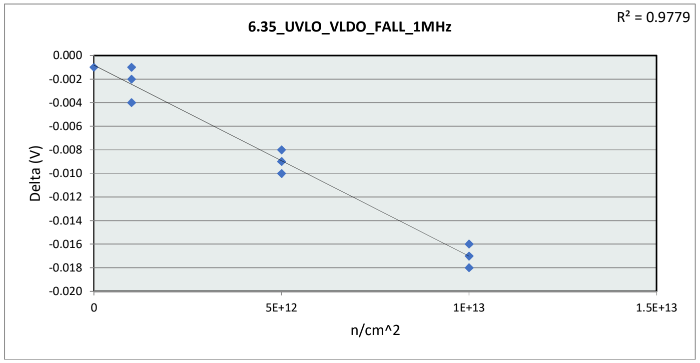


	6.34_UVLO_VLDO_RISE_1MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.511	3.528	3.526	3.515
Average	3.511	3.534	3.530	3.522
Max	3.511	3.543	3.536	3.533
UL	3.660	3.660	3.660	3.660

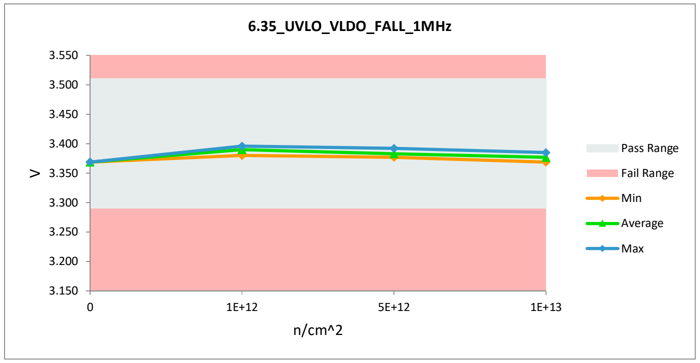


NDD Characterization Report
TPS7H5005-SEP

		6.35_UVLO_VLDO_FALL_1MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	3.370	3.369	-0.001
1E+12	1	3.398	3.396	-0.002
1E+12	2	3.395	3.394	-0.001
1E+12	3	3.384	3.380	-0.004
5E+12	4	3.401	3.392	-0.009
5E+12	5	3.387	3.377	-0.010
5E+12	6	3.387	3.379	-0.008
1E+13	7	3.385	3.369	-0.016
1E+13	8	3.403	3.385	-0.018
1E+13	9	3.393	3.376	-0.017
	Max	3.403	3.396	-0.001
	Average	3.390	3.382	-0.009
	Min	3.370	3.369	-0.018
	Std Dev	0.010	0.010	0.007



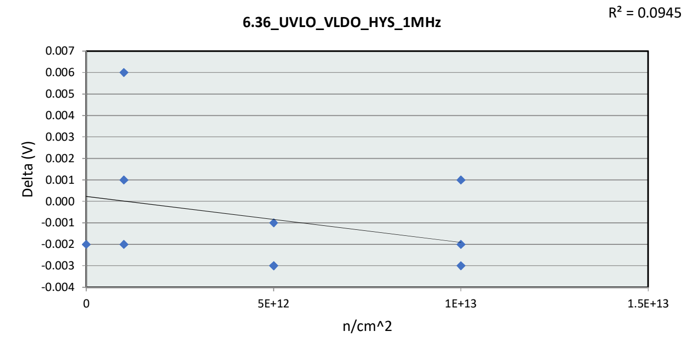
	6.35_UVLO_VLDO_FALL_1MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.369	3.380	3.377	3.369
Average	3.369	3.390	3.383	3.377
Max	3.369	3.396	3.392	3.385
UL	3.510	3.510	3.510	3.510



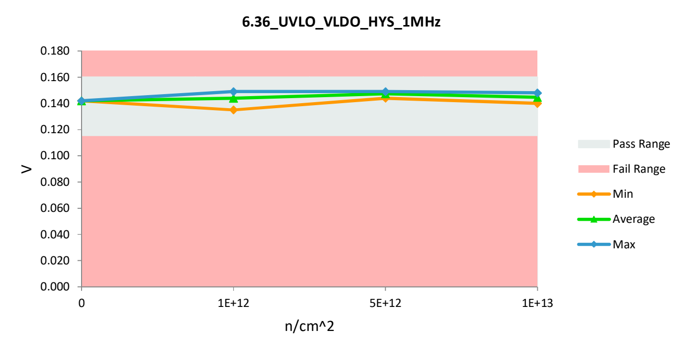
NDD Characterization Report
TPS7H5005-SEP

	6.36_UVLO_VLDO_HYS_1MHz	
Test Site		
Tester		
Test Number		
Unit	V	V
Max Limit	0.16	0.16
Min Limit	0.115	0.115

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.144	0.142	-0.002
1E+12	1	0.137	0.135	-0.002
1E+12	2	0.143	0.149	0.006
1E+12	3	0.147	0.148	0.001
5E+12	4	0.147	0.144	-0.003
5E+12	5	0.152	0.149	-0.003
5E+12	6	0.150	0.149	-0.001
1E+13	7	0.148	0.146	-0.002
1E+13	8	0.151	0.148	-0.003
1E+13	9	0.139	0.140	0.001
	Max	0.152	0.149	0.006
	Average	0.146	0.145	-0.001
	Min	0.137	0.135	-0.003
	Std Dev	0.005	0.005	0.003

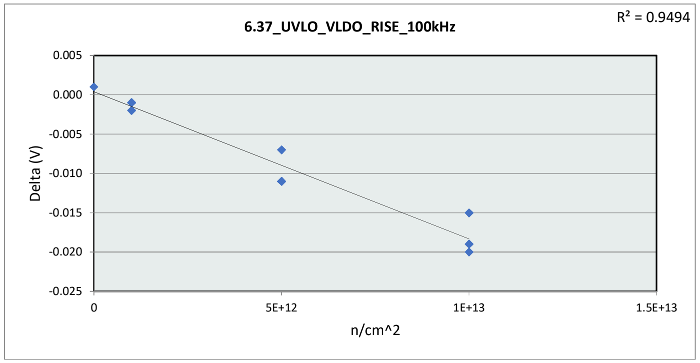


	6.36_UVLO_VLDO_HYS_1MHz			
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.142	0.135	0.144	0.140
Average	0.142	0.144	0.147	0.145
Max	0.142	0.149	0.149	0.148
UL	0.160	0.160	0.160	0.160

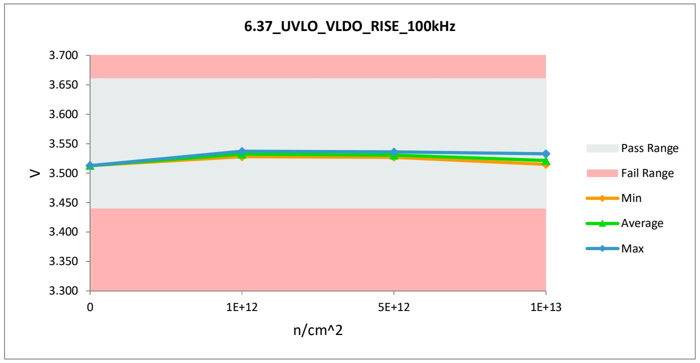


NDD Characterization Report
TPS7H5005-SEP

		6.37_UVLO_VLDO_RISE_100kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.66	3.66	
	Min Limit	3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	3.512	3.513	0.001
1E+12	1	3.533	3.532	-0.001
1E+12	2	3.538	3.537	-0.001
1E+12	3	3.530	3.528	-0.002
5E+12	4	3.547	3.536	-0.011
5E+12	5	3.538	3.527	-0.011
5E+12	6	3.536	3.529	-0.007
1E+13	7	3.534	3.515	-0.019
1E+13	8	3.553	3.533	-0.020
1E+13	9	3.531	3.516	-0.015
	Max	3.553	3.537	0.001
	Average	3.535	3.527	-0.009
	Min	3.512	3.513	-0.020
	Std Dev	0.011	0.009	0.008

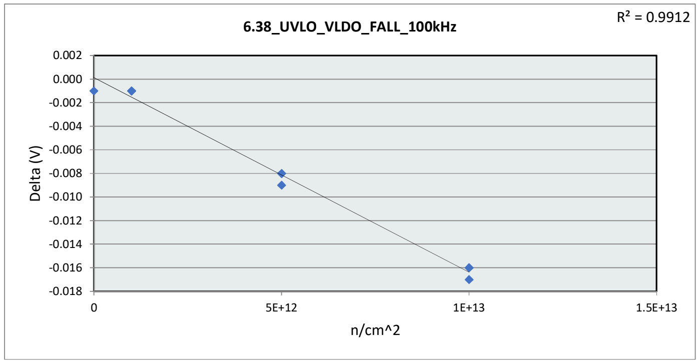


	6.37_UVLO_VLDO_RISE_100k			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.513	3.528	3.527	3.515
Average	3.513	3.532	3.531	3.521
Max	3.513	3.537	3.536	3.533
UL	3.660	3.660	3.660	3.660

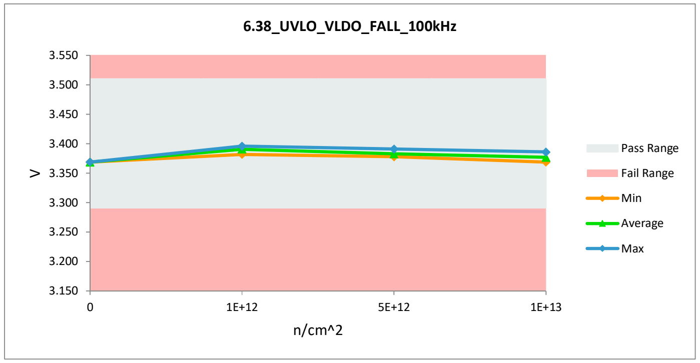


NDD Characterization Report
TPS7H5005-SEP

		6.38_UVLO_VLDO_FALL_100kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	3.370	3.369	-0.001
1E+12	1	3.397	3.396	-0.001
1E+12	2	3.395	3.394	-0.001
1E+12	3	3.383	3.382	-0.001
5E+12	4	3.400	3.391	-0.009
5E+12	5	3.386	3.378	-0.008
5E+12	6	3.387	3.379	-0.008
1E+13	7	3.385	3.369	-0.016
1E+13	8	3.403	3.386	-0.017
1E+13	9	3.392	3.376	-0.016
	Max	3.403	3.396	-0.001
	Average	3.390	3.382	-0.008
	Min	3.370	3.369	-0.017
	Std Dev	0.010	0.010	0.007

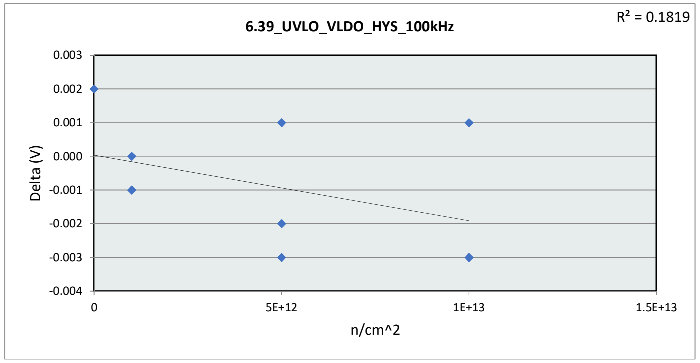


	6.38_UVLO_VLDO_FALL_100k			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.369	3.382	3.378	3.369
Average	3.369	3.391	3.383	3.377
Max	3.369	3.396	3.391	3.386
UL	3.510	3.510	3.510	3.510

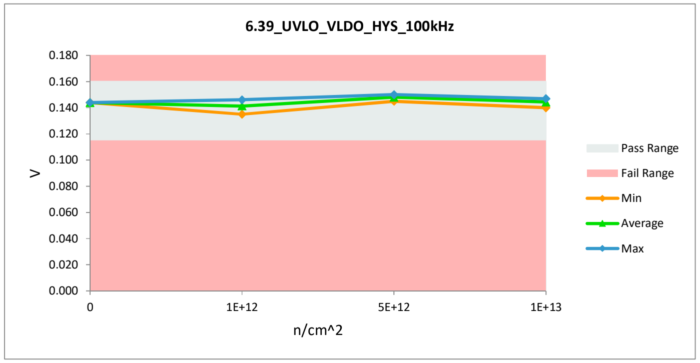


NDD Characterization Report
TPS7H5005-SEP

		6.39_UVLO_VLDO_HYS_100kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.16	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.142	0.144	0.002
1E+12	1	0.136	0.135	-0.001
1E+12	2	0.143	0.143	0.000
1E+12	3	0.147	0.146	-0.001
5E+12	4	0.147	0.145	-0.002
5E+12	5	0.152	0.149	-0.003
5E+12	6	0.149	0.150	0.001
1E+13	7	0.149	0.146	-0.003
1E+13	8	0.150	0.147	-0.003
1E+13	9	0.139	0.140	0.001
	Max	0.152	0.150	0.002
	Average	0.145	0.145	-0.001
	Min	0.136	0.135	-0.003
	Std Dev	0.005	0.004	0.002

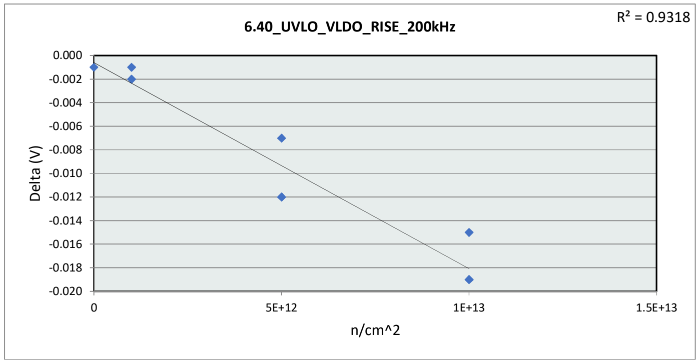


6.39_UVLO_VLDO_HYS_100kH				
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.144	0.135	0.145	0.140
Average	0.144	0.141	0.148	0.144
Max	0.144	0.146	0.150	0.147
UL	0.160	0.160	0.160	0.160

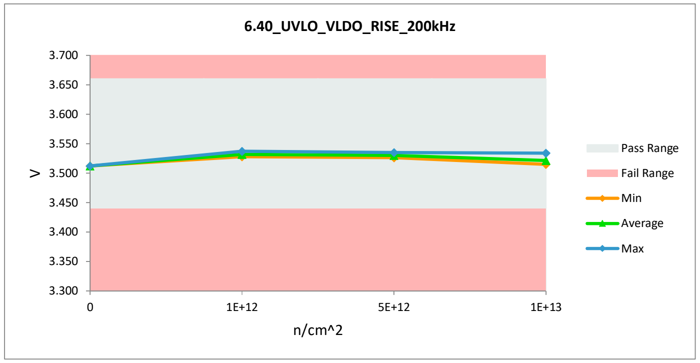


NDD Characterization Report
TPS7H5005-SEP

		6.40_UVLO_VLDO_RISE_200kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.66	3.66	
	Min Limit	3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	3.513	3.512	-0.001
1E+12	1	3.533	3.531	-0.002
1E+12	2	3.538	3.537	-0.001
1E+12	3	3.530	3.528	-0.002
5E+12	4	3.547	3.535	-0.012
5E+12	5	3.538	3.526	-0.012
5E+12	6	3.536	3.529	-0.007
1E+13	7	3.534	3.515	-0.019
1E+13	8	3.553	3.534	-0.019
1E+13	9	3.531	3.516	-0.015
	Max	3.553	3.537	-0.001
	Average	3.535	3.526	-0.009
	Min	3.513	3.512	-0.019
	Std Dev	0.011	0.009	0.007

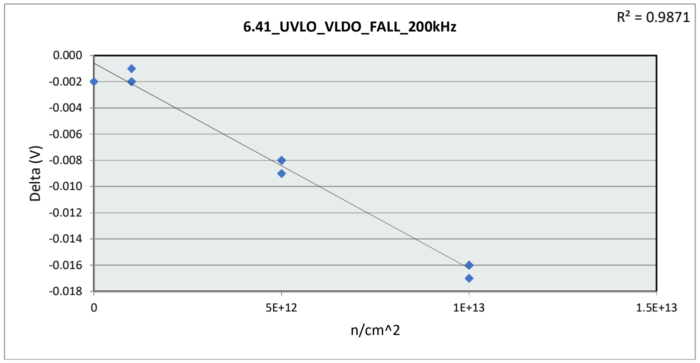


	6.40_UVLO_VLDO_RISE_200k			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.512	3.528	3.526	3.515
Average	3.512	3.532	3.530	3.522
Max	3.512	3.537	3.535	3.534
UL	3.660	3.660	3.660	3.660

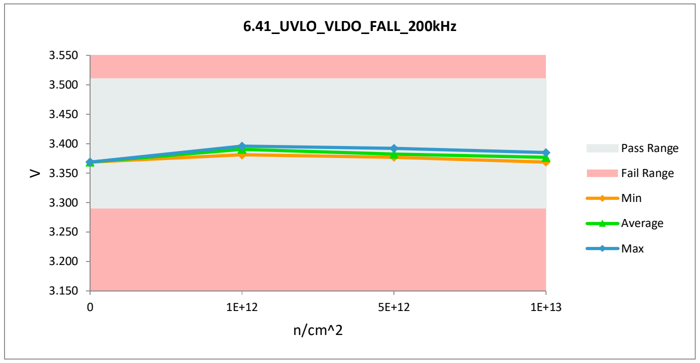


NDD Characterization Report
TPS7H5005-SEP

		6.41_UVLO_VLDO_FALL_200kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	3.371	3.369	-0.002
1E+12	1	3.398	3.396	-0.002
1E+12	2	3.395	3.394	-0.001
1E+12	3	3.383	3.381	-0.002
5E+12	4	3.400	3.392	-0.008
5E+12	5	3.386	3.377	-0.009
5E+12	6	3.386	3.378	-0.008
1E+13	7	3.385	3.369	-0.016
1E+13	8	3.402	3.385	-0.017
1E+13	9	3.393	3.377	-0.016
	Max	3.402	3.396	-0.001
	Average	3.390	3.382	-0.008
	Min	3.371	3.369	-0.017
	Std Dev	0.009	0.010	0.006

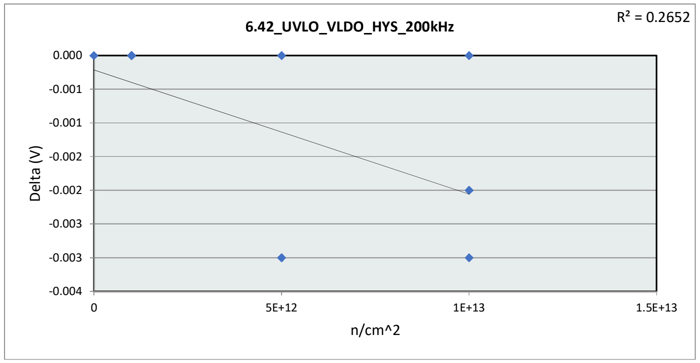


	6.41_UVLO_VLDO_FALL_200k			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.369	3.381	3.377	3.369
Average	3.369	3.390	3.382	3.377
Max	3.369	3.396	3.392	3.385
UL	3.510	3.510	3.510	3.510

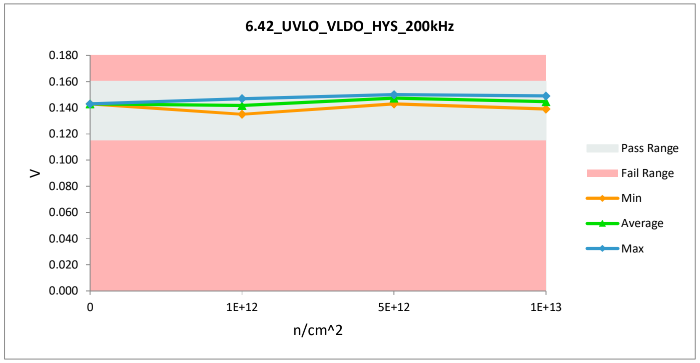


NDD Characterization Report
TPS7H5005-SEP

		6.42_UVLO_VLDO_HYS_200kHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.16	0.16	
Min Limit		0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.143	0.143	0.000
1E+12	1	0.135	0.135	0.000
1E+12	2	0.143	0.143	0.000
1E+12	3	0.147	0.147	0.000
5E+12	4	0.146	0.143	-0.003
5E+12	5	0.152	0.149	-0.003
5E+12	6	0.150	0.150	0.000
1E+13	7	0.149	0.146	-0.003
1E+13	8	0.151	0.149	-0.002
1E+13	9	0.139	0.139	0.000
	Max	0.152	0.150	0.000
	Average	0.146	0.144	-0.001
	Min	0.135	0.135	-0.003
	Std Dev	0.006	0.005	0.001

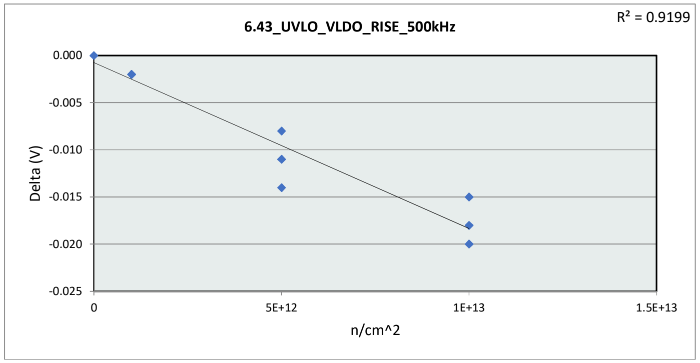


	6.42_UVLO_VLDO_HYS_200kH			
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.143	0.135	0.143	0.139
Average	0.143	0.142	0.147	0.145
Max	0.143	0.147	0.150	0.149
UL	0.160	0.160	0.160	0.160

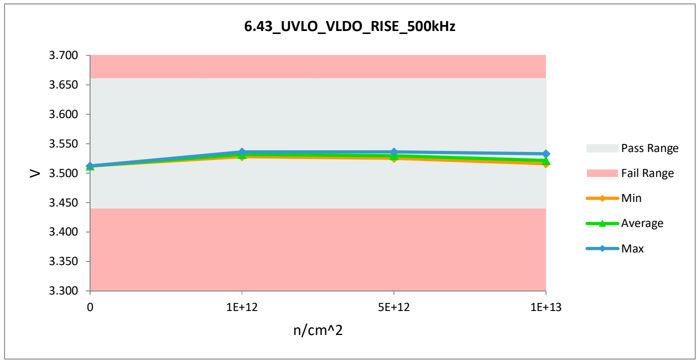


NDD Characterization Report
TPS7H5005-SEP

		6.43_UVLO_VLDO_RISE_500kHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.66	3.66	
Min Limit		3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	3.512	3.512	0.000
1E+12	1	3.533	3.531	-0.002
1E+12	2	3.538	3.536	-0.002
1E+12	3	3.530	3.528	-0.002
5E+12	4	3.547	3.536	-0.011
5E+12	5	3.539	3.525	-0.014
5E+12	6	3.536	3.528	-0.008
1E+13	7	3.534	3.516	-0.018
1E+13	8	3.553	3.533	-0.020
1E+13	9	3.531	3.516	-0.015
	Max	3.553	3.536	0.000
	Average	3.535	3.526	-0.009
	Min	3.512	3.512	-0.020
	Std Dev	0.011	0.009	0.007

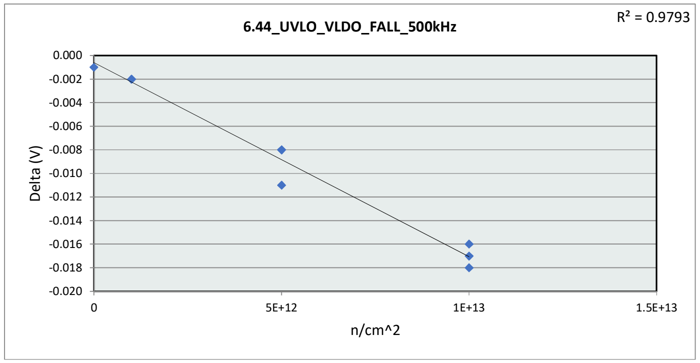


	6.43_UVLO_VLDO_RISE_500k			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.512	3.528	3.525	3.516
Average	3.512	3.532	3.530	3.522
Max	3.512	3.536	3.536	3.533
UL	3.660	3.660	3.660	3.660

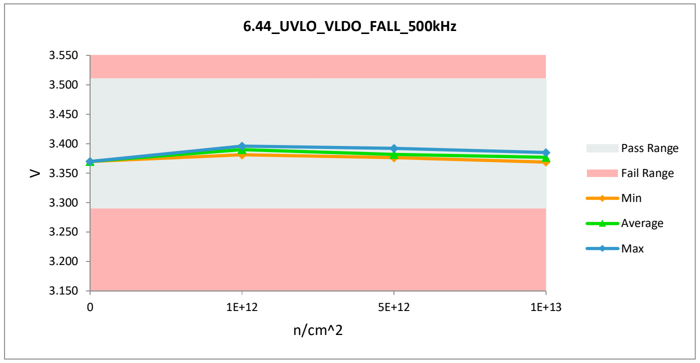


NDD Characterization Report
TPS7H5005-SEP

		6.44_UVLO_VLDO_FALL_500kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	3.371	3.370	-0.001
1E+12	1	3.398	3.396	-0.002
1E+12	2	3.395	3.393	-0.002
1E+12	3	3.383	3.381	-0.002
5E+12	4	3.400	3.392	-0.008
5E+12	5	3.387	3.376	-0.011
5E+12	6	3.386	3.378	-0.008
1E+13	7	3.385	3.369	-0.016
1E+13	8	3.403	3.385	-0.018
1E+13	9	3.393	3.376	-0.017
	Max	3.403	3.396	-0.001
	Average	3.390	3.382	-0.009
	Min	3.371	3.369	-0.018
	Std Dev	0.010	0.010	0.007

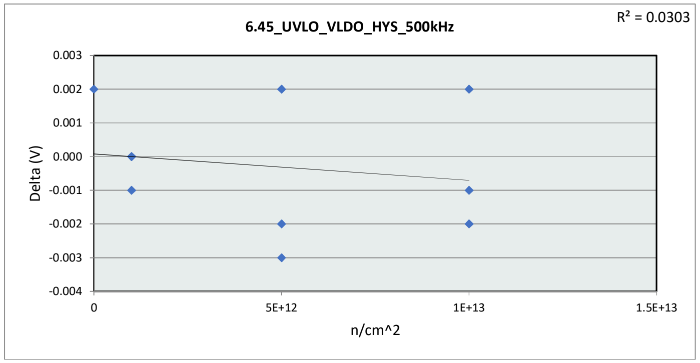


	6.44_UVLO_VLDO_FALL_500k			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.370	3.381	3.376	3.369
Average	3.370	3.390	3.382	3.377
Max	3.370	3.396	3.392	3.385
UL	3.510	3.510	3.510	3.510

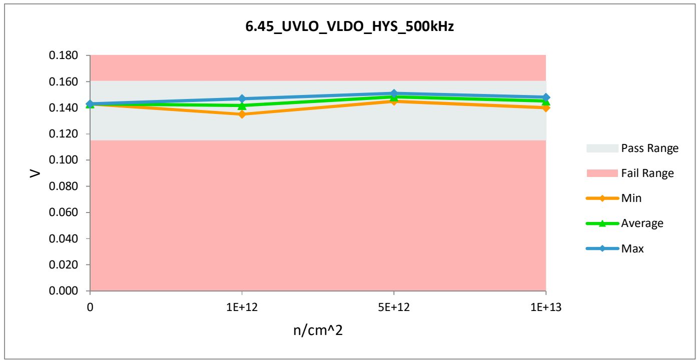


NDD Characterization Report
TPS7H5005-SEP

		6.45_UVLO_VLDO_HYS_500kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.16	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.141	0.143	0.002
1E+12	1	0.135	0.135	0.000
1E+12	2	0.143	0.143	0.000
1E+12	3	0.148	0.147	-0.001
5E+12	4	0.147	0.145	-0.002
5E+12	5	0.152	0.149	-0.003
5E+12	6	0.149	0.151	0.002
1E+13	7	0.149	0.147	-0.002
1E+13	8	0.149	0.148	-0.001
1E+13	9	0.138	0.140	0.002
	Max	0.152	0.151	0.002
	Average	0.145	0.145	0.000
	Min	0.135	0.135	-0.003
	Std Dev	0.006	0.005	0.002

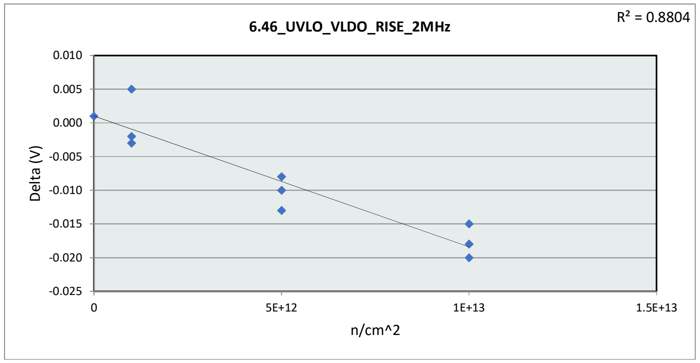


	6.45_UVLO_VLDO_HYS_500kH			
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.143	0.135	0.145	0.140
Average	0.143	0.142	0.148	0.145
Max	0.143	0.147	0.151	0.148
UL	0.160	0.160	0.160	0.160

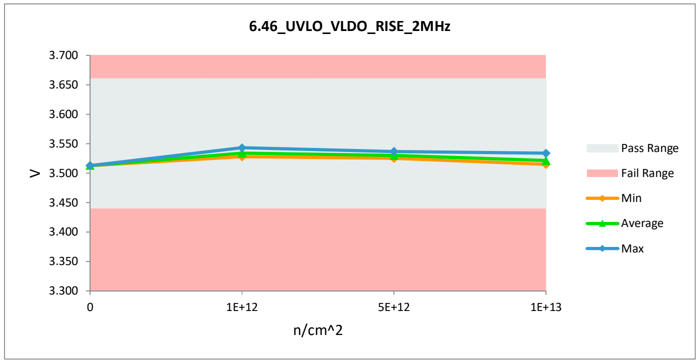


NDD Characterization Report
TPS7H5005-SEP

		6.46_UVLO_VLDO_RISE_2MHz		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		3.66	3.66	
Min Limit		3.44	3.44	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	3.512	3.513	0.001
1E+12	1	3.534	3.531	-0.003
1E+12	2	3.538	3.543	0.005
1E+12	3	3.530	3.528	-0.002
5E+12	4	3.547	3.537	-0.010
5E+12	5	3.538	3.525	-0.013
5E+12	6	3.536	3.528	-0.008
1E+13	7	3.533	3.515	-0.018
1E+13	8	3.554	3.534	-0.020
1E+13	9	3.531	3.516	-0.015
	Max	3.554	3.543	0.005
	Average	3.535	3.527	-0.008
	Min	3.512	3.513	-0.020
	Std Dev	0.011	0.010	0.008

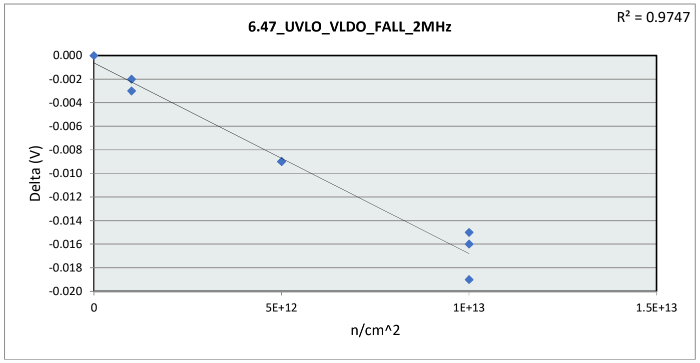


	6.46_UVLO_VLDO_RISE_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.66	V		
Min Limit	3.44	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.440	3.440	3.440	3.440
Min	3.513	3.528	3.525	3.515
Average	3.513	3.534	3.530	3.522
Max	3.513	3.543	3.537	3.534
UL	3.660	3.660	3.660	3.660

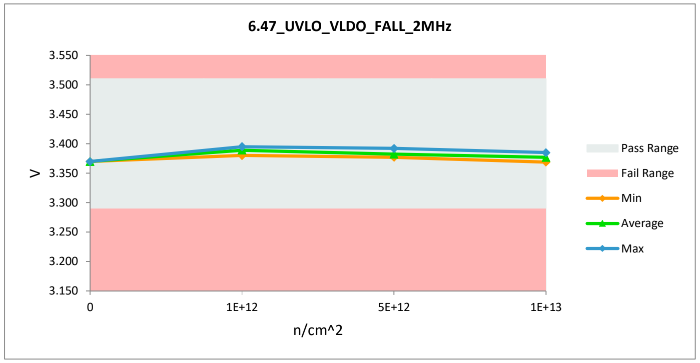


NDD Characterization Report
TPS7H5005-SEP

		6.47_UVLO_VLDO_FALL_2MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	3.51	3.51	
	Min Limit	3.29	3.29	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	3.370	3.370	0.000
1E+12	1	3.397	3.395	-0.002
1E+12	2	3.395	3.392	-0.003
1E+12	3	3.382	3.380	-0.002
5E+12	4	3.401	3.392	-0.009
5E+12	5	3.386	3.377	-0.009
5E+12	6	3.387	3.378	-0.009
1E+13	7	3.384	3.369	-0.015
1E+13	8	3.404	3.385	-0.019
1E+13	9	3.392	3.376	-0.016
	Max	3.404	3.395	0.000
	Average	3.390	3.381	-0.008
	Min	3.370	3.369	-0.019
	Std Dev	0.010	0.009	0.007

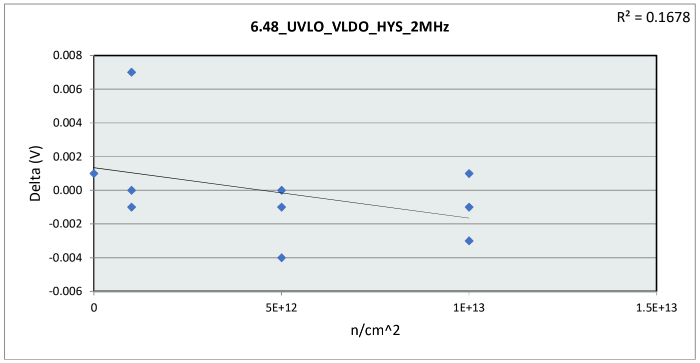


	6.47_UVLO_VLDO_FALL_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	3.51	V		
Min Limit	3.29	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	3.290	3.290	3.290	3.290
Min	3.370	3.380	3.377	3.369
Average	3.370	3.389	3.382	3.377
Max	3.370	3.395	3.392	3.385
UL	3.510	3.510	3.510	3.510

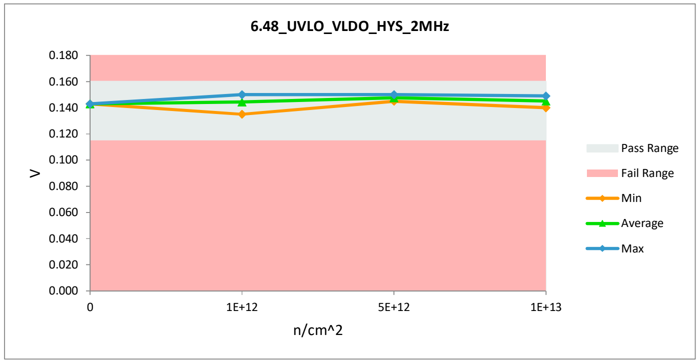


NDD Characterization Report
TPS7H5005-SEP

		6.48_UVLO_VLDO_HYS_2MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.16	0.16	
	Min Limit	0.115	0.115	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.142	0.143	0.001
1E+12	1	0.136	0.135	-0.001
1E+12	2	0.143	0.150	0.007
1E+12	3	0.148	0.148	0.000
5E+12	4	0.146	0.145	-0.001
5E+12	5	0.152	0.148	-0.004
5E+12	6	0.150	0.150	0.000
1E+13	7	0.149	0.146	-0.003
1E+13	8	0.150	0.149	-0.001
1E+13	9	0.139	0.140	0.001
	Max	0.152	0.150	0.007
	Average	0.146	0.145	0.000
	Min	0.136	0.135	-0.004
	Std Dev	0.005	0.005	0.003

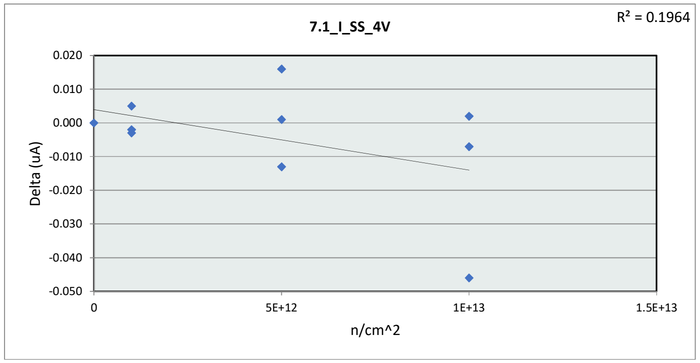


	6.48_UVLO_VLDO_HYS_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	0.16	V		
Min Limit	0.115	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.115	0.115	0.115	0.115
Min	0.143	0.135	0.145	0.140
Average	0.143	0.144	0.148	0.145
Max	0.143	0.150	0.150	0.149
UL	0.160	0.160	0.160	0.160

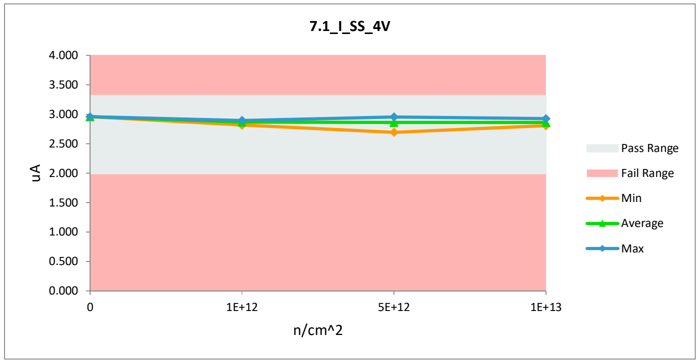


NDD Characterization Report
TPS7H5005-SEP

		7.1_I_SS_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	3.32	3.32	
	Min Limit	1.98	1.98	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	2.959	2.959	0.000
1E+12	1	2.891	2.896	0.005
1E+12	2	2.897	2.894	-0.003
1E+12	3	2.817	2.815	-0.002
5E+12	4	2.708	2.695	-0.013
5E+12	5	2.934	2.935	0.001
5E+12	6	2.939	2.955	0.016
1E+13	7	2.814	2.807	-0.007
1E+13	8	2.894	2.848	-0.046
1E+13	9	2.925	2.927	0.002
	Max	2.959	2.959	0.016
	Average	2.878	2.873	-0.005
	Min	2.708	2.695	-0.046
	Std Dev	0.077	0.083	0.016

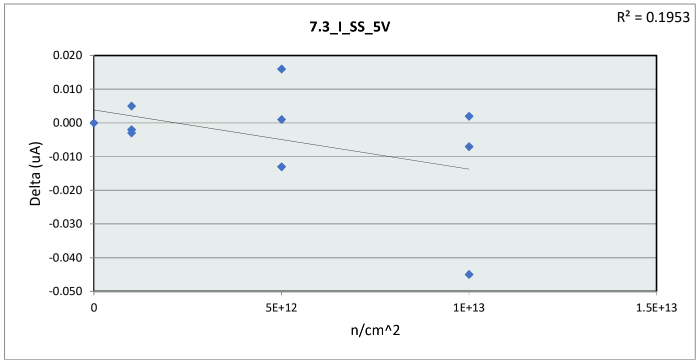


	7.1_I_SS_4V			
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.959	2.815	2.695	2.807
Average	2.959	2.868	2.862	2.861
Max	2.959	2.896	2.955	2.927
UL	3.320	3.320	3.320	3.320

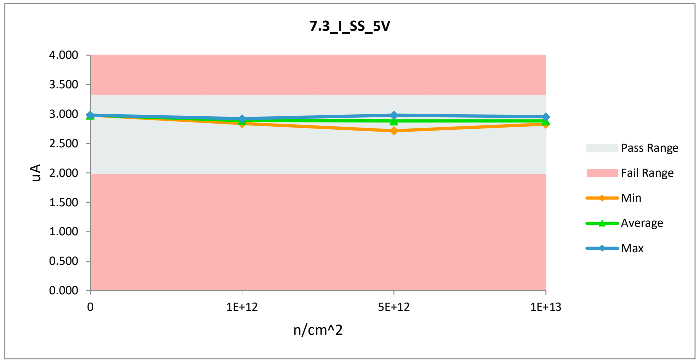


NDD Characterization Report
TPS7H5005-SEP

		7.3_I_SS_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	3.32	3.32	
	Min Limit	1.98	1.98	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	2.981	2.981	0.000
1E+12	1	2.914	2.919	0.005
1E+12	2	2.921	2.918	-0.003
1E+12	3	2.840	2.838	-0.002
5E+12	4	2.730	2.717	-0.013
5E+12	5	2.957	2.958	0.001
5E+12	6	2.963	2.979	0.016
1E+13	7	2.836	2.829	-0.007
1E+13	8	2.916	2.871	-0.045
1E+13	9	2.950	2.952	0.002
	Max	2.981	2.981	0.016
	Average	2.901	2.896	-0.005
	Min	2.730	2.717	-0.045
	Std Dev	0.077	0.083	0.016

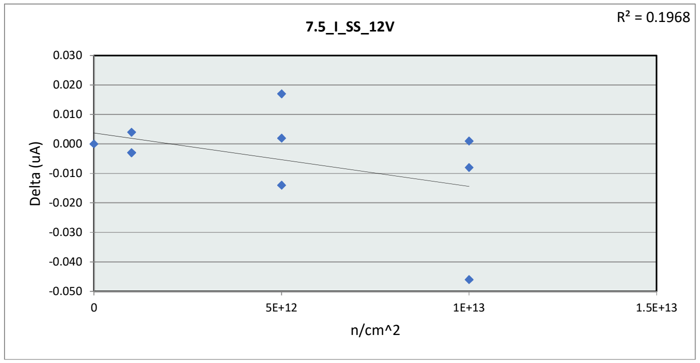


	7.3_I_SS_5V			
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.981	2.838	2.717	2.829
Average	2.981	2.892	2.885	2.884
Max	2.981	2.919	2.979	2.952
UL	3.320	3.320	3.320	3.320

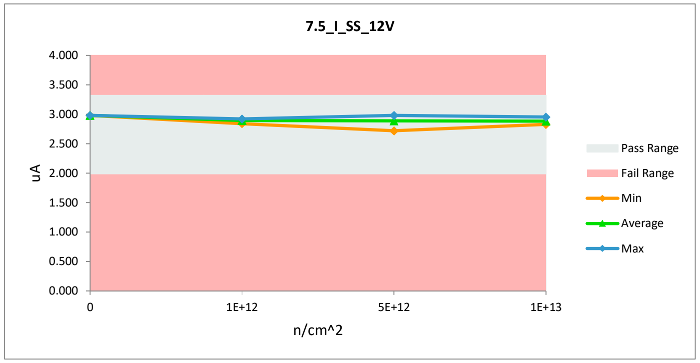


NDD Characterization Report
TPS7H5005-SEP

		7.5_I_SS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	3.32	3.32	
	Min Limit	1.98	1.98	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	2.983	2.983	0.000
1E+12	1	2.916	2.920	0.004
1E+12	2	2.922	2.919	-0.003
1E+12	3	2.843	2.840	-0.003
5E+12	4	2.732	2.718	-0.014
5E+12	5	2.958	2.960	0.002
5E+12	6	2.964	2.981	0.017
1E+13	7	2.837	2.829	-0.008
1E+13	8	2.918	2.872	-0.046
1E+13	9	2.953	2.954	0.001
	Max	2.983	2.983	0.017
	Average	2.903	2.898	-0.005
	Min	2.732	2.718	-0.046
	Std Dev	0.077	0.084	0.017

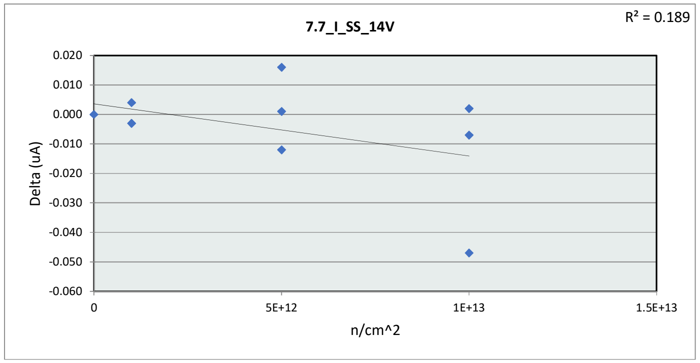


	7.5_I_SS_12V			
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.983	2.840	2.718	2.829
Average	2.983	2.893	2.886	2.885
Max	2.983	2.920	2.981	2.954
UL	3.320	3.320	3.320	3.320

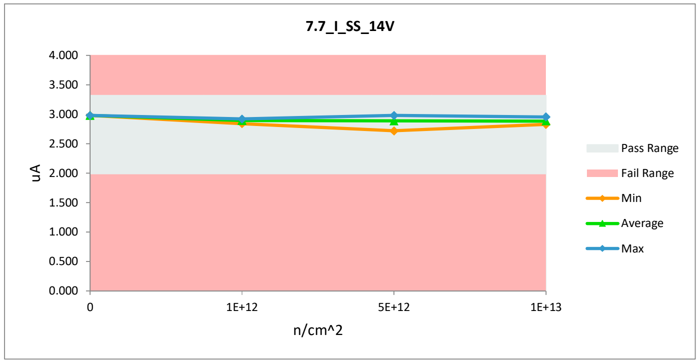


NDD Characterization Report
TPS7H5005-SEP

		7.7_I_SS_14V		
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		3.32	3.32	
Min Limit		1.98	1.98	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	2.983	2.983	0.000
1E+12	1	2.916	2.920	0.004
1E+12	2	2.922	2.919	-0.003
1E+12	3	2.844	2.841	-0.003
5E+12	4	2.731	2.719	-0.012
5E+12	5	2.958	2.959	0.001
5E+12	6	2.965	2.981	0.016
1E+13	7	2.837	2.830	-0.007
1E+13	8	2.919	2.872	-0.047
1E+13	9	2.953	2.955	0.002
	Max	2.983	2.983	0.016
	Average	2.903	2.898	-0.005
	Min	2.731	2.719	-0.047
	Std Dev	0.077	0.083	0.017

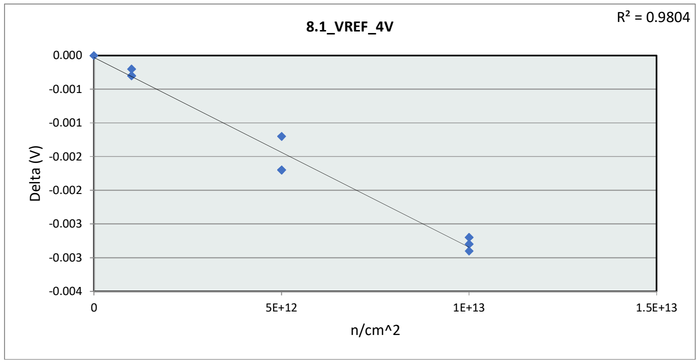


7.7_I_SS_14V				
Test Site				
Tester				
Test Number				
Max Limit	3.32	uA		
Min Limit	1.98	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1.980	1.980	1.980	1.980
Min	2.983	2.841	2.719	2.830
Average	2.983	2.893	2.886	2.886
Max	2.983	2.920	2.981	2.955
UL	3.320	3.320	3.320	3.320

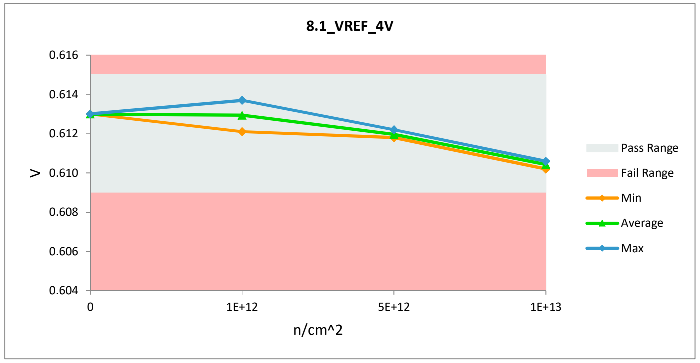


NDD Characterization Report
TPS7H5005-SEP

		8.1_VREF_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.615	0.615	
	Min Limit	0.609	0.609	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.613	0.613	0.000
1E+12	1	0.614	0.614	0.000
1E+12	2	0.612	0.612	0.000
1E+12	3	0.613	0.613	0.000
5E+12	4	0.614	0.612	-0.002
5E+12	5	0.613	0.612	-0.002
5E+12	6	0.613	0.612	-0.001
1E+13	7	0.613	0.611	-0.003
1E+13	8	0.613	0.610	-0.003
1E+13	9	0.613	0.610	-0.003
	Max	0.614	0.614	0.000
	Average	0.613	0.612	-0.001
	Min	0.612	0.610	-0.003
	Std Dev	0.000	0.001	0.001

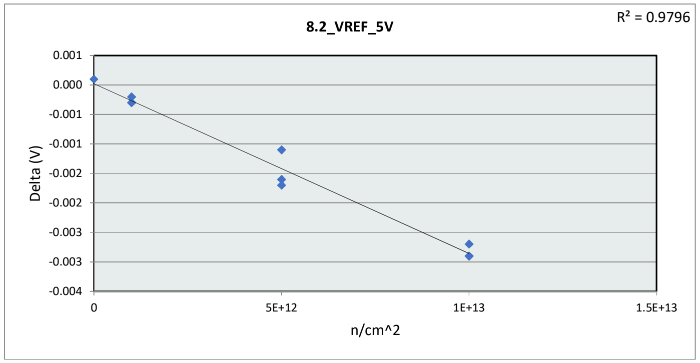


	8.1_VREF_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.615	V		
Min Limit	0.609	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.612	0.612	0.610
Average	0.613	0.613	0.612	0.610
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

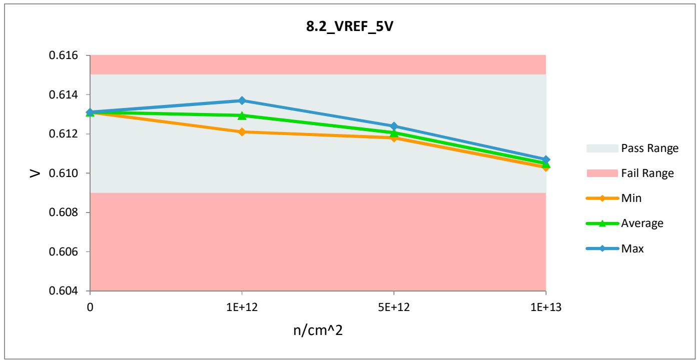


NDD Characterization Report
TPS7H5005-SEP

		8.2_VREF_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.615	0.615	
Min Limit		0.609	0.609	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.613	0.613	0.000
1E+12	1	0.614	0.614	0.000
1E+12	2	0.612	0.612	0.000
1E+12	3	0.613	0.613	0.000
5E+12	4	0.614	0.612	-0.002
5E+12	5	0.613	0.612	-0.002
5E+12	6	0.613	0.612	-0.001
1E+13	7	0.614	0.611	-0.003
1E+13	8	0.613	0.610	-0.003
1E+13	9	0.613	0.610	-0.003
	Max	0.614	0.614	0.000
	Average	0.613	0.612	-0.001
	Min	0.612	0.610	-0.003
	Std Dev	0.000	0.001	0.001

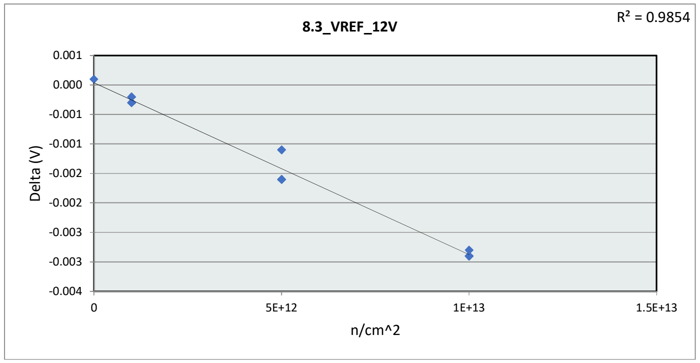


	8.2_VREF_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.615	V		
Min Limit	0.609	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.612	0.612	0.610
Average	0.613	0.613	0.612	0.611
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

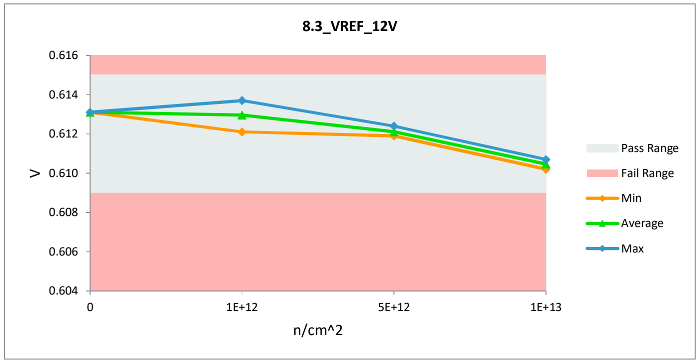


NDD Characterization Report
TPS7H5005-SEP

		8.3_VREF_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.615	0.615	
	Min Limit	0.609	0.609	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.613	0.613	0.000
1E+12	1	0.614	0.614	0.000
1E+12	2	0.612	0.612	0.000
1E+12	3	0.613	0.613	0.000
5E+12	4	0.614	0.612	-0.002
5E+12	5	0.613	0.612	-0.002
5E+12	6	0.613	0.612	-0.001
1E+13	7	0.614	0.611	-0.003
1E+13	8	0.613	0.610	-0.003
1E+13	9	0.613	0.610	-0.003
	Max	0.614	0.614	0.000
	Average	0.613	0.612	-0.001
	Min	0.612	0.610	-0.003
	Std Dev	0.000	0.001	0.001

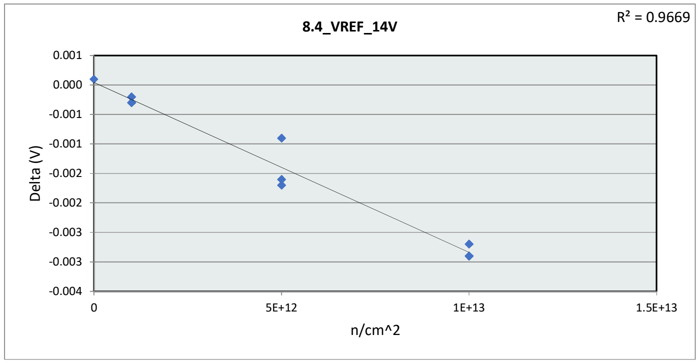


	8.3_VREF_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.615	V		
Min Limit	0.609	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.612	0.612	0.610
Average	0.613	0.613	0.612	0.610
Max	0.613	0.614	0.612	0.611
UL	0.615	0.615	0.615	0.615

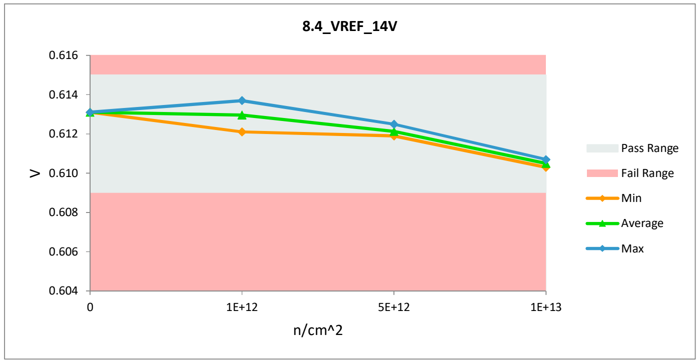


NDD Characterization Report
TPS7H5005-SEP

		8.4_VREF_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.615	0.615	
	Min Limit	0.609	0.609	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.613	0.613	0.000
1E+12	1	0.614	0.614	0.000
1E+12	2	0.612	0.612	0.000
1E+12	3	0.613	0.613	0.000
5E+12	4	0.614	0.612	-0.002
5E+12	5	0.614	0.612	-0.002
5E+12	6	0.613	0.613	-0.001
1E+13	7	0.614	0.611	-0.003
1E+13	8	0.613	0.610	-0.003
1E+13	9	0.613	0.610	-0.003
	Max	0.614	0.614	0.000
	Average	0.613	0.612	-0.001
	Min	0.612	0.610	-0.003
	Std Dev	0.000	0.001	0.001

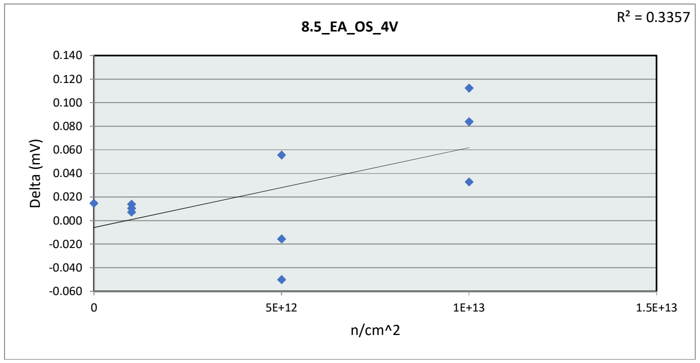


	8.4_VREF_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.615	V		
Min Limit	0.609	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.609	0.609	0.609	0.609
Min	0.613	0.612	0.612	0.610
Average	0.613	0.613	0.612	0.611
Max	0.613	0.614	0.613	0.611
UL	0.615	0.615	0.615	0.615

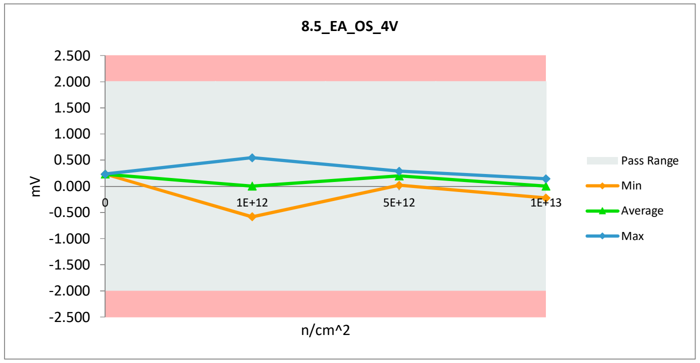


NDD Characterization Report
TPS7H5005-SEP

		8.5_EA_OS_4V		
Test Site				
Tester				
Test Number				
Unit		mV	mV	
Max Limit		2	2	
Min Limit		-2	-2	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.218	0.233	0.015
1E+12	1	0.533	0.547	0.014
1E+12	2	-0.589	-0.582	0.007
1E+12	3	0.039	0.049	0.010
5E+12	4	0.070	0.020	-0.050
5E+12	5	0.291	0.276	-0.016
5E+12	6	0.234	0.290	0.056
1E+13	7	0.014	0.098	0.084
1E+13	8	0.034	0.147	0.112
1E+13	9	-0.256	-0.223	0.033
	Max	0.533	0.547	0.112
	Average	0.059	0.085	0.027
	Min	-0.589	-0.582	-0.050
	Std Dev	0.309	0.310	0.047

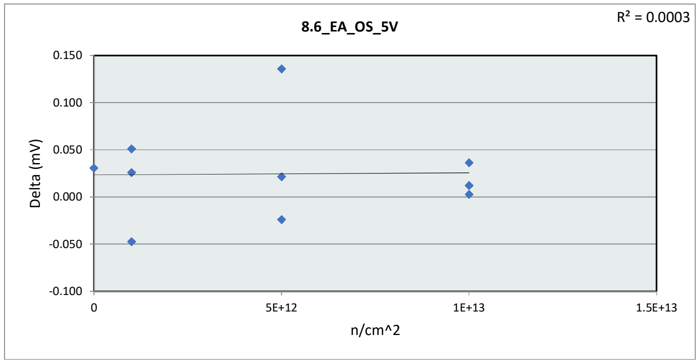


	8.5_EA_OS_4V			
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.233	-0.582	0.020	-0.223
Average	0.233	0.005	0.195	0.007
Max	0.233	0.547	0.290	0.147
UL	2.000	2.000	2.000	2.000

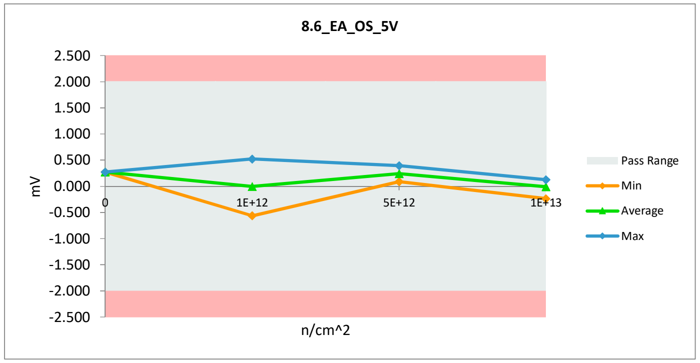


NDD Characterization Report
TPS7H5005-SEP

		8.6_EA_OS_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	mV	mV	
	Max Limit	2	2	
	Min Limit	-2	-2	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.242	0.273	0.031
1E+12	1	0.568	0.521	-0.047
1E+12	2	-0.614	-0.563	0.051
1E+12	3	0.000	0.026	0.026
5E+12	4	0.067	0.089	0.022
5E+12	5	0.269	0.245	-0.024
5E+12	6	0.258	0.393	0.136
1E+13	7	0.072	0.084	0.012
1E+13	8	0.089	0.125	0.036
1E+13	9	-0.239	-0.236	0.003
	Max	0.568	0.521	0.136
	Average	0.071	0.096	0.025
	Min	-0.614	-0.563	-0.047
	Std Dev	0.320	0.312	0.049

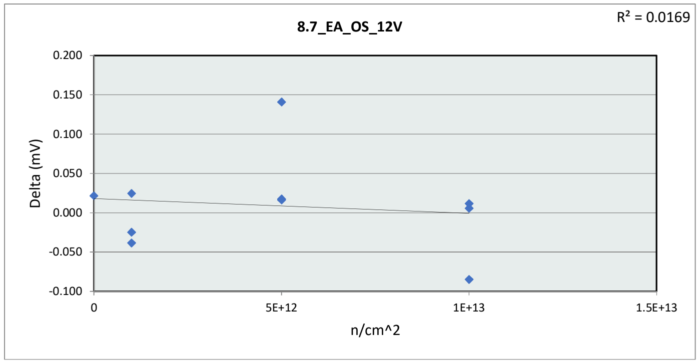


	8.6_EA_OS_5V			
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.273	-0.563	0.089	-0.236
Average	0.273	-0.005	0.242	-0.009
Max	0.273	0.521	0.393	0.125
UL	2.000	2.000	2.000	2.000

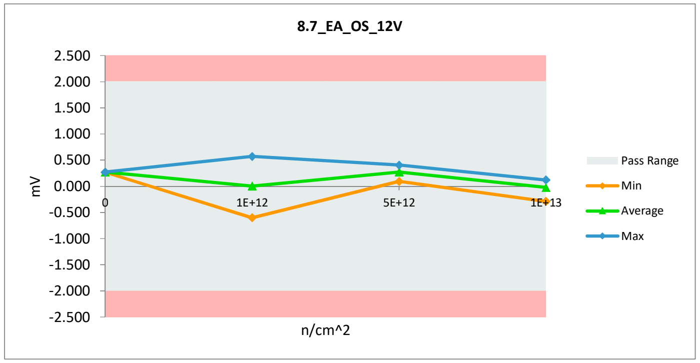


NDD Characterization Report
TPS7H5005-SEP

		8.7_EA_OS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	mV	mV	
	Max Limit	2	2	
	Min Limit	-2	-2	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.249	0.270	0.022
1E+12	1	0.548	0.572	0.025
1E+12	2	-0.563	-0.601	-0.038
1E+12	3	0.067	0.042	-0.025
5E+12	4	0.076	0.094	0.017
5E+12	5	0.308	0.324	0.016
5E+12	6	0.267	0.408	0.141
1E+13	7	0.085	0.097	0.012
1E+13	8	0.117	0.123	0.006
1E+13	9	-0.203	-0.288	-0.085
	Max	0.548	0.572	0.141
	Average	0.095	0.104	0.009
	Min	-0.563	-0.601	-0.085
	Std Dev	0.303	0.341	0.058

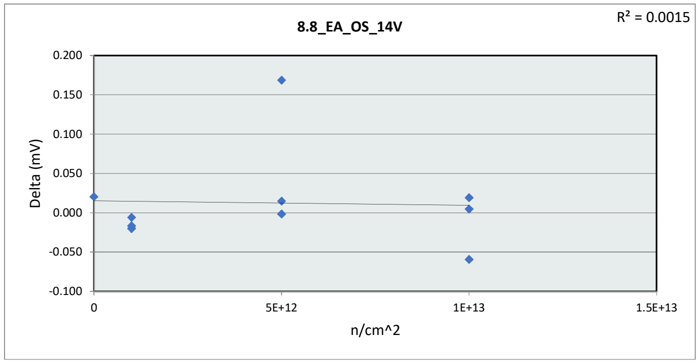


	8.7_EA_OS_12V			
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.270	-0.602	0.094	-0.288
Average	0.270	0.004	0.275	-0.023
Max	0.270	0.572	0.408	0.123
UL	2.000	2.000	2.000	2.000

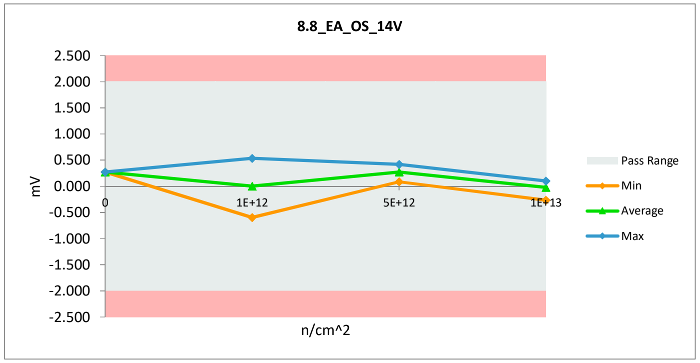


NDD Characterization Report
TPS7H5005-SEP

		8.8_EA_OS_14V		
Test Site				
Tester				
Test Number				
Unit		mV	mV	
Max Limit		2	2	
Min Limit		-2	-2	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.253	0.274	0.020
1E+12	1	0.539	0.534	-0.006
1E+12	2	-0.577	-0.597	-0.020
1E+12	3	0.082	0.065	-0.017
5E+12	4	0.071	0.086	0.015
5E+12	5	0.317	0.315	-0.001
5E+12	6	0.252	0.421	0.169
1E+13	7	0.081	0.100	0.019
1E+13	8	0.098	0.103	0.005
1E+13	9	-0.206	-0.266	-0.059
	Max	0.539	0.534	0.169
	Average	0.091	0.103	0.012
	Min	-0.577	-0.597	-0.059
	Std Dev	0.305	0.331	0.060

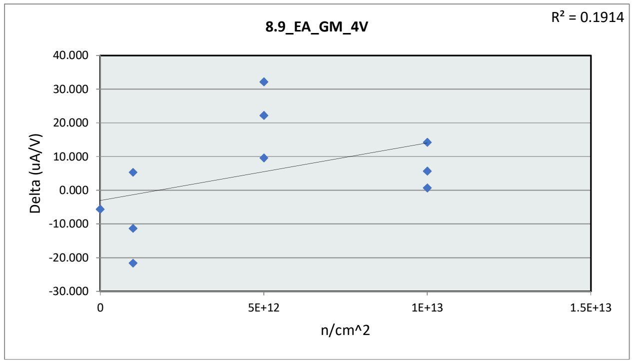


	8.8_EA_OS_14V			
Test Site				
Tester				
Test Number				
Max Limit	2	mV		
Min Limit	-2	mV		
n/cm^2	0	1E+12	5E+12	1E+13
LL	-2.000	-2.000	-2.000	-2.000
Min	0.274	-0.597	0.086	-0.266
Average	0.274	0.000	0.274	-0.021
Max	0.274	0.534	0.421	0.103
UL	2.000	2.000	2.000	2.000

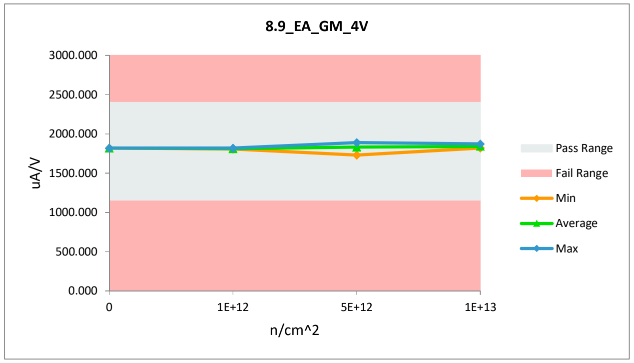


NDD Characterization Report
TPS7H5005-SEP

		8.9_EA_GM_4V		
Test Site				
Tester				
Test Number				
Unit		uA/V	uA/V	
Max Limit		2400	2400	
Min Limit		1150	1150	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1823.640	1818.008	-5.632
1E+12	1	1829.307	1818.008	-11.299
1E+12	2	1834.047	1812.421	-21.626
1E+12	3	1799.503	1804.846	5.343
5E+12	4	1721.314	1730.939	9.625
5E+12	5	1865.731	1887.934	22.203
5E+12	6	1840.737	1872.927	32.190
1E+13	7	1806.867	1821.087	14.220
1E+13	8	1829.307	1834.999	5.692
1E+13	9	1869.963	1870.693	0.730
	Max	1869.963	1887.934	32.190
	Average	1822.042	1827.186	5.145
	Min	1721.314	1730.939	-21.626
	Std Dev	41.755	44.625	15.804

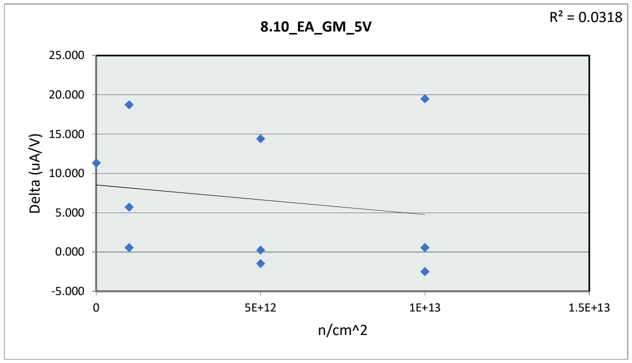


	8.9_EA_GM_4V			
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1818.008	1804.846	1730.939	1821.087
Average	1818.008	1811.758	1830.600	1842.260
Max	1818.008	1818.008	1887.934	1870.693
UL	2400.000	2400.000	2400.000	2400.000

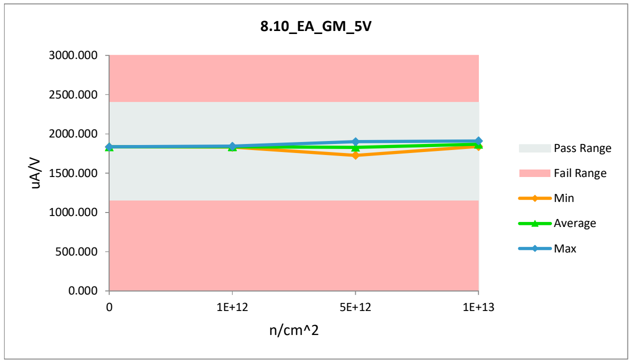


NDD Characterization Report
TPS7H5005-SEP

		8.10_EA_GM_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA/V	uA/V	
	Max Limit	2400	2400	
	Min Limit	1150	1150	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1823.650	1834.999	11.349
1E+12	1	1841.313	1841.879	0.566
1E+12	2	1835.019	1840.737	5.718
1E+12	3	1812.421	1831.174	18.753
5E+12	4	1726.353	1726.602	0.249
5E+12	5	1903.625	1902.157	-1.468
5E+12	6	1844.400	1858.807	14.407
1E+13	7	1835.009	1854.502	19.493
1E+13	8	1840.162	1840.727	0.565
1E+13	9	1912.467	1909.974	-2.493
	Max	1912.467	1909.974	19.493
	Average	1837.442	1844.156	6.714
	Min	1726.353	1726.602	-2.493
	Std Dev	50.825	49.573	8.557

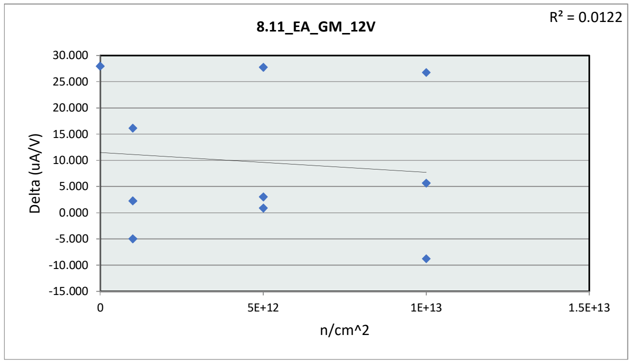


	8.10_EA_GM_5V			
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1834.999	1831.174	1726.602	1840.727
Average	1834.999	1837.930	1829.189	1868.401
Max	1834.999	1841.879	1902.157	1909.974
UL	2400.000	2400.000	2400.000	2400.000

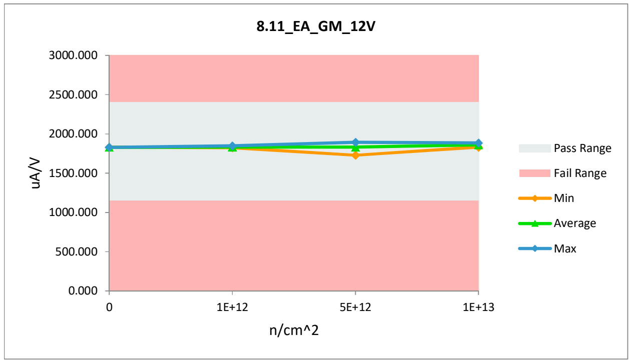


NDD Characterization Report
TPS7H5005-SEP

		8.11_EA_GM_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA/V	uA/V	
	Max Limit	2400	2400	
	Min Limit	1150	1150	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1801.338	1829.297	27.959
1E+12	1	1830.345	1846.501	16.156
1E+12	2	1828.609	1823.640	-4.969
1E+12	3	1829.307	1831.574	2.267
5E+12	4	1727.384	1728.291	0.907
5E+12	5	1890.966	1893.997	3.031
5E+12	6	1838.659	1866.406	27.747
1E+13	7	1825.069	1830.724	5.655
1E+13	8	1843.205	1869.953	26.748
1E+13	9	1894.008	1885.250	-8.758
	Max	1894.008	1893.997	27.959
	Average	1830.889	1840.563	9.674
	Min	1727.384	1728.291	-8.758
	Std Dev	46.468	46.684	13.907

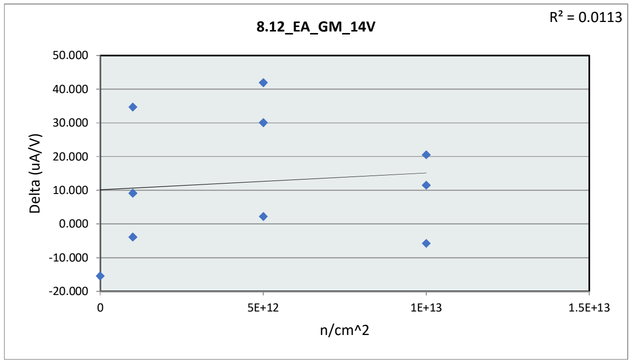


	8.11_EA_GM_12V			
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1829.297	1823.640	1728.291	1830.724
Average	1829.297	1833.905	1829.565	1861.976
Max	1829.297	1846.501	1893.997	1885.250
UL	2400.000	2400.000	2400.000	2400.000

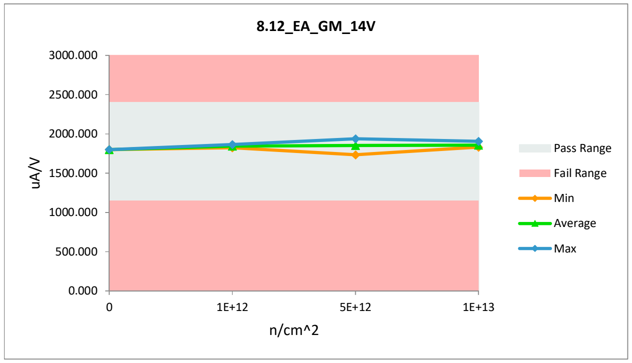


NDD Characterization Report
TPS7H5005-SEP

		8.12_EA_GM_14V		
Test Site				
Tester				
Test Number				
Unit		uA/V	uA/V	
Max Limit		2400	2400	
Min Limit		1150	1150	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1816.768	1801.329	-15.439
1E+12	1	1831.584	1840.737	9.153
1E+12	2	1829.307	1864.032	34.725
1E+12	3	1826.877	1823.036	-3.841
5E+12	4	1731.082	1733.300	2.218
5E+12	5	1907.499	1937.614	30.115
5E+12	6	1845.546	1887.519	41.973
1E+13	7	1809.752	1830.255	20.503
1E+13	8	1840.737	1834.999	-5.738
1E+13	9	1894.008	1905.506	11.498
	Max	1907.499	1937.614	41.973
	Average	1833.316	1845.833	12.517
	Min	1731.082	1733.300	-15.439
	Std Dev	47.996	57.352	18.959

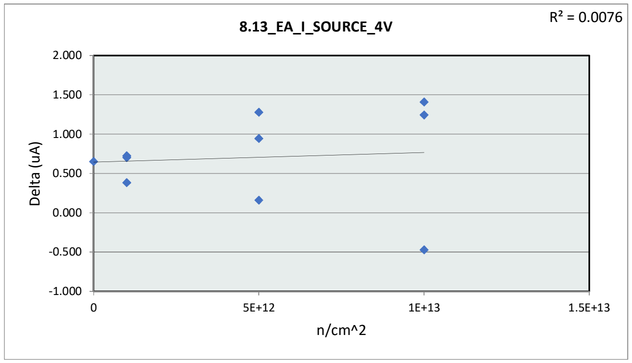


	8.12_EA_GM_14V			
Test Site				
Tester				
Test Number				
Max Limit	2400	uA/V		
Min Limit	1150	uA/V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1150.000	1150.000	1150.000	1150.000
Min	1801.329	1823.036	1733.300	1830.255
Average	1801.329	1842.602	1852.811	1856.920
Max	1801.329	1864.032	1937.614	1905.506
UL	2400.000	2400.000	2400.000	2400.000

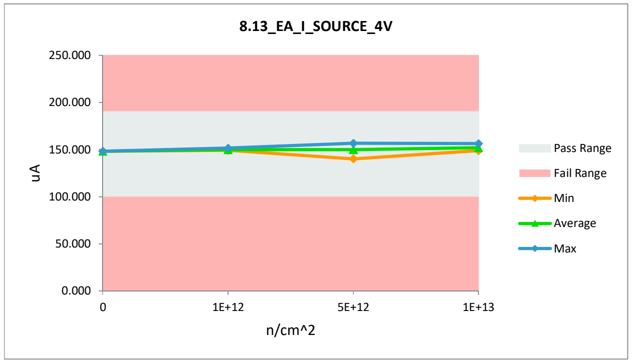


NDD Characterization Report
TPS7H5005-SEP

		8.13_EA_I_SOURCE_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	190	190	
	Min Limit	100	100	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	147.658	148.308	0.650
1E+12	1	148.744	149.468	0.724
1E+12	2	150.719	151.421	0.702
1E+12	3	148.745	149.128	0.383
5E+12	4	140.094	140.255	0.161
5E+12	5	155.944	156.888	0.944
5E+12	6	151.693	152.973	1.280
1E+13	7	147.535	148.943	1.408
1E+13	8	150.653	150.181	-0.472
1E+13	9	155.148	156.393	1.245
	Max	155.944	156.888	1.408
	Average	149.693	150.396	0.703
	Min	140.094	140.255	-0.472
	Std Dev	4.442	4.686	0.574

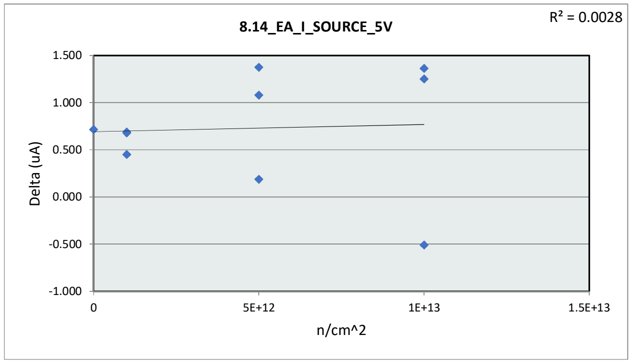


	8.13_EA_I_SOURCE_4V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	148.308	149.128	140.255	148.943
Average	148.308	150.006	150.039	151.839
Max	148.308	151.421	156.888	156.393
UL	190.000	190.000	190.000	190.000

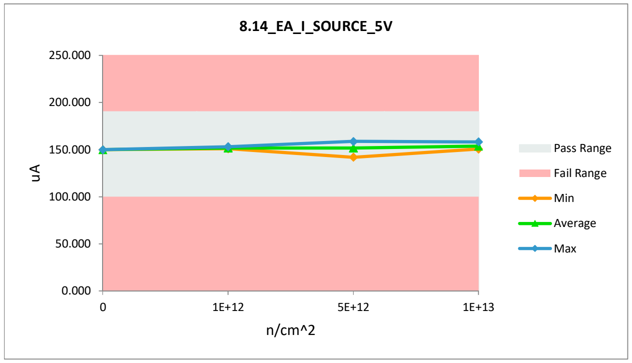


NDD Characterization Report
TPS7H5005-SEP

		8.14_EA_I_SOURCE_5V		
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		190	190	
Min Limit		100	100	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	149.243	149.958	0.715
1E+12	1	150.498	151.188	0.690
1E+12	2	152.432	153.111	0.679
1E+12	3	150.372	150.824	0.452
5E+12	4	141.697	141.885	0.188
5E+12	5	157.552	158.633	1.081
5E+12	6	153.443	154.819	1.376
1E+13	7	149.391	150.755	1.364
1E+13	8	152.203	151.693	-0.510
1E+13	9	156.910	158.162	1.252
	Max	157.552	158.633	1.376
	Average	151.374	152.103	0.729
	Min	141.697	141.885	-0.510
	Std Dev	4.457	4.728	0.590

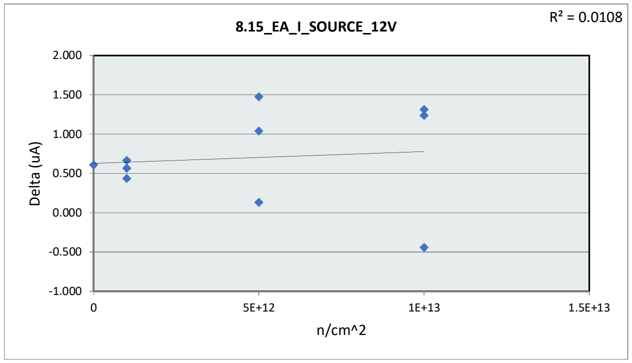


	8.14_EA_I_SOURCE_5V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	149.958	150.824	141.885	150.755
Average	149.958	151.708	151.779	153.537
Max	149.958	153.111	158.633	158.162
UL	190.000	190.000	190.000	190.000

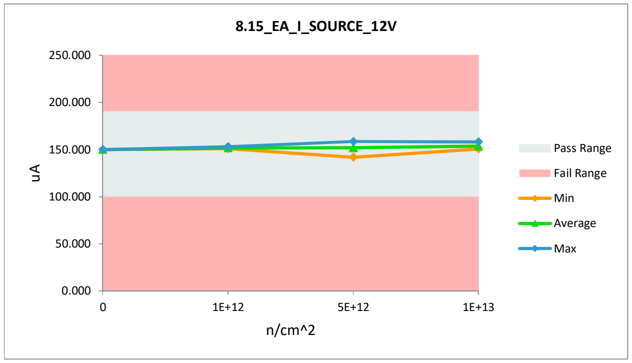


NDD Characterization Report
TPS7H5005-SEP

		8.15_EA_I_SOURCE_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	190	190	
	Min Limit	100	100	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	149.421	150.029	0.608
1E+12	1	150.692	151.255	0.563
1E+12	2	152.478	153.142	0.664
1E+12	3	150.442	150.876	0.434
5E+12	4	141.826	141.958	0.132
5E+12	5	157.593	158.630	1.037
5E+12	6	153.428	154.901	1.473
1E+13	7	149.399	150.709	1.310
1E+13	8	152.223	151.780	-0.443
1E+13	9	156.997	158.231	1.234
	Max	157.593	158.630	1.473
	Average	151.450	152.151	0.701
	Min	141.826	141.958	-0.443
	Std Dev	4.430	4.720	0.587

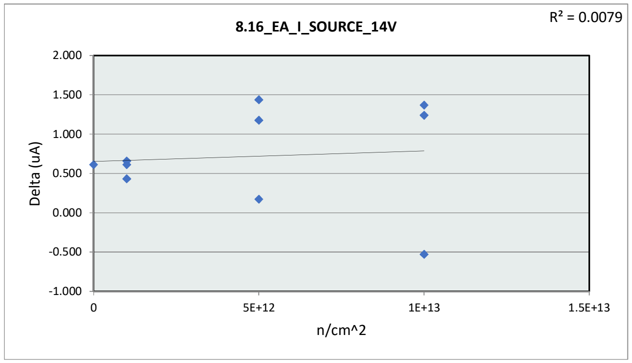


	8.15_EA_I_SOURCE_12V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	150.029	150.876	141.958	150.709
Average	150.029	151.758	151.830	153.573
Max	150.029	153.142	158.630	158.231
UL	190.000	190.000	190.000	190.000

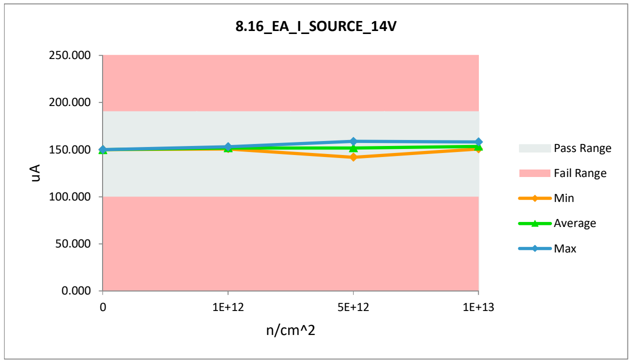


NDD Characterization Report
TPS7H5005-SEP

		8.16_EA_I_SOURCE_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	190	190	
	Min Limit	100	100	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	149.327	149.937	0.610
1E+12	1	150.501	151.156	0.655
1E+12	2	152.406	153.015	0.609
1E+12	3	150.382	150.810	0.428
5E+12	4	141.757	141.926	0.169
5E+12	5	157.476	158.649	1.173
5E+12	6	153.358	154.794	1.436
1E+13	7	149.338	150.704	1.366
1E+13	8	152.147	151.617	-0.530
1E+13	9	156.889	158.127	1.238
	Max	157.476	158.649	1.436
	Average	151.358	152.074	0.715
	Min	141.757	141.926	-0.530
	Std Dev	4.420	4.717	0.613

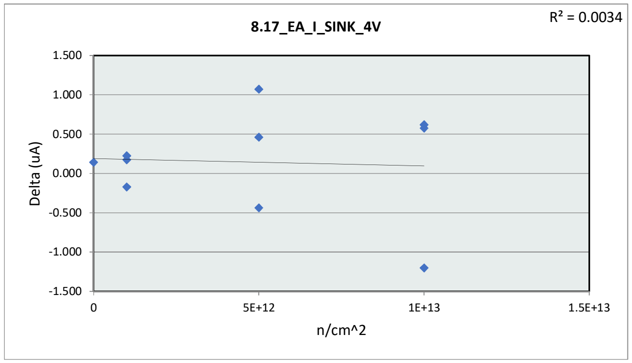


	8.16_EA_I_SOURCE_14V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	149.937	150.810	141.926	150.704
Average	149.937	151.660	151.790	153.483
Max	149.937	153.015	158.649	158.127
UL	190.000	190.000	190.000	190.000

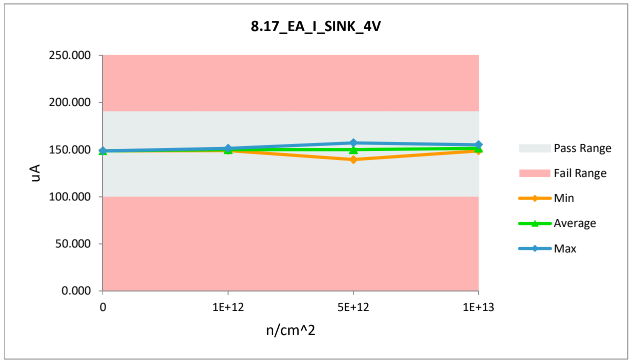


NDD Characterization Report
TPS7H5005-SEP

		8.17_EA_I_SINK_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	190	190	
	Min Limit	100	100	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	148.495	148.635	0.140
1E+12	1	151.167	151.390	0.223
1E+12	2	148.815	148.985	0.170
1E+12	3	149.405	149.231	-0.174
5E+12	4	139.736	139.297	-0.439
5E+12	5	156.667	157.126	0.459
5E+12	6	152.138	153.207	1.069
1E+13	7	148.067	148.685	0.618
1E+13	8	151.630	150.425	-1.205
1E+13	9	154.666	155.240	0.574
	Max	156.667	157.126	1.069
	Average	150.079	150.222	0.143
	Min	139.736	139.297	-1.205
	Std Dev	4.569	4.829	0.635

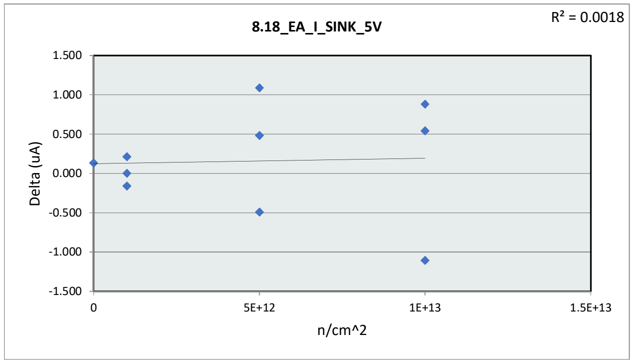


	8.17_EA_I_SINK_4V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	148.635	148.985	139.297	148.685
Average	148.635	149.869	149.877	151.450
Max	148.635	151.390	157.126	155.240
UL	190.000	190.000	190.000	190.000

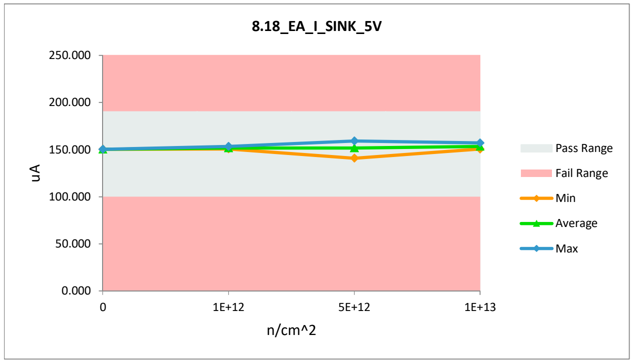


NDD Characterization Report
TPS7H5005-SEP

		8.18_EA_I_SINK_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	uA	uA	
	Max Limit	190	190	
	Min Limit	100	100	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	150.196	150.328	0.132
1E+12	1	153.080	153.291	0.211
1E+12	2	150.736	150.735	-0.001
1E+12	3	151.198	151.037	-0.161
5E+12	4	141.398	140.905	-0.493
5E+12	5	158.562	159.043	0.481
5E+12	6	153.929	155.015	1.086
1E+13	7	149.697	150.576	0.879
1E+13	8	153.313	152.204	-1.109
1E+13	9	156.520	157.059	0.539
	Max	158.562	159.043	1.086
	Average	151.863	152.019	0.156
	Min	141.398	140.905	-1.109
	Std Dev	4.632	4.904	0.649

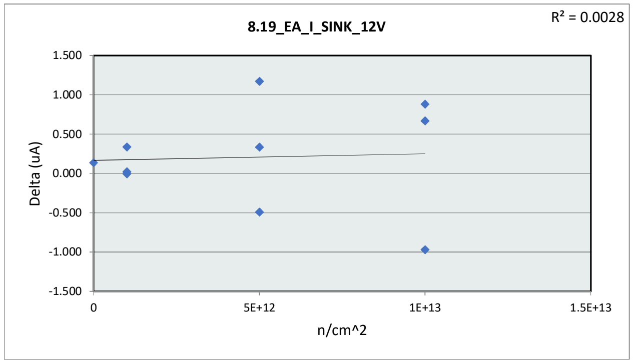


	8.18_EA_I_SINK_5V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	150.328	150.735	140.905	150.576
Average	150.328	151.688	151.654	153.280
Max	150.328	153.291	159.043	157.059
UL	190.000	190.000	190.000	190.000

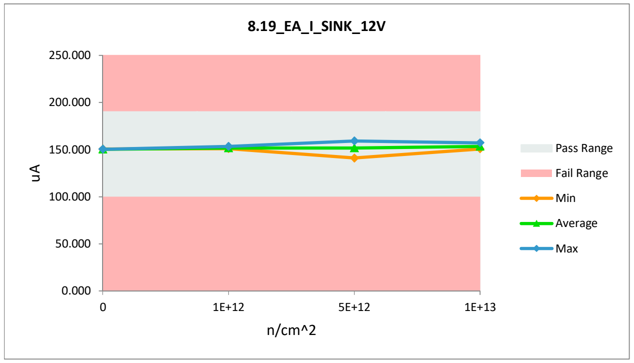


NDD Characterization Report
TPS7H5005-SEP

		8.19_EA_I_SINK_12V		
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		190	190	
Min Limit		100	100	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	150.302	150.437	0.135
1E+12	1	153.260	153.252	-0.008
1E+12	2	150.548	150.882	0.334
1E+12	3	151.166	151.185	0.019
5E+12	4	141.493	141.000	-0.493
5E+12	5	158.672	159.005	0.333
5E+12	6	153.957	155.127	1.170
1E+13	7	149.846	150.726	0.880
1E+13	8	153.356	152.384	-0.972
1E+13	9	156.638	157.304	0.666
	Max	158.672	159.005	1.170
	Average	151.924	152.130	0.206
	Min	141.493	141.000	-0.972
	Std Dev	4.642	4.893	0.632

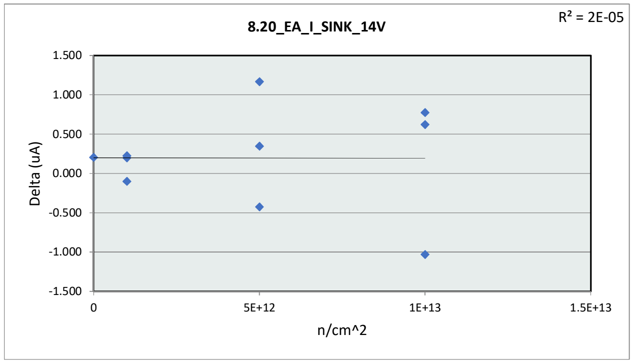


	8.19_EA_I_SINK_12V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	150.437	150.882	141.000	150.726
Average	150.437	151.773	151.711	153.471
Max	150.437	153.252	159.005	157.304
UL	190.000	190.000	190.000	190.000

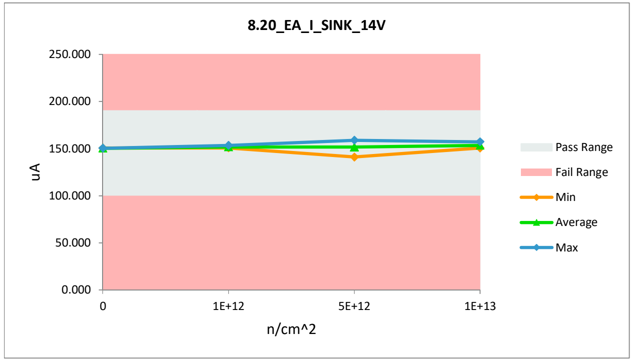


NDD Characterization Report
TPS7H5005-SEP

		8.20_EA_I_SINK_14V		
Test Site				
Tester				
Test Number				
Unit		uA	uA	
Max Limit		190	190	
Min Limit		100	100	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	150.244	150.447	0.203
1E+12	1	153.066	153.262	0.196
1E+12	2	150.546	150.767	0.221
1E+12	3	151.099	150.997	-0.102
5E+12	4	141.427	141.000	-0.427
5E+12	5	158.484	158.828	0.344
5E+12	6	153.802	154.966	1.164
1E+13	7	149.788	150.560	0.772
1E+13	8	153.281	152.248	-1.033
1E+13	9	156.512	157.132	0.620
	Max	158.484	158.828	1.164
	Average	151.825	152.021	0.196
	Min	141.427	141.000	-1.033
	Std Dev	4.604	4.847	0.620

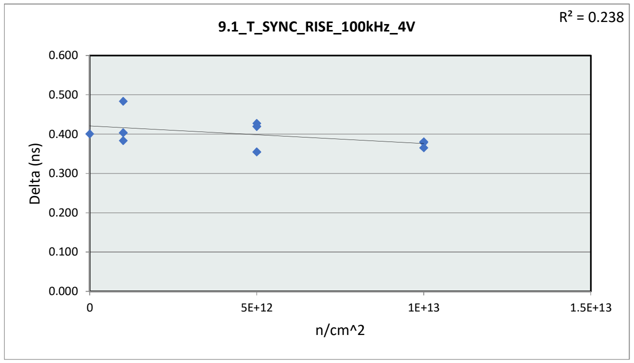


	8.20_EA_I_SINK_14V			
Test Site				
Tester				
Test Number				
Max Limit	190	uA		
Min Limit	100	uA		
n/cm^2	0	1E+12	5E+12	1E+13
LL	100.000	100.000	100.000	100.000
Min	150.447	150.767	141.000	150.560
Average	150.447	151.675	151.598	153.313
Max	150.447	153.262	158.828	157.132
UL	190.000	190.000	190.000	190.000

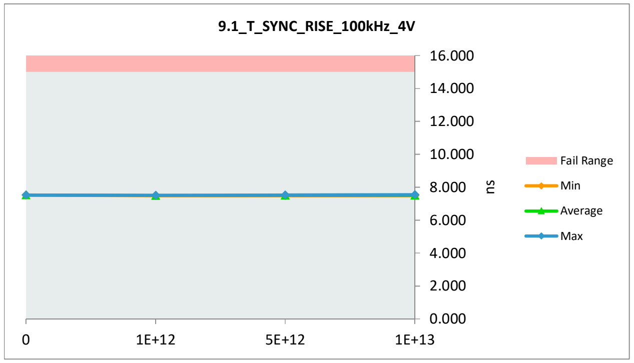


NDD Characterization Report
TPS7H5005-SEP

		9.1_T_SYNC_RISE_100kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.121	7.521	0.400
1E+12	1	7.122	7.505	0.383
1E+12	2	7.092	7.495	0.403
1E+12	3	7.006	7.489	0.483
5E+12	4	7.058	7.477	0.419
5E+12	5	7.101	7.528	0.427
5E+12	6	7.139	7.493	0.354
1E+13	7	7.110	7.490	0.380
1E+13	8	7.177	7.542	0.365
1E+13	9	7.110	7.488	0.378
	Max	7.177	7.542	0.483
	Average	7.104	7.503	0.399
	Min	7.006	7.477	0.354
	Std Dev	0.046	0.021	0.037

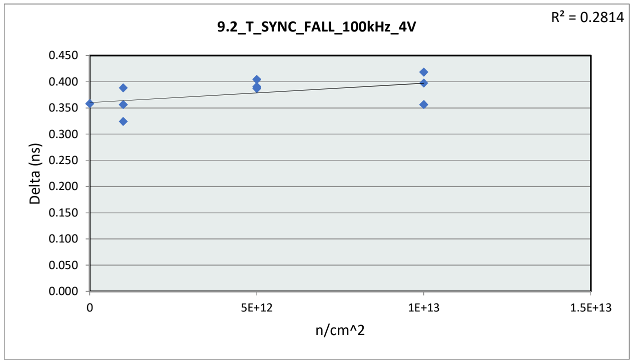


	9.1_T_SYNC_RISE_100kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.521	7.489	7.477	7.488
Average	7.521	7.496	7.499	7.507
Max	7.521	7.505	7.528	7.542
UL	15.000	15.000	15.000	15.000

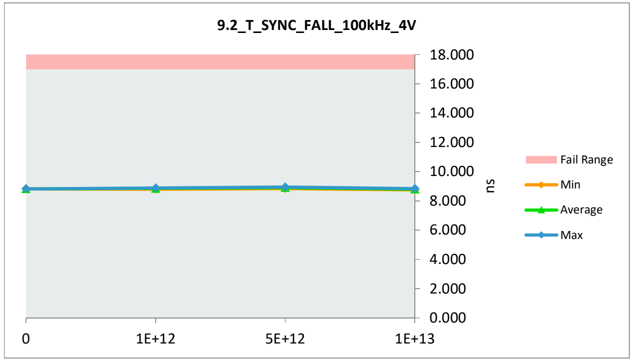


NDD Characterization Report
TPS7H5005-SEP

		9.2_T_SYNC_FALL_100kHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.465	8.823	0.358
1E+12	1	8.508	8.864	0.356
1E+12	2	8.482	8.870	0.388
1E+12	3	8.467	8.791	0.324
5E+12	4	8.539	8.926	0.387
5E+12	5	8.535	8.939	0.404
5E+12	6	8.453	8.843	0.390
1E+13	7	8.374	8.792	0.418
1E+13	8	8.438	8.835	0.397
1E+13	9	8.396	8.752	0.356
	Max	8.539	8.939	0.418
	Average	8.466	8.844	0.378
	Min	8.374	8.752	0.324
	Std Dev	0.054	0.059	0.028

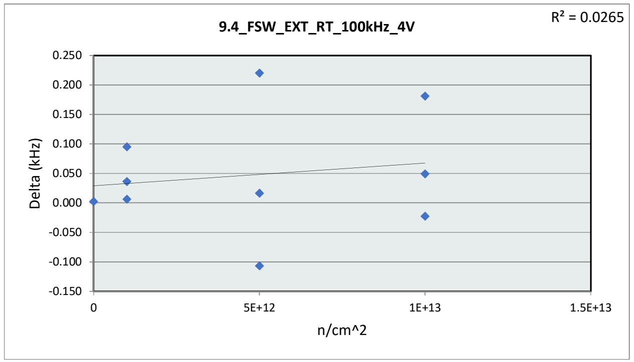


	9.2_T_SYNC_FALL_100kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.823	8.791	8.843	8.752
Average	8.823	8.842	8.903	8.793
Max	8.823	8.870	8.939	8.835
UL	17.000	17.000	17.000	17.000

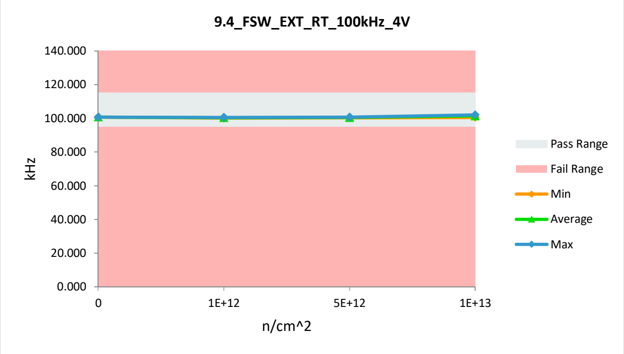


NDD Characterization Report
TPS7H5005-SEP

		9.4_FSW_EXT_RT_100kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	115	115	
	Min Limit	95	95	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	100.693	100.695	0.002
1E+12	1	100.044	100.080	0.036
1E+12	2	100.267	100.362	0.095
1E+12	3	100.579	100.585	0.006
5E+12	4	100.628	100.521	-0.107
5E+12	5	100.671	100.687	0.016
5E+12	6	100.098	100.318	0.220
1E+13	7	101.407	101.588	0.181
1E+13	8	100.670	100.647	-0.023
1E+13	9	102.061	102.110	0.049
	Max	102.061	102.110	0.220
	Average	100.712	100.759	0.048
	Min	100.044	100.080	-0.107
	Std Dev	0.610	0.618	0.096

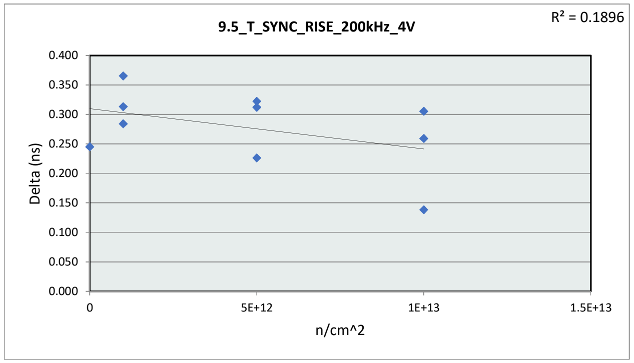


	9.4_FSW_EXT_RT_100kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	100.695	100.080	100.318	100.647
Average	100.695	100.342	100.509	101.448
Max	100.695	100.585	100.687	102.110
UL	115.000	115.000	115.000	115.000

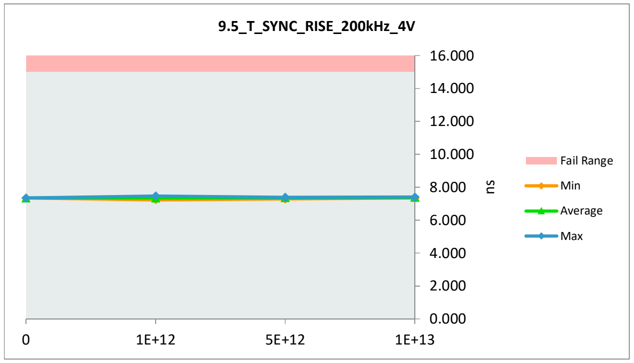


NDD Characterization Report
TPS7H5005-SEP

		9.5_T_SYNC_RISE_200kHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		15	15	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.099	7.344	0.245
1E+12	1	7.104	7.469	0.365
1E+12	2	7.012	7.325	0.313
1E+12	3	6.947	7.231	0.284
5E+12	4	7.068	7.390	0.322
5E+12	5	7.057	7.283	0.226
5E+12	6	7.077	7.389	0.312
1E+13	7	7.090	7.395	0.305
1E+13	8	7.245	7.383	0.138
1E+13	9	7.081	7.340	0.259
	Max	7.245	7.469	0.365
	Average	7.078	7.355	0.277
	Min	6.947	7.231	0.138
	Std Dev	0.075	0.066	0.064

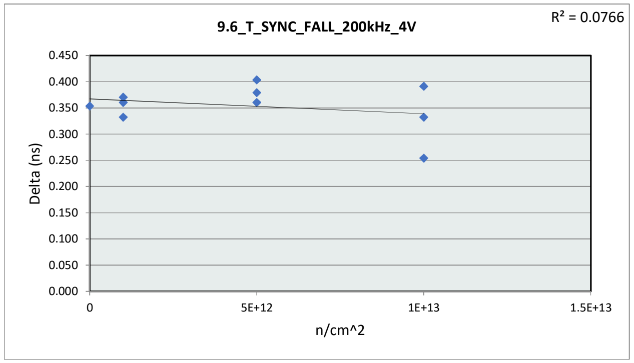


	9.5_T_SYNC_RISE_200kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.344	7.231	7.283	7.340
Average	7.344	7.342	7.354	7.373
Max	7.344	7.469	7.390	7.395
UL	15.000	15.000	15.000	15.000

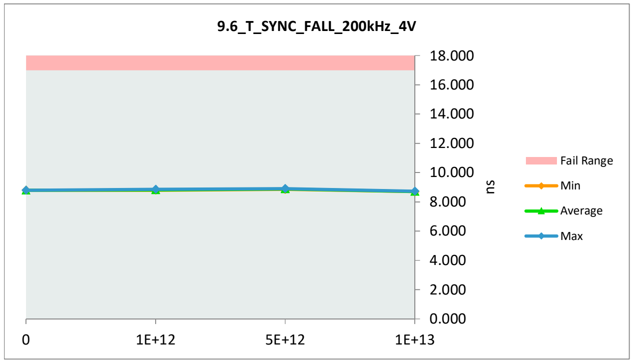


NDD Characterization Report
TPS7H5005-SEP

		9.6_T_SYNC_FALL_200kHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.443	8.796	0.353
1E+12	1	8.485	8.855	0.370
1E+12	2	8.440	8.800	0.360
1E+12	3	8.463	8.795	0.332
5E+12	4	8.523	8.883	0.360
5E+12	5	8.531	8.910	0.379
5E+12	6	8.451	8.854	0.403
1E+13	7	8.333	8.724	0.391
1E+13	8	8.442	8.696	0.254
1E+13	9	8.376	8.708	0.332
	Max	8.531	8.910	0.403
	Average	8.449	8.802	0.353
	Min	8.333	8.696	0.254
	Std Dev	0.060	0.075	0.042

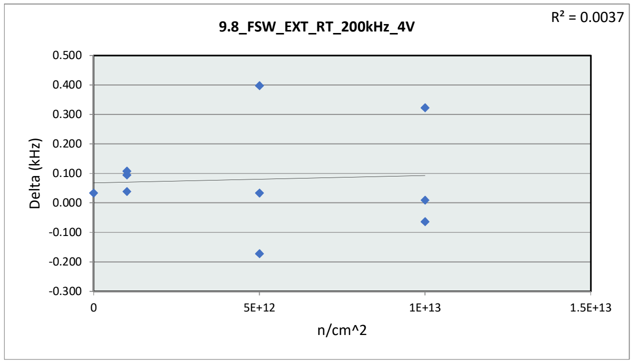


	9.6_T_SYNC_FALL_200kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.796	8.795	8.854	8.696
Average	8.796	8.817	8.882	8.709
Max	8.796	8.855	8.910	8.724
UL	17.000	17.000	17.000	17.000

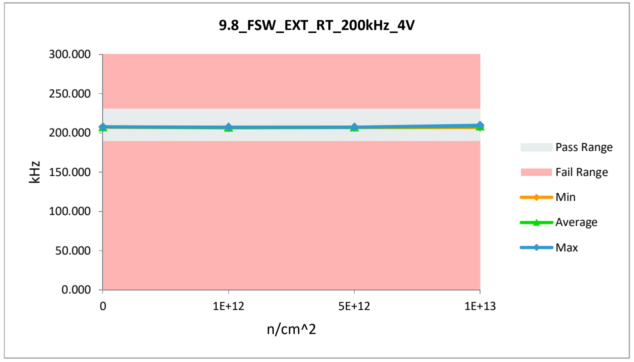


NDD Characterization Report
TPS7H5005-SEP

		9.8_FSW_EXT_RT_200kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	230	230	
	Min Limit	190	190	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	207.423	207.456	0.033
1E+12	1	206.399	206.493	0.094
1E+12	2	206.865	206.972	0.107
1E+12	3	207.222	207.260	0.038
5E+12	4	207.311	207.138	-0.173
5E+12	5	206.956	206.989	0.033
5E+12	6	206.887	207.284	0.397
1E+13	7	208.743	209.065	0.322
1E+13	8	206.933	206.869	-0.064
1E+13	9	209.656	209.665	0.009
	Max	209.656	209.665	0.397
	Average	207.440	207.519	0.080
	Min	206.399	206.493	-0.173
	Std Dev	0.994	1.018	0.169

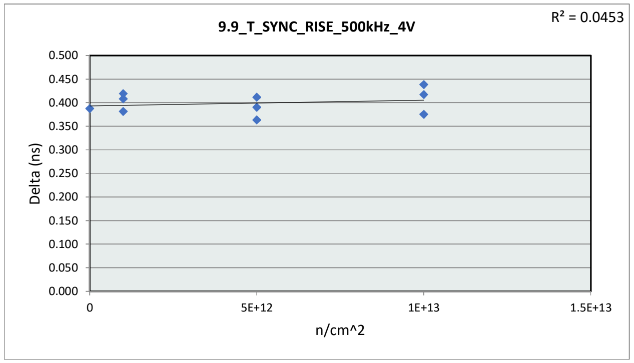


	9.8_FSW_EXT_RT_200kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	207.456	206.493	206.989	206.869
Average	207.456	206.908	207.137	208.533
Max	207.456	207.260	207.284	209.665
UL	230.000	230.000	230.000	230.000

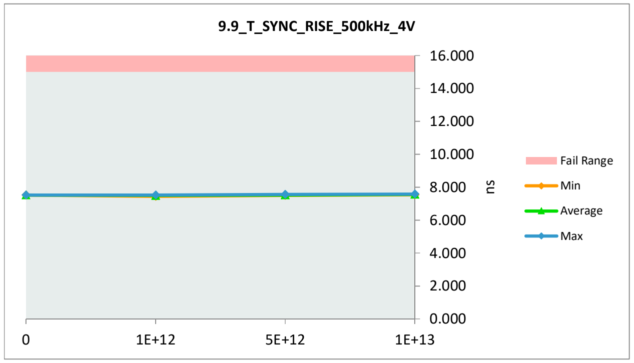


NDD Characterization Report
TPS7H5005-SEP

		9.9_T_SYNC_RISE_500kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.141	7.528	0.387
1E+12	1	7.124	7.532	0.408
1E+12	2	7.127	7.508	0.381
1E+12	3	7.031	7.450	0.419
5E+12	4	7.122	7.512	0.390
5E+12	5	7.135	7.498	0.363
5E+12	6	7.155	7.566	0.411
1E+13	7	7.174	7.549	0.375
1E+13	8	7.149	7.587	0.438
1E+13	9	7.126	7.543	0.417
	Max	7.174	7.587	0.438
	Average	7.128	7.527	0.399
	Min	7.031	7.450	0.363
	Std Dev	0.038	0.038	0.023

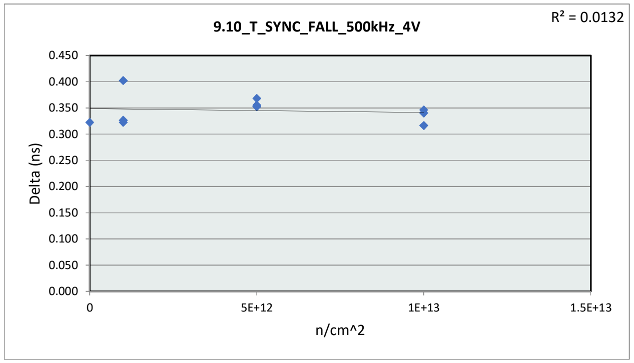


	9.9_T_SYNC_RISE_500kHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.528	7.450	7.498	7.543
Average	7.528	7.497	7.525	7.560
Max	7.528	7.532	7.566	7.587
UL	15.000	15.000	15.000	15.000

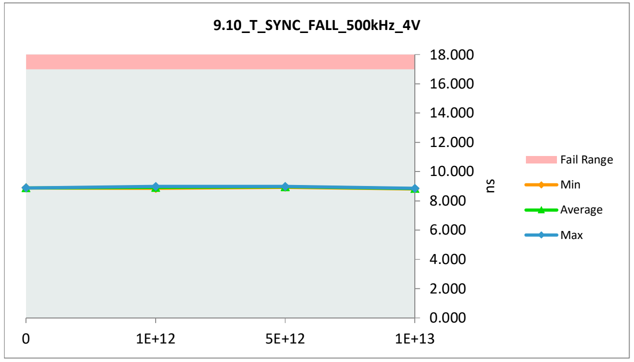


NDD Characterization Report
TPS7H5005-SEP

		9.10_T_SYNC_FALL_500kHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.561	8.883	0.322
1E+12	1	8.581	8.983	0.402
1E+12	2	8.578	8.900	0.322
1E+12	3	8.523	8.849	0.326
5E+12	4	8.612	8.980	0.368
5E+12	5	8.619	8.971	0.352
5E+12	6	8.565	8.920	0.355
1E+13	7	8.475	8.821	0.346
1E+13	8	8.538	8.854	0.316
1E+13	9	8.479	8.819	0.340
	Max	8.619	8.983	0.402
	Average	8.553	8.898	0.345
	Min	8.475	8.819	0.316
	Std Dev	0.050	0.064	0.026

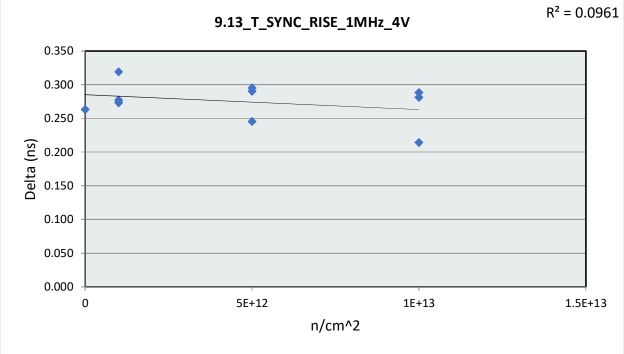


	9.10_T_SYNC_FALL_500kHz_4			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.883	8.849	8.920	8.819
Average	8.883	8.911	8.957	8.831
Max	8.883	8.983	8.980	8.854
UL	17.000	17.000	17.000	17.000

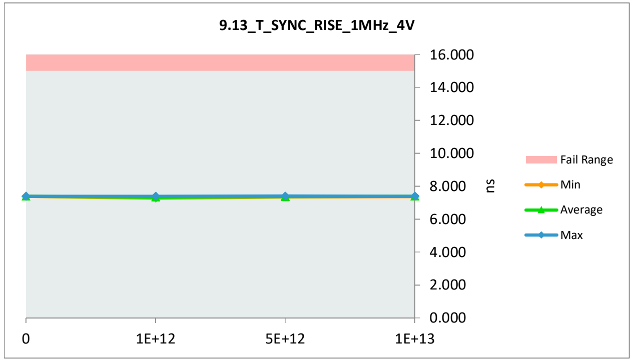


NDD Characterization Report
TPS7H5005-SEP

		9.13_T_SYNC_RISE_1MHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		15	15	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.120	7.383	0.263
1E+12	1	7.072	7.391	0.319
1E+12	2	7.084	7.361	0.277
1E+12	3	6.992	7.265	0.273
5E+12	4	7.066	7.361	0.295
5E+12	5	7.103	7.348	0.245
5E+12	6	7.103	7.393	0.290
1E+13	7	7.114	7.395	0.281
1E+13	8	7.176	7.390	0.214
1E+13	9	7.070	7.358	0.288
	Max	7.176	7.395	0.319
	Average	7.090	7.364	0.274
	Min	6.992	7.265	0.214
	Std Dev	0.047	0.039	0.029

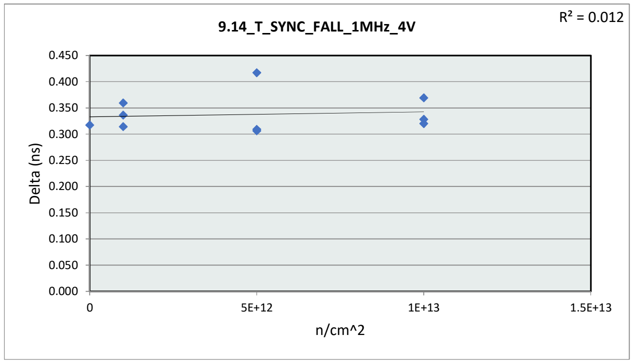


	9.13_T_SYNC_RISE_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.383	7.265	7.348	7.358
Average	7.383	7.339	7.367	7.381
Max	7.383	7.391	7.393	7.395
UL	15.000	15.000	15.000	15.000

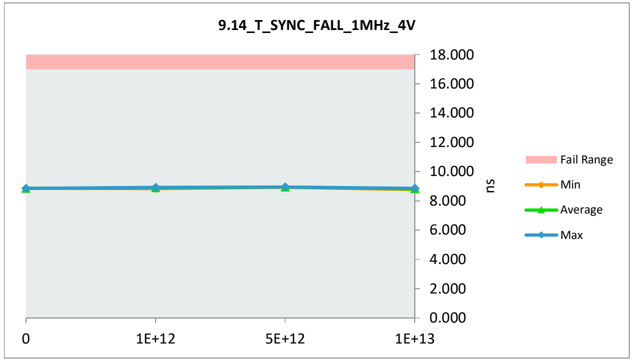


NDD Characterization Report
TPS7H5005-SEP

		9.14_T_SYNC_FALL_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.534	8.851	0.317
1E+12	1	8.600	8.914	0.314
1E+12	2	8.550	8.909	0.359
1E+12	3	8.501	8.837	0.336
5E+12	4	8.639	8.948	0.309
5E+12	5	8.635	8.941	0.306
5E+12	6	8.506	8.923	0.417
1E+13	7	8.435	8.804	0.369
1E+13	8	8.546	8.866	0.320
1E+13	9	8.450	8.778	0.328
	Max	8.639	8.948	0.417
	Average	8.540	8.877	0.337
	Min	8.435	8.778	0.306
	Std Dev	0.070	0.059	0.035

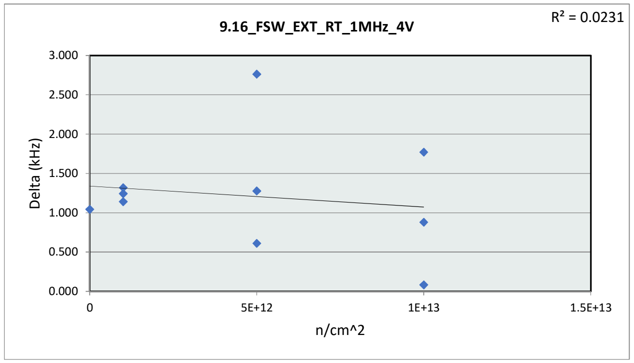


	9.14_T_SYNC_FALL_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.851	8.837	8.923	8.778
Average	8.851	8.887	8.937	8.816
Max	8.851	8.914	8.948	8.866
UL	17.000	17.000	17.000	17.000

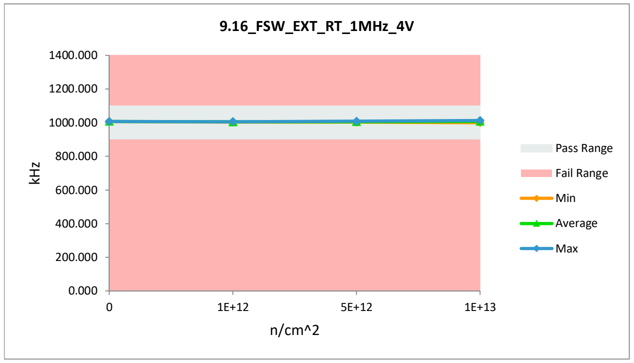


NDD Characterization Report
TPS7H5005-SEP

		9.16_FSW_EXT_RT_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	1100	1100	
	Min Limit	900	900	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1006.099	1007.139	1.040
1E+12	1	1002.035	1003.351	1.316
1E+12	2	1004.278	1005.519	1.241
1E+12	3	1004.706	1005.844	1.138
5E+12	4	1003.819	1004.427	0.608
5E+12	5	1001.761	1003.035	1.274
5E+12	6	1005.940	1008.700	2.760
1E+13	7	1007.972	1009.740	1.768
1E+13	8	998.702	998.784	0.082
1E+13	9	1012.073	1012.950	0.877
	Max	1012.073	1012.950	2.760
	Average	1004.738	1005.949	1.210
	Min	998.702	998.784	0.082
	Std Dev	3.670	3.965	0.708



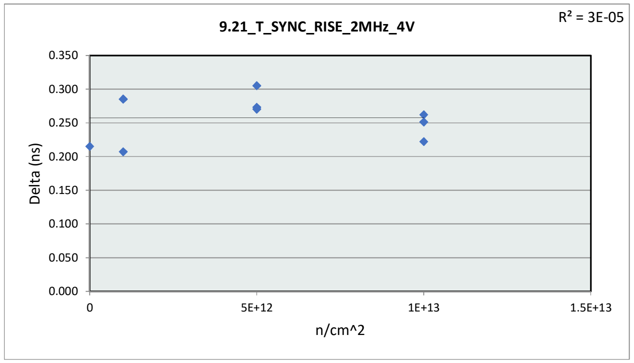
	9.16_FSW_EXT_RT_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1007.139	1003.351	1003.035	998.784
Average	1007.139	1004.905	1005.387	1007.158
Max	1007.139	1005.844	1008.700	1012.950
UL	1100.000	1100.000	1100.000	1100.000



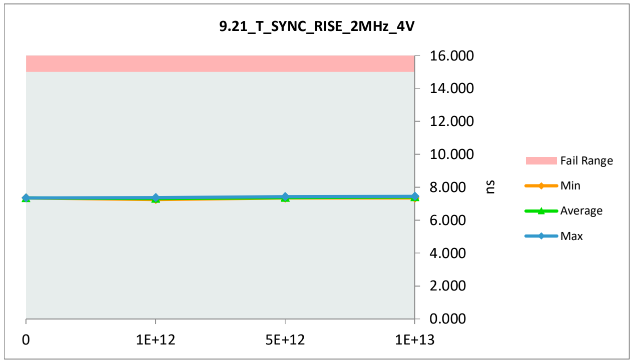
NDD Characterization Report
TPS7H5005-SEP

	9.21_T_SYNC_RISE_2MHz_4V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	15	15
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.133	7.348	0.215
1E+12	1	7.076	7.361	0.285
1E+12	2	7.067	7.352	0.285
1E+12	3	7.038	7.245	0.207
5E+12	4	7.086	7.356	0.270
5E+12	5	7.064	7.337	0.273
5E+12	6	7.114	7.419	0.305
1E+13	7	7.177	7.428	0.251
1E+13	8	7.188	7.450	0.262
1E+13	9	7.118	7.340	0.222
	Max	7.188	7.450	0.305
	Average	7.106	7.364	0.257
	Min	7.038	7.245	0.207
	Std Dev	0.049	0.058	0.033

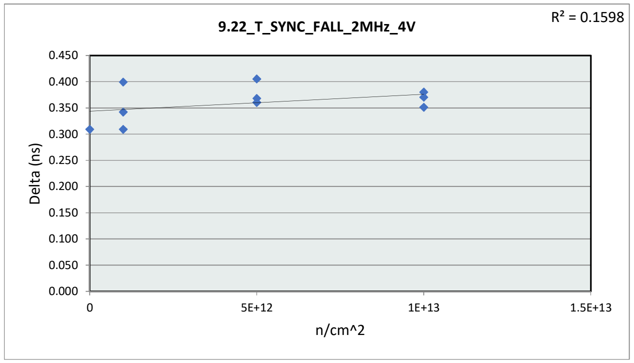


	9.21_T_SYNC_RISE_2MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.348	7.245	7.337	7.340
Average	7.348	7.319	7.371	7.406
Max	7.348	7.361	7.419	7.450
UL	15.000	15.000	15.000	15.000

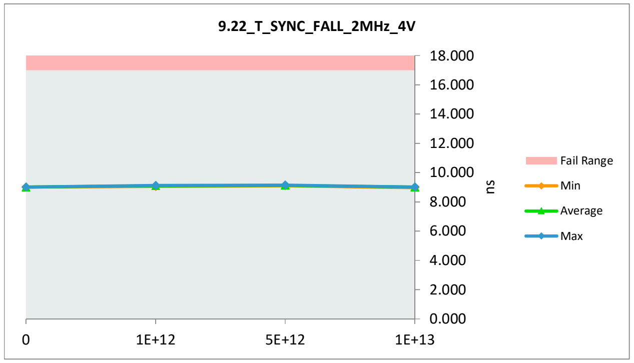


NDD Characterization Report
TPS7H5005-SEP

		9.22_T_SYNC_FALL_2MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.701	9.010	0.309
1E+12	1	8.782	9.124	0.342
1E+12	2	8.728	9.127	0.399
1E+12	3	8.731	9.040	0.309
5E+12	4	8.768	9.136	0.368
5E+12	5	8.791	9.151	0.360
5E+12	6	8.698	9.103	0.405
1E+13	7	8.594	8.974	0.380
1E+13	8	8.673	9.024	0.351
1E+13	9	8.645	9.015	0.370
	Max	8.791	9.151	0.405
	Average	8.711	9.070	0.359
	Min	8.594	8.974	0.309
	Std Dev	0.062	0.064	0.033

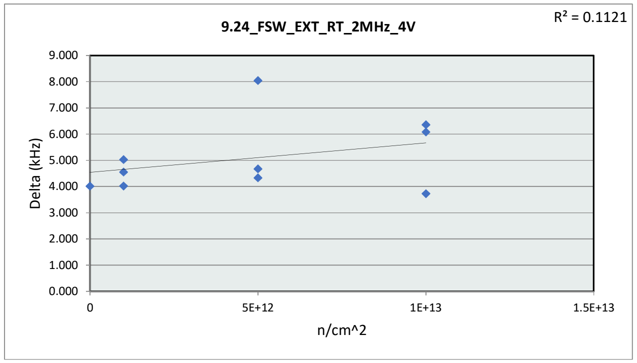


	9.22_T_SYNC_FALL_2MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	9.010	9.040	9.103	8.974
Average	9.010	9.097	9.130	9.004
Max	9.010	9.127	9.151	9.024
UL	17.000	17.000	17.000	17.000

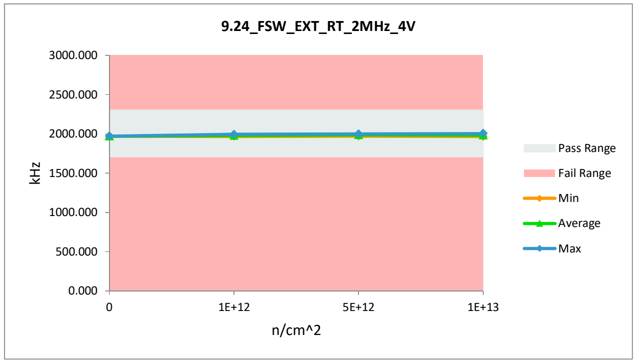


NDD Characterization Report
TPS7H5005-SEP

		9.24_FSW_EXT_RT_2MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	2300	2300	
	Min Limit	1700	1700	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1968.715	1972.725	4.010
1E+12	1	1964.443	1968.462	4.019
1E+12	2	1973.996	1978.542	4.546
1E+12	3	1989.729	1994.751	5.022
5E+12	4	1994.521	1999.186	4.665
5E+12	5	1968.239	1972.563	4.324
5E+12	6	1979.475	1987.514	8.039
1E+13	7	1999.176	2005.250	6.074
1E+13	8	1961.210	1967.564	6.354
1E+13	9	1977.064	1980.790	3.726
	Max	1999.176	2005.250	8.039
	Average	1977.657	1982.735	5.078
	Min	1961.210	1967.564	3.726
	Std Dev	13.013	13.349	1.354

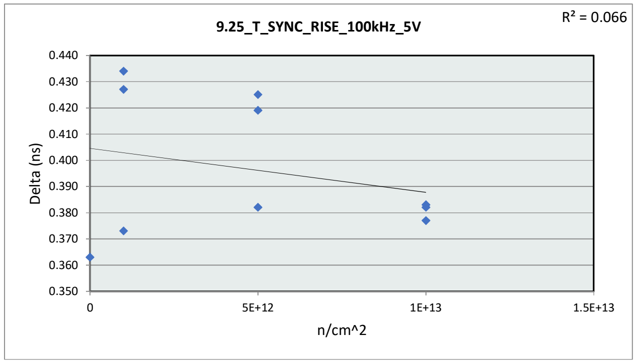


	9.24_FSW_EXT_RT_2MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	1972.725	1968.462	1972.563	1967.564
Average	1972.725	1980.585	1986.421	1984.535
Max	1972.725	1994.751	1999.186	2005.250
UL	2300.000	2300.000	2300.000	2300.000

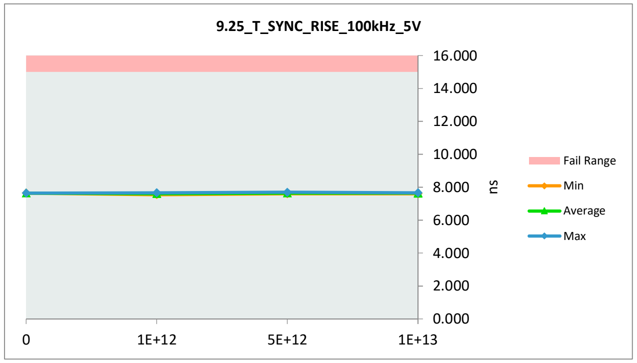


NDD Characterization Report
TPS7H5005-SEP

		9.25_T_SYNC_RISE_100kHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.284	7.647	0.363
1E+12	1	7.227	7.654	0.427
1E+12	2	7.242	7.615	0.373
1E+12	3	7.112	7.546	0.434
5E+12	4	7.201	7.626	0.425
5E+12	5	7.219	7.601	0.382
5E+12	6	7.271	7.690	0.419
1E+13	7	7.254	7.637	0.383
1E+13	8	7.279	7.656	0.377
1E+13	9	7.224	7.606	0.382
	Max	7.284	7.690	0.434
	Average	7.231	7.628	0.396
	Min	7.112	7.546	0.363
	Std Dev	0.050	0.039	0.026



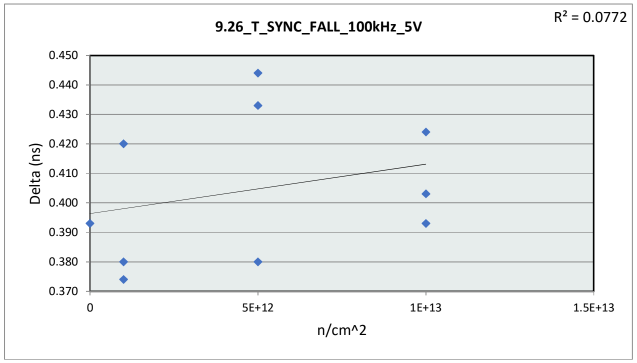
	9.25_T_SYNC_RISE_100kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.647	7.546	7.601	7.606
Average	7.647	7.605	7.639	7.633
Max	7.647	7.654	7.690	7.656
UL	15.000	15.000	15.000	15.000



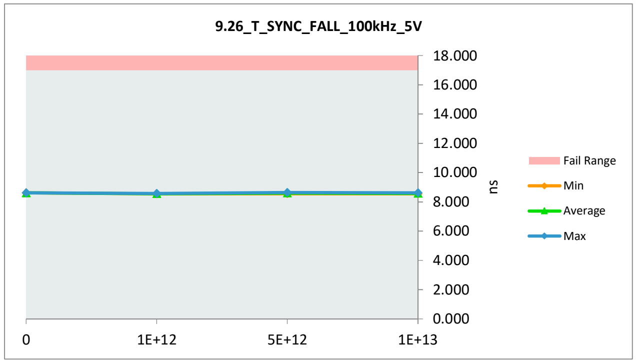
NDD Characterization Report
TPS7H5005-SEP

	9.26_T_SYNC_FALL_100kHz_5V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	17	17
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.216	8.609	0.393
1E+12	1	8.175	8.549	0.374
1E+12	2	8.154	8.574	0.420
1E+12	3	8.185	8.565	0.380
5E+12	4	8.194	8.638	0.444
5E+12	5	8.163	8.596	0.433
5E+12	6	8.173	8.553	0.380
1E+13	7	8.148	8.572	0.424
1E+13	8	8.215	8.608	0.393
1E+13	9	8.143	8.546	0.403
	Max	8.216	8.638	0.444
	Average	8.177	8.581	0.404
	Min	8.143	8.546	0.374
	Std Dev	0.026	0.031	0.024

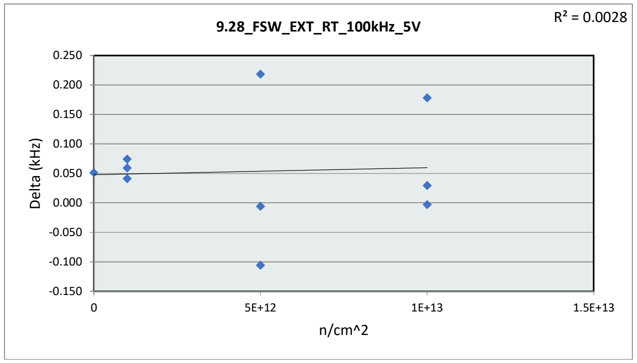


	9.26_T_SYNC_FALL_100kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.609	8.549	8.553	8.546
Average	8.609	8.563	8.596	8.575
Max	8.609	8.574	8.638	8.608
UL	17.000	17.000	17.000	17.000

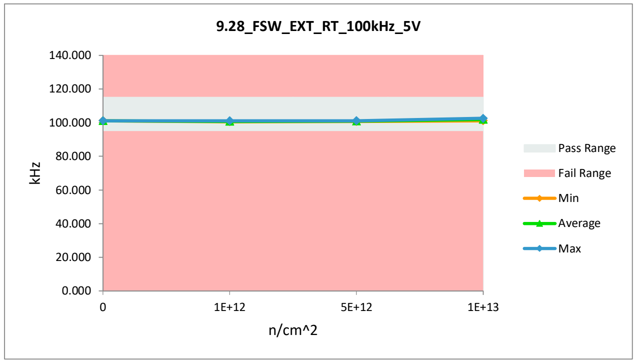


NDD Characterization Report
TPS7H5005-SEP

		9.28_FSW_EXT_RT_100kHz_5V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		115	115	
Min Limit		95	95	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	101.135	101.186	0.051
1E+12	1	100.507	100.566	0.059
1E+12	2	100.721	100.795	0.074
1E+12	3	100.974	101.015	0.041
5E+12	4	101.064	100.958	-0.106
5E+12	5	101.131	101.125	-0.006
5E+12	6	100.523	100.741	0.218
1E+13	7	101.874	102.052	0.178
1E+13	8	101.134	101.131	-0.003
1E+13	9	102.533	102.562	0.029
	Max	102.533	102.562	0.218
	Average	101.160	101.213	0.053
	Min	100.507	100.566	-0.106
	Std Dev	0.621	0.620	0.092

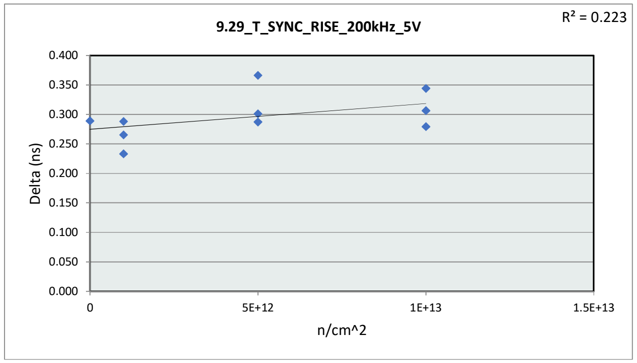


	9.28_FSW_EXT_RT_100kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	101.186	100.566	100.741	101.131
Average	101.186	100.792	100.941	101.915
Max	101.186	101.015	101.125	102.562
UL	115.000	115.000	115.000	115.000

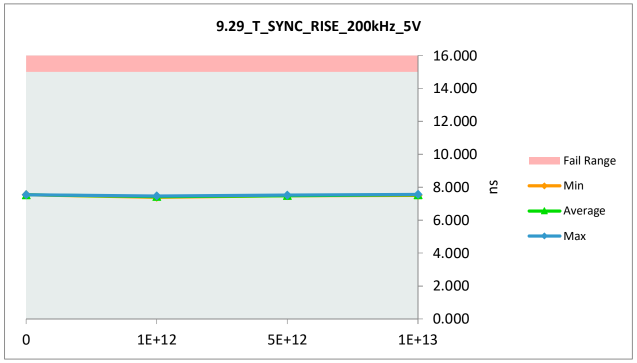


NDD Characterization Report
TPS7H5005-SEP

		9.29_T_SYNC_RISE_200kHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		15	15	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.246	7.535	0.289
1E+12	1	7.180	7.468	0.288
1E+12	2	7.184	7.449	0.265
1E+12	3	7.152	7.385	0.233
5E+12	4	7.196	7.483	0.287
5E+12	5	7.124	7.490	0.366
5E+12	6	7.217	7.518	0.301
1E+13	7	7.227	7.533	0.306
1E+13	8	7.284	7.563	0.279
1E+13	9	7.162	7.506	0.344
	Max	7.284	7.563	0.366
	Average	7.197	7.493	0.296
	Min	7.124	7.385	0.233
	Std Dev	0.048	0.051	0.038



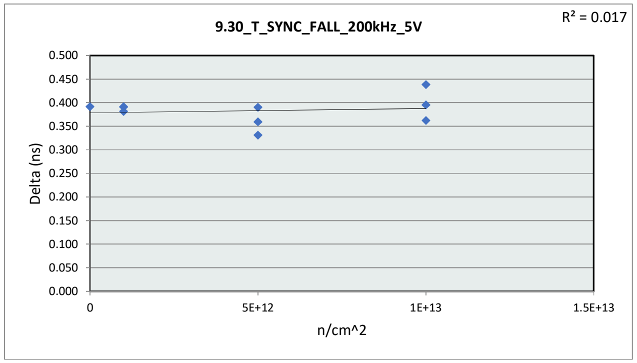
9.29_T_SYNC_RISE_200kHz_5				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.535	7.385	7.483	7.506
Average	7.535	7.434	7.497	7.534
Max	7.535	7.468	7.518	7.563
UL	15.000	15.000	15.000	15.000



NDD Characterization Report
TPS7H5005-SEP

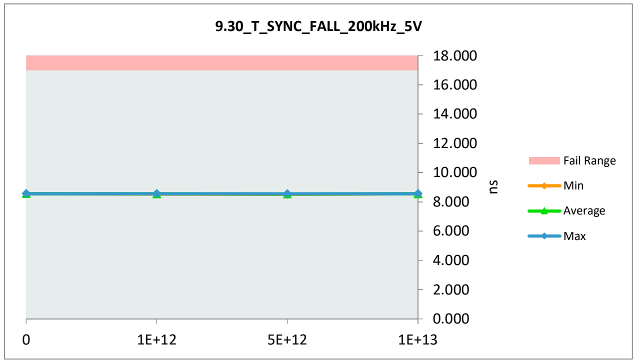
	9.30_T_SYNC_FALL_200kHz_5V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	17	17
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.162	8.553	0.391
1E+12	1	8.172	8.553	0.381
1E+12	2	8.153	8.544	0.391
1E+12	3	8.145	8.536	0.391
5E+12	4	8.171	8.502	0.331
5E+12	5	8.193	8.552	0.359
5E+12	6	8.147	8.537	0.390
1E+13	7	8.179	8.541	0.362
1E+13	8	8.162	8.557	0.395
1E+13	9	8.109	8.547	0.438
	Max	8.193	8.557	0.438
	Average	8.159	8.542	0.383
	Min	8.109	8.502	0.331
	Std Dev	0.023	0.016	0.028



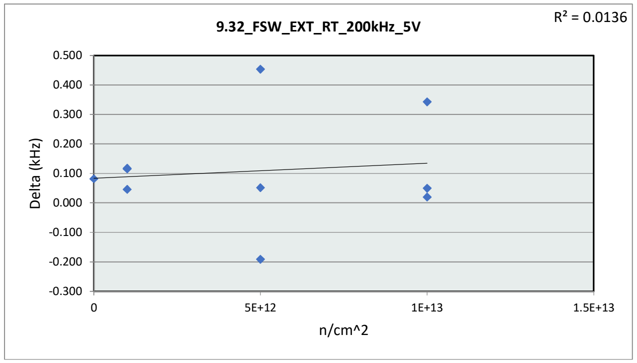
	9.30_T_SYNC_FALL_200kHz_5	
Test Site		
Tester		
Test Number		
Max Limit	17	ns
Min Limit		ns

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.553	8.536	8.502	8.541
Average	8.553	8.544	8.530	8.548
Max	8.553	8.553	8.552	8.557
UL	17.000	17.000	17.000	17.000

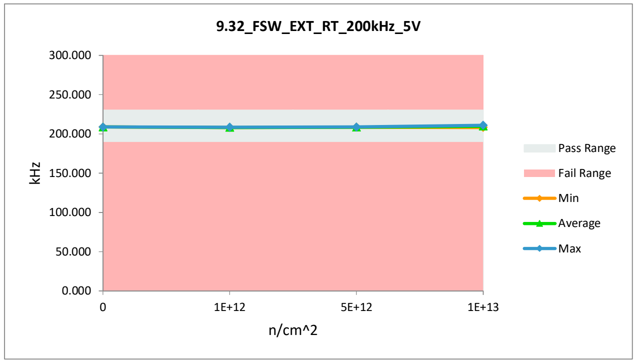


NDD Characterization Report
TPS7H5005-SEP

		9.32_FSW_EXT_RT_200kHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	230	230	
	Min Limit	190	190	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	208.718	208.799	0.081
1E+12	1	207.782	207.897	0.115
1E+12	2	208.152	208.269	0.117
1E+12	3	208.406	208.451	0.045
5E+12	4	208.570	208.378	-0.192
5E+12	5	208.340	208.391	0.051
5E+12	6	208.139	208.592	0.453
1E+13	7	210.024	210.366	0.342
1E+13	8	208.212	208.231	0.019
1E+13	9	210.854	210.903	0.049
	Max	210.854	210.903	0.453
	Average	208.720	208.828	0.108
	Min	207.782	207.897	-0.192
	Std Dev	0.961	0.989	0.177

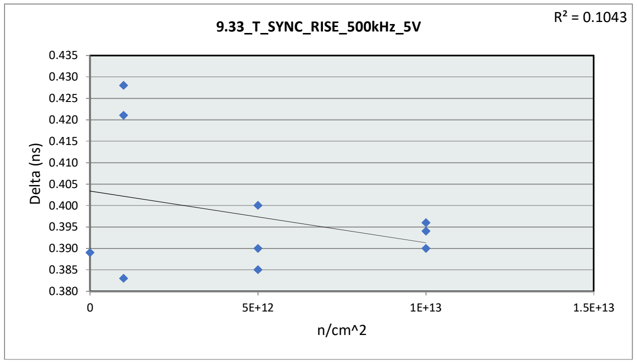


	9.32_FSW_EXT_RT_200kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	208.799	207.897	208.378	208.231
Average	208.799	208.206	208.454	209.833
Max	208.799	208.451	208.592	210.903
UL	230.000	230.000	230.000	230.000

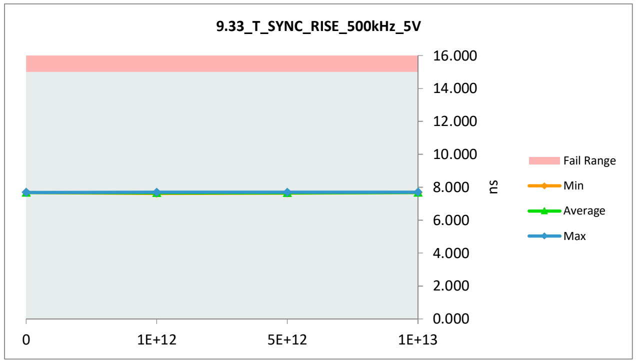


NDD Characterization Report
TPS7H5005-SEP

		9.33_T_SYNC_RISE_500kHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.299	7.688	0.389
1E+12	1	7.293	7.676	0.383
1E+12	2	7.268	7.689	0.421
1E+12	3	7.200	7.628	0.428
5E+12	4	7.255	7.655	0.400
5E+12	5	7.262	7.647	0.385
5E+12	6	7.299	7.689	0.390
1E+13	7	7.280	7.674	0.394
1E+13	8	7.306	7.696	0.390
1E+13	9	7.277	7.673	0.396
	Max	7.306	7.696	0.428
	Average	7.274	7.672	0.398
	Min	7.200	7.628	0.383
	Std Dev	0.031	0.022	0.015

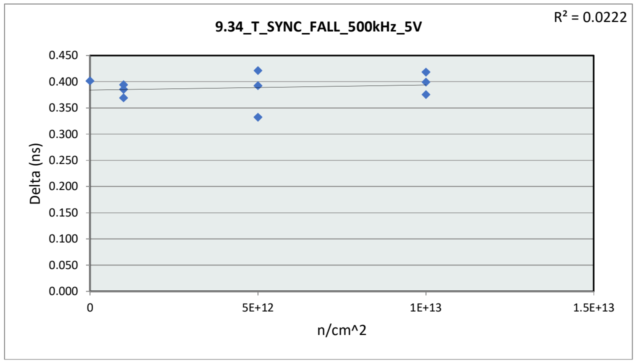


	9.33_T_SYNC_RISE_500kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.688	7.628	7.647	7.673
Average	7.688	7.664	7.664	7.681
Max	7.688	7.689	7.689	7.696
UL	15.000	15.000	15.000	15.000

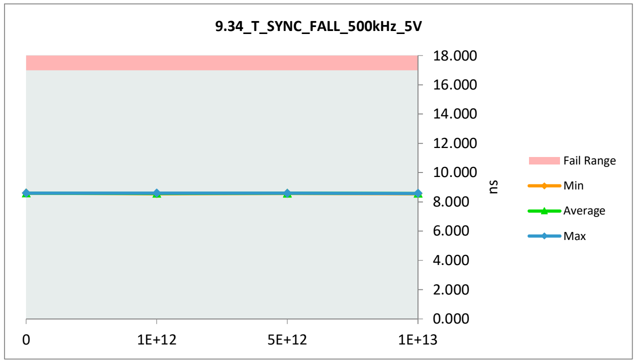


NDD Characterization Report
TPS7H5005-SEP

		9.34_T_SYNC_FALL_500kHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.194	8.595	0.401
1E+12	1	8.198	8.592	0.394
1E+12	2	8.203	8.572	0.369
1E+12	3	8.168	8.553	0.385
5E+12	4	8.254	8.586	0.332
5E+12	5	8.181	8.573	0.392
5E+12	6	8.166	8.587	0.421
1E+13	7	8.183	8.558	0.375
1E+13	8	8.182	8.581	0.399
1E+13	9	8.162	8.580	0.418
	Max	8.254	8.595	0.421
	Average	8.189	8.578	0.389
	Min	8.162	8.553	0.332
	Std Dev	0.027	0.014	0.026

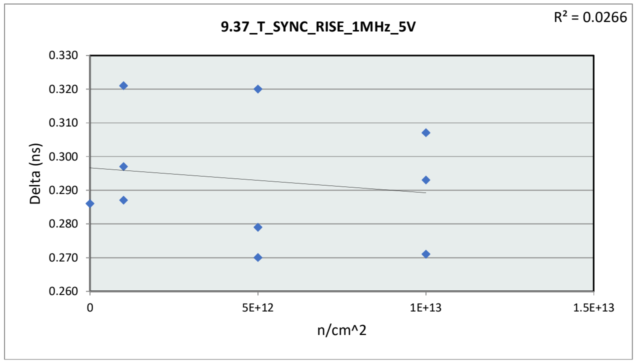


	9.34_T_SYNC_FALL_500kHz_5			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.595	8.553	8.573	8.558
Average	8.595	8.572	8.582	8.573
Max	8.595	8.592	8.587	8.581
UL	17.000	17.000	17.000	17.000

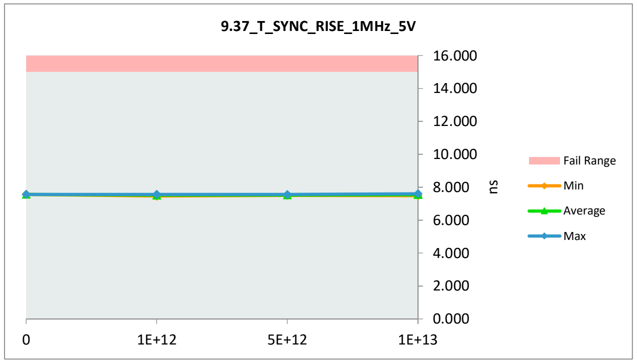


NDD Characterization Report
TPS7H5005-SEP

		9.37_T_SYNC_RISE_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.276	7.562	0.286
1E+12	1	7.239	7.526	0.287
1E+12	2	7.241	7.562	0.321
1E+12	3	7.160	7.457	0.297
5E+12	4	7.234	7.554	0.320
5E+12	5	7.238	7.517	0.279
5E+12	6	7.232	7.502	0.270
1E+13	7	7.285	7.592	0.307
1E+13	8	7.266	7.559	0.293
1E+13	9	7.214	7.485	0.271
	Max	7.285	7.592	0.321
	Average	7.238	7.532	0.293
	Min	7.160	7.457	0.270
	Std Dev	0.035	0.042	0.018

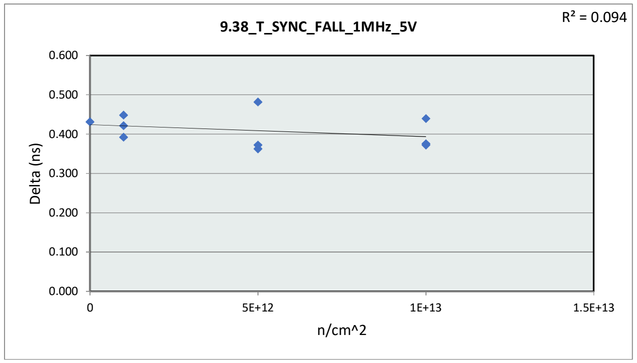


	9.37_T_SYNC_RISE_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.562	7.457	7.502	7.485
Average	7.562	7.515	7.524	7.545
Max	7.562	7.562	7.554	7.592
UL	15.000	15.000	15.000	15.000

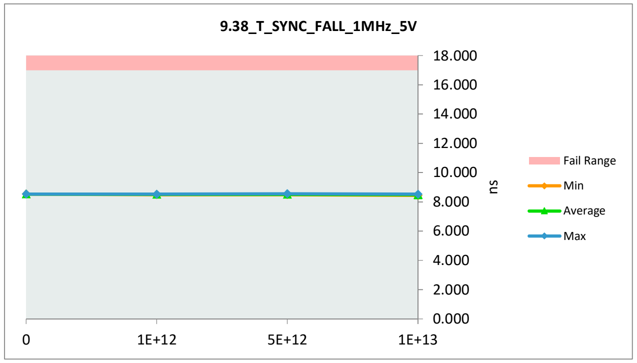


NDD Characterization Report
TPS7H5005-SEP

		9.38_T_SYNC_FALL_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.097	8.528	0.431
1E+12	1	8.069	8.517	0.448
1E+12	2	8.099	8.520	0.421
1E+12	3	8.101	8.493	0.392
5E+12	4	8.135	8.497	0.362
5E+12	5	8.118	8.490	0.372
5E+12	6	8.065	8.546	0.481
1E+13	7	8.082	8.521	0.439
1E+13	8	8.105	8.477	0.372
1E+13	9	8.061	8.436	0.375
	Max	8.135	8.546	0.481
	Average	8.093	8.502	0.409
	Min	8.061	8.436	0.362
	Std Dev	0.024	0.031	0.040

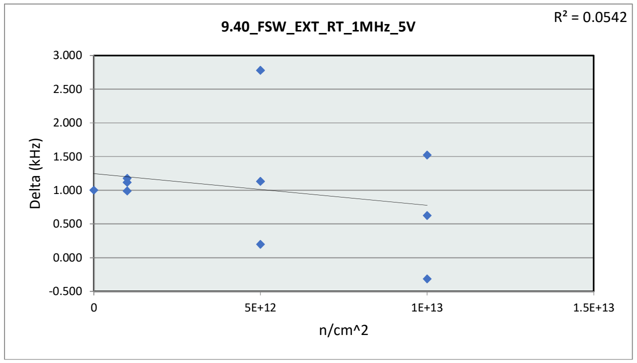


	9.38_T_SYNC_FALL_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.528	8.493	8.490	8.436
Average	8.528	8.510	8.511	8.478
Max	8.528	8.520	8.546	8.521
UL	17.000	17.000	17.000	17.000

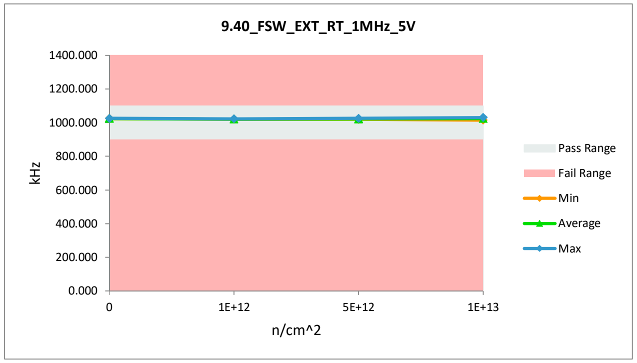


NDD Characterization Report
TPS7H5005-SEP

		9.40_FSW_EXT_RT_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	1100	1100	
	Min Limit	900	900	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1023.810	1024.808	0.998
1E+12	1	1019.145	1020.322	1.177
1E+12	2	1021.598	1022.715	1.117
1E+12	3	1020.074	1021.061	0.987
5E+12	4	1019.381	1019.577	0.196
5E+12	5	1018.968	1020.097	1.129
5E+12	6	1022.652	1025.428	2.776
1E+13	7	1023.720	1025.241	1.521
1E+13	8	1015.302	1014.985	-0.317
1E+13	9	1030.093	1030.717	0.624
	Max	1030.093	1030.717	2.776
	Average	1021.474	1022.495	1.021
	Min	1015.302	1014.985	-0.317
	Std Dev	3.977	4.302	0.817

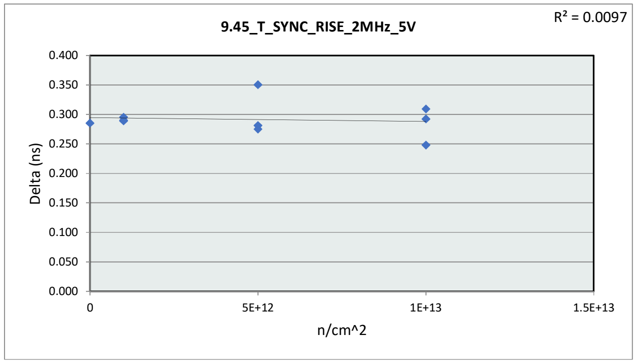


	9.40_FSW_EXT_RT_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1024.808	1020.322	1019.577	1014.985
Average	1024.808	1021.366	1021.701	1023.648
Max	1024.808	1022.715	1025.428	1030.717
UL	1100.000	1100.000	1100.000	1100.000

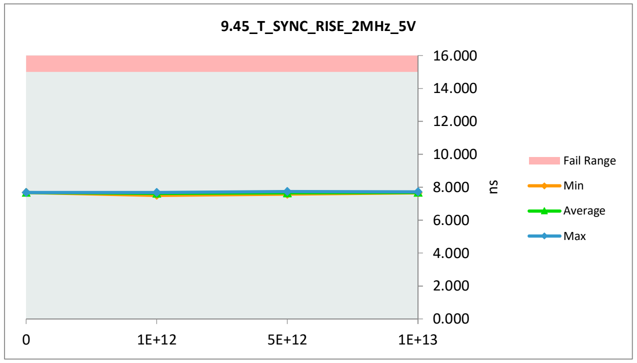


NDD Characterization Report
TPS7H5005-SEP

		9.45_T_SYNC_RISE_2MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.398	7.683	0.285
1E+12	1	7.379	7.668	0.289
1E+12	2	7.386	7.681	0.295
1E+12	3	7.221	7.511	0.290
5E+12	4	7.294	7.569	0.275
5E+12	5	7.387	7.668	0.281
5E+12	6	7.382	7.732	0.350
1E+13	7	7.380	7.672	0.292
1E+13	8	7.405	7.714	0.309
1E+13	9	7.411	7.659	0.248
	Max	7.411	7.732	0.350
	Average	7.364	7.656	0.291
	Min	7.221	7.511	0.248
	Std Dev	0.060	0.066	0.026

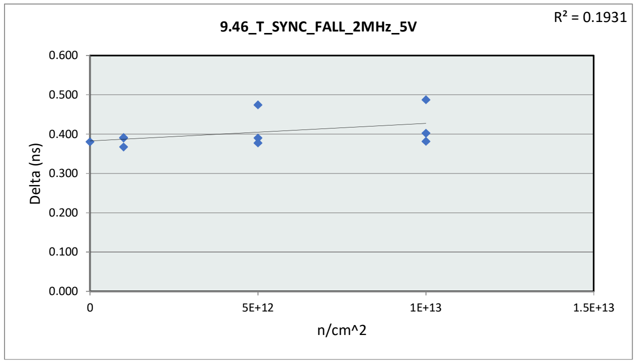


	9.45_T_SYNC_RISE_2MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.683	7.511	7.569	7.659
Average	7.683	7.620	7.656	7.682
Max	7.683	7.681	7.732	7.714
UL	15.000	15.000	15.000	15.000

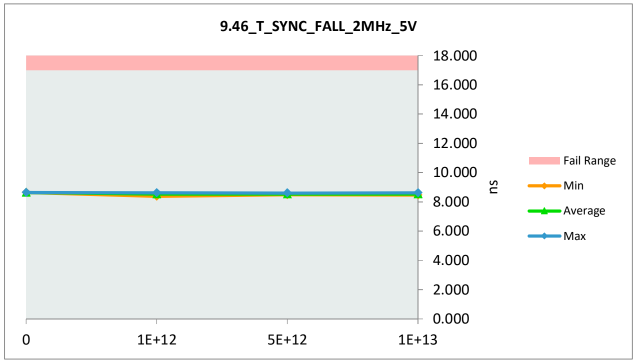


NDD Characterization Report
TPS7H5005-SEP

		9.46_T_SYNC_FALL_2MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.267	8.647	0.380
1E+12	1	8.236	8.626	0.390
1E+12	2	8.197	8.588	0.391
1E+12	3	8.020	8.387	0.367
5E+12	4	8.093	8.483	0.390
5E+12	5	8.229	8.606	0.377
5E+12	6	8.053	8.527	0.474
1E+13	7	8.007	8.494	0.487
1E+13	8	8.091	8.472	0.381
1E+13	9	8.228	8.630	0.402
	Max	8.267	8.647	0.487
	Average	8.142	8.546	0.404
	Min	8.007	8.387	0.367
	Std Dev	0.099	0.086	0.042

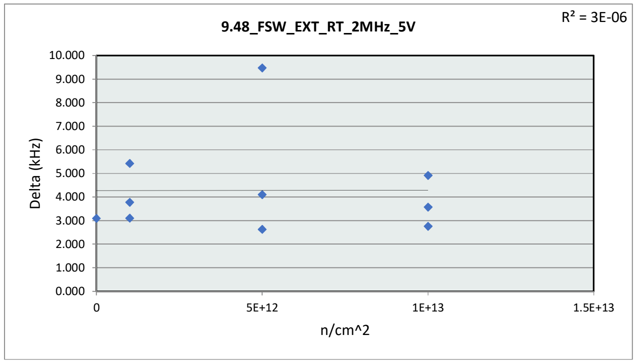


	9.46_T_SYNC_FALL_2MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.647	8.387	8.483	8.472
Average	8.647	8.534	8.539	8.532
Max	8.647	8.626	8.606	8.630
UL	17.000	17.000	17.000	17.000

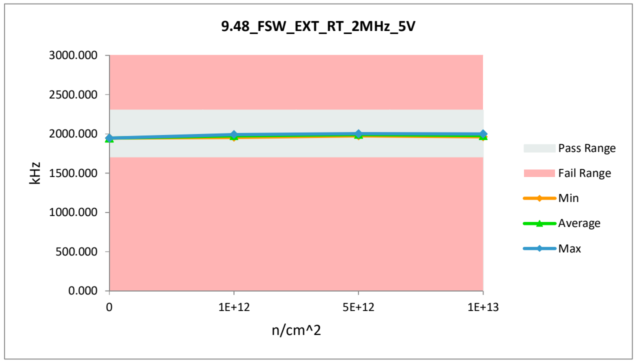


NDD Characterization Report
TPS7H5005-SEP

		9.48_FSW_EXT_RT_2MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	2300	2300	
	Min Limit	1700	1700	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1942.645	1945.731	3.086
1E+12	1	1953.163	1956.259	3.096
1E+12	2	1973.671	1979.084	5.413
1E+12	3	1987.549	1991.321	3.772
5E+12	4	1994.683	1997.309	2.626
5E+12	5	1970.293	1974.385	4.092
5E+12	6	1993.000	2002.465	9.465
1E+13	7	1994.736	1998.305	3.569
1E+13	8	1967.317	1970.068	2.751
1E+13	9	1956.380	1961.286	4.906
	Max	1994.736	2002.465	9.465
	Average	1973.344	1977.621	4.278
	Min	1942.645	1945.731	2.626
	Std Dev	18.810	19.523	2.035

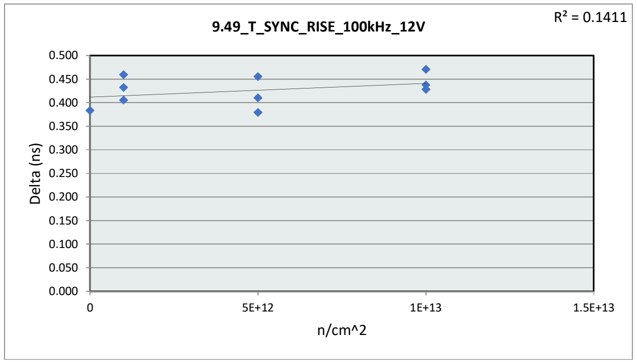


	9.48_FSW_EXT_RT_2MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	1945.731	1956.259	1974.385	1961.286
Average	1945.731	1975.555	1991.386	1976.553
Max	1945.731	1991.321	2002.465	1998.305
UL	2300.000	2300.000	2300.000	2300.000

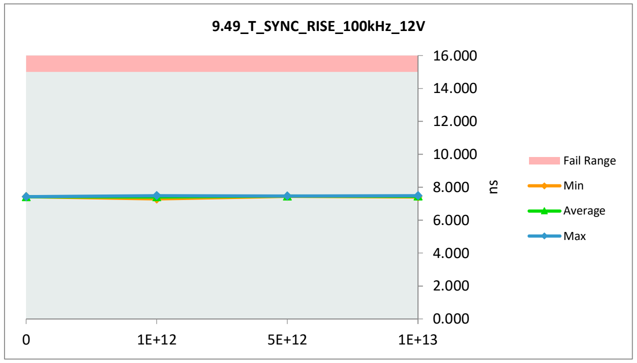


NDD Characterization Report
TPS7H5005-SEP

		9.49_T_SYNC_RISE_100kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.042	7.425	0.383
1E+12	1	7.002	7.461	0.459
1E+12	2	7.085	7.490	0.405
1E+12	3	6.849	7.281	0.432
5E+12	4	7.060	7.439	0.379
5E+12	5	7.010	7.465	0.455
5E+12	6	7.043	7.453	0.410
1E+13	7	7.056	7.484	0.428
1E+13	8	7.031	7.468	0.437
1E+13	9	6.937	7.407	0.470
	Max	7.085	7.490	0.470
	Average	7.012	7.437	0.426
	Min	6.849	7.281	0.379
	Std Dev	0.070	0.061	0.031

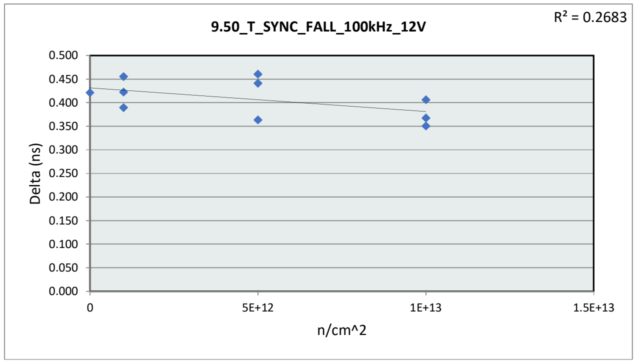


	9.49_T_SYNC_RISE_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.425	7.281	7.439	7.407
Average	7.425	7.411	7.452	7.453
Max	7.425	7.490	7.465	7.484
UL	15.000	15.000	15.000	15.000

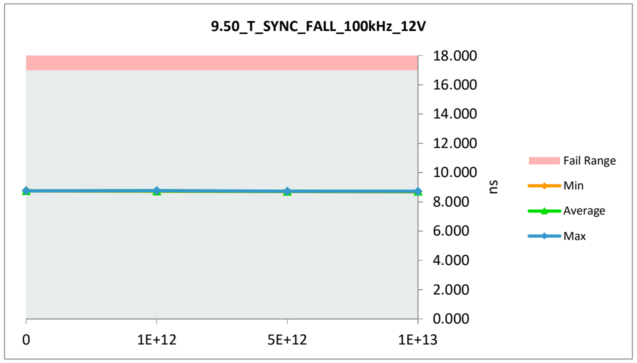


NDD Characterization Report
TPS7H5005-SEP

		9.50_T_SYNC_FALL_100kHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.338	8.759	0.421
1E+12	1	8.307	8.762	0.455
1E+12	2	8.325	8.714	0.389
1E+12	3	8.317	8.739	0.422
5E+12	4	8.338	8.701	0.363
5E+12	5	8.281	8.722	0.441
5E+12	6	8.259	8.719	0.460
1E+13	7	8.343	8.693	0.350
1E+13	8	8.312	8.718	0.406
1E+13	9	8.335	8.702	0.367
	Max	8.343	8.762	0.460
	Average	8.316	8.723	0.407
	Min	8.259	8.693	0.350
	Std Dev	0.027	0.024	0.039

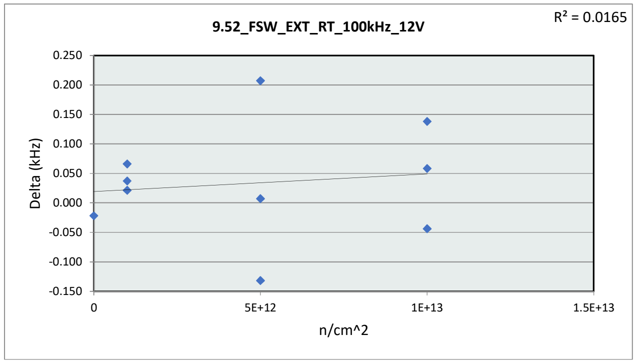


	9.50_T_SYNC_FALL_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.759	8.714	8.701	8.693
Average	8.759	8.738	8.714	8.704
Max	8.759	8.762	8.722	8.718
UL	17.000	17.000	17.000	17.000

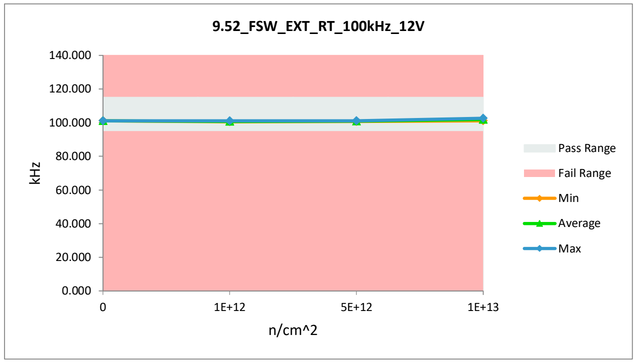


NDD Characterization Report
TPS7H5005-SEP

		9.52_FSW_EXT_RT_100kHz_12V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		115	115	
Min Limit		95	95	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	101.198	101.176	-0.022
1E+12	1	100.556	100.577	0.021
1E+12	2	100.748	100.814	0.066
1E+12	3	101.016	101.053	0.037
5E+12	4	101.076	100.944	-0.132
5E+12	5	101.160	101.167	0.007
5E+12	6	100.556	100.763	0.207
1E+13	7	101.909	102.047	0.138
1E+13	8	101.185	101.141	-0.044
1E+13	9	102.559	102.617	0.058
	Max	102.559	102.617	0.207
	Average	101.196	101.230	0.034
	Min	100.556	100.577	-0.132
	Std Dev	0.618	0.627	0.094



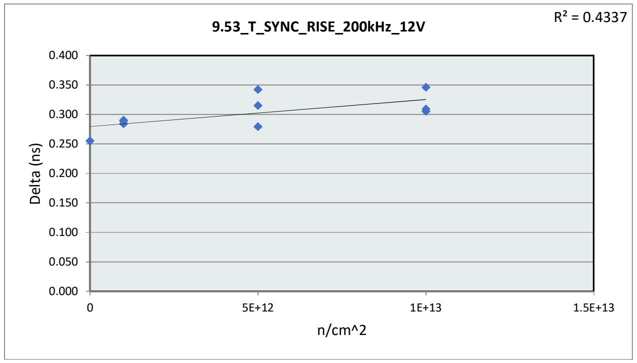
	9.52_FSW_EXT_RT_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	101.176	100.577	100.763	101.141
Average	101.176	100.815	100.958	101.935
Max	101.176	101.053	101.167	102.617
UL	115.000	115.000	115.000	115.000



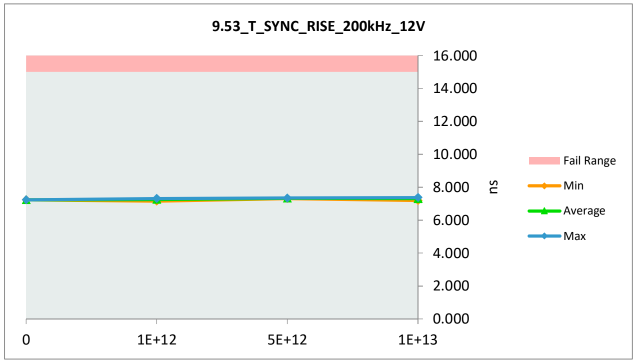
NDD Characterization Report
TPS7H5005-SEP

	9.53_T_SYNC_RISE_200kHz_12V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	15	15
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.981	7.236	0.255
1E+12	1	7.023	7.313	0.290
1E+12	2	7.017	7.301	0.284
1E+12	3	6.863	7.152	0.289
5E+12	4	6.996	7.338	0.342
5E+12	5	7.008	7.323	0.315
5E+12	6	7.031	7.310	0.279
1E+13	7	7.068	7.373	0.305
1E+13	8	7.034	7.343	0.309
1E+13	9	6.838	7.184	0.346
	Max	7.068	7.373	0.346
	Average	6.986	7.287	0.301
	Min	6.838	7.152	0.255
	Std Dev	0.075	0.072	0.028

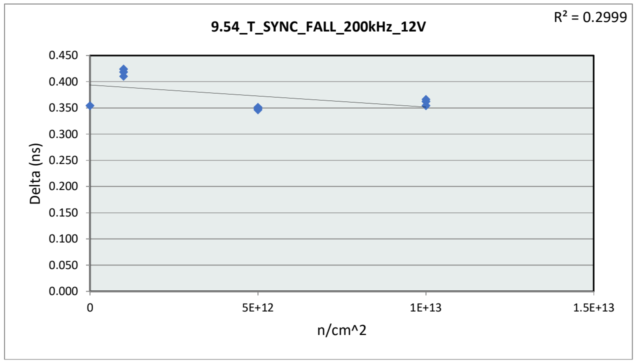


	9.53_T_SYNC_RISE_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.236	7.152	7.310	7.184
Average	7.236	7.255	7.324	7.300
Max	7.236	7.313	7.338	7.373
UL	15.000	15.000	15.000	15.000

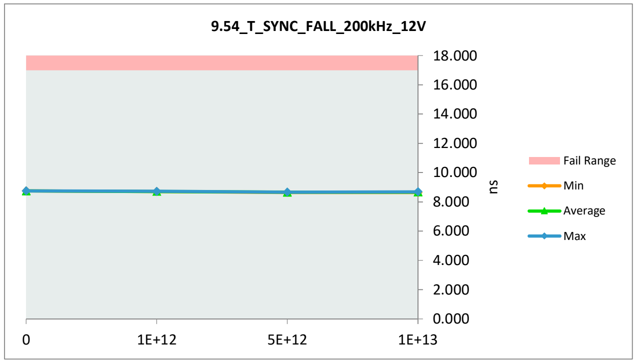


NDD Characterization Report
TPS7H5005-SEP

		9.54_T_SYNC_FALL_200kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.388	8.742	0.354
1E+12	1	8.299	8.717	0.418
1E+12	2	8.280	8.704	0.424
1E+12	3	8.296	8.706	0.410
5E+12	4	8.319	8.667	0.348
5E+12	5	8.308	8.659	0.351
5E+12	6	8.286	8.632	0.346
1E+13	7	8.294	8.660	0.366
1E+13	8	8.283	8.637	0.354
1E+13	9	8.323	8.685	0.362
	Max	8.388	8.742	0.424
	Average	8.308	8.681	0.373
	Min	8.280	8.632	0.346
	Std Dev	0.032	0.036	0.031

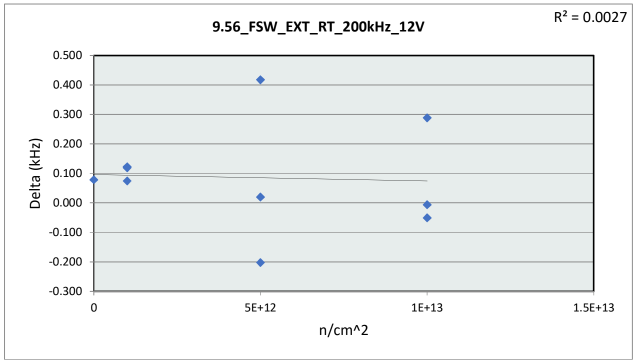


	9.54_T_SYNC_FALL_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.742	8.704	8.632	8.637
Average	8.742	8.709	8.653	8.661
Max	8.742	8.717	8.667	8.685
UL	17.000	17.000	17.000	17.000

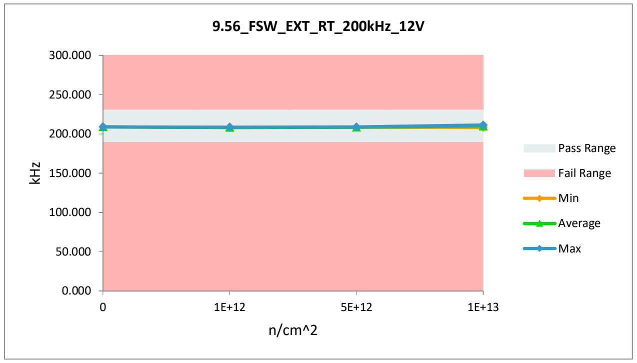


NDD Characterization Report
TPS7H5005-SEP

		9.56_FSW_EXT_RT_200kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	230	230	
	Min Limit	190	190	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	208.805	208.883	0.078
1E+12	1	207.845	207.919	0.074
1E+12	2	208.213	208.332	0.119
1E+12	3	208.475	208.597	0.122
5E+12	4	208.628	208.425	-0.203
5E+12	5	208.476	208.495	0.019
5E+12	6	208.226	208.643	0.417
1E+13	7	210.123	210.411	0.288
1E+13	8	208.305	208.298	-0.007
1E+13	9	211.238	211.187	-0.051
	Max	211.238	211.187	0.417
	Average	208.833	208.919	0.086
	Min	207.845	207.919	-0.203
	Std Dev	1.041	1.038	0.173

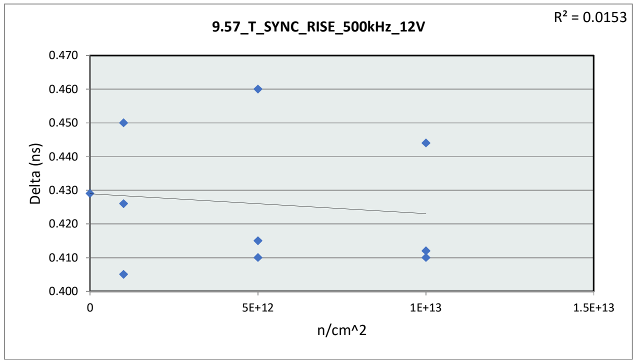


	9.56_FSW_EXT_RT_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	208.883	207.919	208.425	208.298
Average	208.883	208.283	208.521	209.965
Max	208.883	208.597	208.643	211.187
UL	230.000	230.000	230.000	230.000

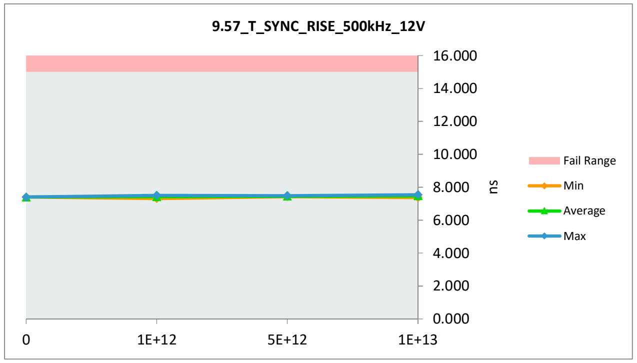


NDD Characterization Report
TPS7H5005-SEP

		9.57_T_SYNC_RISE_500kHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.973	7.402	0.429
1E+12	1	7.008	7.434	0.426
1E+12	2	7.053	7.503	0.450
1E+12	3	6.913	7.318	0.405
5E+12	4	7.012	7.422	0.410
5E+12	5	7.020	7.435	0.415
5E+12	6	7.022	7.482	0.460
1E+13	7	7.123	7.535	0.412
1E+13	8	7.072	7.516	0.444
1E+13	9	6.963	7.373	0.410
	Max	7.123	7.535	0.460
	Average	7.016	7.442	0.426
	Min	6.913	7.318	0.405
	Std Dev	0.059	0.068	0.019



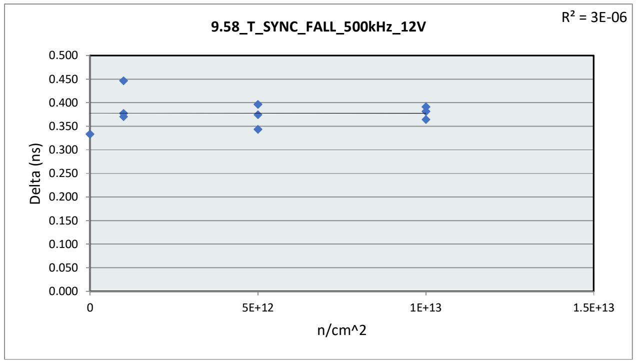
	9.57_T_SYNC_RISE_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.402	7.318	7.422	7.373
Average	7.402	7.418	7.446	7.475
Max	7.402	7.503	7.482	7.535
UL	15.000	15.000	15.000	15.000



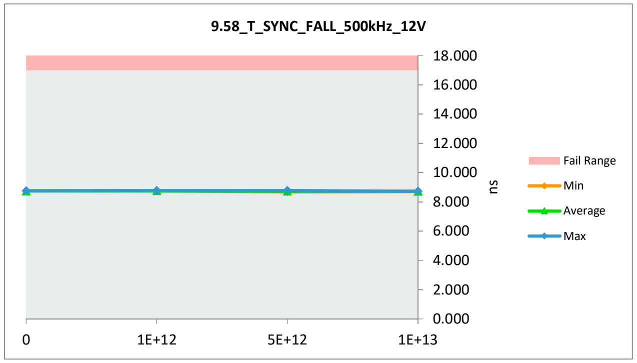
NDD Characterization Report
TPS7H5005-SEP

	9.58_T_SYNC_FALL_500kHz_12V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	17	17
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.416	8.749	0.333
1E+12	1	8.371	8.741	0.370
1E+12	2	8.324	8.770	0.446
1E+12	3	8.369	8.746	0.377
5E+12	4	8.377	8.773	0.396
5E+12	5	8.374	8.717	0.343
5E+12	6	8.317	8.691	0.374
1E+13	7	8.318	8.709	0.391
1E+13	8	8.337	8.718	0.381
1E+13	9	8.368	8.732	0.364
	Max	8.416	8.773	0.446
	Average	8.357	8.735	0.377
	Min	8.317	8.691	0.333
	Std Dev	0.032	0.026	0.031

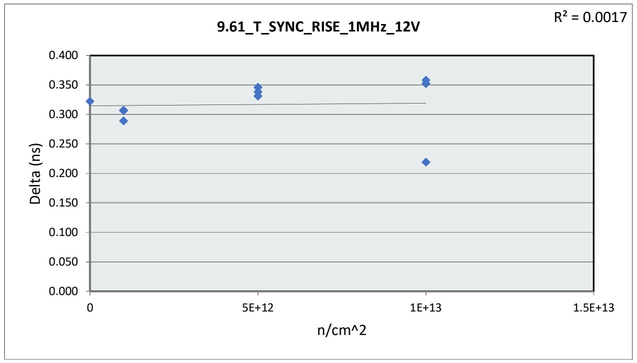


	9.58_T_SYNC_FALL_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.749	8.741	8.691	8.709
Average	8.749	8.752	8.727	8.720
Max	8.749	8.770	8.773	8.732
UL	17.000	17.000	17.000	17.000

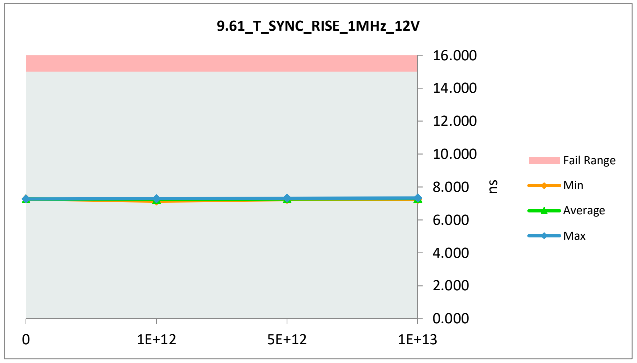


NDD Characterization Report
TPS7H5005-SEP

		9.61_T_SYNC_RISE_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.949	7.271	0.322
1E+12	1	6.939	7.245	0.306
1E+12	2	6.994	7.283	0.289
1E+12	3	6.836	7.143	0.307
5E+12	4	6.945	7.276	0.331
5E+12	5	6.894	7.232	0.338
5E+12	6	6.971	7.317	0.346
1E+13	7	7.075	7.294	0.219
1E+13	8	6.979	7.331	0.352
1E+13	9	6.880	7.238	0.358
	Max	7.075	7.331	0.358
	Average	6.946	7.263	0.317
	Min	6.836	7.143	0.219
	Std Dev	0.067	0.053	0.041

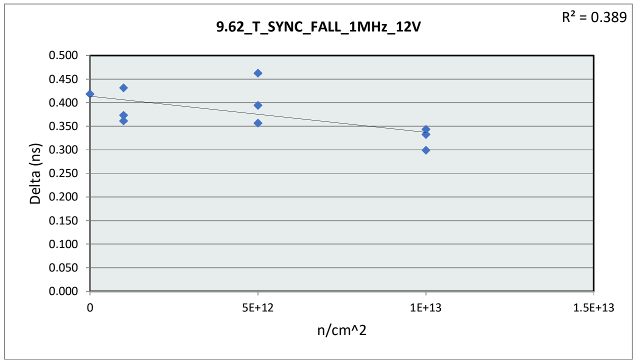


	9.61_T_SYNC_RISE_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.271	7.143	7.232	7.238
Average	7.271	7.224	7.275	7.288
Max	7.271	7.283	7.317	7.331
UL	15.000	15.000	15.000	15.000

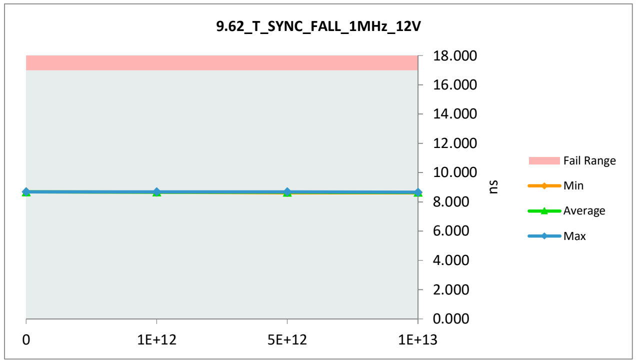


NDD Characterization Report
TPS7H5005-SEP

		9.62_T_SYNC_FALL_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.259	8.677	0.418
1E+12	1	8.286	8.647	0.361
1E+12	2	8.251	8.682	0.431
1E+12	3	8.301	8.674	0.373
5E+12	4	8.262	8.656	0.394
5E+12	5	8.269	8.625	0.356
5E+12	6	8.215	8.677	0.462
1E+13	7	8.322	8.621	0.299
1E+13	8	8.308	8.651	0.343
1E+13	9	8.292	8.624	0.332
	Max	8.322	8.682	0.462
	Average	8.276	8.653	0.377
	Min	8.215	8.621	0.299
	Std Dev	0.032	0.024	0.050

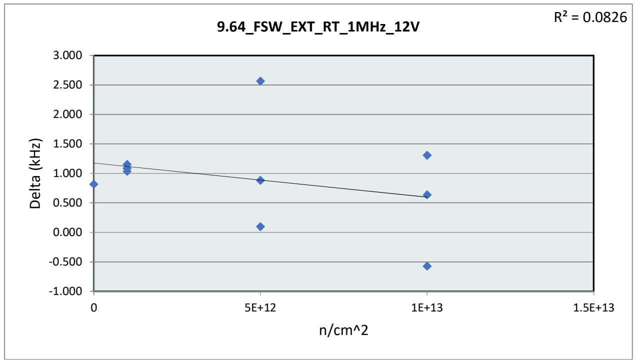


	9.62_T_SYNC_FALL_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.677	8.647	8.625	8.621
Average	8.677	8.668	8.653	8.632
Max	8.677	8.682	8.677	8.651
UL	17.000	17.000	17.000	17.000

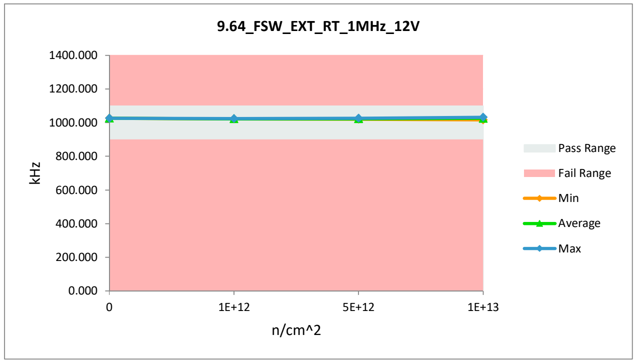


NDD Characterization Report
TPS7H5005-SEP

		9.64_FSW_EXT_RT_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	1100	1100	
	Min Limit	900	900	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1025.604	1026.418	0.814
1E+12	1	1020.594	1021.679	1.085
1E+12	2	1022.845	1023.993	1.148
1E+12	3	1021.454	1022.487	1.033
5E+12	4	1020.502	1020.595	0.093
5E+12	5	1020.426	1021.305	0.879
5E+12	6	1024.074	1026.638	2.564
1E+13	7	1024.936	1026.242	1.306
1E+13	8	1016.722	1016.145	-0.577
1E+13	9	1031.876	1032.510	0.634
	Max	1031.876	1032.510	2.564
	Average	1022.903	1023.801	0.898
	Min	1016.722	1016.145	-0.577
	Std Dev	4.094	4.448	0.814

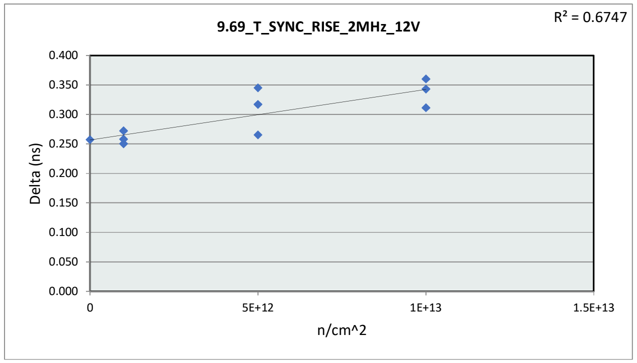


	9.64_FSW_EXT_RT_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1026.418	1021.679	1020.595	1016.145
Average	1026.418	1022.720	1022.846	1024.966
Max	1026.418	1023.993	1026.638	1032.510
UL	1100.000	1100.000	1100.000	1100.000

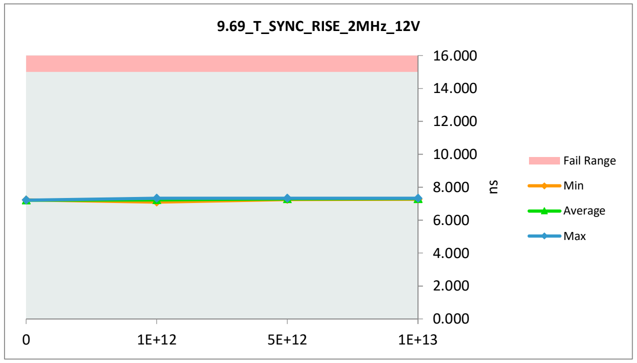


NDD Characterization Report
TPS7H5005-SEP

		9.69_T_SYNC_RISE_2MHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		15	15	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.963	7.220	0.257
1E+12	1	7.075	7.333	0.258
1E+12	2	7.031	7.281	0.250
1E+12	3	6.826	7.098	0.272
5E+12	4	6.936	7.253	0.317
5E+12	5	7.011	7.276	0.265
5E+12	6	6.988	7.333	0.345
1E+13	7	6.981	7.324	0.343
1E+13	8	7.016	7.327	0.311
1E+13	9	6.904	7.264	0.360
	Max	7.075	7.333	0.360
	Average	6.973	7.271	0.298
	Min	6.826	7.098	0.250
	Std Dev	0.071	0.072	0.042

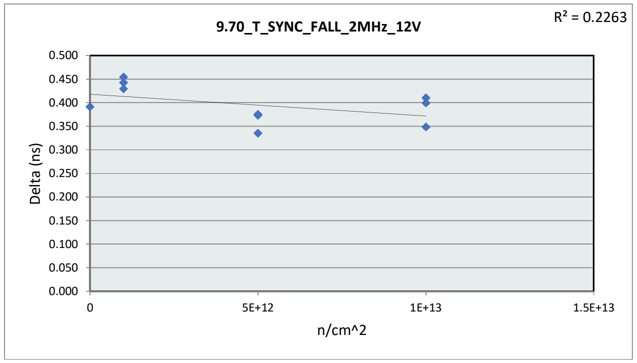


	9.69_T_SYNC_RISE_2MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.220	7.098	7.253	7.264
Average	7.220	7.237	7.287	7.305
Max	7.220	7.333	7.333	7.327
UL	15.000	15.000	15.000	15.000

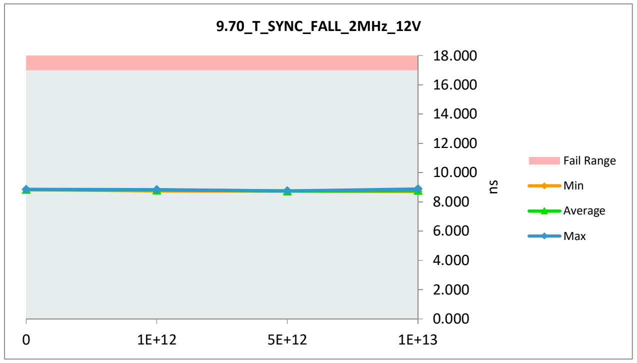


NDD Characterization Report
TPS7H5005-SEP

		9.70_T_SYNC_FALL_2MHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.456	8.847	0.391
1E+12	1	8.396	8.838	0.442
1E+12	2	8.324	8.753	0.429
1E+12	3	8.362	8.816	0.454
5E+12	4	8.398	8.733	0.335
5E+12	5	8.385	8.758	0.373
5E+12	6	8.372	8.747	0.375
1E+13	7	8.362	8.710	0.348
1E+13	8	8.320	8.719	0.399
1E+13	9	8.471	8.881	0.410
	Max	8.471	8.881	0.454
	Average	8.385	8.780	0.396
	Min	8.320	8.710	0.335
	Std Dev	0.049	0.060	0.039

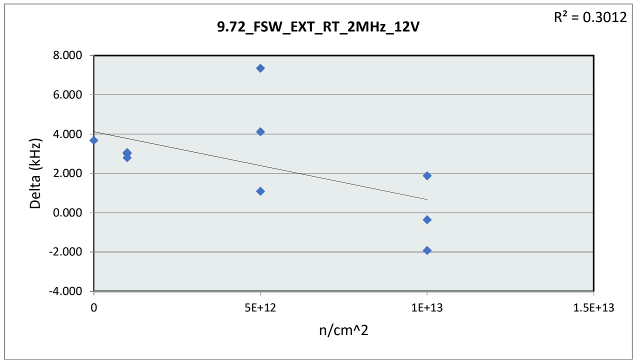


	9.70_T_SYNC_FALL_2MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.847	8.753	8.733	8.710
Average	8.847	8.802	8.746	8.770
Max	8.847	8.838	8.758	8.881
UL	17.000	17.000	17.000	17.000

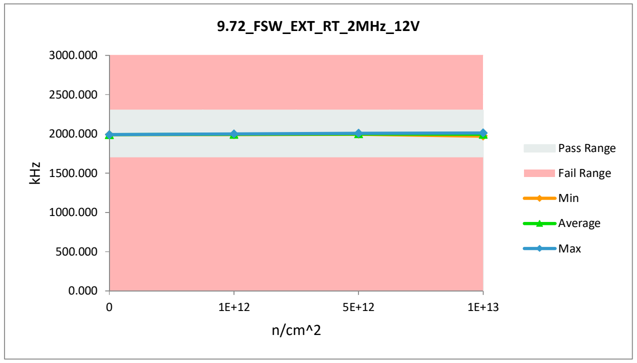


NDD Characterization Report
TPS7H5005-SEP

		9.72_FSW_EXT_RT_2MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	2300	2300	
	Min Limit	1700	1700	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1986.278	1989.950	3.672
1E+12	1	1985.796	1988.796	3.000
1E+12	2	1997.290	2000.080	2.790
1E+12	3	1990.749	1993.803	3.054
5E+12	4	1995.206	1996.290	1.084
5E+12	5	1991.538	1995.647	4.109
5E+12	6	1998.501	2005.847	7.346
1E+13	7	1995.963	1997.839	1.876
1E+13	8	1973.646	1971.718	-1.928
1E+13	9	2012.097	2011.729	-0.368
	Max	2012.097	2011.729	7.346
	Average	1992.706	1995.170	2.463
	Min	1973.646	1971.718	-1.928
	Std Dev	10.028	10.753	2.545

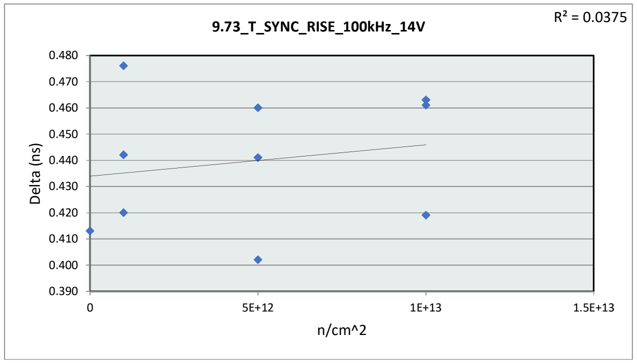


	9.72_FSW_EXT_RT_2MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	1989.950	1988.796	1995.647	1971.718
Average	1989.950	1994.226	1999.261	1993.762
Max	1989.950	2000.080	2005.847	2011.729
UL	2300.000	2300.000	2300.000	2300.000

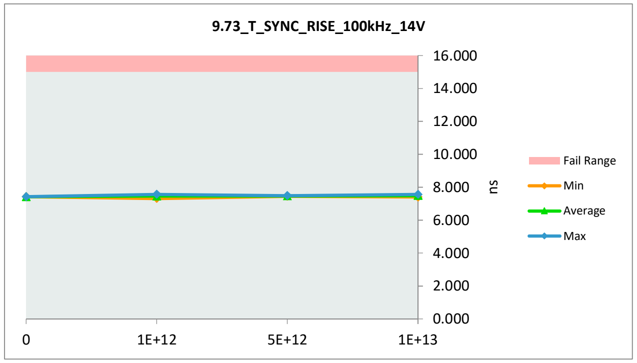


NDD Characterization Report
TPS7H5005-SEP

		9.73_T_SYNC_RISE_100kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.013	7.426	0.413
1E+12	1	7.025	7.467	0.442
1E+12	2	7.095	7.571	0.476
1E+12	3	6.897	7.317	0.420
5E+12	4	7.008	7.468	0.460
5E+12	5	7.010	7.451	0.441
5E+12	6	7.084	7.486	0.402
1E+13	7	7.045	7.508	0.463
1E+13	8	7.101	7.562	0.461
1E+13	9	6.976	7.395	0.419
	Max	7.101	7.571	0.476
	Average	7.025	7.465	0.440
	Min	6.897	7.317	0.402
	Std Dev	0.061	0.076	0.025



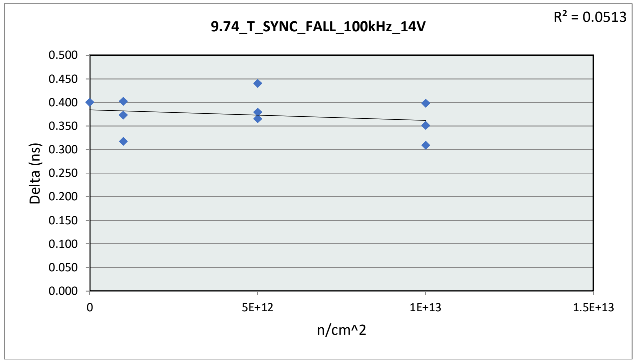
	9.73_T_SYNC_RISE_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.426	7.317	7.451	7.395
Average	7.426	7.452	7.468	7.488
Max	7.426	7.571	7.486	7.562
UL	15.000	15.000	15.000	15.000



NDD Characterization Report
TPS7H5005-SEP

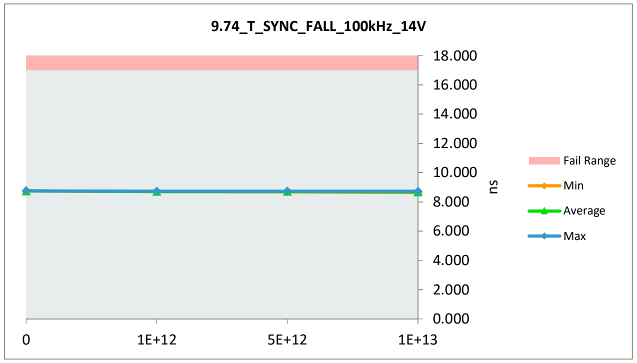
	9.74_T_SYNC_FALL_100kHz_14V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	17	17
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.343	8.743	0.400
1E+12	1	8.327	8.700	0.373
1E+12	2	8.320	8.722	0.402
1E+12	3	8.388	8.705	0.317
5E+12	4	8.322	8.701	0.379
5E+12	5	8.359	8.724	0.365
5E+12	6	8.254	8.694	0.440
1E+13	7	8.285	8.636	0.351
1E+13	8	8.362	8.671	0.309
1E+13	9	8.322	8.720	0.398
	Max	8.388	8.743	0.440
	Average	8.328	8.702	0.373
	Min	8.254	8.636	0.309
	Std Dev	0.039	0.030	0.040



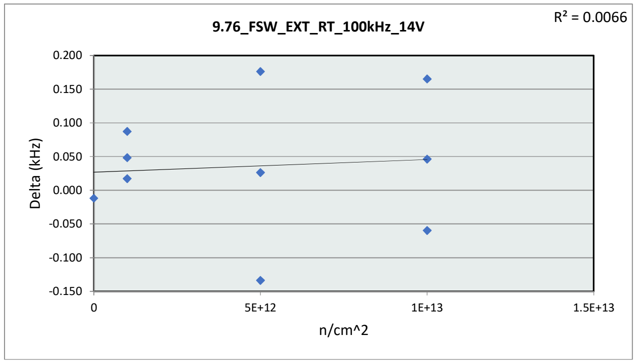
	9.74_T_SYNC_FALL_100kHz_1	
Test Site		
Tester		
Test Number		
Max Limit	17	ns
Min Limit		ns

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.743	8.700	8.694	8.636
Average	8.743	8.709	8.706	8.676
Max	8.743	8.722	8.724	8.720
UL	17.000	17.000	17.000	17.000

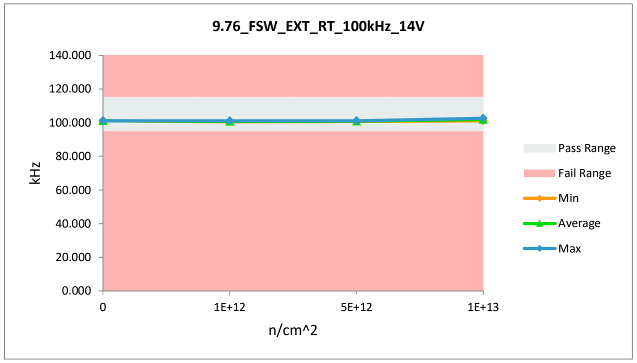


NDD Characterization Report
TPS7H5005-SEP

		9.76_FSW_EXT_RT_100kHz_14V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		115	115	
Min Limit		95	95	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	101.200	101.188	-0.012
1E+12	1	100.530	100.578	0.048
1E+12	2	100.712	100.799	0.087
1E+12	3	100.993	101.010	0.017
5E+12	4	101.076	100.942	-0.134
5E+12	5	101.139	101.165	0.026
5E+12	6	100.572	100.748	0.176
1E+13	7	101.897	102.062	0.165
1E+13	8	101.191	101.131	-0.060
1E+13	9	102.581	102.627	0.046
	Max	102.581	102.627	0.176
	Average	101.189	101.225	0.036
	Min	100.530	100.578	-0.134
	Std Dev	0.627	0.635	0.094



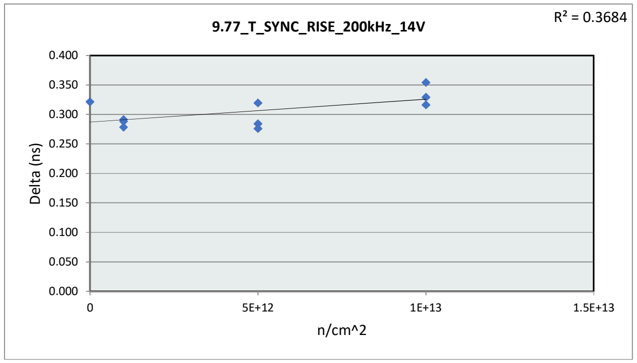
	9.76_FSW_EXT_RT_100kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	115	kHz		
Min Limit	95	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	95.000	95.000	95.000	95.000
Min	101.188	100.578	100.748	101.131
Average	101.188	100.796	100.952	101.940
Max	101.188	101.010	101.165	102.627
UL	115.000	115.000	115.000	115.000



NDD Characterization Report
TPS7H5005-SEP

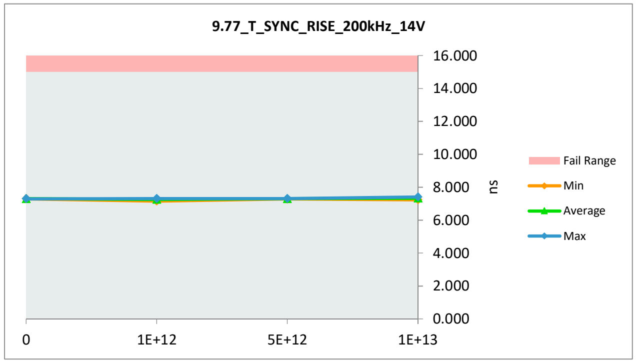
	9.77_T_SYNC_RISE_200kHz_14V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	15	15
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.978	7.299	0.321
1E+12	1	6.999	7.290	0.291
1E+12	2	7.025	7.313	0.288
1E+12	3	6.885	7.163	0.278
5E+12	4	7.002	7.321	0.319
5E+12	5	7.003	7.279	0.276
5E+12	6	7.021	7.305	0.284
1E+13	7	7.081	7.410	0.329
1E+13	8	7.043	7.359	0.316
1E+13	9	6.878	7.232	0.354
	Max	7.081	7.410	0.354
	Average	6.991	7.297	0.306
	Min	6.878	7.163	0.276
	Std Dev	0.064	0.067	0.026



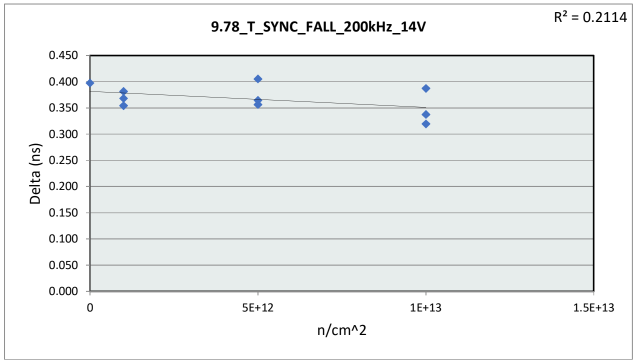
	9.77_T_SYNC_RISE_200kHz_1	
Test Site		
Tester		
Test Number		
Max Limit	15	ns
Min Limit		ns

n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.299	7.163	7.279	7.232
Average	7.299	7.255	7.302	7.334
Max	7.299	7.313	7.321	7.410
UL	15.000	15.000	15.000	15.000

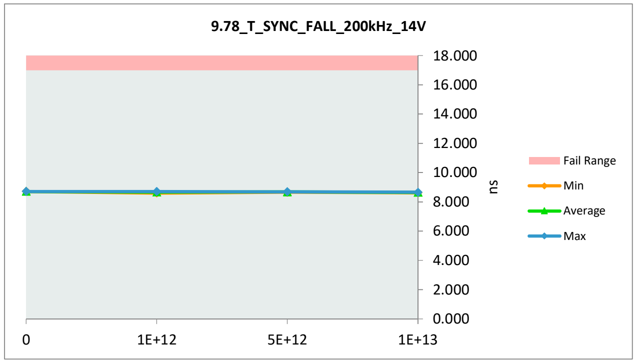


NDD Characterization Report
TPS7H5005-SEP

		9.78_T_SYNC_FALL_200kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.317	8.714	0.397
1E+12	1	8.319	8.673	0.354
1E+12	2	8.236	8.604	0.368
1E+12	3	8.323	8.704	0.381
5E+12	4	8.325	8.681	0.356
5E+12	5	8.281	8.686	0.405
5E+12	6	8.289	8.653	0.364
1E+13	7	8.306	8.625	0.319
1E+13	8	8.257	8.644	0.387
1E+13	9	8.319	8.656	0.337
	Max	8.325	8.714	0.405
	Average	8.297	8.664	0.367
	Min	8.236	8.604	0.319
	Std Dev	0.031	0.034	0.027

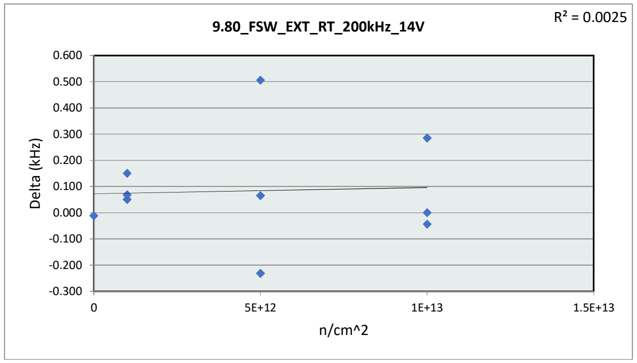


	9.78_T_SYNC_FALL_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.714	8.604	8.653	8.625
Average	8.714	8.660	8.673	8.642
Max	8.714	8.704	8.686	8.656
UL	17.000	17.000	17.000	17.000

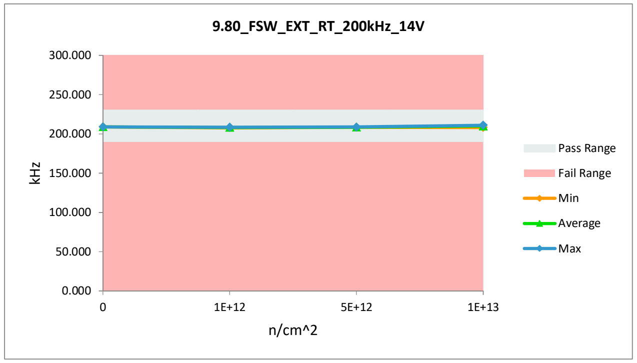


NDD Characterization Report
TPS7H5005-SEP

		9.80_FSW_EXT_RT_200kHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	230	230	
	Min Limit	190	190	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	208.851	208.839	-0.012
1E+12	1	207.832	207.882	0.050
1E+12	2	208.190	208.340	0.150
1E+12	3	208.493	208.561	0.068
5E+12	4	208.615	208.383	-0.232
5E+12	5	208.431	208.496	0.065
5E+12	6	208.203	208.708	0.505
1E+13	7	210.109	210.394	0.285
1E+13	8	208.312	208.268	-0.044
1E+13	9	211.133	211.133	0.000
	Max	211.133	211.133	0.505
	Average	208.817	208.900	0.084
	Min	207.832	207.882	-0.232
	Std Dev	1.018	1.030	0.199

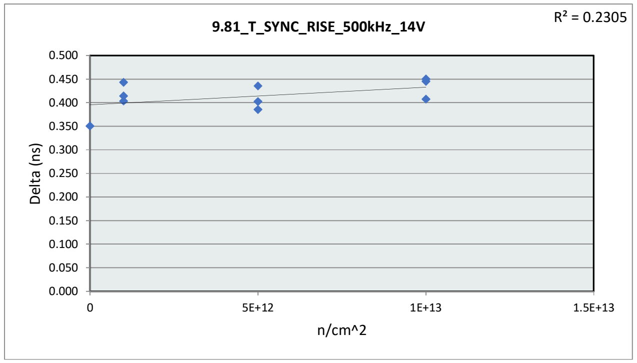


	9.80_FSW_EXT_RT_200kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	230	kHz		
Min Limit	190	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	190.000	190.000	190.000	190.000
Min	208.839	207.882	208.383	208.268
Average	208.839	208.261	208.529	209.932
Max	208.839	208.561	208.708	211.133
UL	230.000	230.000	230.000	230.000

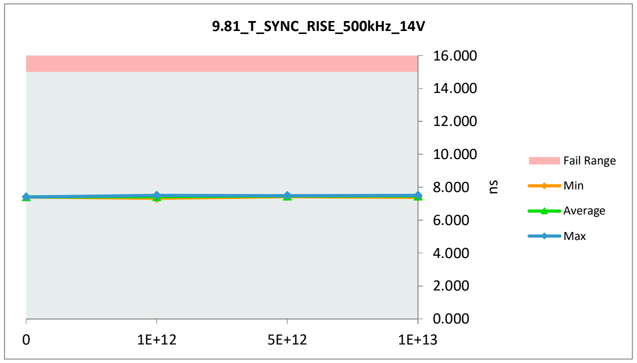


NDD Characterization Report
TPS7H5005-SEP

		9.81_T_SYNC_RISE_500kHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		15	15	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.057	7.407	0.350
1E+12	1	7.015	7.429	0.414
1E+12	2	7.060	7.503	0.443
1E+12	3	6.918	7.321	0.403
5E+12	4	7.051	7.436	0.385
5E+12	5	7.032	7.434	0.402
5E+12	6	7.054	7.489	0.435
1E+13	7	7.089	7.496	0.407
1E+13	8	7.053	7.498	0.445
1E+13	9	6.940	7.390	0.450
	Max	7.089	7.503	0.450
	Average	7.027	7.440	0.413
	Min	6.918	7.321	0.350
	Std Dev	0.055	0.058	0.031

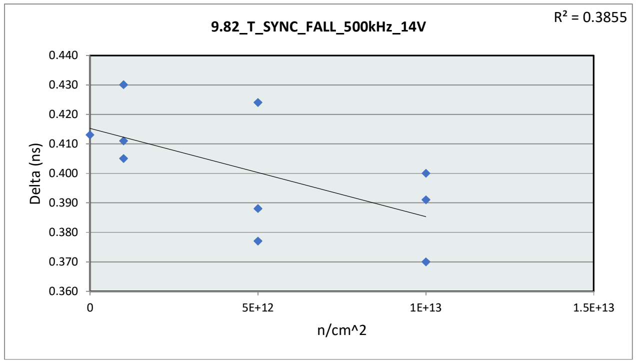


	9.81_T_SYNC_RISE_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.407	7.321	7.434	7.390
Average	7.407	7.418	7.453	7.461
Max	7.407	7.503	7.489	7.498
UL	15.000	15.000	15.000	15.000

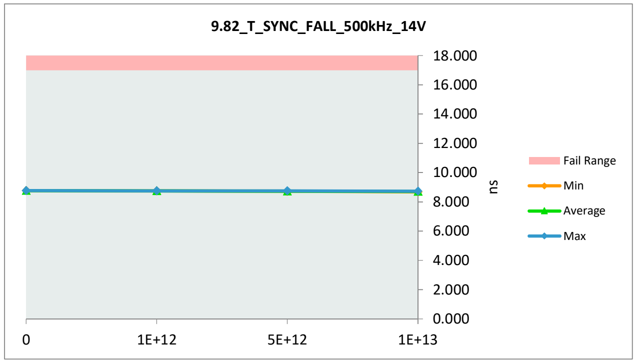


NDD Characterization Report
TPS7H5005-SEP

		9.82_T_SYNC_FALL_500kHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.362	8.775	0.413
1E+12	1	8.350	8.755	0.405
1E+12	2	8.318	8.748	0.430
1E+12	3	8.344	8.755	0.411
5E+12	4	8.348	8.736	0.388
5E+12	5	8.333	8.710	0.377
5E+12	6	8.326	8.750	0.424
1E+13	7	8.278	8.678	0.400
1E+13	8	8.317	8.708	0.391
1E+13	9	8.363	8.733	0.370
	Max	8.363	8.775	0.430
	Average	8.334	8.735	0.401
	Min	8.278	8.678	0.370
	Std Dev	0.026	0.029	0.020

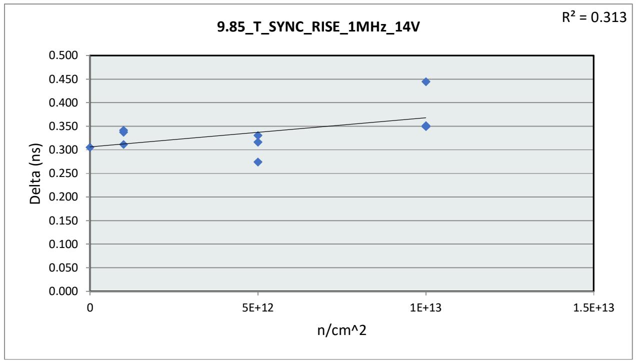


	9.82_T_SYNC_FALL_500kHz_1			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.775	8.748	8.710	8.678
Average	8.775	8.753	8.732	8.706
Max	8.775	8.755	8.750	8.733
UL	17.000	17.000	17.000	17.000

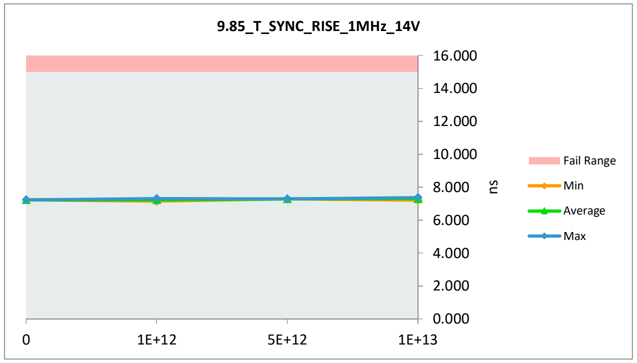


NDD Characterization Report
TPS7H5005-SEP

		9.85_T_SYNC_RISE_1MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	15	15	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.928	7.233	0.305
1E+12	1	6.924	7.261	0.337
1E+12	2	6.998	7.309	0.311
1E+12	3	6.805	7.146	0.341
5E+12	4	6.971	7.287	0.316
5E+12	5	6.955	7.285	0.330
5E+12	6	7.024	7.298	0.274
1E+13	7	6.930	7.374	0.444
1E+13	8	6.970	7.319	0.349
1E+13	9	6.864	7.215	0.351
	Max	7.024	7.374	0.444
	Average	6.937	7.273	0.336
	Min	6.805	7.146	0.274
	Std Dev	0.064	0.063	0.045

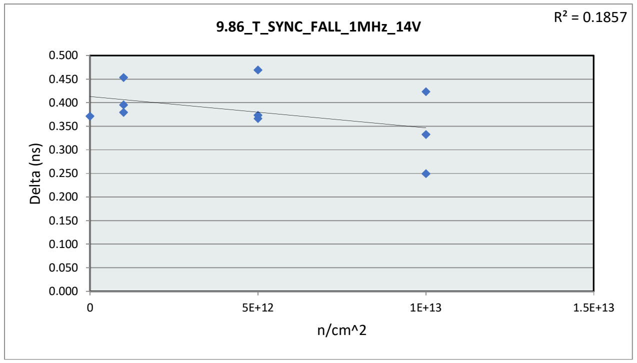


9.85_T_SYNC_RISE_1MHz_14V				
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.233	7.146	7.285	7.215
Average	7.233	7.239	7.290	7.303
Max	7.233	7.309	7.298	7.374
UL	15.000	15.000	15.000	15.000

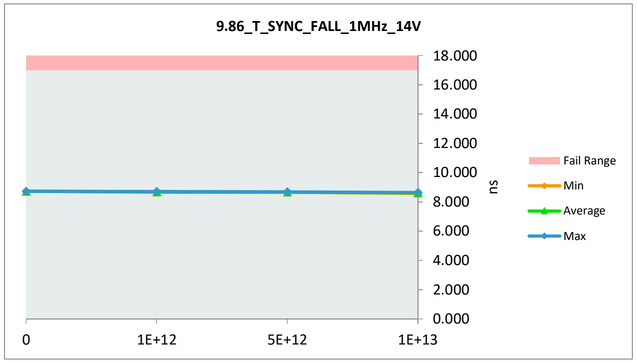


NDD Characterization Report
TPS7H5005-SEP

		9.86_T_SYNC_FALL_1MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.345	8.716	0.371
1E+12	1	8.286	8.665	0.379
1E+12	2	8.256	8.651	0.395
1E+12	3	8.249	8.702	0.453
5E+12	4	8.290	8.656	0.366
5E+12	5	8.275	8.648	0.373
5E+12	6	8.209	8.678	0.469
1E+13	7	8.316	8.565	0.249
1E+13	8	8.213	8.636	0.423
1E+13	9	8.305	8.637	0.332
	Max	8.345	8.716	0.469
	Average	8.274	8.655	0.381
	Min	8.209	8.565	0.249
	Std Dev	0.044	0.041	0.062

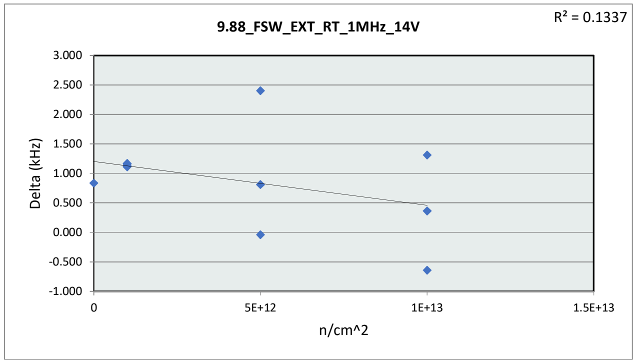


	9.86_T_SYNC_FALL_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.716	8.651	8.648	8.565
Average	8.716	8.673	8.661	8.613
Max	8.716	8.702	8.678	8.637
UL	17.000	17.000	17.000	17.000

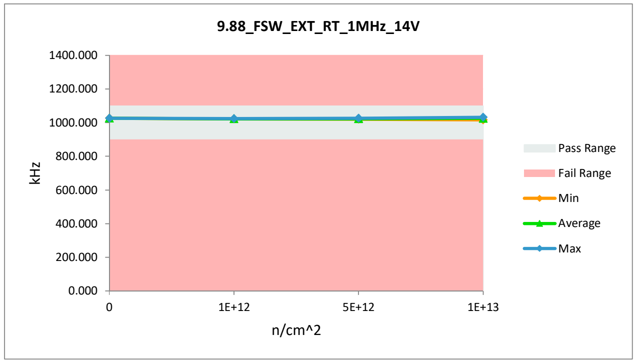


NDD Characterization Report
TPS7H5005-SEP

		9.88_FSW_EXT_RT_1MHz_14V		
Test Site				
Tester				
Test Number				
Unit		kHz	kHz	
Max Limit		1100	1100	
Min Limit		900	900	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1025.476	1026.308	0.832
1E+12	1	1020.542	1021.683	1.141
1E+12	2	1022.806	1023.971	1.165
1E+12	3	1021.340	1022.452	1.112
5E+12	4	1020.470	1020.429	-0.041
5E+12	5	1020.314	1021.122	0.808
5E+12	6	1024.073	1026.472	2.399
1E+13	7	1024.862	1026.172	1.310
1E+13	8	1016.713	1016.069	-0.644
1E+13	9	1031.939	1032.302	0.363
	Max	1031.939	1032.302	2.399
	Average	1022.854	1023.698	0.845
	Min	1016.713	1016.069	-0.644
	Std Dev	4.115	4.421	0.825

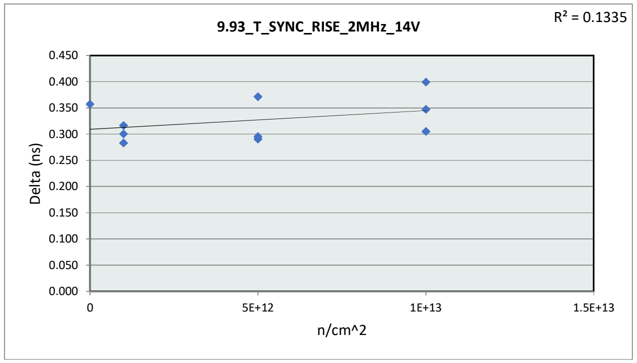


	9.88_FSW_EXT_RT_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	1100	kHz		
Min Limit	900	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	900.000	900.000	900.000	900.000
Min	1026.308	1021.683	1020.429	1016.069
Average	1026.308	1022.702	1022.674	1024.848
Max	1026.308	1023.971	1026.472	1032.302
UL	1100.000	1100.000	1100.000	1100.000

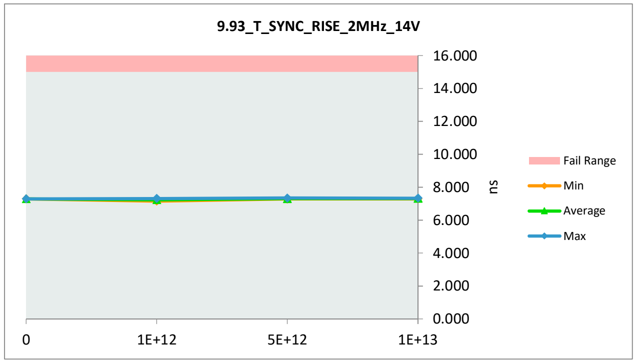


NDD Characterization Report
TPS7H5005-SEP

		9.93_T_SYNC_RISE_2MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		15	15	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.936	7.293	0.357
1E+12	1	6.912	7.212	0.300
1E+12	2	7.039	7.322	0.283
1E+12	3	6.841	7.157	0.316
5E+12	4	6.991	7.281	0.290
5E+12	5	6.986	7.281	0.295
5E+12	6	6.966	7.337	0.371
1E+13	7	6.991	7.338	0.347
1E+13	8	7.010	7.315	0.305
1E+13	9	6.892	7.291	0.399
	Max	7.039	7.338	0.399
	Average	6.956	7.283	0.326
	Min	6.841	7.157	0.283
	Std Dev	0.060	0.057	0.040

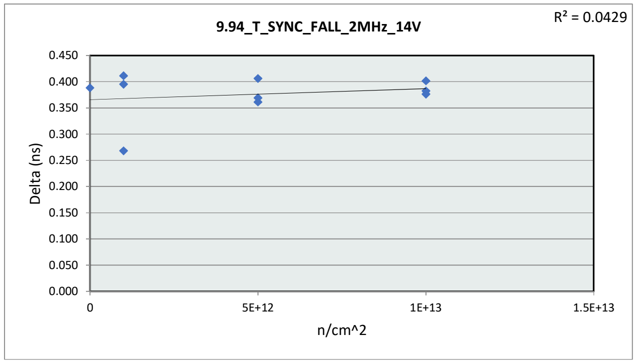


	9.93_T_SYNC_RISE_2MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	15	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.293	7.157	7.281	7.291
Average	7.293	7.230	7.300	7.315
Max	7.293	7.322	7.337	7.338
UL	15.000	15.000	15.000	15.000

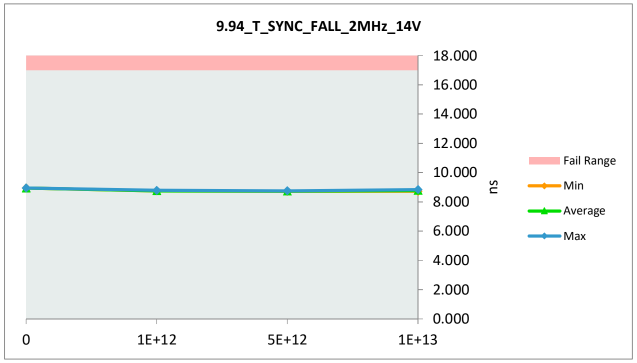


NDD Characterization Report
TPS7H5005-SEP

		9.94_T_SYNC_FALL_2MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.558	8.946	0.388
1E+12	1	8.489	8.757	0.268
1E+12	2	8.366	8.777	0.411
1E+12	3	8.358	8.753	0.395
5E+12	4	8.362	8.723	0.361
5E+12	5	8.346	8.752	0.406
5E+12	6	8.349	8.718	0.369
1E+13	7	8.342	8.718	0.376
1E+13	8	8.355	8.756	0.401
1E+13	9	8.457	8.839	0.382
	Max	8.558	8.946	0.411
	Average	8.398	8.774	0.376
	Min	8.342	8.718	0.268
	Std Dev	0.076	0.070	0.041

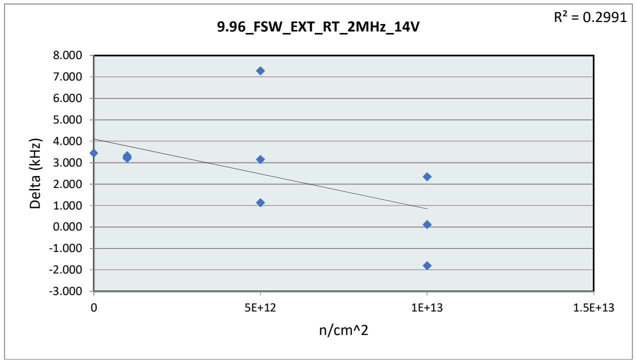


	9.94_T_SYNC_FALL_2MHz_14			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	8.946	8.753	8.718	8.718
Average	8.946	8.762	8.731	8.771
Max	8.946	8.777	8.752	8.839
UL	17.000	17.000	17.000	17.000

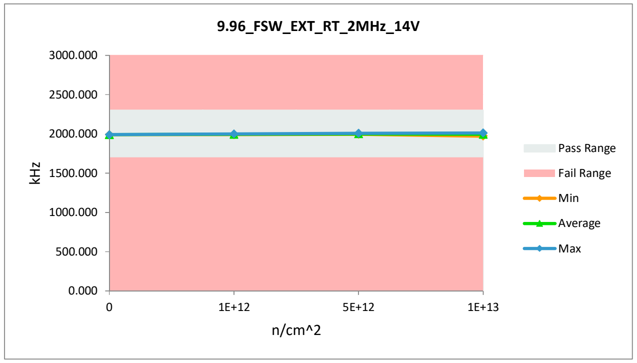


NDD Characterization Report
TPS7H5005-SEP

		9.96_FSW_EXT_RT_2MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	kHz	kHz	
	Max Limit	2300	2300	
	Min Limit	1700	1700	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1985.985	1989.420	3.435
1E+12	1	1985.412	1988.727	3.315
1E+12	2	1996.841	2000.079	3.238
1E+12	3	1990.506	1993.708	3.202
5E+12	4	1995.319	1996.451	1.132
5E+12	5	1991.453	1994.593	3.140
5E+12	6	1998.221	2005.504	7.283
1E+13	7	1995.578	1997.914	2.336
1E+13	8	1973.302	1971.497	-1.805
1E+13	9	2011.371	2011.482	0.111
	Max	2011.371	2011.482	7.283
	Average	1992.399	1994.938	2.539
	Min	1973.302	1971.497	-1.805
	Std Dev	9.952	10.765	2.403

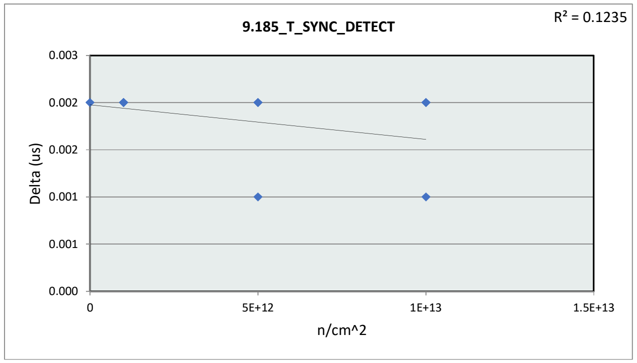


	9.96_FSW_EXT_RT_2MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	2300	kHz		
Min Limit	1700	kHz		
n/cm^2	0	1E+12	5E+12	1E+13
LL	1700.000	1700.000	1700.000	1700.000
Min	1989.420	1988.727	1994.593	1971.497
Average	1989.420	1994.171	1998.849	1993.631
Max	1989.420	2000.079	2005.504	2011.482
UL	2300.000	2300.000	2300.000	2300.000

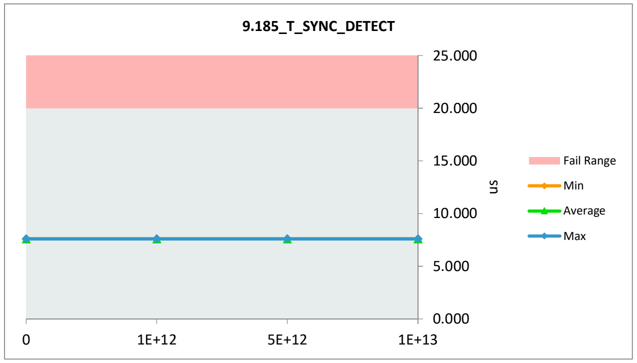


NDD Characterization Report
TPS7H5005-SEP

		9.185_T_SYNC_DETECT		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	20	20	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.587	7.589	0.002
1E+12	1	7.587	7.589	0.002
1E+12	2	7.587	7.589	0.002
1E+12	3	7.585	7.587	0.002
5E+12	4	7.587	7.589	0.002
5E+12	5	7.587	7.589	0.002
5E+12	6	7.587	7.588	0.001
1E+13	7	7.587	7.588	0.001
1E+13	8	7.588	7.590	0.002
1E+13	9	7.585	7.587	0.002
	Max	7.588	7.590	0.002
	Average	7.587	7.589	0.002
	Min	7.585	7.587	0.001
	Std Dev	0.001	0.001	0.000

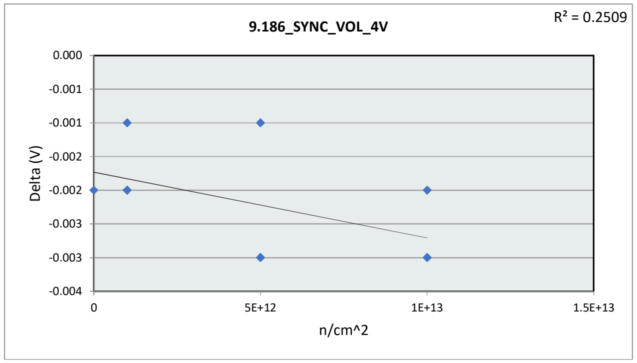


	9.185_T_SYNC_DETECT			
Test Site				
Tester				
Test Number				
Max Limit	20	us		
Min Limit		us		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	7.589	7.587	7.588	7.587
Average	7.589	7.588	7.589	7.588
Max	7.589	7.589	7.589	7.590
UL	20.000	20.000	20.000	20.000

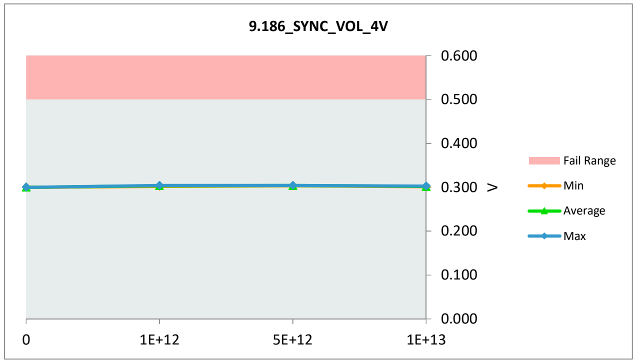


NDD Characterization Report
TPS7H5005-SEP

		9.186_SYNC_VOL_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.5	0.5	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.302	0.300	-0.002
1E+12	1	0.305	0.304	-0.001
1E+12	2	0.306	0.304	-0.002
1E+12	3	0.304	0.302	-0.002
5E+12	4	0.306	0.303	-0.003
5E+12	5	0.307	0.304	-0.003
5E+12	6	0.305	0.304	-0.001
1E+13	7	0.304	0.301	-0.003
1E+13	8	0.305	0.303	-0.002
1E+13	9	0.304	0.301	-0.003
	Max	0.307	0.304	-0.001
	Average	0.305	0.303	-0.002
	Min	0.302	0.300	-0.003
	Std Dev	0.001	0.002	0.001

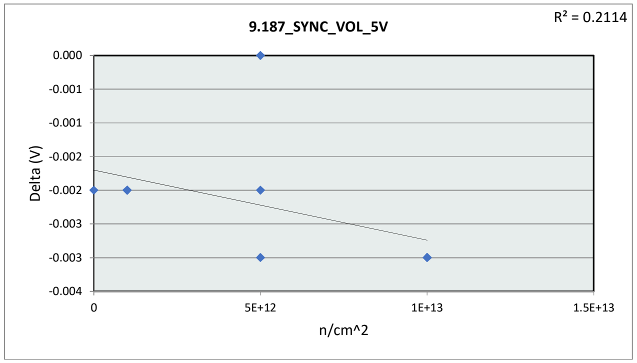


	9.186_SYNC_VOL_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.300	0.302	0.303	0.301
Average	0.300	0.303	0.304	0.302
Max	0.300	0.304	0.304	0.303
UL	0.500	0.500	0.500	0.500

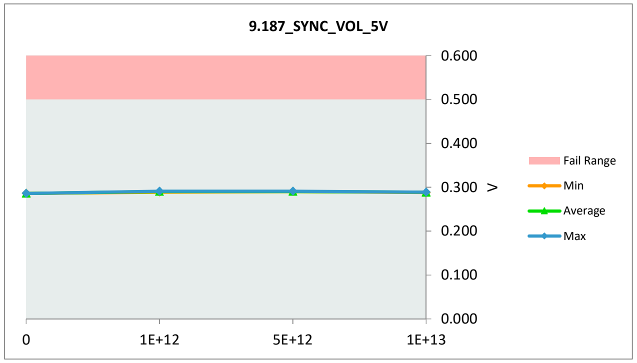


NDD Characterization Report
TPS7H5005-SEP

		9.187_SYNC_VOL_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.5	0.5	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.288	0.286	-0.002
1E+12	1	0.292	0.290	-0.002
1E+12	2	0.293	0.291	-0.002
1E+12	3	0.291	0.289	-0.002
5E+12	4	0.292	0.290	-0.002
5E+12	5	0.293	0.290	-0.003
5E+12	6	0.291	0.291	0.000
1E+13	7	0.291	0.288	-0.003
1E+13	8	0.292	0.289	-0.003
1E+13	9	0.291	0.288	-0.003
	Max	0.293	0.291	0.000
	Average	0.291	0.289	-0.002
	Min	0.288	0.286	-0.003
	Std Dev	0.001	0.002	0.001

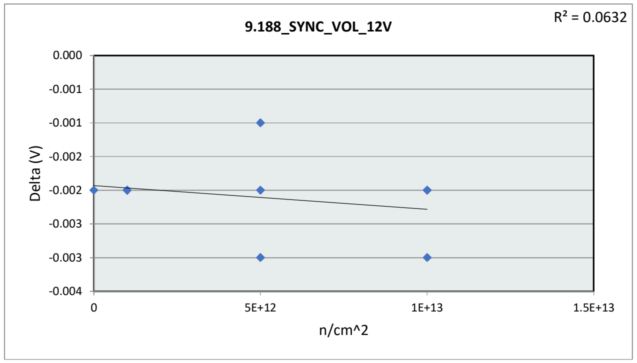


	9.187_SYNC_VOL_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.286	0.289	0.290	0.288
Average	0.286	0.290	0.290	0.288
Max	0.286	0.291	0.291	0.289
UL	0.500	0.500	0.500	0.500

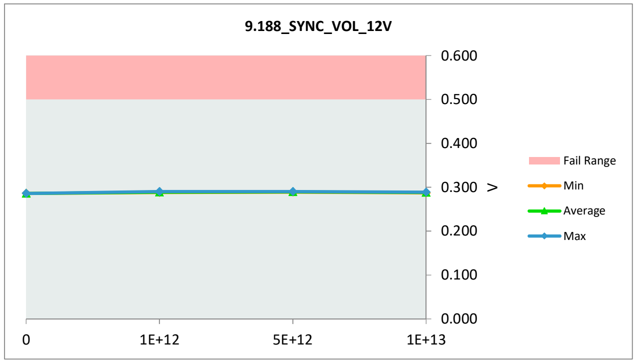


NDD Characterization Report
TPS7H5005-SEP

		9.188_SYNC_VOL_12V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.5	0.5	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.288	0.286	-0.002
1E+12	1	0.291	0.289	-0.002
1E+12	2	0.292	0.290	-0.002
1E+12	3	0.290	0.288	-0.002
5E+12	4	0.292	0.289	-0.003
5E+12	5	0.292	0.290	-0.002
5E+12	6	0.291	0.290	-0.001
1E+13	7	0.290	0.288	-0.002
1E+13	8	0.291	0.289	-0.002
1E+13	9	0.290	0.287	-0.003
	Max	0.292	0.290	-0.001
	Average	0.291	0.289	-0.002
	Min	0.288	0.286	-0.003
	Std Dev	0.001	0.001	0.001

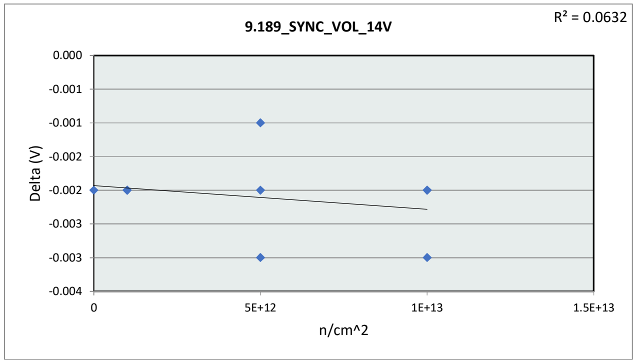


	9.188_SYNC_VOL_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.286	0.288	0.289	0.287
Average	0.286	0.289	0.290	0.288
Max	0.286	0.290	0.290	0.289
UL	0.500	0.500	0.500	0.500

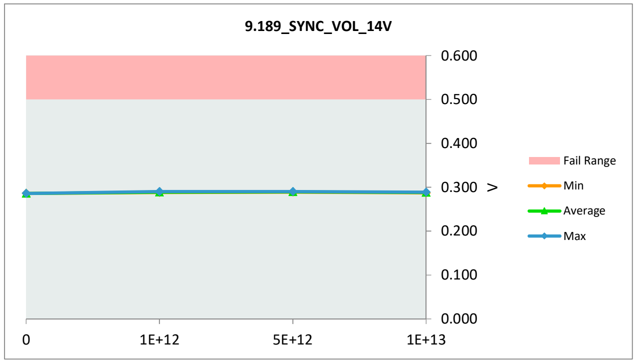


NDD Characterization Report
TPS7H5005-SEP

		9.189_SYNC_VOL_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.5	0.5	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.288	0.286	-0.002
1E+12	1	0.291	0.289	-0.002
1E+12	2	0.292	0.290	-0.002
1E+12	3	0.290	0.288	-0.002
5E+12	4	0.292	0.289	-0.003
5E+12	5	0.292	0.290	-0.002
5E+12	6	0.291	0.290	-0.001
1E+13	7	0.290	0.288	-0.002
1E+13	8	0.291	0.289	-0.002
1E+13	9	0.290	0.287	-0.003
	Max	0.292	0.290	-0.001
	Average	0.291	0.289	-0.002
	Min	0.288	0.286	-0.003
	Std Dev	0.001	0.001	0.001

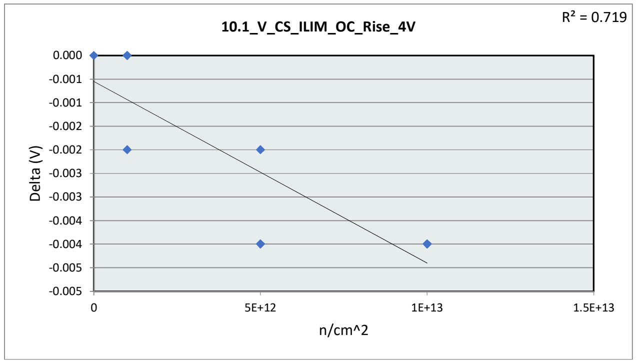


	9.189_SYNC_VOL_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.5	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	0.286	0.288	0.289	0.287
Average	0.286	0.289	0.290	0.288
Max	0.286	0.290	0.290	0.289
UL	0.500	0.500	0.500	0.500

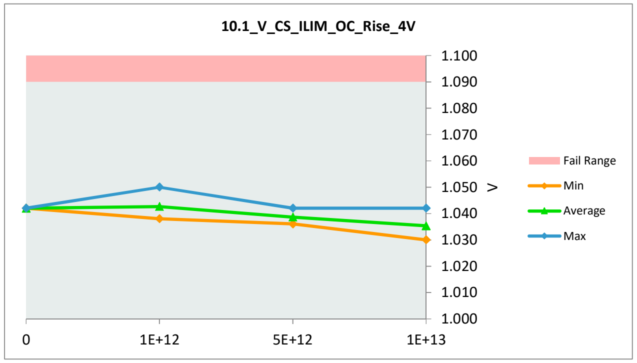


NDD Characterization Report
TPS7H5005-SEP

		10.1_V_CS_ILIM_OC_Rise_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.09	1.09	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.042	1.042	0.000
1E+12	1	1.050	1.050	0.000
1E+12	2	1.040	1.038	-0.002
1E+12	3	1.040	1.040	0.000
5E+12	4	1.042	1.038	-0.004
5E+12	5	1.046	1.042	-0.004
5E+12	6	1.038	1.036	-0.002
1E+13	7	1.046	1.042	-0.004
1E+13	8	1.038	1.034	-0.004
1E+13	9	1.034	1.030	-0.004
	Max	1.050	1.050	0.000
	Average	1.042	1.039	-0.002
	Min	1.034	1.030	-0.004
	Std Dev	0.005	0.005	0.002

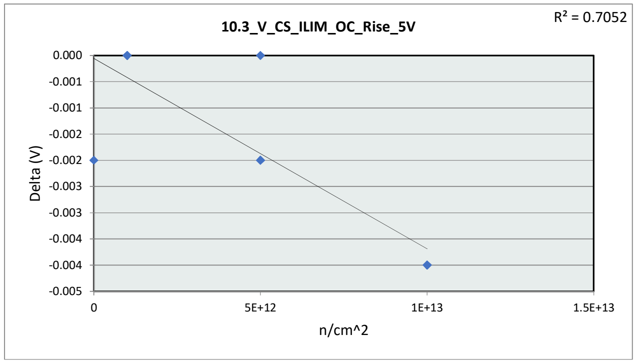


	10.1_V_CS_ILIM_OC_Rise_4V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.042	1.038	1.036	1.030
Average	1.042	1.043	1.039	1.035
Max	1.042	1.050	1.042	1.042
UL	1.090	1.090	1.090	1.090

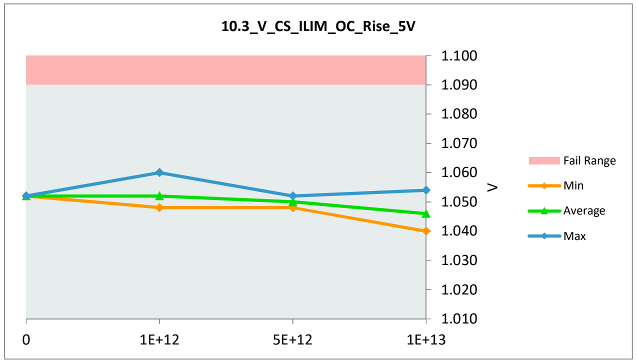


NDD Characterization Report
TPS7H5005-SEP

		10.3_V_CS_ILIM_OC_Rise_5V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.09	1.09	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.054	1.052	-0.002
1E+12	1	1.060	1.060	0.000
1E+12	2	1.048	1.048	0.000
1E+12	3	1.048	1.048	0.000
5E+12	4	1.052	1.050	-0.002
5E+12	5	1.054	1.052	-0.002
5E+12	6	1.048	1.048	0.000
1E+13	7	1.058	1.054	-0.004
1E+13	8	1.048	1.044	-0.004
1E+13	9	1.044	1.040	-0.004
	Max	1.060	1.060	0.000
	Average	1.051	1.050	-0.002
	Min	1.044	1.040	-0.004
	Std Dev	0.005	0.005	0.002

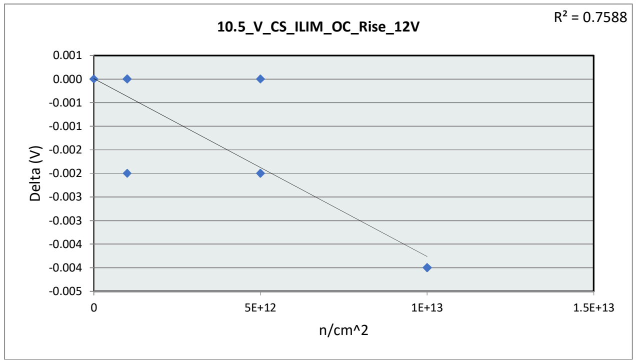


	10.3_V_CS_ILIM_OC_Rise_5V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.052	1.048	1.048	1.040
Average	1.052	1.052	1.050	1.046
Max	1.052	1.060	1.052	1.054
UL	1.090	1.090	1.090	1.090

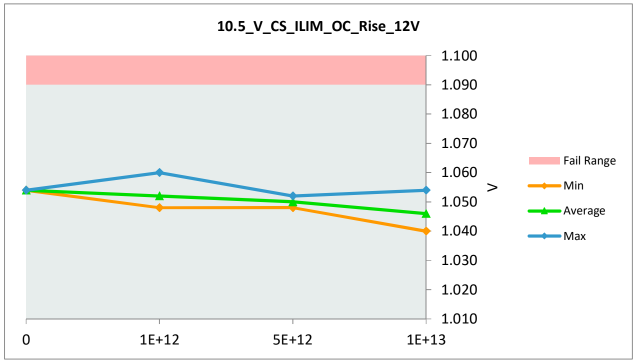


NDD Characterization Report
TPS7H5005-SEP

		10.5_V_CS_ILIM_OC_Rise_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	1.09	1.09	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.054	1.054	0.000
1E+12	1	1.062	1.060	-0.002
1E+12	2	1.048	1.048	0.000
1E+12	3	1.048	1.048	0.000
5E+12	4	1.052	1.050	-0.002
5E+12	5	1.054	1.052	-0.002
5E+12	6	1.048	1.048	0.000
1E+13	7	1.058	1.054	-0.004
1E+13	8	1.048	1.044	-0.004
1E+13	9	1.044	1.040	-0.004
	Max	1.062	1.060	0.000
	Average	1.052	1.050	-0.002
	Min	1.044	1.040	-0.004
	Std Dev	0.005	0.006	0.002

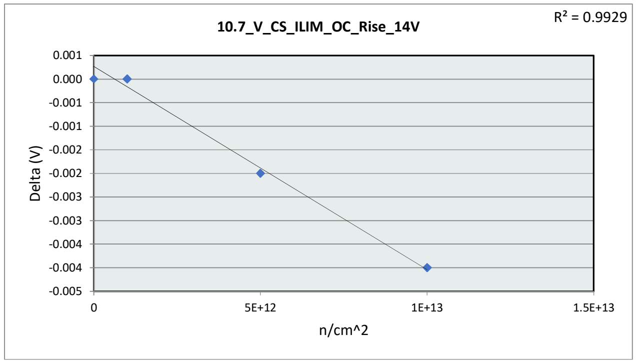


	10.5_V_CS_ILIM_OC_Rise_12V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.054	1.048	1.048	1.040
Average	1.054	1.052	1.050	1.046
Max	1.054	1.060	1.052	1.054
UL	1.090	1.090	1.090	1.090

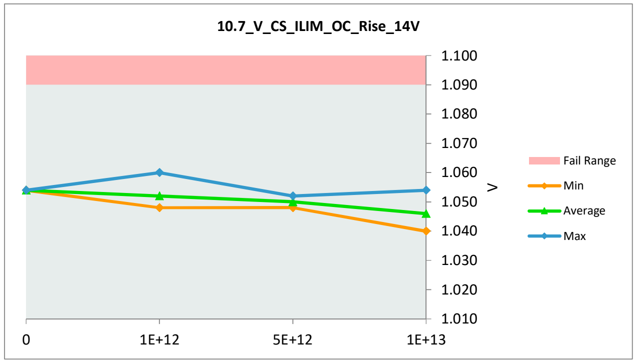


NDD Characterization Report
TPS7H5005-SEP

		10.7_V_CS_ILIM_OC_Rise_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		1.09	1.09	
Min Limit				
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	1.054	1.054	0.000
1E+12	1	1.060	1.060	0.000
1E+12	2	1.048	1.048	0.000
1E+12	3	1.048	1.048	0.000
5E+12	4	1.052	1.050	-0.002
5E+12	5	1.054	1.052	-0.002
5E+12	6	1.050	1.048	-0.002
1E+13	7	1.058	1.054	-0.004
1E+13	8	1.048	1.044	-0.004
1E+13	9	1.044	1.040	-0.004
	Max	1.060	1.060	0.000
	Average	1.052	1.050	-0.002
	Min	1.044	1.040	-0.004
	Std Dev	0.005	0.006	0.002

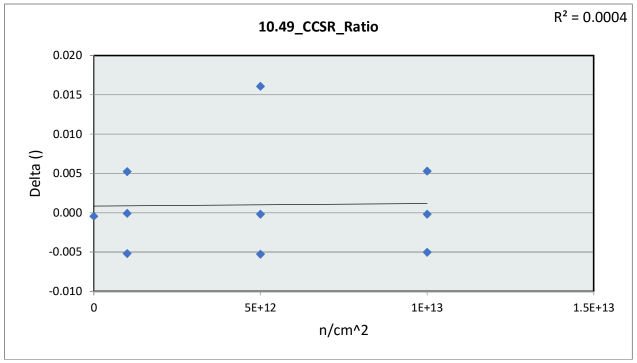


	10.7_V_CS_ILIM_OC_Rise_14V			
Test Site				
Tester				
Test Number				
Max Limit	1.09	V		
Min Limit		V		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	1.054	1.048	1.048	1.040
Average	1.054	1.052	1.050	1.046
Max	1.054	1.060	1.052	1.054
UL	1.090	1.090	1.090	1.090

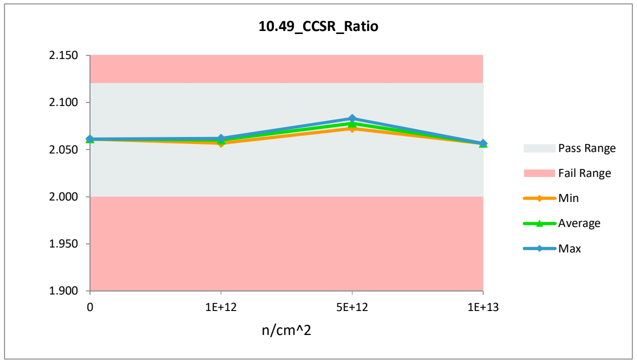


NDD Characterization Report
TPS7H5005-SEP

		10.49_CCSR_Ratio		
	Test Site			
	Tester			
	Test Number			
	Unit			
	Max Limit	2.12	2.12	
	Min Limit	2	2	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	2.062	2.061	0.000
1E+12	1	2.062	2.057	-0.005
1E+12	2	2.062	2.061	0.000
1E+12	3	2.057	2.062	0.005
5E+12	4	2.083	2.078	-0.005
5E+12	5	2.067	2.083	0.016
5E+12	6	2.073	2.072	0.000
1E+13	7	2.051	2.056	0.005
1E+13	8	2.057	2.056	0.000
1E+13	9	2.062	2.056	-0.005
	Max	2.083	2.083	0.016
	Average	2.063	2.064	0.001
	Min	2.051	2.056	-0.005
	Std Dev	0.009	0.010	0.007

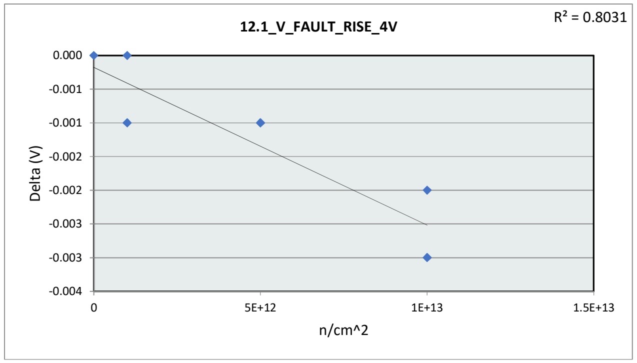


	10.49_CCSR_Ratio			
Test Site				
Tester				
Test Number				
Max Limit	2.12			
Min Limit	2			
n/cm^2	0	1E+12	5E+12	1E+13
LL	2.000	2.000	2.000	2.000
Min	2.061	2.057	2.072	2.056
Average	2.061	2.060	2.078	2.056
Max	2.061	2.062	2.083	2.056
UL	2.120	2.120	2.120	2.120

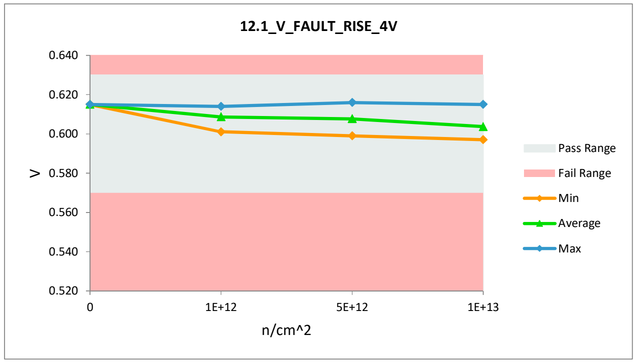


NDD Characterization Report
TPS7H5005-SEP

		12.1_V_FAULT_RISE_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.57	0.57	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.615	0.615	0.000
1E+12	1	0.611	0.611	0.000
1E+12	2	0.602	0.601	-0.001
1E+12	3	0.615	0.614	-0.001
5E+12	4	0.609	0.608	-0.001
5E+12	5	0.617	0.616	-0.001
5E+12	6	0.600	0.599	-0.001
1E+13	7	0.618	0.615	-0.003
1E+13	8	0.600	0.597	-0.003
1E+13	9	0.601	0.599	-0.002
	Max	0.618	0.616	0.000
	Average	0.609	0.607	-0.001
	Min	0.600	0.597	-0.003
	Std Dev	0.007	0.008	0.001

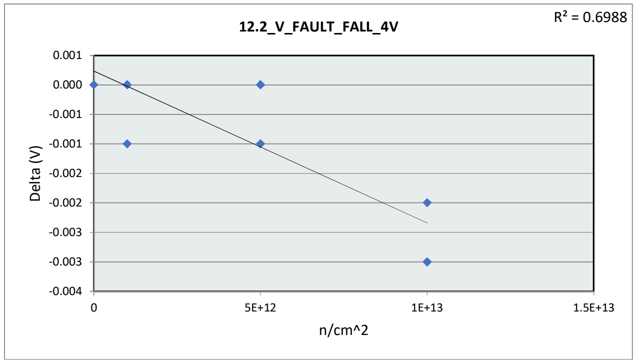


	12.1_V_FAULT_RISE_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.615	0.601	0.599	0.597
Average	0.615	0.609	0.608	0.604
Max	0.615	0.614	0.616	0.615
UL	0.630	0.630	0.630	0.630

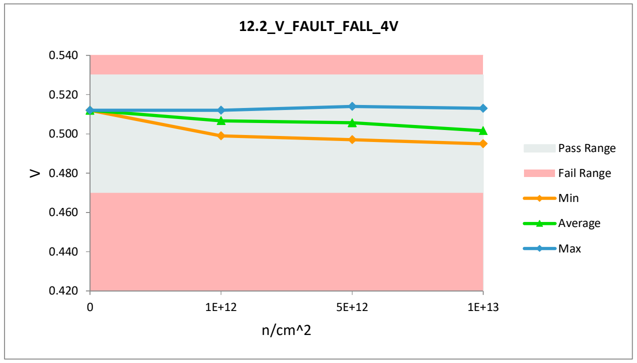


NDD Characterization Report
TPS7H5005-SEP

		12.2_V_FAULT_FALL_4V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.53	0.53	
Min Limit		0.47	0.47	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.512	0.512	0.000
1E+12	1	0.509	0.509	0.000
1E+12	2	0.499	0.499	0.000
1E+12	3	0.513	0.512	-0.001
5E+12	4	0.506	0.506	0.000
5E+12	5	0.515	0.514	-0.001
5E+12	6	0.497	0.497	0.000
1E+13	7	0.516	0.513	-0.003
1E+13	8	0.498	0.495	-0.003
1E+13	9	0.499	0.497	-0.002
	Max	0.516	0.514	0.000
	Average	0.506	0.505	-0.001
	Min	0.497	0.495	-0.003
	Std Dev	0.008	0.008	0.001

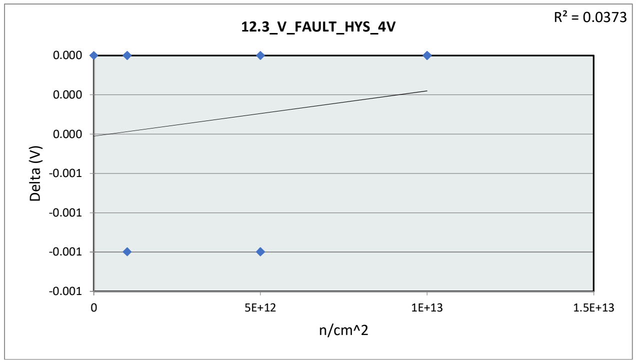


	12.2_V_FAULT_FALL_4V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.512	0.499	0.497	0.495
Average	0.512	0.507	0.506	0.502
Max	0.512	0.512	0.514	0.513
UL	0.530	0.530	0.530	0.530

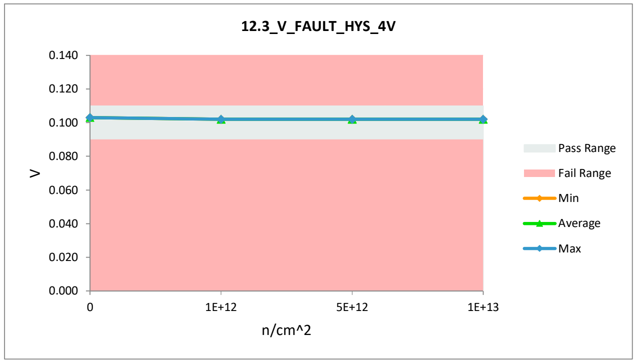


NDD Characterization Report
TPS7H5005-SEP

		12.3_V_FAULT_HYS_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.11	0.11	
	Min Limit	0.09	0.09	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.103	0.103	0.000
1E+12	1	0.102	0.102	0.000
1E+12	2	0.103	0.102	-0.001
1E+12	3	0.102	0.102	0.000
5E+12	4	0.103	0.102	-0.001
5E+12	5	0.102	0.102	0.000
5E+12	6	0.103	0.102	-0.001
1E+13	7	0.102	0.102	0.000
1E+13	8	0.102	0.102	0.000
1E+13	9	0.102	0.102	0.000
	Max	0.103	0.103	0.000
	Average	0.102	0.102	0.000
	Min	0.102	0.102	-0.001
	Std Dev	0.001	0.000	0.000

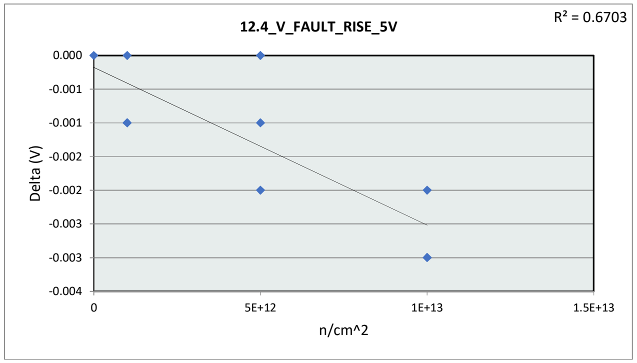


12.3_V_FAULT_HYS_4V				
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.103	0.102	0.102	0.102
Average	0.103	0.102	0.102	0.102
Max	0.103	0.102	0.102	0.102
UL	0.110	0.110	0.110	0.110

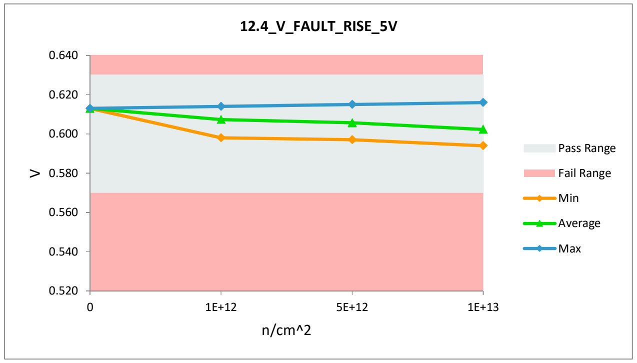


NDD Characterization Report
TPS7H5005-SEP

		12.4_V_FAULT_RISE_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.57	0.57	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.613	0.613	0.000
1E+12	1	0.610	0.610	0.000
1E+12	2	0.599	0.598	-0.001
1E+12	3	0.615	0.614	-0.001
5E+12	4	0.606	0.605	-0.001
5E+12	5	0.617	0.615	-0.002
5E+12	6	0.597	0.597	0.000
1E+13	7	0.619	0.616	-0.003
1E+13	8	0.597	0.594	-0.003
1E+13	9	0.599	0.597	-0.002
	Max	0.619	0.616	0.000
	Average	0.607	0.606	-0.001
	Min	0.597	0.594	-0.003
	Std Dev	0.009	0.009	0.001

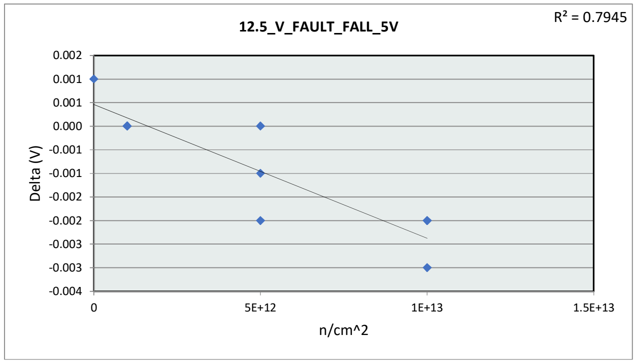


	12.4_V_FAULT_RISE_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.613	0.598	0.597	0.594
Average	0.613	0.607	0.606	0.602
Max	0.613	0.614	0.615	0.616
UL	0.630	0.630	0.630	0.630

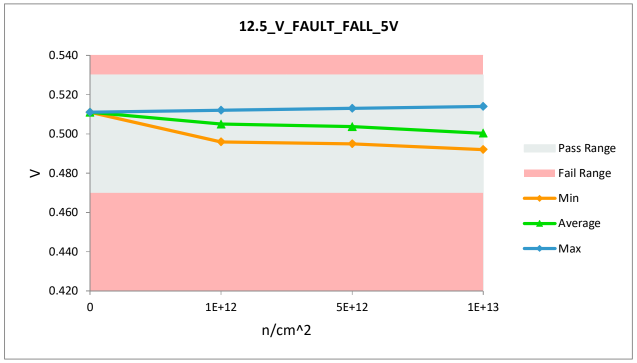


NDD Characterization Report
TPS7H5005-SEP

		12.5_V_FAULT_FALL_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.47	0.47	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.510	0.511	0.001
1E+12	1	0.507	0.507	0.000
1E+12	2	0.496	0.496	0.000
1E+12	3	0.512	0.512	0.000
5E+12	4	0.504	0.503	-0.001
5E+12	5	0.515	0.513	-0.002
5E+12	6	0.495	0.495	0.000
1E+13	7	0.516	0.514	-0.002
1E+13	8	0.495	0.492	-0.003
1E+13	9	0.497	0.495	-0.002
	Max	0.516	0.514	0.001
	Average	0.505	0.504	-0.001
	Min	0.495	0.492	-0.003
	Std Dev	0.008	0.009	0.001

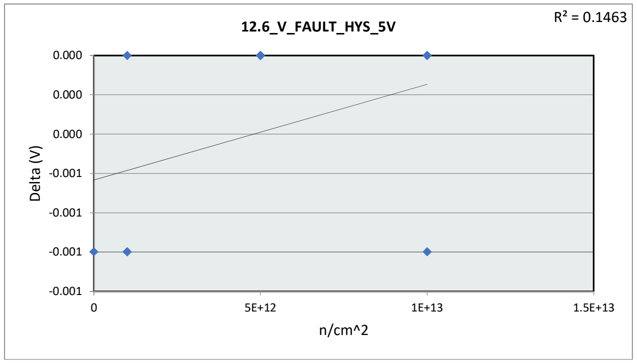


12.5_V_FAULT_FALL_5V				
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.511	0.496	0.495	0.492
Average	0.511	0.505	0.504	0.500
Max	0.511	0.512	0.513	0.514
UL	0.530	0.530	0.530	0.530

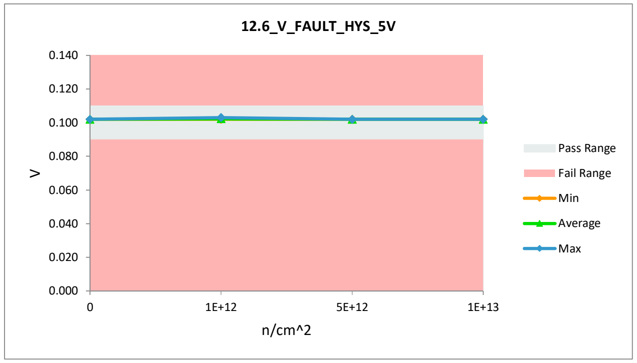


NDD Characterization Report
TPS7H5005-SEP

		12.6_V_FAULT_HYS_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.11	0.11	
	Min Limit	0.09	0.09	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.103	0.102	-0.001
1E+12	1	0.103	0.103	0.000
1E+12	2	0.103	0.102	-0.001
1E+12	3	0.103	0.102	-0.001
5E+12	4	0.102	0.102	0.000
5E+12	5	0.102	0.102	0.000
5E+12	6	0.102	0.102	0.000
1E+13	7	0.103	0.102	-0.001
1E+13	8	0.102	0.102	0.000
1E+13	9	0.102	0.102	0.000
	Max	0.103	0.103	0.000
	Average	0.102	0.102	0.000
	Min	0.102	0.102	-0.001
	Std Dev	0.001	0.000	0.001

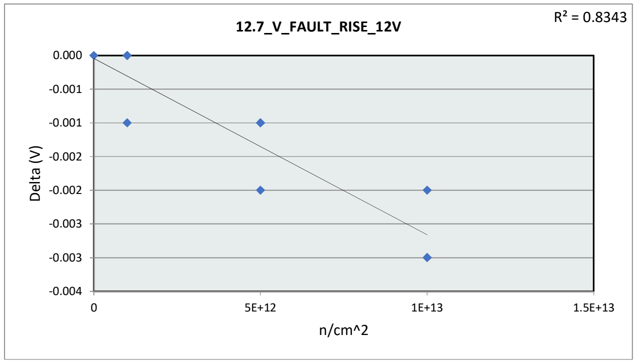


	12.6_V_FAULT_HYS_5V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.102	0.102
Average	0.102	0.102	0.102	0.102
Max	0.102	0.103	0.102	0.102
UL	0.110	0.110	0.110	0.110

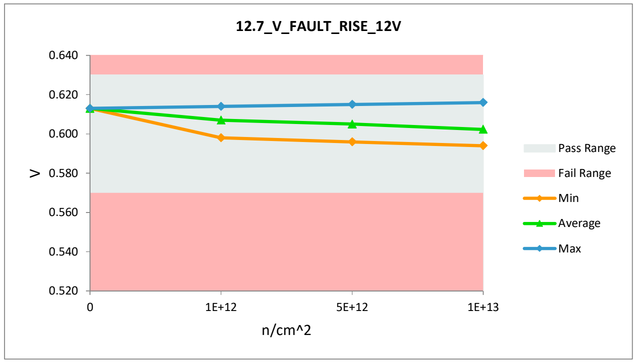


NDD Characterization Report
TPS7H5005-SEP

		12.7_V_FAULT_RISE_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.63	0.63	
	Min Limit	0.57	0.57	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.613	0.613	0.000
1E+12	1	0.610	0.609	-0.001
1E+12	2	0.598	0.598	0.000
1E+12	3	0.614	0.614	0.000
5E+12	4	0.606	0.604	-0.002
5E+12	5	0.616	0.615	-0.001
5E+12	6	0.597	0.596	-0.001
1E+13	7	0.619	0.616	-0.003
1E+13	8	0.597	0.594	-0.003
1E+13	9	0.599	0.597	-0.002
	Max	0.619	0.616	0.000
	Average	0.607	0.606	-0.001
	Min	0.597	0.594	-0.003
	Std Dev	0.009	0.009	0.001

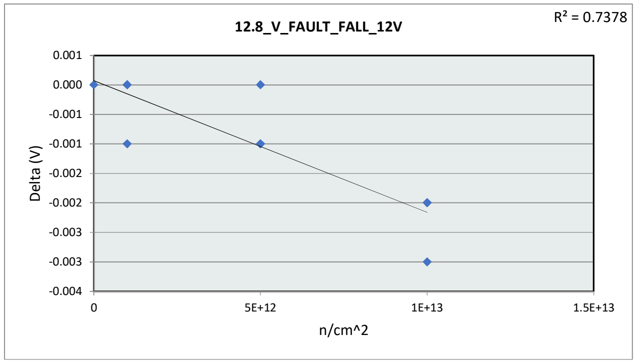


	12.7_V_FAULT_RISE_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.613	0.598	0.596	0.594
Average	0.613	0.607	0.605	0.602
Max	0.613	0.614	0.615	0.616
UL	0.630	0.630	0.630	0.630

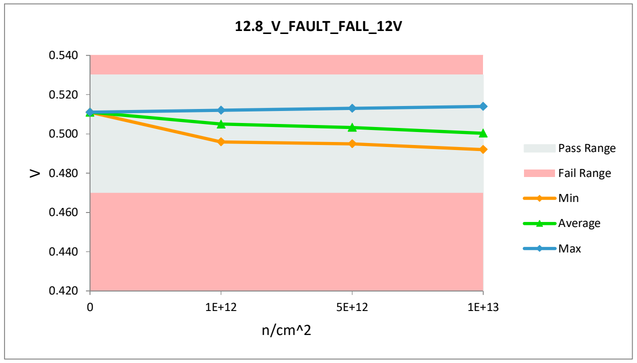


NDD Characterization Report
TPS7H5005-SEP

		12.8_V_FAULT_FALL_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.47	0.47	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.511	0.511	0.000
1E+12	1	0.508	0.507	-0.001
1E+12	2	0.496	0.496	0.000
1E+12	3	0.512	0.512	0.000
5E+12	4	0.503	0.502	-0.001
5E+12	5	0.514	0.513	-0.001
5E+12	6	0.495	0.495	0.000
1E+13	7	0.516	0.514	-0.002
1E+13	8	0.495	0.492	-0.003
1E+13	9	0.497	0.495	-0.002
	Max	0.516	0.514	0.000
	Average	0.505	0.504	-0.001
	Min	0.495	0.492	-0.003
	Std Dev	0.008	0.009	0.001

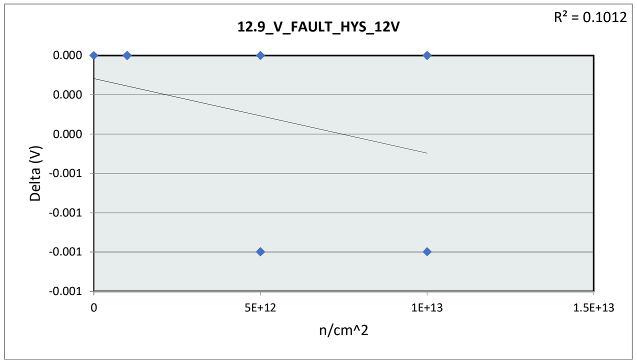


	12.8_V_FAULT_FALL_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.511	0.496	0.495	0.492
Average	0.511	0.505	0.503	0.500
Max	0.511	0.512	0.513	0.514
UL	0.530	0.530	0.530	0.530

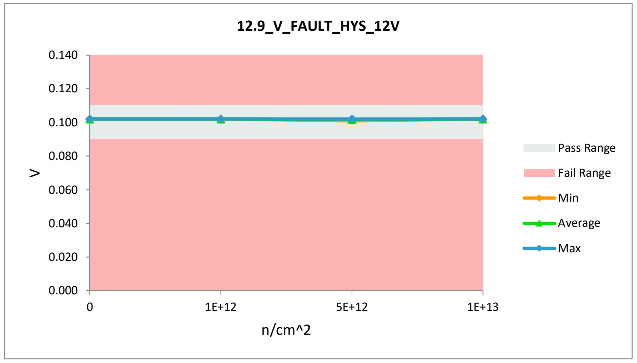


NDD Characterization Report
TPS7H5005-SEP

		12.9_V_FAULT_HYS_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.11	0.11	
	Min Limit	0.09	0.09	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.102	0.102	0.000
1E+12	1	0.102	0.102	0.000
1E+12	2	0.102	0.102	0.000
1E+12	3	0.102	0.102	0.000
5E+12	4	0.103	0.102	-0.001
5E+12	5	0.102	0.102	0.000
5E+12	6	0.102	0.101	-0.001
1E+13	7	0.103	0.102	-0.001
1E+13	8	0.102	0.102	0.000
1E+13	9	0.102	0.102	0.000
	Max	0.103	0.102	0.000
	Average	0.102	0.102	0.000
	Min	0.102	0.101	-0.001
	Std Dev	0.000	0.000	0.000

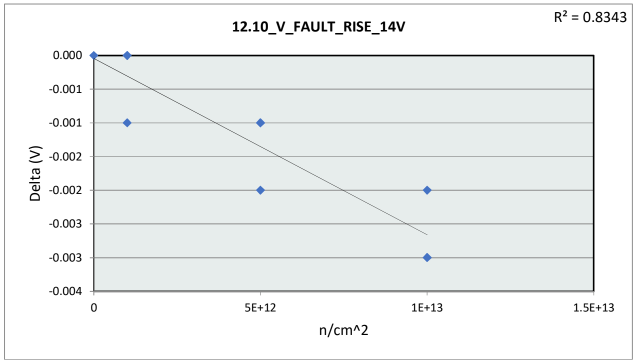


	12.9_V_FAULT_HYS_12V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.101	0.102
Average	0.102	0.102	0.102	0.102
Max	0.102	0.102	0.102	0.102
UL	0.110	0.110	0.110	0.110

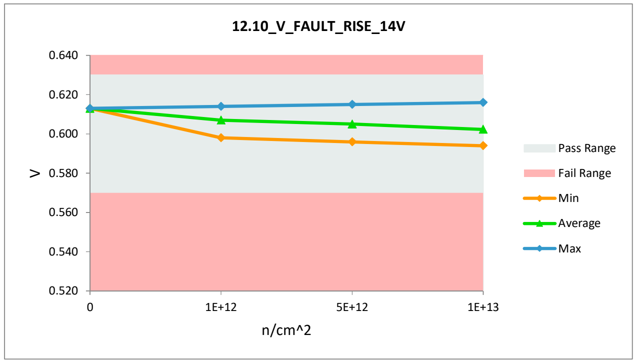


NDD Characterization Report
TPS7H5005-SEP

		12.10_V_FAULT_RISE_14V		
Test Site				
Tester				
Test Number				
Unit		V	V	
Max Limit		0.63	0.63	
Min Limit		0.57	0.57	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.613	0.613	0.000
1E+12	1	0.610	0.609	-0.001
1E+12	2	0.598	0.598	0.000
1E+12	3	0.614	0.614	0.000
5E+12	4	0.606	0.604	-0.002
5E+12	5	0.616	0.615	-0.001
5E+12	6	0.597	0.596	-0.001
1E+13	7	0.619	0.616	-0.003
1E+13	8	0.597	0.594	-0.003
1E+13	9	0.599	0.597	-0.002
	Max	0.619	0.616	0.000
	Average	0.607	0.606	-0.001
	Min	0.597	0.594	-0.003
	Std Dev	0.009	0.009	0.001

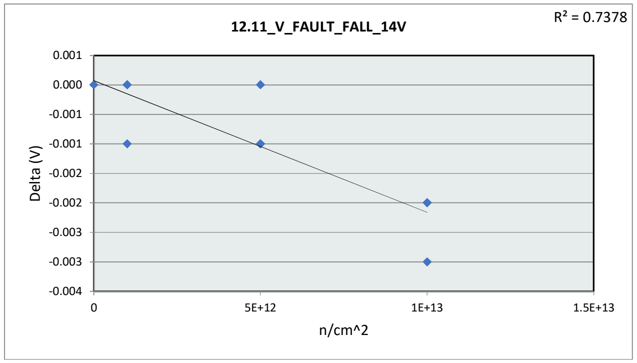


	12.10_V_FAULT_RISE_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.63	V		
Min Limit	0.57	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.570	0.570	0.570	0.570
Min	0.613	0.598	0.596	0.594
Average	0.613	0.607	0.605	0.602
Max	0.613	0.614	0.615	0.616
UL	0.630	0.630	0.630	0.630

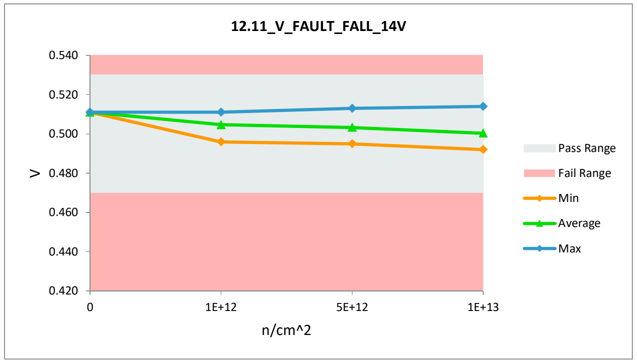


NDD Characterization Report
TPS7H5005-SEP

		12.11_V_FAULT_FALL_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.53	0.53	
	Min Limit	0.47	0.47	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.511	0.511	0.000
1E+12	1	0.507	0.507	0.000
1E+12	2	0.496	0.496	0.000
1E+12	3	0.512	0.511	-0.001
5E+12	4	0.503	0.502	-0.001
5E+12	5	0.514	0.513	-0.001
5E+12	6	0.495	0.495	0.000
1E+13	7	0.516	0.514	-0.002
1E+13	8	0.495	0.492	-0.003
1E+13	9	0.497	0.495	-0.002
	Max	0.516	0.514	0.000
	Average	0.505	0.504	-0.001
	Min	0.495	0.492	-0.003
	Std Dev	0.008	0.009	0.001

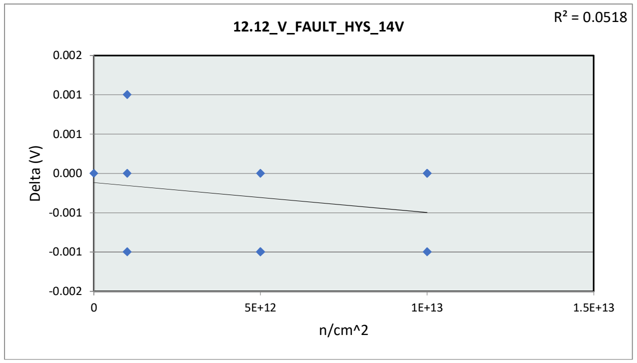


	12.11_V_FAULT_FALL_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.53	V		
Min Limit	0.47	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.470	0.470	0.470	0.470
Min	0.511	0.496	0.495	0.492
Average	0.511	0.505	0.503	0.500
Max	0.511	0.511	0.513	0.514
UL	0.530	0.530	0.530	0.530

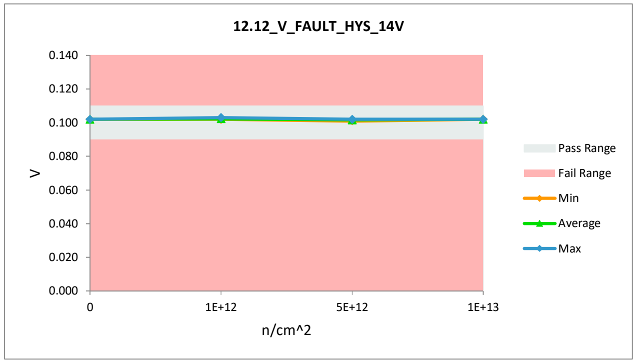


NDD Characterization Report
TPS7H5005-SEP

		12.12_V_FAULT_HYS_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	V	V	
	Max Limit	0.11	0.11	
	Min Limit	0.09	0.09	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.102	0.102	0.000
1E+12	1	0.103	0.102	-0.001
1E+12	2	0.102	0.102	0.000
1E+12	3	0.102	0.103	0.001
5E+12	4	0.103	0.102	-0.001
5E+12	5	0.102	0.102	0.000
5E+12	6	0.102	0.101	-0.001
1E+13	7	0.103	0.102	-0.001
1E+13	8	0.102	0.102	0.000
1E+13	9	0.102	0.102	0.000
	Max	0.103	0.103	0.001
	Average	0.102	0.102	0.000
	Min	0.102	0.101	-0.001
	Std Dev	0.000	0.000	0.001

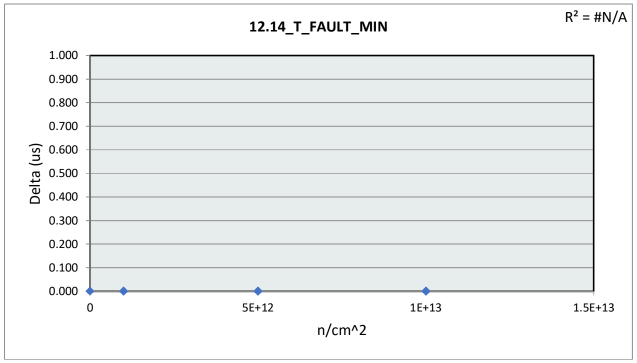


	12.12_V_FAULT_HYS_14V			
Test Site				
Tester				
Test Number				
Max Limit	0.11	V		
Min Limit	0.09	V		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.090	0.090	0.090	0.090
Min	0.102	0.102	0.101	0.102
Average	0.102	0.102	0.102	0.102
Max	0.102	0.103	0.102	0.102
UL	0.110	0.110	0.110	0.110

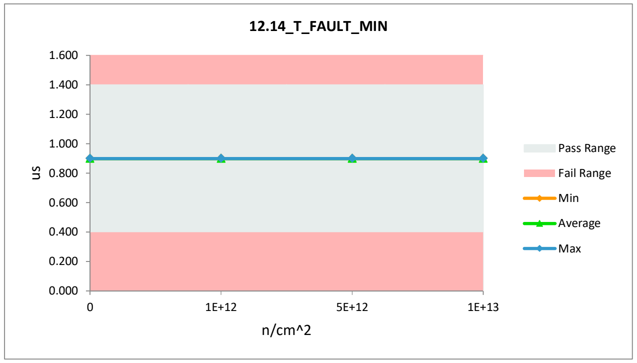


NDD Characterization Report
TPS7H5005-SEP

		12.14_T_FAULT_MIN		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	1.4	1.4	
	Min Limit	0.4	0.4	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	0.900	0.900	0.000
1E+12	1	0.900	0.900	0.000
1E+12	2	0.900	0.900	0.000
1E+12	3	0.900	0.900	0.000
5E+12	4	0.900	0.900	0.000
5E+12	5	0.900	0.900	0.000
5E+12	6	0.900	0.900	0.000
1E+13	7	0.900	0.900	0.000
1E+13	8	0.900	0.900	0.000
1E+13	9	0.900	0.900	0.000
	Max	0.900	0.900	0.000
	Average	0.900	0.900	0.000
	Min	0.900	0.900	0.000
	Std Dev	0.000	0.000	0.000

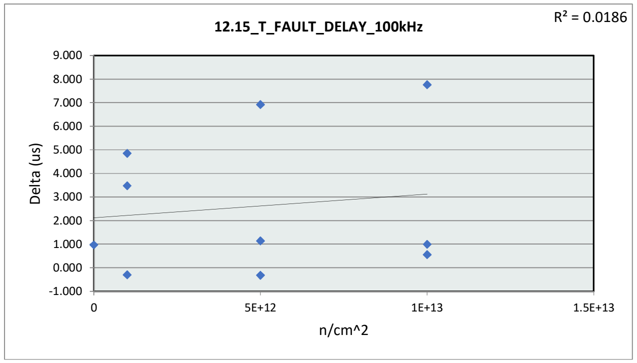


	12.14_T_FAULT_MIN			
Test Site				
Tester				
Test Number				
Max Limit	1.4	us		
Min Limit	0.4	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.400	0.400	0.400	0.400
Min	0.900	0.900	0.900	0.900
Average	0.900	0.900	0.900	0.900
Max	0.900	0.900	0.900	0.900
UL	1.400	1.400	1.400	1.400

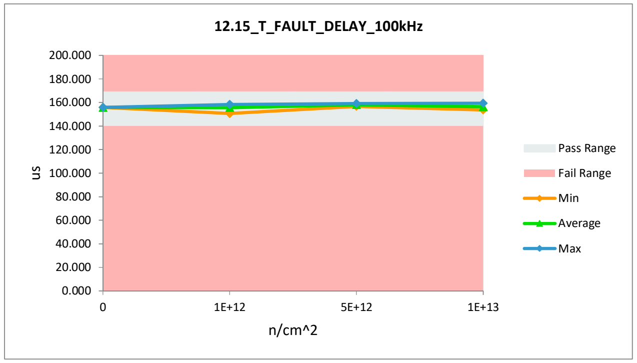


NDD Characterization Report
TPS7H5005-SEP

		12.15_T_FAULT_DELAY_100kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	169	169	
	Min Limit	140	140	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	154.827	155.790	0.963
1E+12	1	150.907	150.601	-0.306
1E+12	2	152.785	157.631	4.846
1E+12	3	154.986	158.458	3.472
5E+12	4	152.189	159.104	6.915
5E+12	5	157.332	158.466	1.134
5E+12	6	157.116	156.791	-0.325
1E+13	7	155.094	155.640	0.546
1E+13	8	152.584	153.574	0.990
1E+13	9	151.651	159.405	7.754
	Max	157.332	159.405	7.754
	Average	153.947	156.546	2.599
	Min	150.907	150.601	-0.325
	Std Dev	2.248	2.766	2.974

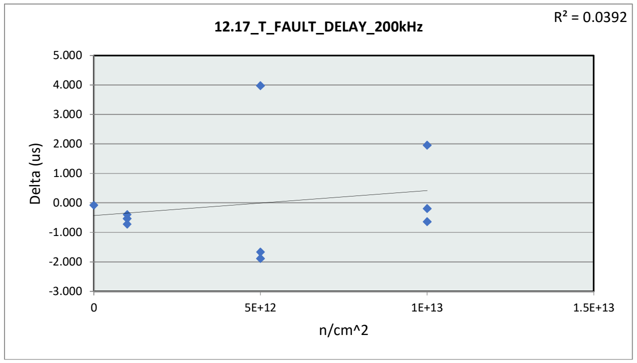


	12.15_T_FAULT_DELAY_100kH			
Test Site				
Tester				
Test Number				
Max Limit	169	us		
Min Limit	140	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	140.000	140.000	140.000	140.000
Min	155.790	150.601	156.791	153.574
Average	155.790	155.563	158.120	156.206
Max	155.790	158.458	159.104	159.405
UL	169.000	169.000	169.000	169.000

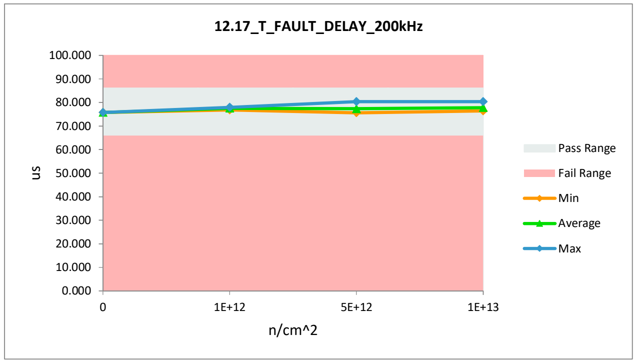


NDD Characterization Report
TPS7H5005-SEP

		12.17_T_FAULT_DELAY_200kHz		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	86	86	
	Min Limit	66	66	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	75.807	75.726	-0.081
1E+12	1	77.189	76.789	-0.400
1E+12	2	78.388	77.848	-0.540
1E+12	3	78.673	77.944	-0.729
5E+12	4	77.347	75.678	-1.669
5E+12	5	76.336	80.307	3.971
5E+12	6	77.900	76.008	-1.892
1E+13	7	76.761	76.560	-0.201
1E+13	8	77.080	76.441	-0.639
1E+13	9	78.359	80.308	1.949
	Max	78.673	80.308	3.971
	Average	77.384	77.361	-0.023
	Min	75.807	75.678	-1.892
	Std Dev	0.942	1.735	1.744

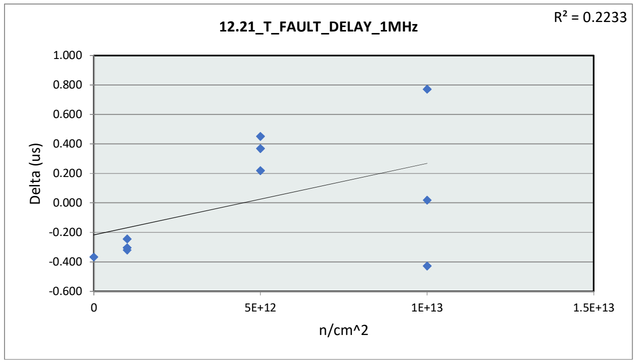


	12.17_T_FAULT_DELAY_200kH			
Test Site				
Tester				
Test Number				
Max Limit	86	us		
Min Limit	66	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	66.000	66.000	66.000	66.000
Min	75.726	76.789	75.678	76.441
Average	75.726	77.527	77.331	77.770
Max	75.726	77.944	80.307	80.308
UL	86.000	86.000	86.000	86.000

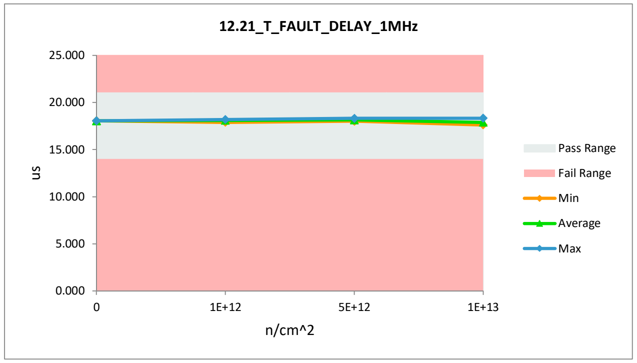


NDD Characterization Report
TPS7H5005-SEP

		12.21_T_FAULT_DELAY_1MHz		
Test Site				
Tester				
Test Number				
Unit		us	us	
Max Limit		21	21	
Min Limit		14	14	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	18.409	18.041	-0.368
1E+12	1	18.466	18.145	-0.321
1E+12	2	18.195	17.889	-0.306
1E+12	3	18.443	18.197	-0.246
5E+12	4	17.884	18.102	0.218
5E+12	5	17.946	18.314	0.368
5E+12	6	17.552	18.002	0.450
1E+13	7	18.036	17.607	-0.429
1E+13	8	17.689	17.706	0.017
1E+13	9	17.562	18.333	0.771
	Max	18.466	18.333	0.771
	Average	18.018	18.034	0.015
	Min	17.552	17.607	-0.429
	Std Dev	0.353	0.241	0.416

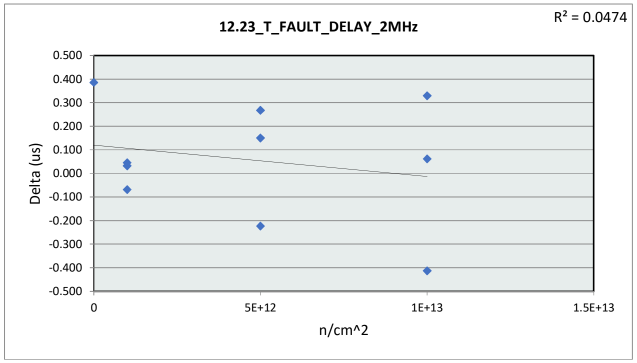


	12.21_T_FAULT_DELAY_1MHz			
Test Site				
Tester				
Test Number				
Max Limit	21	us		
Min Limit	14	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	14.000	14.000	14.000	14.000
Min	18.041	17.889	18.002	17.607
Average	18.041	18.077	18.139	17.882
Max	18.041	18.197	18.314	18.333
UL	21.000	21.000	21.000	21.000

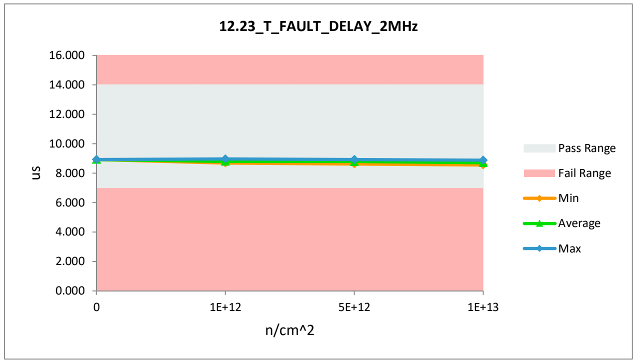


NDD Characterization Report
TPS7H5005-SEP

		12.23_T_FAULT_DELAY_2MHz		
	Test Site			
	Tester			
	Test Number			
	Unit	us	us	
	Max Limit	14	14	
	Min Limit	7	7	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.541	8.926	0.385
1E+12	1	8.807	8.738	-0.069
1E+12	2	8.929	8.961	0.032
1E+12	3	8.632	8.677	0.045
5E+12	4	8.777	8.927	0.150
5E+12	5	8.855	8.631	-0.224
5E+12	6	8.518	8.785	0.267
1E+13	7	8.643	8.704	0.061
1E+13	8	8.972	8.558	-0.414
1E+13	9	8.548	8.877	0.329
	Max	8.972	8.961	0.385
	Average	8.722	8.778	0.056
	Min	8.518	8.558	-0.414
	Std Dev	0.167	0.139	0.248

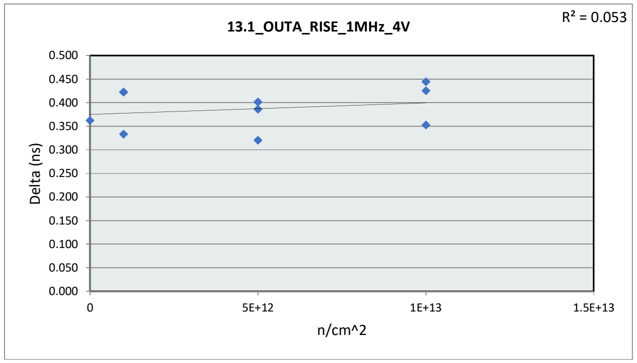


	12.23_T_FAULT_DELAY_2MHz			
Test Site				
Tester				
Test Number				
Max Limit	14	us		
Min Limit	7	us		
n/cm^2	0	1E+12	5E+12	1E+13
LL	7.000	7.000	7.000	7.000
Min	8.926	8.677	8.631	8.558
Average	8.926	8.792	8.781	8.713
Max	8.926	8.961	8.927	8.877
UL	14.000	14.000	14.000	14.000

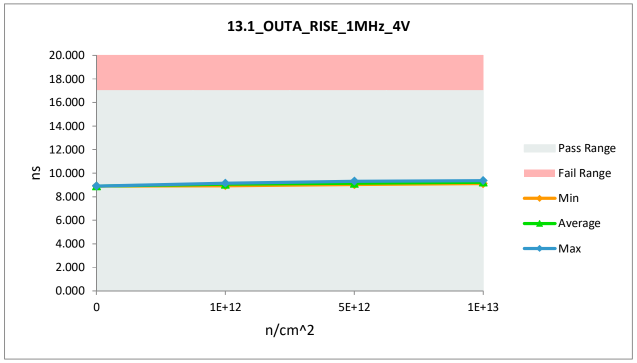


NDD Characterization Report
TPS7H5005-SEP

		13.1_OUTA_RISE_1MHz_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.547	8.909	0.362
1E+12	1	8.806	9.139	0.333
1E+12	2	8.689	9.111	0.422
1E+12	3	8.510	8.932	0.422
5E+12	4	8.707	9.027	0.320
5E+12	5	8.688	9.074	0.386
5E+12	6	8.919	9.320	0.401
1E+13	7	8.927	9.371	0.444
1E+13	8	8.759	9.111	0.352
1E+13	9	8.808	9.233	0.425
	Max	8.927	9.371	0.444
	Average	8.736	9.123	0.387
	Min	8.510	8.909	0.320
	Std Dev	0.139	0.152	0.043

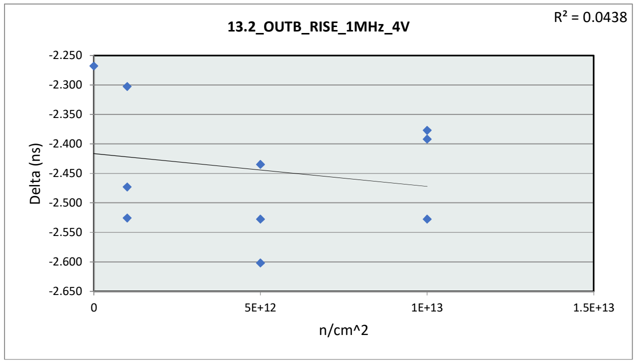


	13.1_OUTA_RISE_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.909	8.932	9.027	9.111
Average	8.909	9.061	9.140	9.238
Max	8.909	9.139	9.320	9.371
UL	17.000	17.000	17.000	17.000

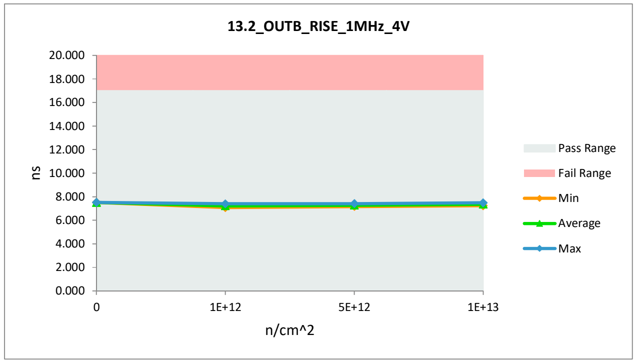


NDD Characterization Report
TPS7H5005-SEP

		13.2_OUTB_RISE_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	9.778	7.510	-2.268
1E+12	1	9.689	7.216	-2.473
1E+12	2	9.702	7.399	-2.303
1E+12	3	9.594	7.068	-2.526
5E+12	4	9.695	7.167	-2.528
5E+12	5	9.848	7.246	-2.602
5E+12	6	9.849	7.414	-2.435
1E+13	7	9.757	7.380	-2.377
1E+13	8	9.873	7.481	-2.392
1E+13	9	9.757	7.229	-2.528
	Max	9.873	7.510	-2.268
	Average	9.754	7.311	-2.443
	Min	9.594	7.068	-2.602
	Std Dev	0.087	0.146	0.108

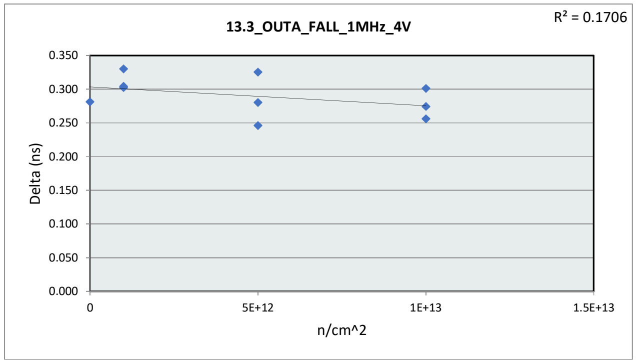


	13.2_OUTB_RISE_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.510	7.068	7.167	7.229
Average	7.510	7.228	7.276	7.363
Max	7.510	7.399	7.414	7.481
UL	17.000	17.000	17.000	17.000

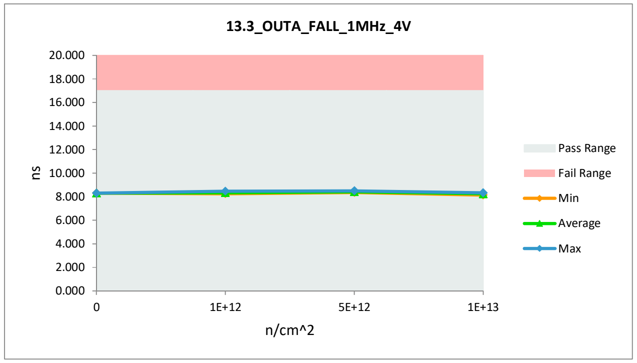


NDD Characterization Report
TPS7H5005-SEP

		13.3_OUTA_FALL_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.022	8.303	0.281
1E+12	1	8.159	8.461	0.302
1E+12	2	7.949	8.279	0.330
1E+12	3	7.949	8.253	0.304
5E+12	4	8.136	8.382	0.246
5E+12	5	8.219	8.499	0.280
5E+12	6	8.043	8.368	0.325
1E+13	7	7.876	8.150	0.274
1E+13	8	8.067	8.323	0.256
1E+13	9	7.956	8.257	0.301
	Max	8.219	8.499	0.330
	Average	8.038	8.328	0.290
	Min	7.876	8.150	0.246
	Std Dev	0.109	0.104	0.028

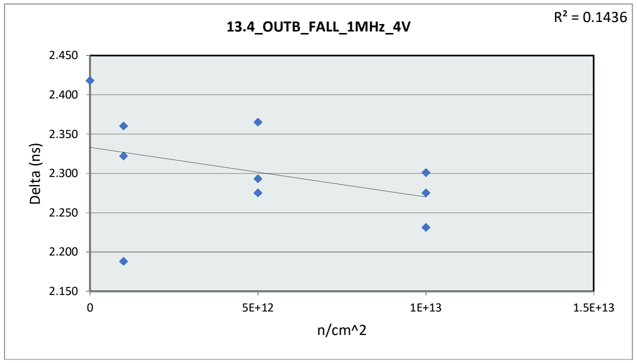


	13.3_OUTA_FALL_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.303	8.253	8.368	8.150
Average	8.303	8.331	8.416	8.243
Max	8.303	8.461	8.499	8.323
UL	17.000	17.000	17.000	17.000

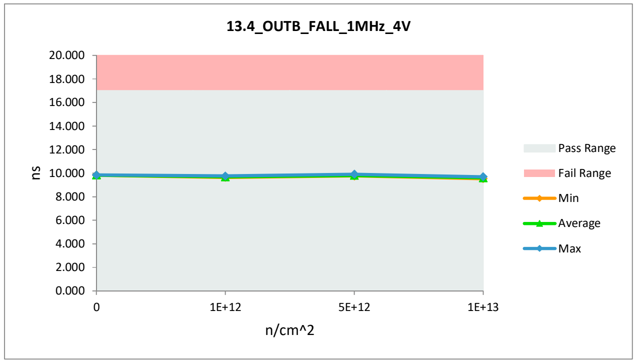


NDD Characterization Report
TPS7H5005-SEP

		13.4_OUTB_FALL_1MHz_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.419	9.837	2.418
1E+12	1	7.573	9.761	2.188
1E+12	2	7.283	9.643	2.360
1E+12	3	7.297	9.619	2.322
5E+12	4	7.495	9.770	2.275
5E+12	5	7.608	9.901	2.293
5E+12	6	7.396	9.761	2.365
1E+13	7	7.252	9.527	2.275
1E+13	8	7.384	9.685	2.301
1E+13	9	7.360	9.591	2.231
	Max	7.608	9.901	2.418
	Average	7.407	9.710	2.303
	Min	7.252	9.527	2.188
	Std Dev	0.120	0.117	0.067

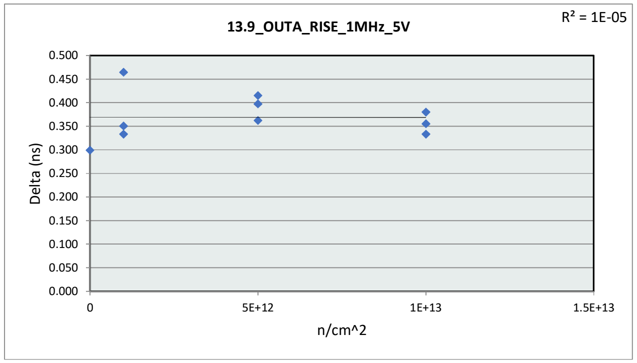


	13.4_OUTB_FALL_1MHz_4V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	9.837	9.619	9.761	9.527
Average	9.837	9.674	9.811	9.601
Max	9.837	9.761	9.901	9.685
UL	17.000	17.000	17.000	17.000

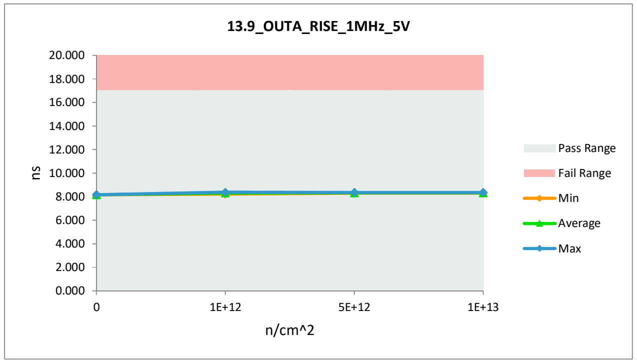


NDD Characterization Report
TPS7H5005-SEP

		13.9_OUTA_RISE_1MHz_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.858	8.157	0.299
1E+12	1	7.990	8.323	0.333
1E+12	2	7.912	8.376	0.464
1E+12	3	7.865	8.215	0.350
5E+12	4	7.948	8.310	0.362
5E+12	5	7.908	8.323	0.415
5E+12	6	7.959	8.356	0.397
1E+13	7	7.999	8.332	0.333
1E+13	8	7.970	8.350	0.380
1E+13	9	7.933	8.288	0.355
	Max	7.999	8.376	0.464
	Average	7.934	8.303	0.369
	Min	7.858	8.157	0.299
	Std Dev	0.049	0.068	0.047

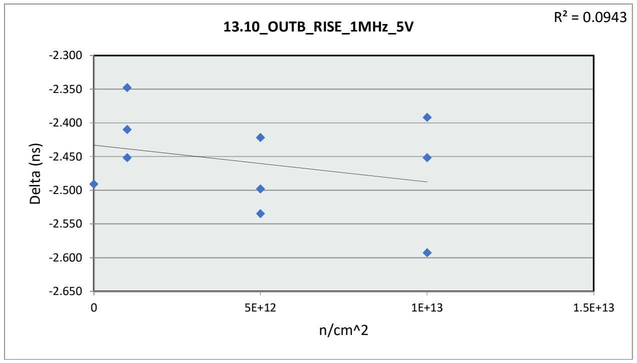


	13.9_OUTA_RISE_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	8.157	8.215	8.310	8.288
Average	8.157	8.305	8.330	8.323
Max	8.157	8.376	8.356	8.350
UL	17.000	17.000	17.000	17.000

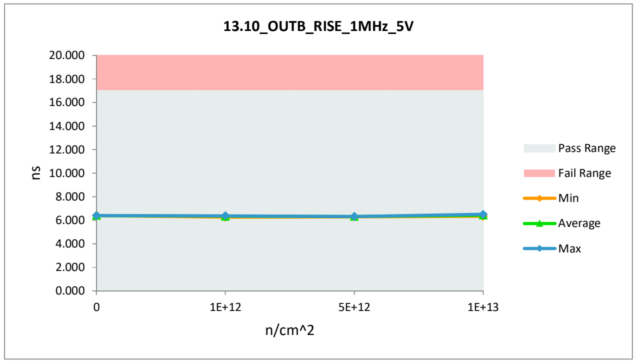


NDD Characterization Report
TPS7H5005-SEP

		13.10_OUTB_RISE_1MHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.895	6.404	-2.491
1E+12	1	8.784	6.332	-2.452
1E+12	2	8.736	6.388	-2.348
1E+12	3	8.666	6.256	-2.410
5E+12	4	8.740	6.318	-2.422
5E+12	5	8.854	6.319	-2.535
5E+12	6	8.797	6.299	-2.498
1E+13	7	8.885	6.493	-2.392
1E+13	8	8.950	6.498	-2.452
1E+13	9	8.919	6.326	-2.593
	Max	8.950	6.498	-2.348
	Average	8.823	6.363	-2.459
	Min	8.666	6.256	-2.593
	Std Dev	0.092	0.081	0.072

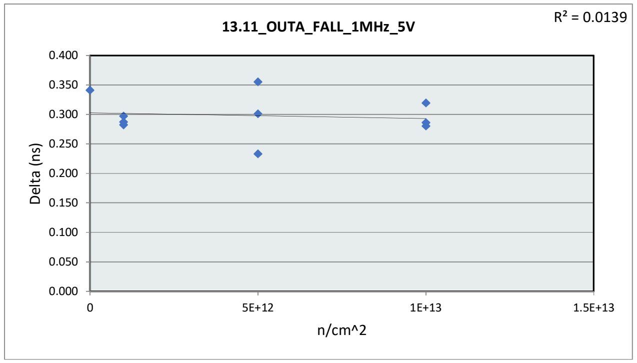


	13.10_OUTB_RISE_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.404	6.256	6.299	6.326
Average	6.404	6.325	6.312	6.439
Max	6.404	6.388	6.319	6.498
UL	17.000	17.000	17.000	17.000

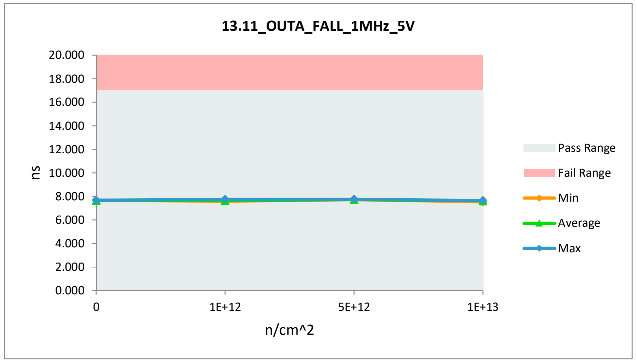


NDD Characterization Report
TPS7H5005-SEP

		13.11_OUTA_FALL_1MHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.321	7.662	0.341
1E+12	1	7.447	7.744	0.297
1E+12	2	7.337	7.619	0.282
1E+12	3	7.297	7.584	0.287
5E+12	4	7.463	7.764	0.301
5E+12	5	7.492	7.725	0.233
5E+12	6	7.383	7.738	0.355
1E+13	7	7.259	7.545	0.286
1E+13	8	7.381	7.661	0.280
1E+13	9	7.313	7.632	0.319
	Max	7.492	7.764	0.355
	Average	7.369	7.667	0.298
	Min	7.259	7.545	0.233
	Std Dev	0.078	0.074	0.034

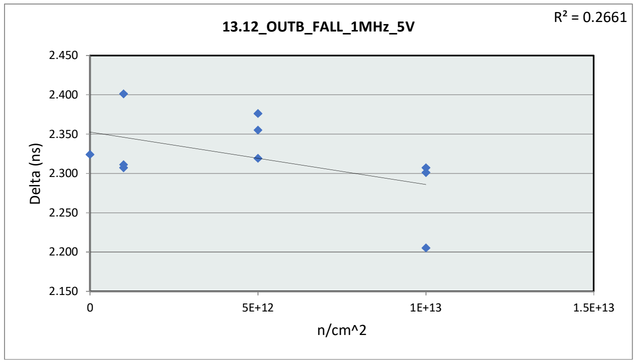


	13.11_OUTA_FALL_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.662	7.584	7.725	7.545
Average	7.662	7.649	7.742	7.613
Max	7.662	7.744	7.764	7.661
UL	17.000	17.000	17.000	17.000

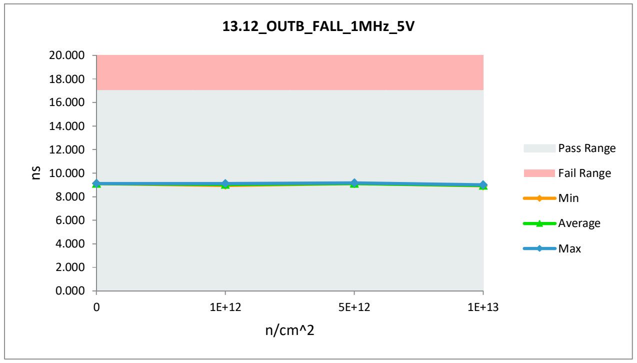


NDD Characterization Report
TPS7H5005-SEP

		13.12_OUTB_FALL_1MHz_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.795	9.119	2.324
1E+12	1	6.811	9.118	2.307
1E+12	2	6.638	9.039	2.401
1E+12	3	6.646	8.957	2.311
5E+12	4	6.784	9.103	2.319
5E+12	5	6.800	9.176	2.376
5E+12	6	6.756	9.111	2.355
1E+13	7	6.609	8.916	2.307
1E+13	8	6.713	9.014	2.301
1E+13	9	6.715	8.920	2.205
	Max	6.811	9.176	2.401
	Average	6.727	9.047	2.321
	Min	6.609	8.916	2.205
	Std Dev	0.074	0.092	0.053

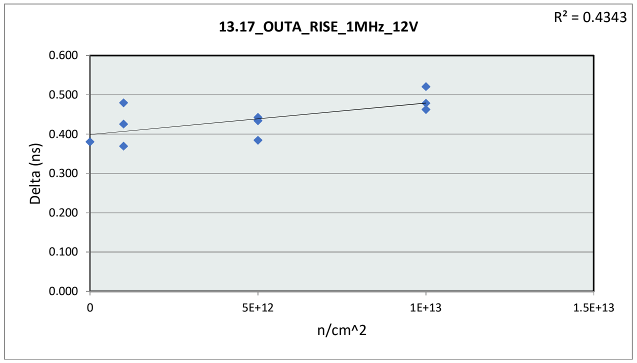


	13.12_OUTB_FALL_1MHz_5V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	9.119	8.957	9.103	8.916
Average	9.119	9.038	9.130	8.950
Max	9.119	9.118	9.176	9.014
UL	17.000	17.000	17.000	17.000

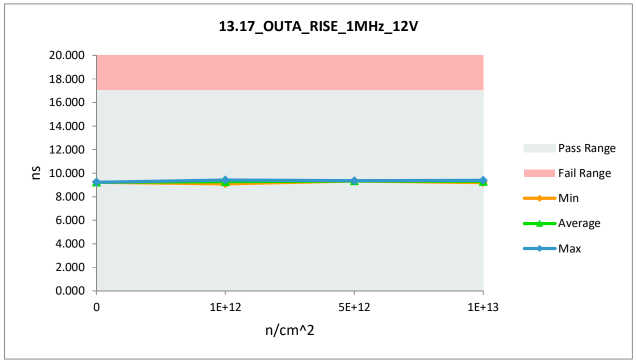


NDD Characterization Report
TPS7H5005-SEP

		13.17_OUTA_RISE_1MHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.855	9.235	0.380
1E+12	1	8.858	9.283	0.425
1E+12	2	8.935	9.414	0.479
1E+12	3	8.724	9.093	0.369
5E+12	4	8.948	9.332	0.384
5E+12	5	8.902	9.344	0.442
5E+12	6	8.902	9.336	0.434
1E+13	7	8.814	9.292	0.478
1E+13	8	8.924	9.386	0.462
1E+13	9	8.687	9.207	0.520
	Max	8.948	9.414	0.520
	Average	8.855	9.292	0.437
	Min	8.687	9.093	0.369
	Std Dev	0.089	0.094	0.049

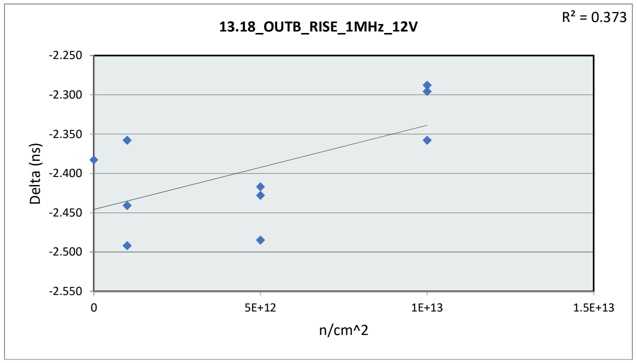


	13.17_OUTA_RISE_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	9.235	9.093	9.332	9.207
Average	9.235	9.263	9.337	9.295
Max	9.235	9.414	9.344	9.386
UL	17.000	17.000	17.000	17.000

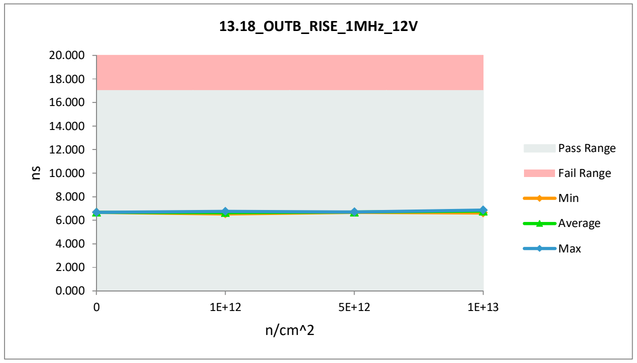


NDD Characterization Report
TPS7H5005-SEP

		13.18_OUTB_RISE_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	9.051	6.668	-2.383
1E+12	1	9.113	6.621	-2.492
1E+12	2	9.122	6.764	-2.358
1E+12	3	8.965	6.524	-2.441
5E+12	4	9.135	6.707	-2.428
5E+12	5	9.166	6.681	-2.485
5E+12	6	9.097	6.680	-2.417
1E+13	7	9.134	6.846	-2.288
1E+13	8	9.150	6.854	-2.296
1E+13	9	8.987	6.629	-2.358
	Max	9.166	6.854	-2.288
	Average	9.092	6.697	-2.395
	Min	8.965	6.524	-2.492
	Std Dev	0.069	0.102	0.071

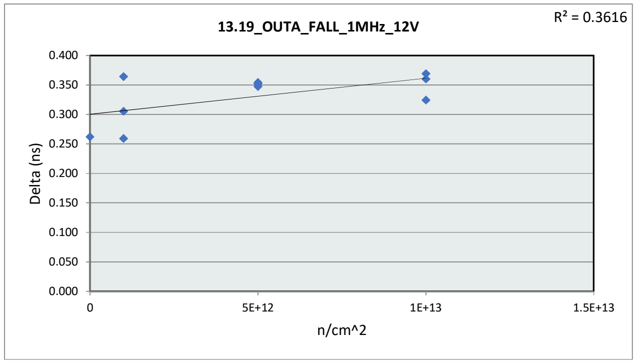


	13.18_OUTB_RISE_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.668	6.524	6.680	6.629
Average	6.668	6.636	6.689	6.776
Max	6.668	6.764	6.707	6.854
UL	17.000	17.000	17.000	17.000

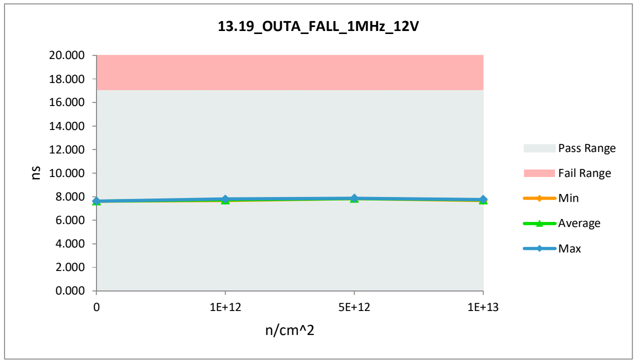


NDD Characterization Report
TPS7H5005-SEP

		13.19_OUTA_FALL_1MHz_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.360	7.622	0.262
1E+12	1	7.492	7.797	0.305
1E+12	2	7.432	7.691	0.259
1E+12	3	7.304	7.668	0.364
5E+12	4	7.516	7.868	0.352
5E+12	5	7.478	7.832	0.354
5E+12	6	7.493	7.840	0.347
1E+13	7	7.303	7.672	0.369
1E+13	8	7.447	7.771	0.324
1E+13	9	7.336	7.696	0.360
	Max	7.516	7.868	0.369
	Average	7.416	7.746	0.330
	Min	7.303	7.622	0.259
	Std Dev	0.083	0.086	0.041

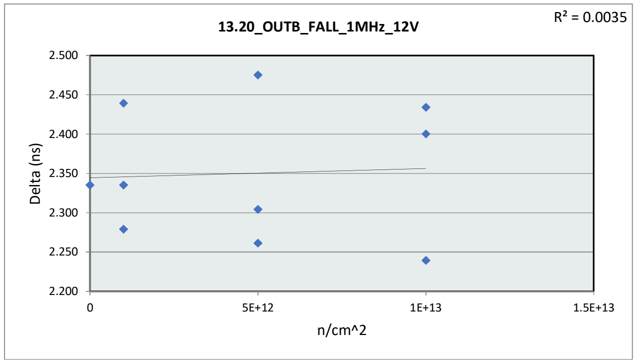


	13.19_OUTA_FALL_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.622	7.668	7.832	7.672
Average	7.622	7.719	7.847	7.713
Max	7.622	7.797	7.868	7.771
UL	17.000	17.000	17.000	17.000

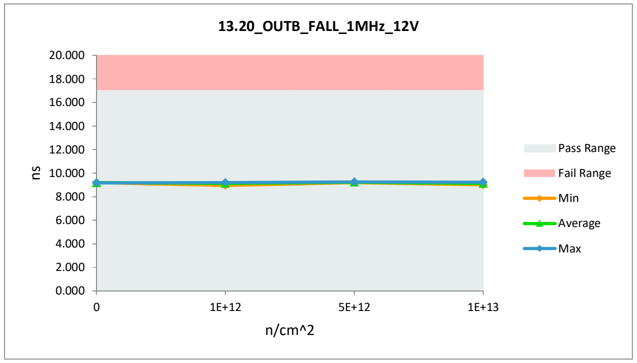


NDD Characterization Report
TPS7H5005-SEP

		13.20_OUTB_FALL_1MHz_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.843	9.178	2.335
1E+12	1	6.873	9.208	2.335
1E+12	2	6.739	9.178	2.439
1E+12	3	6.682	8.961	2.279
5E+12	4	6.934	9.195	2.261
5E+12	5	6.945	9.249	2.304
5E+12	6	6.784	9.259	2.475
1E+13	7	6.720	9.120	2.400
1E+13	8	6.791	9.225	2.434
1E+13	9	6.773	9.012	2.239
	Max	6.945	9.259	2.475
	Average	6.808	9.159	2.350
	Min	6.682	8.961	2.239
	Std Dev	0.089	0.100	0.082

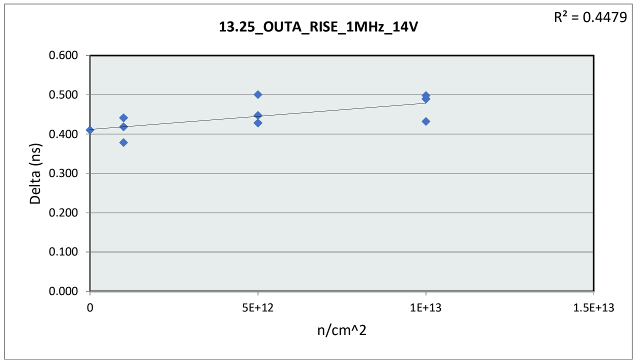


	13.20_OUTB_FALL_1MHz_12V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	9.178	8.961	9.195	9.012
Average	9.178	9.116	9.234	9.119
Max	9.178	9.208	9.259	9.225
UL	17.000	17.000	17.000	17.000

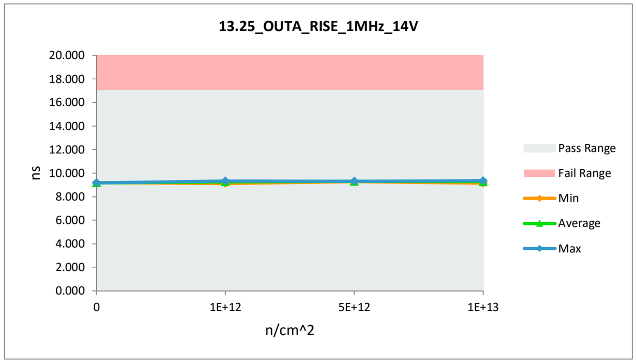


NDD Characterization Report
TPS7H5005-SEP

		13.25_OUTA_RISE_1MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.774	9.184	0.410
1E+12	1	8.860	9.301	0.441
1E+12	2	8.951	9.329	0.378
1E+12	3	8.710	9.128	0.418
5E+12	4	8.860	9.307	0.447
5E+12	5	8.887	9.315	0.428
5E+12	6	8.785	9.285	0.500
1E+13	7	8.797	9.295	0.498
1E+13	8	8.863	9.352	0.489
1E+13	9	8.723	9.155	0.432
	Max	8.951	9.352	0.500
	Average	8.821	9.265	0.444
	Min	8.710	9.128	0.378
	Std Dev	0.076	0.079	0.040

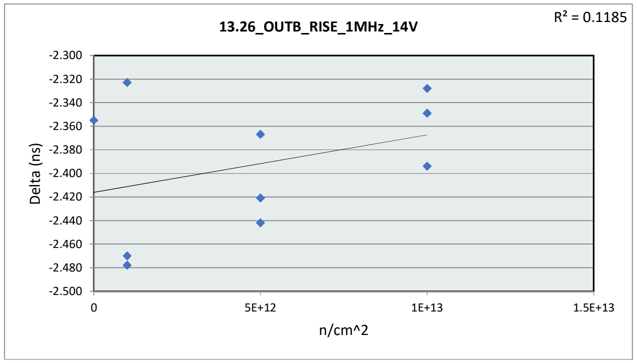


	13.25_OUTA_RISE_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	9.184	9.128	9.285	9.155
Average	9.184	9.253	9.302	9.267
Max	9.184	9.329	9.315	9.352
UL	17.000	17.000	17.000	17.000

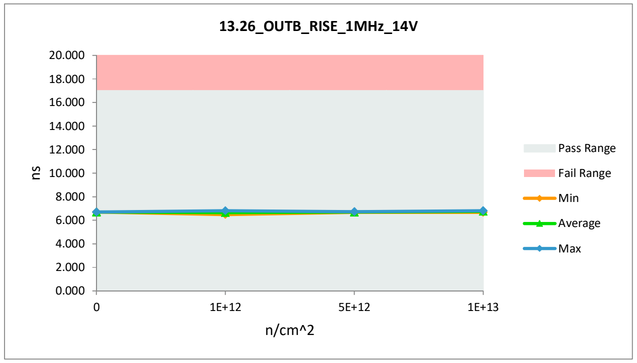


NDD Characterization Report
TPS7H5005-SEP

		13.26_OUTB_RISE_1MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	9.050	6.695	-2.355
1E+12	1	9.117	6.647	-2.470
1E+12	2	9.127	6.804	-2.323
1E+12	3	8.973	6.495	-2.478
5E+12	4	9.117	6.675	-2.442
5E+12	5	9.143	6.722	-2.421
5E+12	6	9.039	6.672	-2.367
1E+13	7	9.158	6.809	-2.349
1E+13	8	9.198	6.804	-2.394
1E+13	9	9.002	6.674	-2.328
	Max	9.198	6.809	-2.323
	Average	9.092	6.700	-2.393
	Min	8.973	6.495	-2.478
	Std Dev	0.073	0.095	0.057

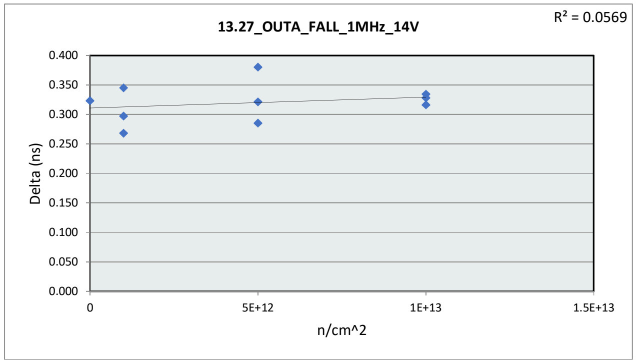


	13.26_OUTB_RISE_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	6.695	6.495	6.672	6.674
Average	6.695	6.649	6.690	6.762
Max	6.695	6.804	6.722	6.809
UL	17.000	17.000	17.000	17.000

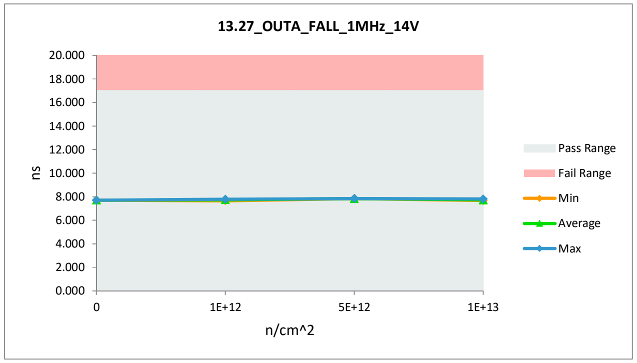


NDD Characterization Report
TPS7H5005-SEP

		13.27_OUTA_FALL_1MHz_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		17	17	
Min Limit		0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.380	7.703	0.323
1E+12	1	7.522	7.790	0.268
1E+12	2	7.430	7.775	0.345
1E+12	3	7.356	7.653	0.297
5E+12	4	7.523	7.844	0.321
5E+12	5	7.556	7.841	0.285
5E+12	6	7.447	7.827	0.380
1E+13	7	7.357	7.673	0.316
1E+13	8	7.463	7.797	0.334
1E+13	9	7.375	7.703	0.328
	Max	7.556	7.844	0.380
	Average	7.441	7.761	0.320
	Min	7.356	7.653	0.268
	Std Dev	0.074	0.072	0.032

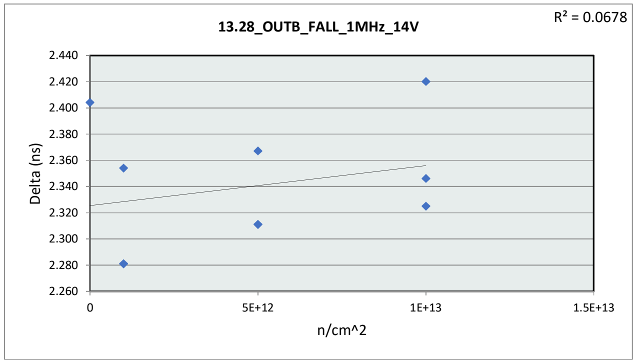


	13.27_OUTA_FALL_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	7.703	7.653	7.827	7.673
Average	7.703	7.739	7.837	7.724
Max	7.703	7.790	7.844	7.797
UL	17.000	17.000	17.000	17.000

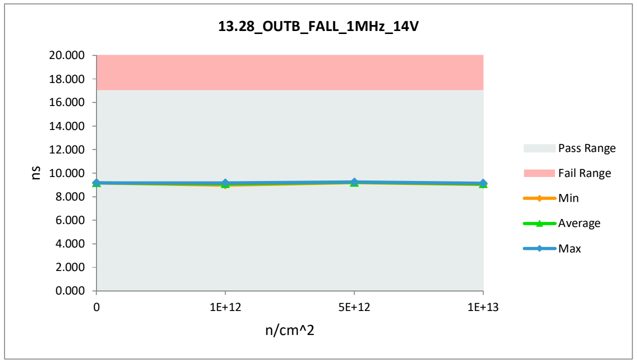


NDD Characterization Report
TPS7H5005-SEP

		13.28_OUTB_FALL_1MHz_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	17	17	
	Min Limit	0	0	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.767	9.171	2.404
1E+12	1	6.889	9.170	2.281
1E+12	2	6.759	9.113	2.354
1E+12	3	6.713	8.994	2.281
5E+12	4	6.887	9.198	2.311
5E+12	5	6.929	9.240	2.311
5E+12	6	6.870	9.237	2.367
1E+13	7	6.676	9.096	2.420
1E+13	8	6.810	9.135	2.325
1E+13	9	6.687	9.033	2.346
	Max	6.929	9.240	2.420
	Average	6.799	9.139	2.340
	Min	6.676	8.994	2.281
	Std Dev	0.092	0.082	0.048

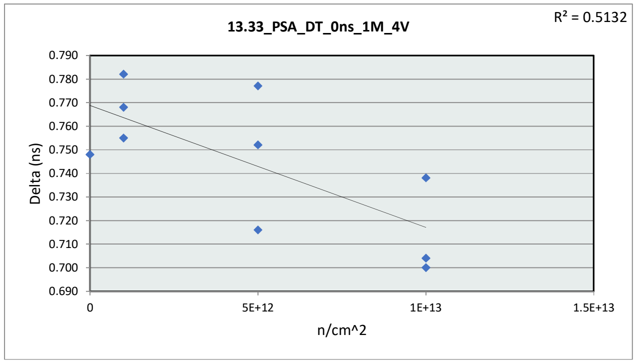


	13.28_OUTB_FALL_1MHz_14V			
Test Site				
Tester				
Test Number				
Max Limit	17	ns		
Min Limit	0	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	0.000	0.000	0.000	0.000
Min	9.171	8.994	9.198	9.033
Average	9.171	9.092	9.225	9.088
Max	9.171	9.170	9.240	9.135
UL	17.000	17.000	17.000	17.000

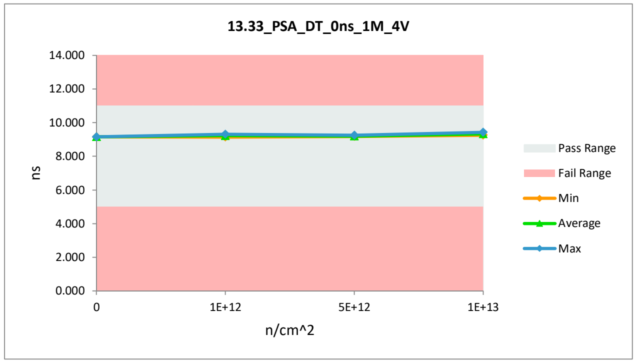


NDD Characterization Report
TPS7H5005-SEP

		13.33_PSA_DT_0ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.408	9.156	0.748
1E+12	1	8.541	9.323	0.782
1E+12	2	8.449	9.204	0.755
1E+12	3	8.367	9.135	0.768
5E+12	4	8.406	9.183	0.777
5E+12	5	8.440	9.192	0.752
5E+12	6	8.536	9.252	0.716
1E+13	7	8.556	9.260	0.704
1E+13	8	8.609	9.309	0.700
1E+13	9	8.693	9.431	0.738
	Max	8.693	9.431	0.782
	Average	8.501	9.245	0.744
	Min	8.367	9.135	0.700
	Std Dev	0.104	0.090	0.029

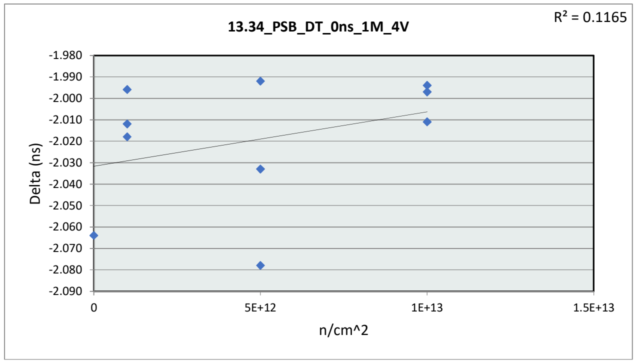


	13.33_PSA_DT_0ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	9.156	9.135	9.183	9.260
Average	9.156	9.221	9.209	9.333
Max	9.156	9.323	9.252	9.431
UL	11.000	11.000	11.000	11.000

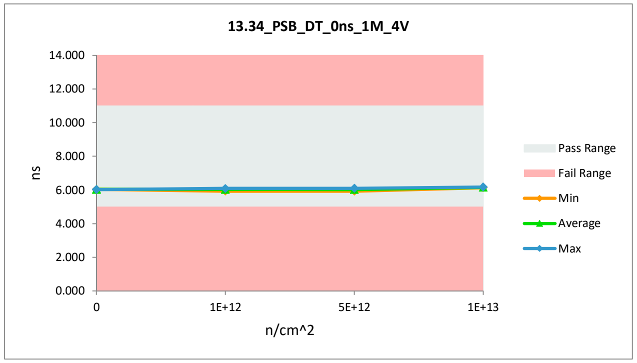


NDD Characterization Report
TPS7H5005-SEP

		13.34_PSB_DT_0ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	8.094	6.030	-2.064
1E+12	1	8.107	6.089	-2.018
1E+12	2	8.070	6.074	-1.996
1E+12	3	7.939	5.927	-2.012
5E+12	4	8.048	6.015	-2.033
5E+12	5	8.011	5.933	-2.078
5E+12	6	8.090	6.098	-1.992
1E+13	7	8.175	6.164	-2.011
1E+13	8	8.165	6.171	-1.994
1E+13	9	8.141	6.144	-1.997
	Max	8.175	6.171	-1.992
	Average	8.084	6.065	-2.019
	Min	7.939	5.927	-2.078
	Std Dev	0.072	0.088	0.030

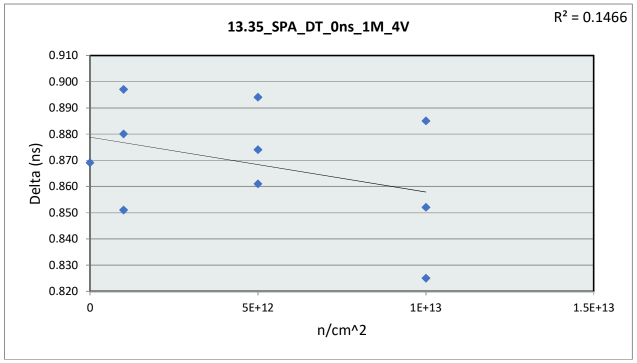


	13.34_PSB_DT_0ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	6.030	5.927	5.933	6.144
Average	6.030	6.030	6.015	6.160
Max	6.030	6.089	6.098	6.171
UL	11.000	11.000	11.000	11.000

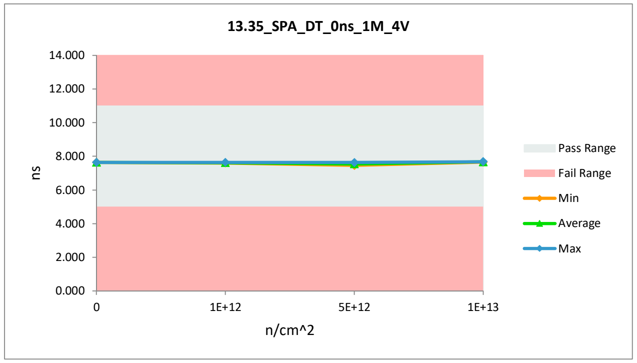


NDD Characterization Report
TPS7H5005-SEP

		13.35_SPA_DT_0ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.770	7.639	0.869
1E+12	1	6.729	7.626	0.897
1E+12	2	6.760	7.640	0.880
1E+12	3	6.748	7.599	0.851
5E+12	4	6.596	7.457	0.861
5E+12	5	6.674	7.548	0.874
5E+12	6	6.739	7.633	0.894
1E+13	7	6.856	7.681	0.825
1E+13	8	6.783	7.668	0.885
1E+13	9	6.804	7.656	0.852
	Max	6.856	7.681	0.897
	Average	6.746	7.615	0.869
	Min	6.596	7.457	0.825
	Std Dev	0.071	0.067	0.022

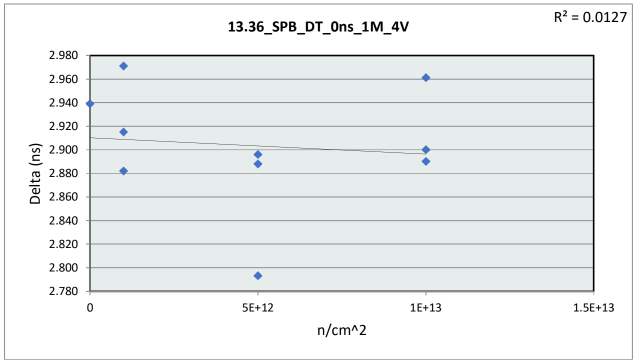


	13.35_SPA_DT_0ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	7.639	7.599	7.457	7.656
Average	7.639	7.622	7.546	7.668
Max	7.639	7.640	7.633	7.681
UL	11.000	11.000	11.000	11.000

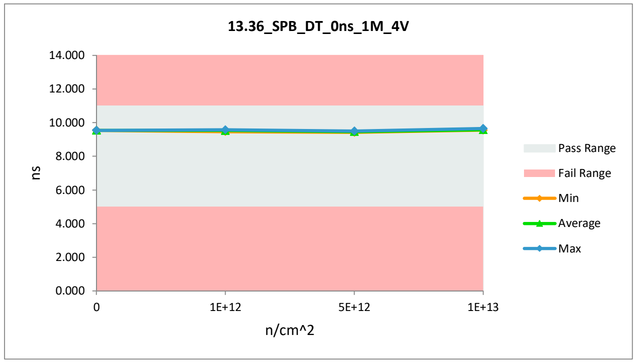


NDD Characterization Report
TPS7H5005-SEP

		13.36_SPB_DT_0ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.603	9.542	2.939
1E+12	1	6.614	9.585	2.971
1E+12	2	6.628	9.543	2.915
1E+12	3	6.589	9.471	2.882
5E+12	4	6.603	9.499	2.896
5E+12	5	6.633	9.426	2.793
5E+12	6	6.604	9.492	2.888
1E+13	7	6.684	9.645	2.961
1E+13	8	6.657	9.557	2.900
1E+13	9	6.665	9.555	2.890
	Max	6.684	9.645	2.971
	Average	6.628	9.531	2.903
	Min	6.589	9.426	2.793
	Std Dev	0.031	0.062	0.050

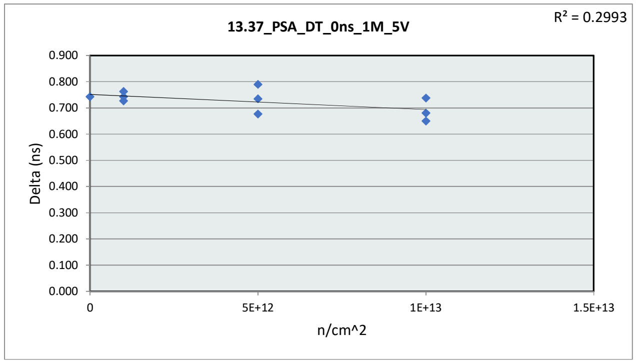


	13.36_SPB_DT_0ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	9.542	9.471	9.426	9.555
Average	9.542	9.533	9.472	9.586
Max	9.542	9.585	9.499	9.645
UL	11.000	11.000	11.000	11.000

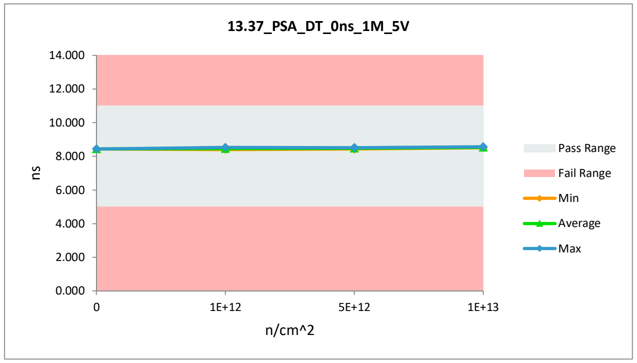


NDD Characterization Report
TPS7H5005-SEP

		13.37_PSA_DT_0ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.697	8.439	0.742
1E+12	1	7.772	8.534	0.762
1E+12	2	7.710	8.436	0.726
1E+12	3	7.658	8.400	0.742
5E+12	4	7.748	8.424	0.676
5E+12	5	7.687	8.476	0.789
5E+12	6	7.787	8.521	0.734
1E+13	7	7.766	8.503	0.737
1E+13	8	7.860	8.540	0.680
1E+13	9	7.921	8.570	0.649
	Max	7.921	8.570	0.789
	Average	7.761	8.484	0.724
	Min	7.658	8.400	0.649
	Std Dev	0.081	0.058	0.043

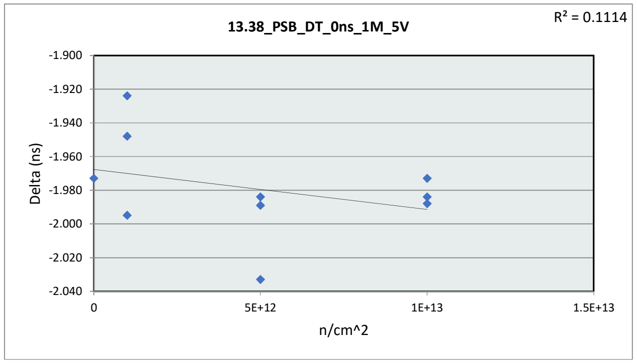


	13.37_PSA_DT_0ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.439	8.400	8.424	8.503
Average	8.439	8.457	8.474	8.538
Max	8.439	8.534	8.521	8.570
UL	11.000	11.000	11.000	11.000

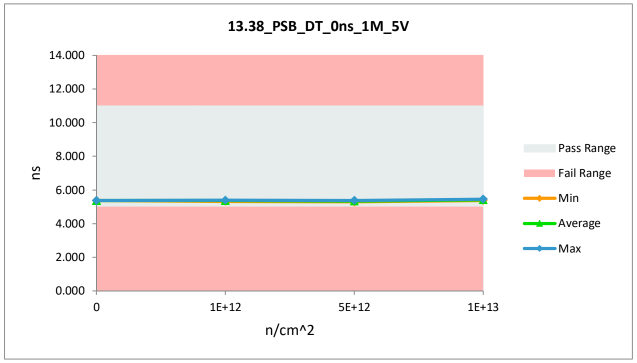


NDD Characterization Report
TPS7H5005-SEP

		13.38_PSB_DT_0ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.338	5.365	-1.973
1E+12	1	7.382	5.387	-1.995
1E+12	2	7.314	5.390	-1.924
1E+12	3	7.268	5.320	-1.948
5E+12	4	7.310	5.326	-1.984
5E+12	5	7.327	5.294	-2.033
5E+12	6	7.368	5.379	-1.989
1E+13	7	7.361	5.377	-1.984
1E+13	8	7.407	5.419	-1.988
1E+13	9	7.430	5.457	-1.973
	Max	7.430	5.457	-1.924
	Average	7.351	5.371	-1.979
	Min	7.268	5.294	-2.033
	Std Dev	0.049	0.048	0.029

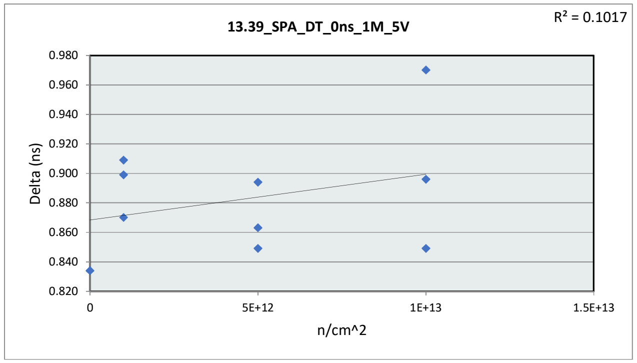


	13.38_PSB_DT_0ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	5.365	5.320	5.294	5.377
Average	5.365	5.366	5.333	5.418
Max	5.365	5.390	5.379	5.457
UL	11.000	11.000	11.000	11.000

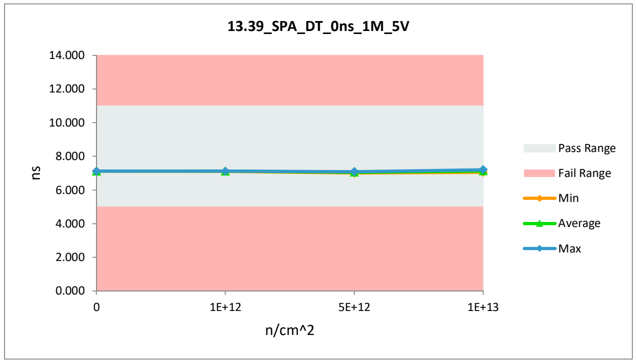


NDD Characterization Report
TPS7H5005-SEP

		13.39_SPA_DT_0ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.282	7.116	0.834
1E+12	1	6.221	7.120	0.899
1E+12	2	6.211	7.120	0.909
1E+12	3	6.233	7.103	0.870
5E+12	4	6.139	7.002	0.863
5E+12	5	6.196	7.090	0.894
5E+12	6	6.214	7.063	0.849
1E+13	7	6.237	7.207	0.970
1E+13	8	6.220	7.116	0.896
1E+13	9	6.201	7.050	0.849
	Max	6.282	7.207	0.970
	Average	6.215	7.099	0.883
	Min	6.139	7.002	0.834
	Std Dev	0.036	0.054	0.040

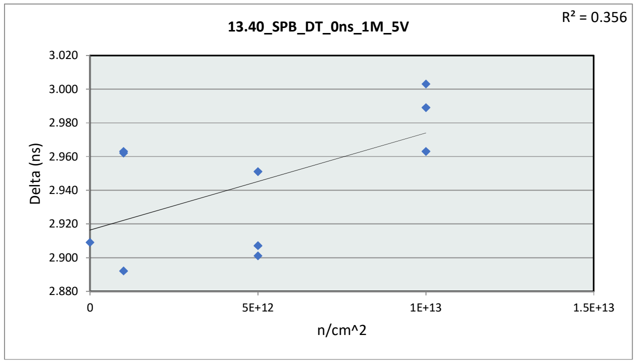


	13.39_SPA_DT_0ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	7.116	7.103	7.002	7.050
Average	7.116	7.114	7.052	7.124
Max	7.116	7.120	7.090	7.207
UL	11.000	11.000	11.000	11.000

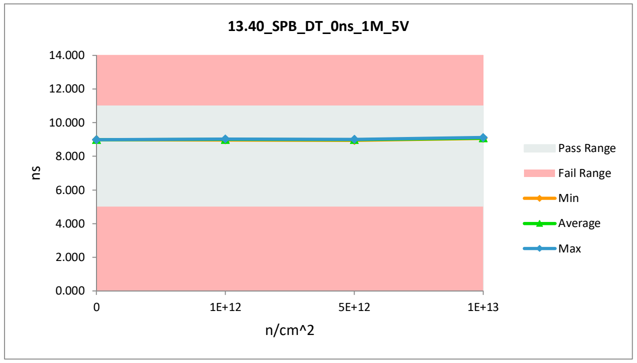


NDD Characterization Report
TPS7H5005-SEP

		13.40_SPB_DT_0ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.079	8.988	2.909
1E+12	1	6.066	9.028	2.962
1E+12	2	6.068	8.960	2.892
1E+12	3	6.045	9.008	2.963
5E+12	4	6.039	8.946	2.907
5E+12	5	6.104	9.005	2.901
5E+12	6	6.049	9.000	2.951
1E+13	7	6.065	9.068	3.003
1E+13	8	6.083	9.072	2.989
1E+13	9	6.151	9.114	2.963
	Max	6.151	9.114	3.003
	Average	6.075	9.019	2.944
	Min	6.039	8.946	2.892
	Std Dev	0.033	0.052	0.039



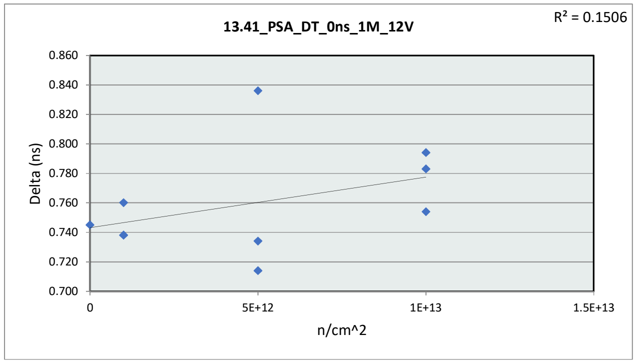
	13.40_SPB_DT_0ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.988	8.960	8.946	9.068
Average	8.988	8.999	8.984	9.085
Max	8.988	9.028	9.005	9.114
UL	11.000	11.000	11.000	11.000



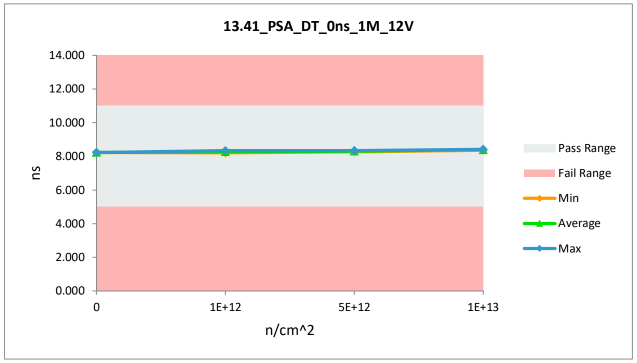
NDD Characterization Report
TPS7H5005-SEP

	13.41_PSA_DT_0ns_1M_12V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	11	11
Min Limit	5	5

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.486	8.231	0.745
1E+12	1	7.574	8.334	0.760
1E+12	2	7.527	8.265	0.738
1E+12	3	7.465	8.203	0.738
5E+12	4	7.552	8.266	0.714
5E+12	5	7.559	8.293	0.734
5E+12	6	7.505	8.341	0.836
1E+13	7	7.608	8.362	0.754
1E+13	8	7.613	8.407	0.794
1E+13	9	7.631	8.414	0.783
	Max	7.631	8.414	0.836
	Average	7.552	8.312	0.760
	Min	7.465	8.203	0.714
	Std Dev	0.056	0.072	0.036

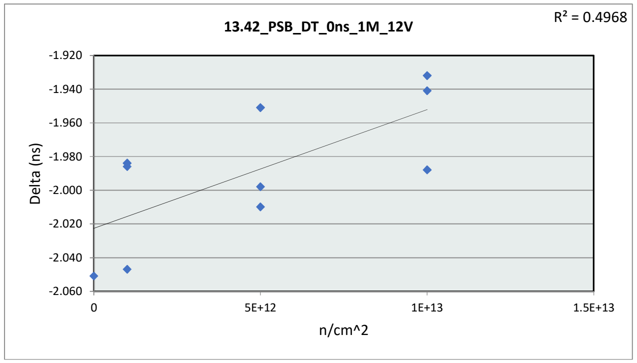


	13.41_PSA_DT_0ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.231	8.203	8.266	8.362
Average	8.231	8.267	8.300	8.394
Max	8.231	8.334	8.341	8.414
UL	11.000	11.000	11.000	11.000

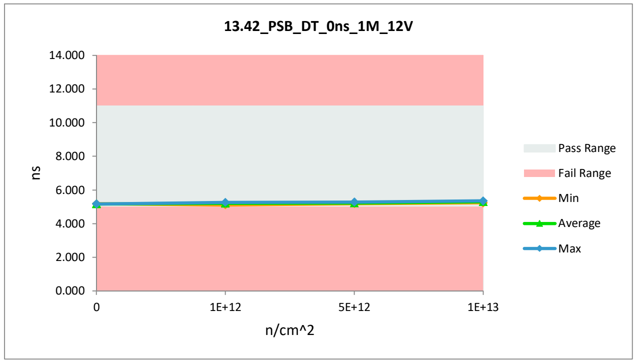


NDD Characterization Report
TPS7H5005-SEP

		13.42_PSB_DT_0ns_1M_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		11	11	
Min Limit		5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.223	5.172	-2.051
1E+12	1	7.244	5.260	-1.984
1E+12	2	7.225	5.239	-1.986
1E+12	3	7.163	5.116	-2.047
5E+12	4	7.205	5.195	-2.010
5E+12	5	7.136	5.185	-1.951
5E+12	6	7.275	5.277	-1.998
1E+13	7	7.245	5.304	-1.941
1E+13	8	7.280	5.348	-1.932
1E+13	9	7.224	5.236	-1.988
	Max	7.280	5.348	-1.932
	Average	7.222	5.233	-1.989
	Min	7.136	5.116	-2.051
	Std Dev	0.045	0.068	0.040

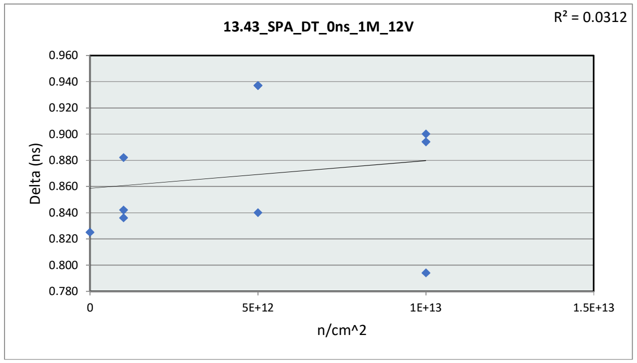


	13.42_PSB_DT_0ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	5.172	5.116	5.185	5.236
Average	5.172	5.205	5.219	5.296
Max	5.172	5.260	5.277	5.348
UL	11.000	11.000	11.000	11.000

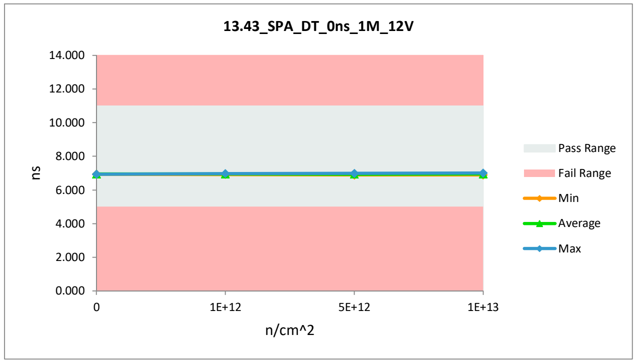


NDD Characterization Report
TPS7H5005-SEP

		13.43_SPA_DT_0ns_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.115	6.940	0.825
1E+12	1	6.089	6.971	0.882
1E+12	2	6.134	6.976	0.842
1E+12	3	6.090	6.926	0.836
5E+12	4	5.955	6.892	0.937
5E+12	5	6.093	6.933	0.840
5E+12	6	6.056	6.993	0.937
1E+13	7	6.117	7.011	0.894
1E+13	8	6.102	6.896	0.794
1E+13	9	6.066	6.966	0.900
	Max	6.134	7.011	0.937
	Average	6.082	6.950	0.869
	Min	5.955	6.892	0.794
	Std Dev	0.050	0.040	0.049

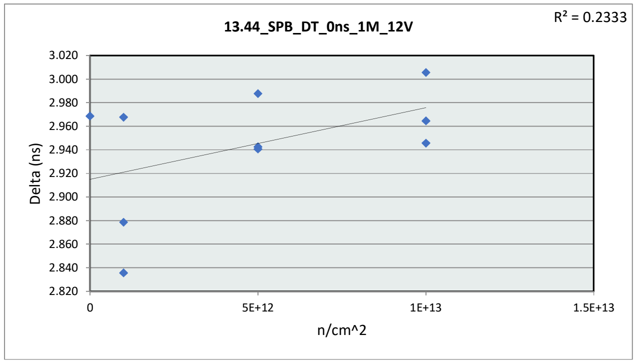


	13.43_SPA_DT_0ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	6.940	6.926	6.892	6.896
Average	6.940	6.958	6.939	6.958
Max	6.940	6.976	6.993	7.011
UL	11.000	11.000	11.000	11.000

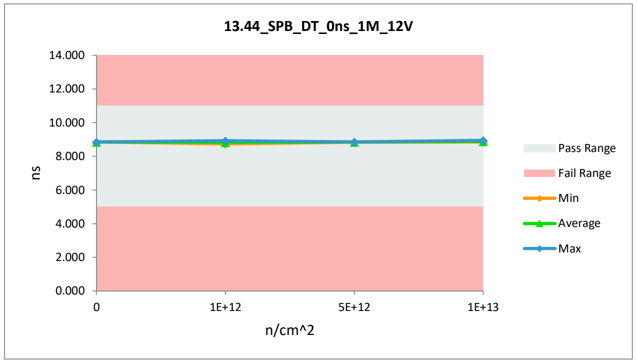


NDD Characterization Report
TPS7H5005-SEP

		13.44_SPB_DT_0ns_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.878	8.847	2.969
1E+12	1	5.948	8.827	2.879
1E+12	2	5.958	8.926	2.968
1E+12	3	5.913	8.749	2.836
5E+12	4	5.855	8.843	2.988
5E+12	5	5.915	8.856	2.941
5E+12	6	5.906	8.849	2.943
1E+13	7	5.944	8.890	2.946
1E+13	8	5.945	8.951	3.006
1E+13	9	5.894	8.859	2.965
	Max	5.958	8.951	3.006
	Average	5.916	8.860	2.944
	Min	5.855	8.749	2.836
	Std Dev	0.034	0.055	0.051

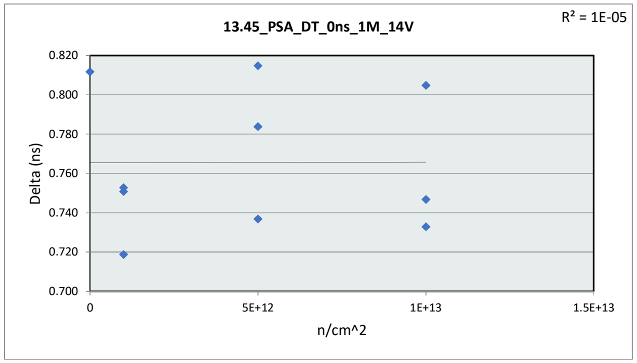


	13.44_SPB_DT_0ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.847	8.749	8.843	8.859
Average	8.847	8.834	8.849	8.900
Max	8.847	8.926	8.856	8.951
UL	11.000	11.000	11.000	11.000

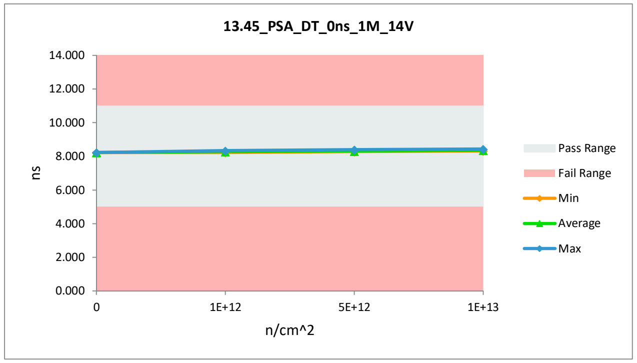


NDD Characterization Report
TPS7H5005-SEP

		13.45_PSA_DT_0ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.422	8.234	0.812
1E+12	1	7.619	8.338	0.719
1E+12	2	7.507	8.260	0.753
1E+12	3	7.474	8.225	0.751
5E+12	4	7.538	8.275	0.737
5E+12	5	7.501	8.285	0.784
5E+12	6	7.577	8.392	0.815
1E+13	7	7.578	8.325	0.747
1E+13	8	7.618	8.351	0.733
1E+13	9	7.628	8.433	0.805
	Max	7.628	8.433	0.815
	Average	7.546	8.312	0.766
	Min	7.422	8.225	0.719
	Std Dev	0.069	0.068	0.035

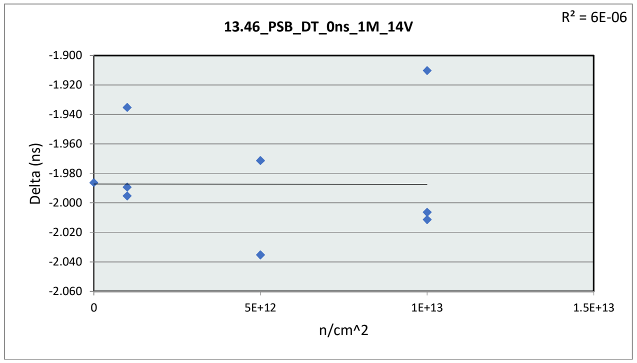


	13.45_PSA_DT_0ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.234	8.225	8.275	8.325
Average	8.234	8.274	8.317	8.370
Max	8.234	8.338	8.392	8.433
UL	11.000	11.000	11.000	11.000

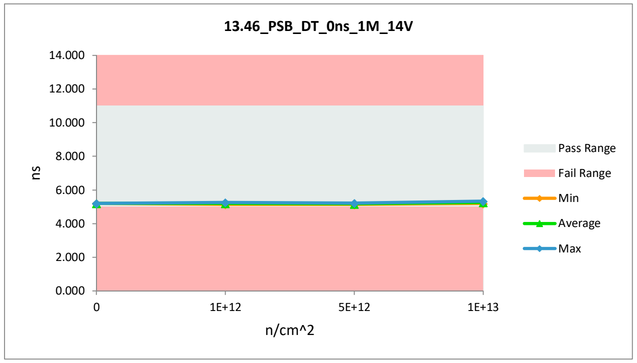


NDD Characterization Report
TPS7H5005-SEP

		13.46_PSB_DT_0ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	7.192	5.206	-1.986
1E+12	1	7.196	5.207	-1.989
1E+12	2	7.197	5.262	-1.935
1E+12	3	7.139	5.144	-1.995
5E+12	4	7.198	5.163	-2.035
5E+12	5	7.180	5.145	-2.035
5E+12	6	7.191	5.220	-1.971
1E+13	7	7.260	5.254	-2.006
1E+13	8	7.246	5.336	-1.910
1E+13	9	7.214	5.203	-2.011
	Max	7.260	5.336	-1.910
	Average	7.201	5.214	-1.987
	Min	7.139	5.144	-2.035
	Std Dev	0.034	0.059	0.040

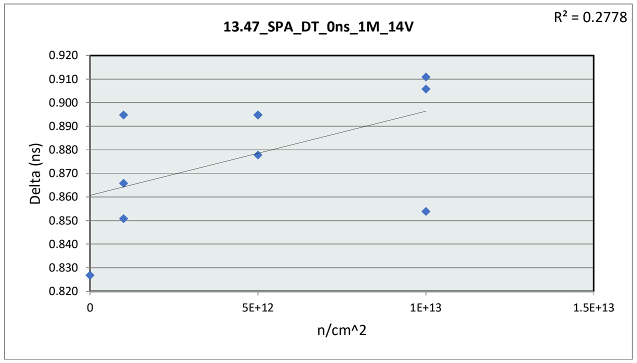


	13.46_PSB_DT_0ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	5.206	5.144	5.145	5.203
Average	5.206	5.204	5.176	5.264
Max	5.206	5.262	5.220	5.336
UL	11.000	11.000	11.000	11.000

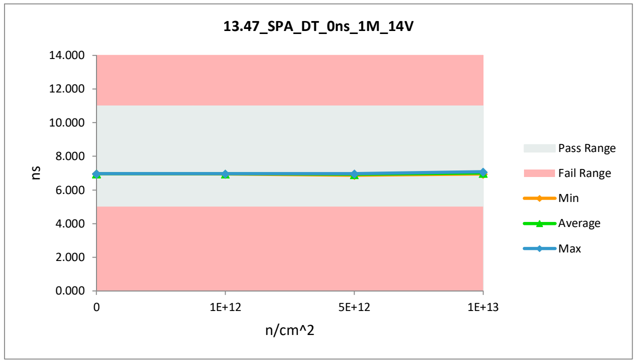


NDD Characterization Report
TPS7H5005-SEP

		13.47_SPA_DT_0ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	11	11	
	Min Limit	5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	6.150	6.977	0.827
1E+12	1	6.110	6.961	0.851
1E+12	2	6.114	6.980	0.866
1E+12	3	6.052	6.947	0.895
5E+12	4	5.988	6.883	0.895
5E+12	5	6.060	6.955	0.895
5E+12	6	6.097	6.975	0.878
1E+13	7	6.173	7.084	0.911
1E+13	8	6.104	6.958	0.854
1E+13	9	6.078	6.984	0.906
	Max	6.173	7.084	0.911
	Average	6.093	6.970	0.878
	Min	5.988	6.883	0.827
	Std Dev	0.052	0.049	0.027

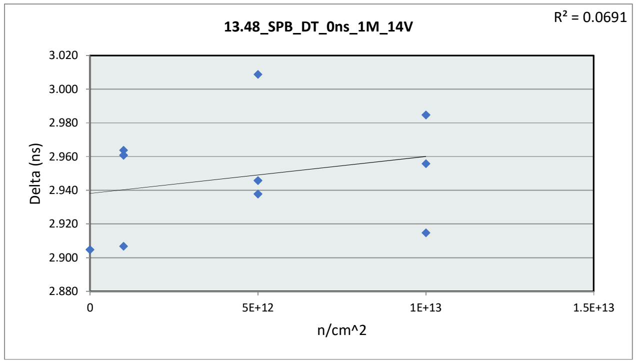


	13.47_SPA_DT_0ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	6.977	6.947	6.883	6.958
Average	6.977	6.963	6.938	7.009
Max	6.977	6.980	6.975	7.084
UL	11.000	11.000	11.000	11.000

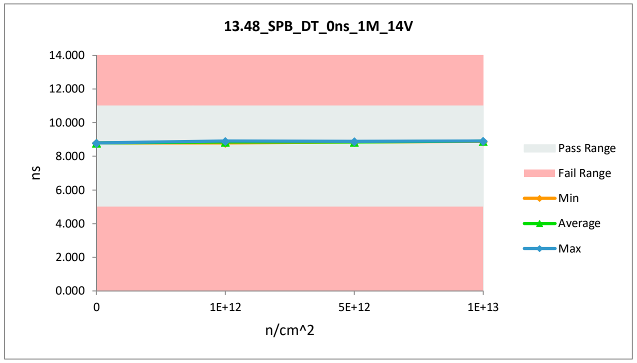


NDD Characterization Report
TPS7H5005-SEP

		13.48_SPB_DT_0ns_1M_14V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		11	11	
Min Limit		5	5	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	5.898	8.803	2.905
1E+12	1	5.936	8.900	2.964
1E+12	2	5.947	8.908	2.961
1E+12	3	5.884	8.791	2.907
5E+12	4	5.878	8.887	3.009
5E+12	5	5.907	8.853	2.946
5E+12	6	5.906	8.844	2.938
1E+13	7	6.000	8.915	2.915
1E+13	8	5.956	8.912	2.956
1E+13	9	5.900	8.885	2.985
	Max	6.000	8.915	3.009
	Average	5.921	8.870	2.949
	Min	5.878	8.791	2.905
	Std Dev	0.038	0.045	0.034

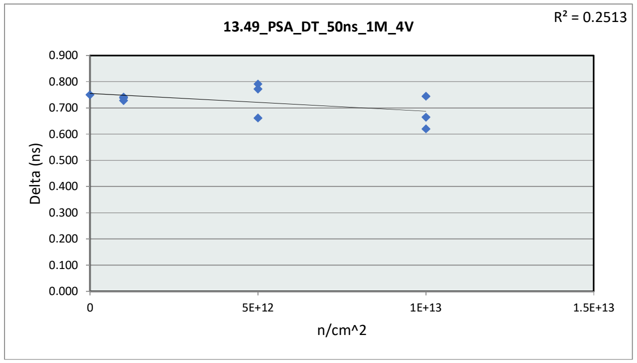


	13.48_SPB_DT_0ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	11	ns		
Min Limit	5	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	5.000	5.000	5.000	5.000
Min	8.803	8.791	8.844	8.885
Average	8.803	8.866	8.861	8.904
Max	8.803	8.908	8.887	8.915
UL	11.000	11.000	11.000	11.000

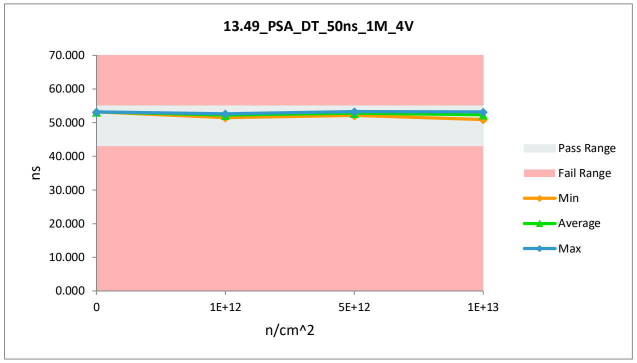


NDD Characterization Report
TPS7H5005-SEP

		13.49_PSA_DT_50ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	52.434	53.186	0.752
1E+12	1	51.836	52.575	0.739
1E+12	2	51.927	52.670	0.743
1E+12	3	50.757	51.487	0.730
5E+12	4	52.108	52.882	0.774
5E+12	5	51.393	52.186	0.793
5E+12	6	52.666	53.329	0.663
1E+13	7	52.228	52.894	0.666
1E+13	8	52.462	53.208	0.746
1E+13	9	50.336	50.957	0.621
	Max	52.666	53.329	0.793
	Average	51.815	52.537	0.723
	Min	50.336	50.957	0.621
	Std Dev	0.766	0.781	0.055

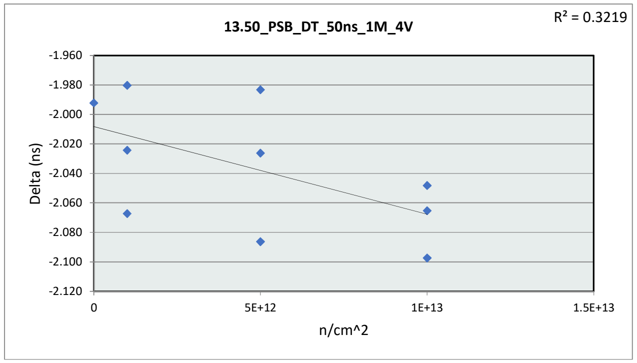


	13.49_PSA_DT_50ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	53.186	51.487	52.186	50.957
Average	53.186	52.244	52.799	52.353
Max	53.186	52.670	53.329	53.208
UL	55.000	55.000	55.000	55.000

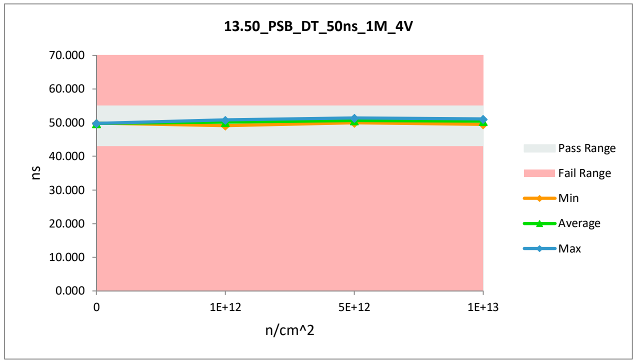


NDD Characterization Report
TPS7H5005-SEP

		13.50_PSB_DT_50ns_1M_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	51.818	49.826	-1.992
1E+12	1	52.883	50.816	-2.067
1E+12	2	52.608	50.584	-2.024
1E+12	3	51.057	49.077	-1.980
5E+12	4	52.727	50.701	-2.026
5E+12	5	51.927	49.944	-1.983
5E+12	6	53.508	51.422	-2.086
1E+13	7	53.152	51.104	-2.048
1E+13	8	52.898	50.833	-2.065
1E+13	9	51.596	49.499	-2.097
	Max	53.508	51.422	-1.980
	Average	52.417	50.381	-2.037
	Min	51.057	49.077	-2.097
	Std Dev	0.777	0.754	0.043

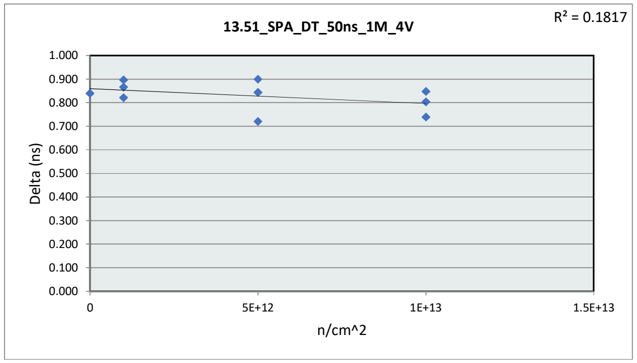


	13.50_PSB_DT_50ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	49.826	49.077	49.944	49.499
Average	49.826	50.159	50.689	50.479
Max	49.826	50.816	51.422	51.104
UL	55.000	55.000	55.000	55.000

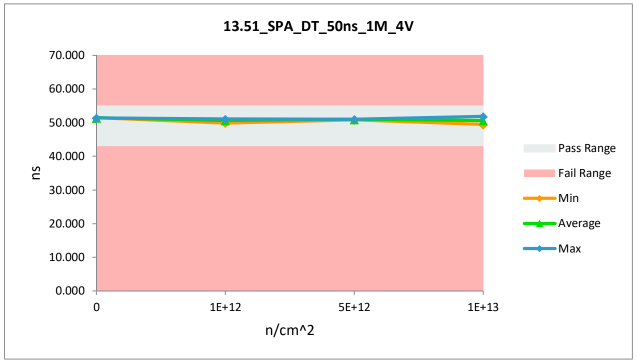


NDD Characterization Report
TPS7H5005-SEP

		13.51_SPA_DT_50ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	50.618	51.459	0.841
1E+12	1	50.079	50.902	0.823
1E+12	2	50.250	51.148	0.898
1E+12	3	49.021	49.889	0.868
5E+12	4	50.206	51.051	0.845
5E+12	5	50.157	51.058	0.901
5E+12	6	50.107	50.829	0.722
1E+13	7	49.847	50.588	0.741
1E+13	8	51.045	51.850	0.805
1E+13	9	48.614	49.463	0.849
	Max	51.045	51.850	0.901
	Average	49.994	50.824	0.829
	Min	48.614	49.463	0.722
	Std Dev	0.709	0.704	0.060

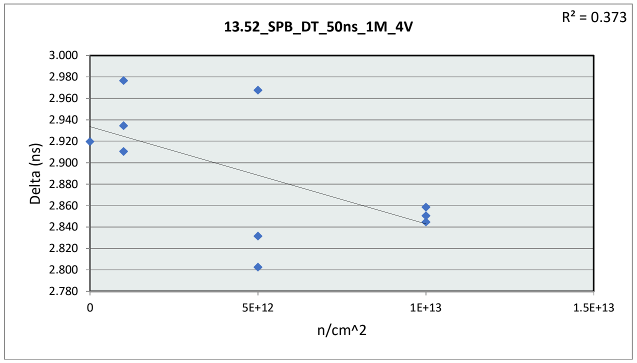


	13.51_SPA_DT_50ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	51.459	49.889	50.829	49.463
Average	51.459	50.646	50.979	50.634
Max	51.459	51.148	51.058	51.850
UL	55.000	55.000	55.000	55.000

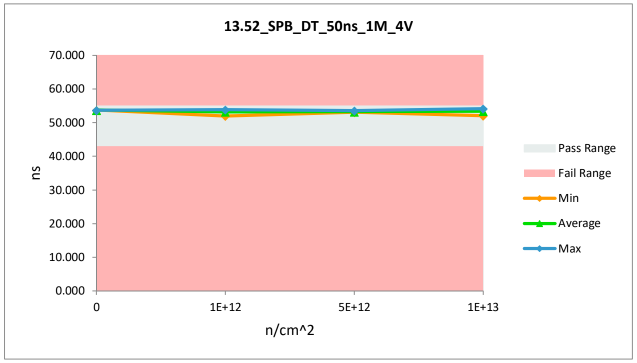


NDD Characterization Report
TPS7H5005-SEP

		13.52_SPB_DT_50ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	50.819	53.739	2.920
1E+12	1	50.926	53.903	2.977
1E+12	2	50.821	53.732	2.911
1E+12	3	49.057	51.992	2.935
5E+12	4	50.603	53.571	2.968
5E+12	5	50.238	53.070	2.832
5E+12	6	50.336	53.139	2.803
1E+13	7	51.160	54.019	2.859
1E+13	8	51.354	54.205	2.851
1E+13	9	49.247	52.092	2.845
	Max	51.354	54.205	2.977
	Average	50.456	53.346	2.890
	Min	49.057	51.992	2.803
	Std Dev	0.767	0.773	0.060

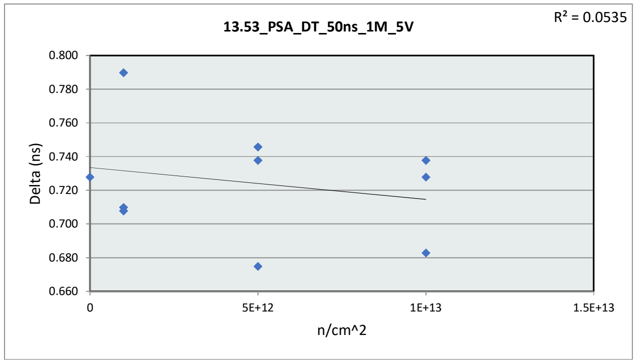


	13.52_SPB_DT_50ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	53.739	51.992	53.070	52.092
Average	53.739	53.209	53.260	53.439
Max	53.739	53.903	53.571	54.205
UL	55.000	55.000	55.000	55.000

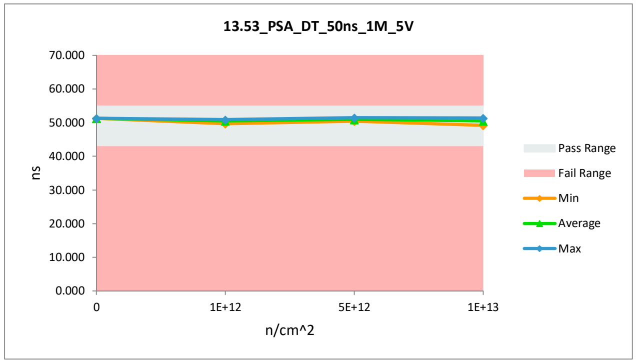


NDD Characterization Report
TPS7H5005-SEP

		13.53_PSA_DT_50ns_1M_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	50.618	51.346	0.728
1E+12	1	50.104	50.894	0.790
1E+12	2	50.195	50.903	0.708
1E+12	3	49.034	49.744	0.710
5E+12	4	50.257	51.003	0.746
5E+12	5	49.715	50.453	0.738
5E+12	6	50.809	51.484	0.675
1E+13	7	50.323	51.006	0.683
1E+13	8	50.635	51.373	0.738
1E+13	9	48.474	49.202	0.728
	Max	50.809	51.484	0.790
	Average	50.016	50.741	0.724
	Min	48.474	49.202	0.675
	Std Dev	0.745	0.742	0.033

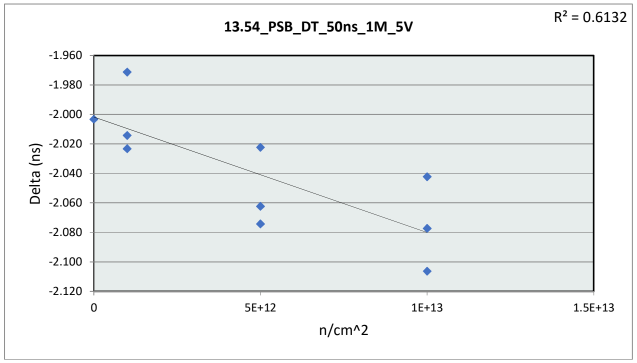


	13.53_PSA_DT_50ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	51.346	49.744	50.453	49.202
Average	51.346	50.514	50.980	50.527
Max	51.346	50.903	51.484	51.373
UL	55.000	55.000	55.000	55.000

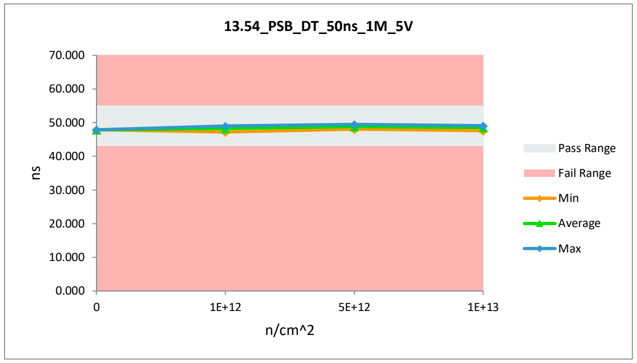


NDD Characterization Report
TPS7H5005-SEP

		13.54_PSB_DT_50ns_1M_5V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	49.930	47.927	-2.003
1E+12	1	51.012	48.998	-2.014
1E+12	2	50.707	48.736	-1.971
1E+12	3	49.217	47.194	-2.023
5E+12	4	50.965	48.943	-2.022
5E+12	5	50.157	48.095	-2.062
5E+12	6	51.549	49.475	-2.074
1E+13	7	51.147	49.105	-2.042
1E+13	8	51.036	48.959	-2.077
1E+13	9	49.711	47.605	-2.106
	Max	51.549	49.475	-1.971
	Average	50.543	48.504	-2.039
	Min	49.217	47.194	-2.106
	Std Dev	0.747	0.747	0.041

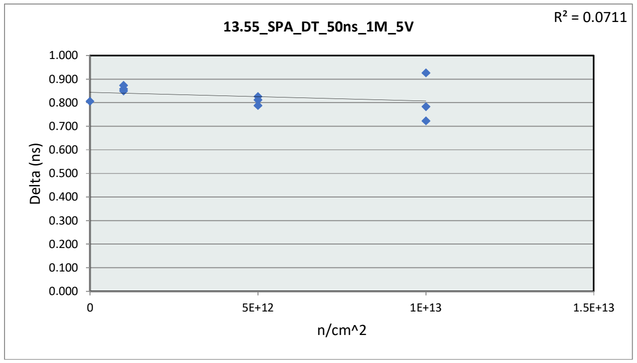


	13.54_PSB_DT_50ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	47.927	47.194	48.095	47.605
Average	47.927	48.309	48.838	48.556
Max	47.927	48.998	49.475	49.105
UL	55.000	55.000	55.000	55.000

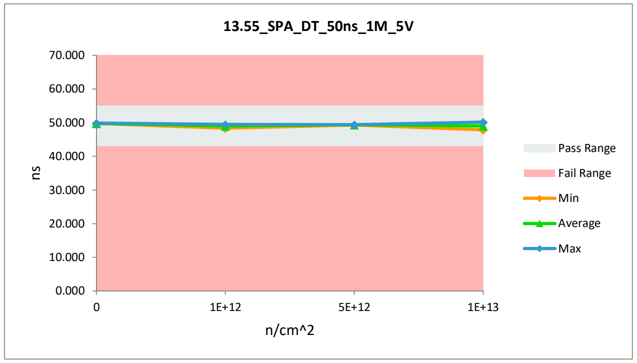


NDD Characterization Report
TPS7H5005-SEP

		13.55_SPA_DT_50ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	49.005	49.813	0.808
1E+12	1	48.470	49.322	0.852
1E+12	2	48.632	49.492	0.860
1E+12	3	47.507	48.382	0.875
5E+12	4	48.604	49.394	0.790
5E+12	5	48.539	49.367	0.828
5E+12	6	48.520	49.333	0.813
1E+13	7	48.253	49.038	0.785
1E+13	8	49.468	50.193	0.725
1E+13	9	46.949	47.877	0.928
	Max	49.468	50.193	0.928
	Average	48.395	49.221	0.826
	Min	46.949	47.877	0.725
	Std Dev	0.712	0.666	0.056

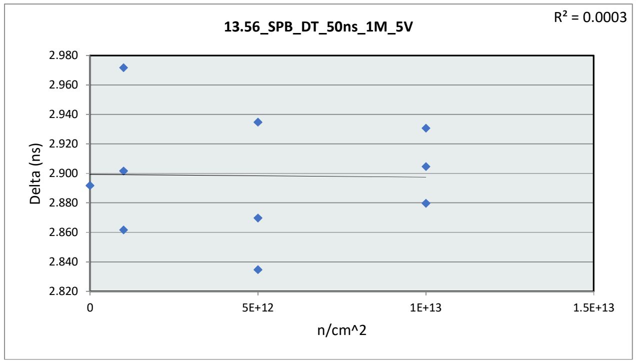


	13.55_SPA_DT_50ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	49.813	48.382	49.333	47.877
Average	49.813	49.065	49.365	49.036
Max	49.813	49.492	49.394	50.193
UL	55.000	55.000	55.000	55.000

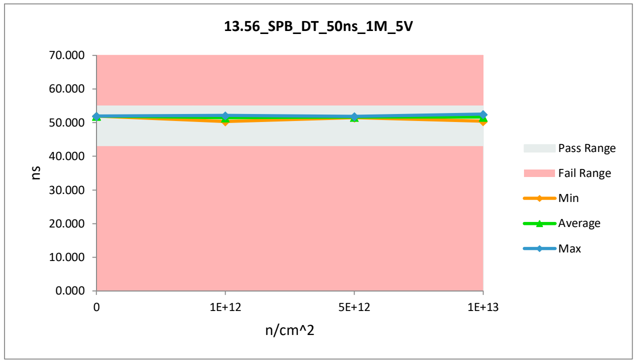


NDD Characterization Report
TPS7H5005-SEP

		13.56_SPB_DT_50ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	49.125	52.017	2.892
1E+12	1	49.280	52.142	2.862
1E+12	2	49.050	52.022	2.972
1E+12	3	47.452	50.354	2.902
5E+12	4	48.973	51.908	2.935
5E+12	5	48.609	51.479	2.870
5E+12	6	48.698	51.533	2.835
1E+13	7	49.364	52.244	2.880
1E+13	8	49.625	52.530	2.905
1E+13	9	47.503	50.434	2.931
	Max	49.625	52.530	2.972
	Average	48.768	51.666	2.898
	Min	47.452	50.354	2.835
	Std Dev	0.743	0.738	0.040

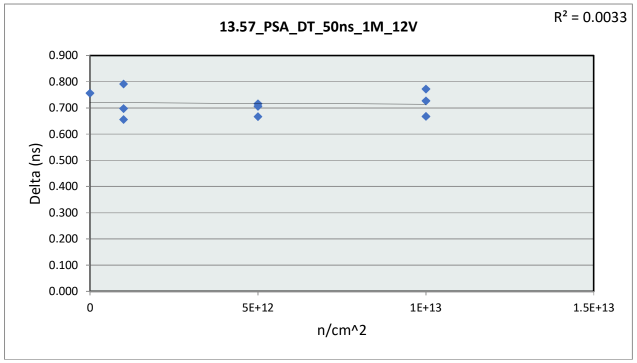


	13.56_SPB_DT_50ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	52.017	50.354	51.479	50.434
Average	52.017	51.506	51.640	51.736
Max	52.017	52.142	51.908	52.530
UL	55.000	55.000	55.000	55.000

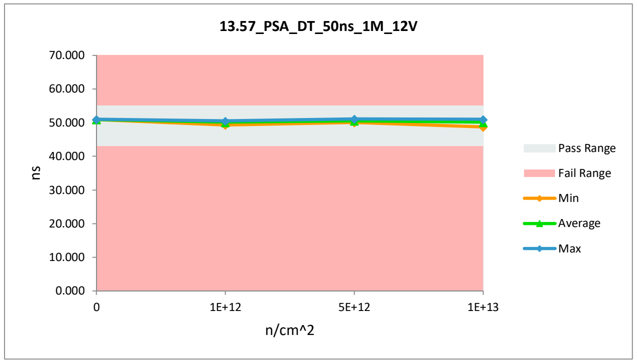


NDD Characterization Report
TPS7H5005-SEP

		13.57_PSA_DT_50ns_1M_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	50.199	50.957	0.758
1E+12	1	49.753	50.546	0.793
1E+12	2	49.823	50.522	0.699
1E+12	3	48.656	49.313	0.657
5E+12	4	49.919	50.587	0.668
5E+12	5	49.339	50.047	0.708
5E+12	6	50.430	51.147	0.717
1E+13	7	49.976	50.704	0.728
1E+13	8	50.210	50.984	0.774
1E+13	9	48.103	48.772	0.669
	Max	50.430	51.147	0.793
	Average	49.641	50.358	0.717
	Min	48.103	48.772	0.657
	Std Dev	0.739	0.768	0.047

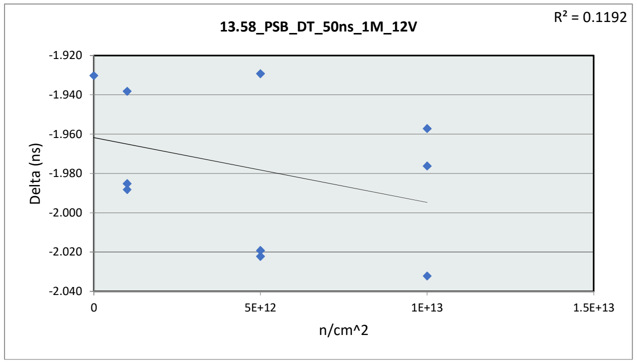


	13.57_PSA_DT_50ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	50.957	49.313	50.047	48.772
Average	50.957	50.127	50.594	50.153
Max	50.957	50.546	51.147	50.984
UL	55.000	55.000	55.000	55.000

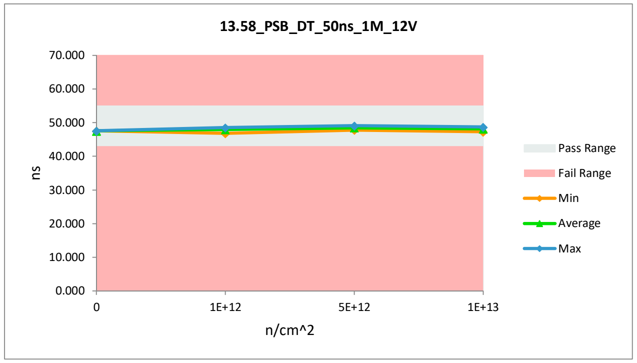


NDD Characterization Report
TPS7H5005-SEP

		13.58_PSB_DT_50ns_1M_12V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		55	55	
Min Limit		43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	49.487	47.557	-1.930
1E+12	1	50.597	48.609	-1.988
1E+12	2	50.316	48.378	-1.938
1E+12	3	48.814	46.829	-1.985
5E+12	4	50.620	48.598	-2.022
5E+12	5	49.756	47.827	-1.929
5E+12	6	51.100	49.081	-2.019
1E+13	7	50.705	48.673	-2.032
1E+13	8	50.577	48.620	-1.957
1E+13	9	49.237	47.261	-1.976
	Max	51.100	49.081	-1.929
	Average	50.121	48.143	-1.978
	Min	48.814	46.829	-2.032
	Std Dev	0.749	0.731	0.039



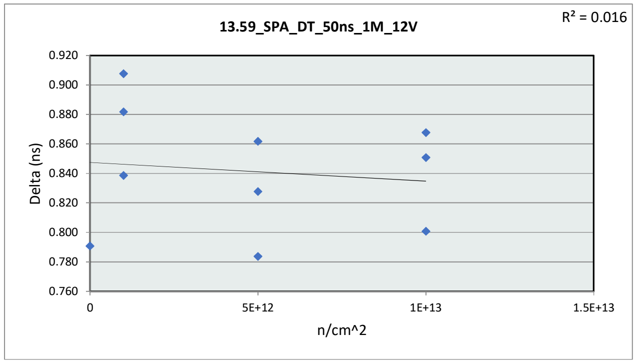
	13.58_PSB_DT_50ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	47.557	46.829	47.827	47.261
Average	47.557	47.939	48.502	48.185
Max	47.557	48.609	49.081	48.673
UL	55.000	55.000	55.000	55.000



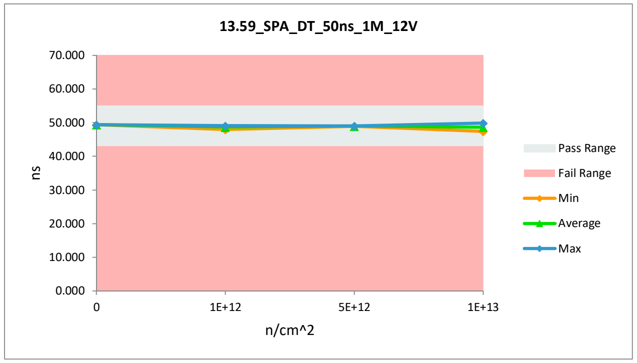
NDD Characterization Report
TPS7H5005-SEP

	13.59_SPA_DT_50ns_1M_12V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	55	55
Min Limit	43	43

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	48.595	49.386	0.791
1E+12	1	48.087	48.995	0.908
1E+12	2	48.199	49.081	0.882
1E+12	3	47.134	47.973	0.839
5E+12	4	48.192	49.054	0.862
5E+12	5	48.187	49.015	0.828
5E+12	6	48.118	48.902	0.784
1E+13	7	47.884	48.685	0.801
1E+13	8	49.032	49.900	0.868
1E+13	9	46.568	47.419	0.851
	Max	49.032	49.900	0.908
	Average	48.000	48.841	0.841
	Min	46.568	47.419	0.784
	Std Dev	0.697	0.698	0.041

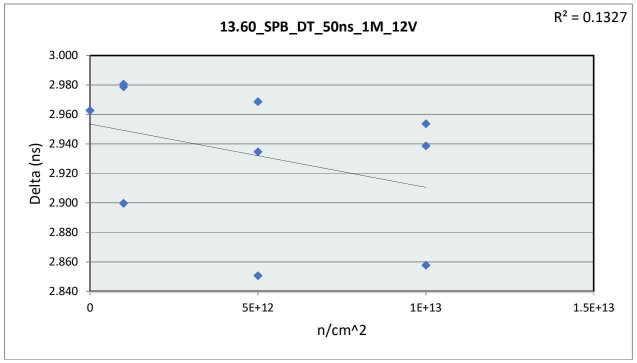


	13.59_SPA_DT_50ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	49.386	47.973	48.902	47.419
Average	49.386	48.683	48.990	48.668
Max	49.386	49.081	49.054	49.900
UL	55.000	55.000	55.000	55.000

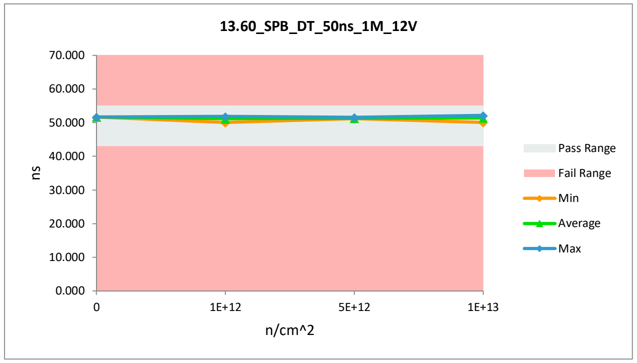


NDD Characterization Report
TPS7H5005-SEP

		13.60_SPB_DT_50ns_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	48.705	51.668	2.963
1E+12	1	48.844	51.823	2.979
1E+12	2	48.759	51.659	2.900
1E+12	3	47.056	50.037	2.981
5E+12	4	48.627	51.562	2.935
5E+12	5	48.215	51.184	2.969
5E+12	6	48.370	51.221	2.851
1E+13	7	48.978	51.917	2.939
1E+13	8	49.280	52.138	2.858
1E+13	9	47.130	50.084	2.954
	Max	49.280	52.138	2.981
	Average	48.396	51.329	2.933
	Min	47.056	50.037	2.851
	Std Dev	0.748	0.728	0.048

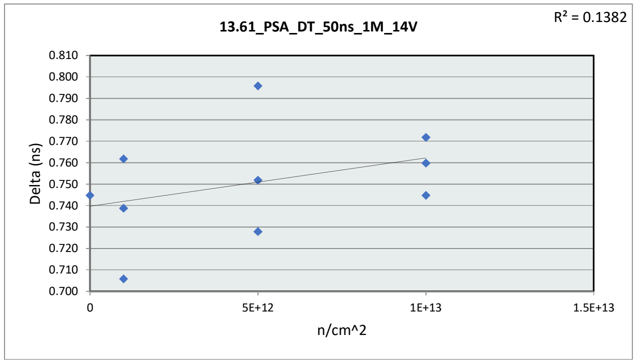


	13.60_SPB_DT_50ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	51.668	50.037	51.184	50.084
Average	51.668	51.173	51.322	51.380
Max	51.668	51.823	51.562	52.138
UL	55.000	55.000	55.000	55.000

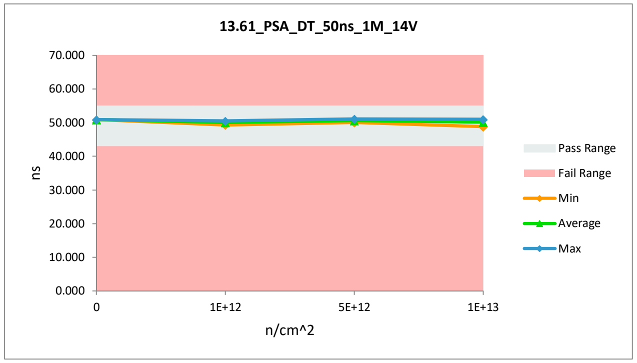


NDD Characterization Report
TPS7H5005-SEP

		13.61_PSA_DT_50ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	50.187	50.932	0.745
1E+12	1	49.801	50.507	0.706
1E+12	2	49.739	50.501	0.762
1E+12	3	48.615	49.354	0.739
5E+12	4	49.904	50.632	0.728
5E+12	5	49.298	50.094	0.796
5E+12	6	50.398	51.150	0.752
1E+13	7	49.958	50.703	0.745
1E+13	8	50.232	50.992	0.760
1E+13	9	48.033	48.805	0.772
	Max	50.398	51.150	0.796
	Average	49.616	50.367	0.751
	Min	48.033	48.805	0.706
	Std Dev	0.758	0.752	0.025

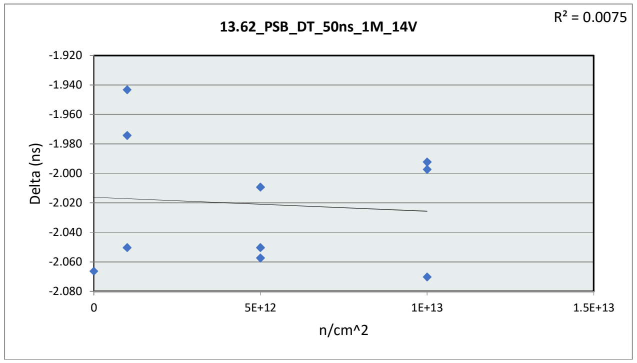


	13.61_PSA_DT_50ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	50.932	49.354	50.094	48.805
Average	50.932	50.121	50.625	50.167
Max	50.932	50.507	51.150	50.992
UL	55.000	55.000	55.000	55.000

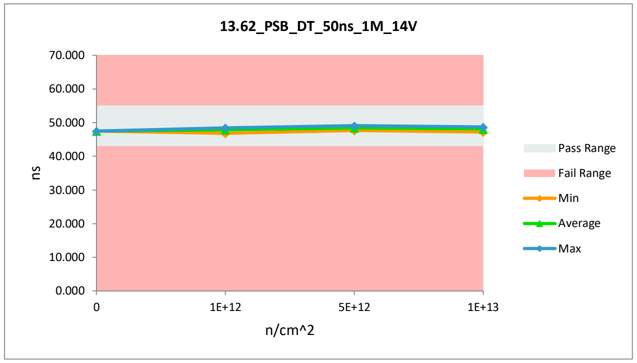


NDD Characterization Report
TPS7H5005-SEP

		13.62_PSB_DT_50ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	49.584	47.518	-2.066
1E+12	1	50.549	48.499	-2.050
1E+12	2	50.344	48.370	-1.974
1E+12	3	48.783	46.840	-1.943
5E+12	4	50.580	48.571	-2.009
5E+12	5	49.780	47.730	-2.050
5E+12	6	51.169	49.112	-2.057
1E+13	7	50.682	48.690	-1.992
1E+13	8	50.602	48.532	-2.070
1E+13	9	49.230	47.233	-1.997
	Max	51.169	49.112	-1.943
	Average	50.130	48.110	-2.021
	Min	48.783	46.840	-2.070
	Std Dev	0.751	0.732	0.044

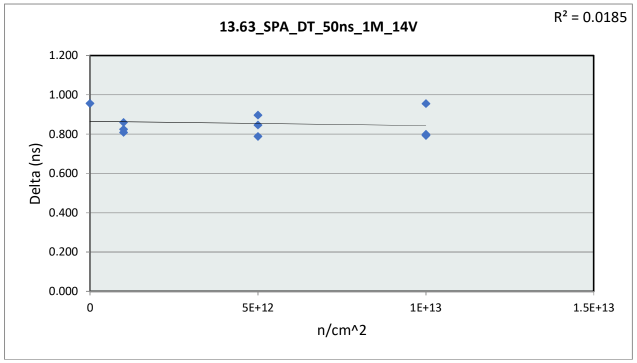


	13.62_PSB_DT_50ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	47.518	46.840	47.730	47.233
Average	47.518	47.903	48.471	48.152
Max	47.518	48.499	49.112	48.690
UL	55.000	55.000	55.000	55.000

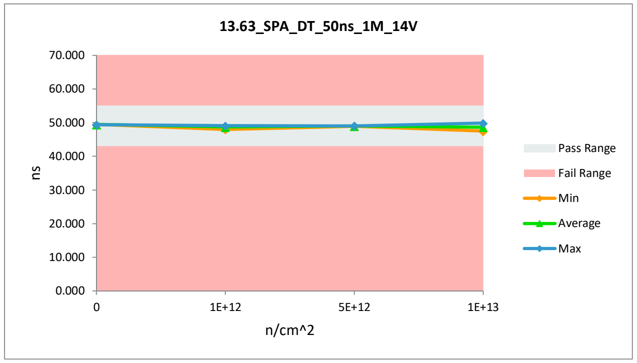


NDD Characterization Report
TPS7H5005-SEP

		13.63_SPA_DT_50ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	48.503	49.461	0.958
1E+12	1	48.100	48.962	0.862
1E+12	2	48.280	49.107	0.827
1E+12	3	47.140	47.951	0.811
5E+12	4	48.175	49.074	0.899
5E+12	5	48.186	49.034	0.848
5E+12	6	48.132	48.922	0.790
1E+13	7	47.874	48.669	0.795
1E+13	8	49.039	49.840	0.801
1E+13	9	46.510	47.467	0.957
	Max	49.039	49.840	0.958
	Average	47.994	48.849	0.855
	Min	46.510	47.467	0.790
	Std Dev	0.705	0.689	0.064

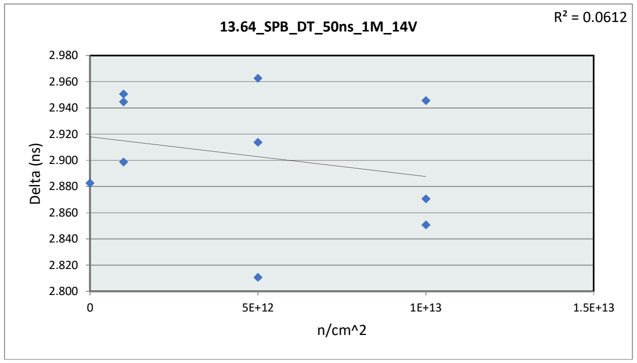


	13.63_SPA_DT_50ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	49.461	47.951	48.922	47.467
Average	49.461	48.673	49.010	48.659
Max	49.461	49.107	49.074	49.840
UL	55.000	55.000	55.000	55.000

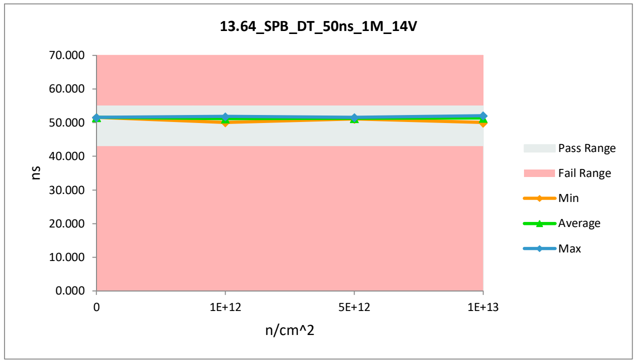


NDD Characterization Report
TPS7H5005-SEP

		13.64_SPB_DT_50ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	55	55	
	Min Limit	43	43	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	48.732	51.615	2.883
1E+12	1	48.885	51.830	2.945
1E+12	2	48.746	51.697	2.951
1E+12	3	47.144	50.043	2.899
5E+12	4	48.625	51.588	2.963
5E+12	5	48.236	51.150	2.914
5E+12	6	48.377	51.188	2.811
1E+13	7	48.984	51.930	2.946
1E+13	8	49.262	52.113	2.851
1E+13	9	47.159	50.030	2.871
	Max	49.262	52.113	2.963
	Average	48.415	51.318	2.903
	Min	47.144	50.030	2.811
	Std Dev	0.726	0.738	0.050

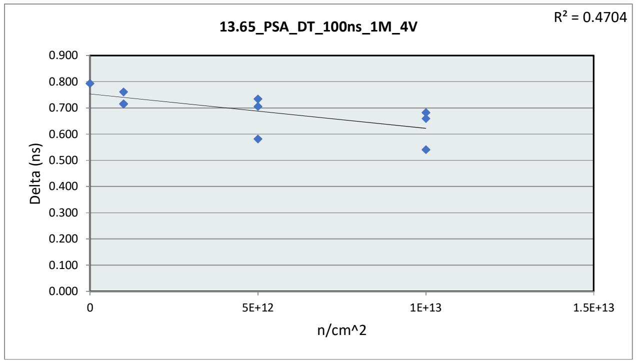


	13.64_SPB_DT_50ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	55	ns		
Min Limit	43	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	43.000	43.000	43.000	43.000
Min	51.615	50.043	51.150	50.030
Average	51.615	51.190	51.309	51.358
Max	51.615	51.830	51.588	52.113
UL	55.000	55.000	55.000	55.000

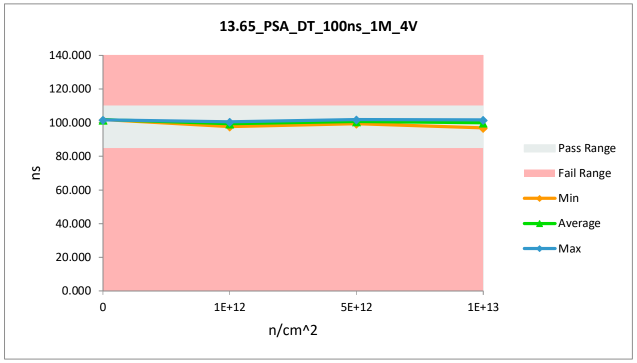


NDD Characterization Report
TPS7H5005-SEP

		13.65_PSA_DT_100ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	100.993	101.788	0.795
1E+12	1	99.430	100.147	0.717
1E+12	2	99.714	100.477	0.763
1E+12	3	97.058	97.774	0.716
5E+12	4	100.217	100.924	0.707
5E+12	5	98.708	99.444	0.736
5E+12	6	101.320	101.903	0.583
1E+13	7	100.539	101.200	0.661
1E+13	8	100.911	101.595	0.684
1E+13	9	96.331	96.873	0.542
	Max	101.320	101.903	0.795
	Average	99.522	100.213	0.690
	Min	96.331	96.873	0.542
	Std Dev	1.693	1.716	0.078

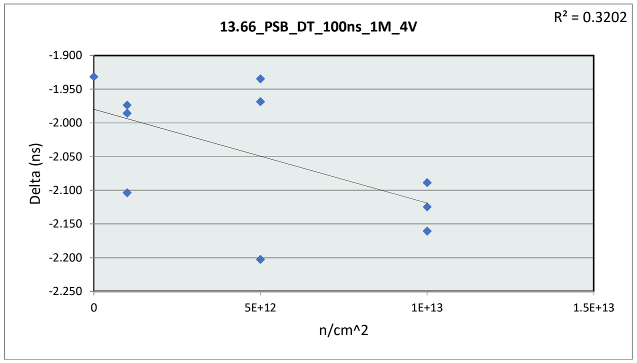


	13.65_PSA_DT_100ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	101.788	97.774	99.444	96.873
Average	101.788	99.466	100.757	99.889
Max	101.788	100.477	101.903	101.595
UL	110.000	110.000	110.000	110.000

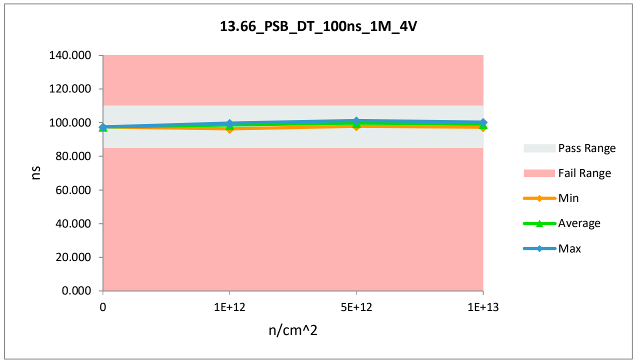


NDD Characterization Report
TPS7H5005-SEP

		13.66_PSB_DT_100ns_1M_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		110	110	
Min Limit		85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	99.404	97.473	-1.931
1E+12	1	101.923	99.820	-2.103
1E+12	2	101.527	99.542	-1.985
1E+12	3	98.240	96.267	-1.973
5E+12	4	101.979	100.045	-1.934
5E+12	5	99.873	97.905	-1.968
5E+12	6	103.429	101.227	-2.202
1E+13	7	102.454	100.366	-2.088
1E+13	8	101.679	99.555	-2.124
1E+13	9	99.458	97.298	-2.160
	Max	103.429	101.227	-1.931
	Average	100.997	98.950	-2.047
	Min	98.240	96.267	-2.202
	Std Dev	1.646	1.601	0.100

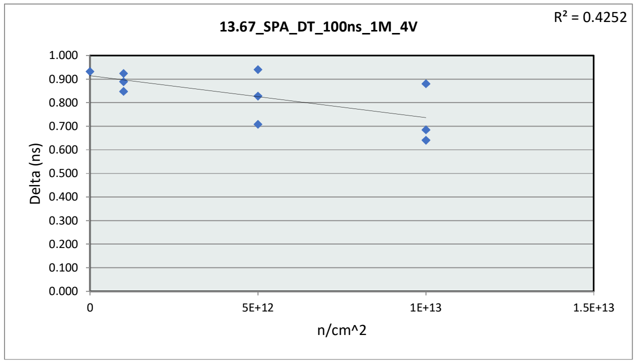


	13.66_PSB_DT_100ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	97.473	96.267	97.905	97.298
Average	97.473	98.543	99.726	99.073
Max	97.473	99.820	101.227	100.366
UL	110.000	110.000	110.000	110.000

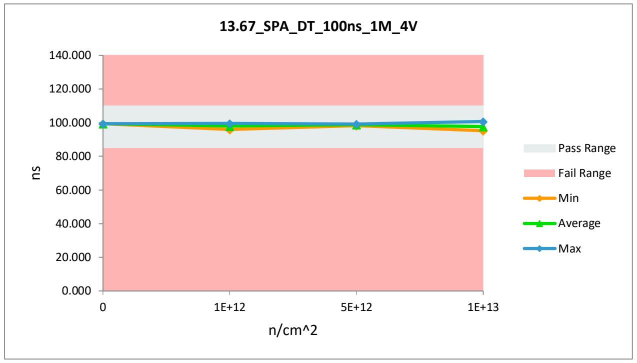


NDD Characterization Report
TPS7H5005-SEP

		13.67_SPA_DT_100ns_1M_4V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	98.461	99.395	0.934
1E+12	1	97.487	98.413	0.926
1E+12	2	98.719	99.568	0.849
1E+12	3	95.028	95.919	0.891
5E+12	4	98.449	99.279	0.830
5E+12	5	98.084	99.026	0.942
5E+12	6	97.553	98.263	0.710
1E+13	7	96.471	97.113	0.642
1E+13	8	100.063	100.749	0.686
1E+13	9	94.357	95.239	0.882
	Max	100.063	100.749	0.942
	Average	97.467	98.296	0.829
	Min	94.357	95.239	0.642
	Std Dev	1.740	1.724	0.110

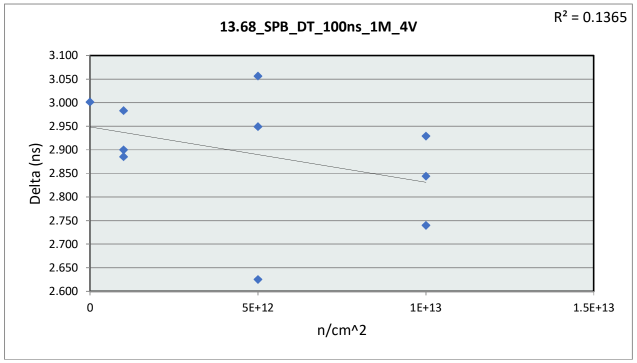


	13.67_SPA_DT_100ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	99.395	95.919	98.263	95.239
Average	99.395	97.967	98.856	97.700
Max	99.395	99.568	99.279	100.749
UL	110.000	110.000	110.000	110.000

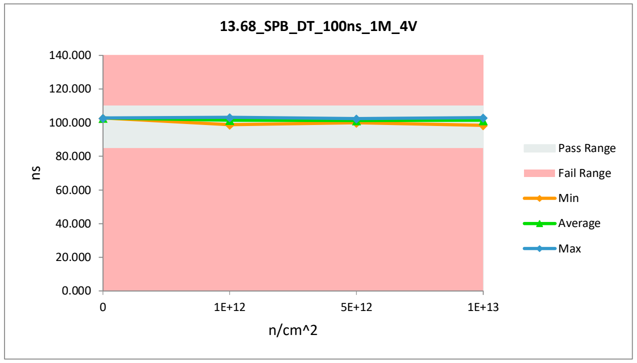


NDD Characterization Report
TPS7H5005-SEP

		13.68_SPB_DT_100ns_1M_4V		
Test Site				
Tester				
Test Number				
Unit		ns	ns	
Max Limit		110	110	
Min Limit		85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	99.759	102.761	3.002
1E+12	1	100.156	103.140	2.984
1E+12	2	99.735	102.636	2.901
1E+12	3	95.845	98.731	2.886
5E+12	4	99.464	102.414	2.950
5E+12	5	98.473	101.530	3.057
5E+12	6	97.322	99.948	2.626
1E+13	7	99.965	102.706	2.741
1E+13	8	100.160	103.005	2.845
1E+13	9	95.550	98.480	2.930
	Max	100.160	103.140	3.057
	Average	98.643	101.535	2.892
	Min	95.550	98.480	2.626
	Std Dev	1.783	1.805	0.128

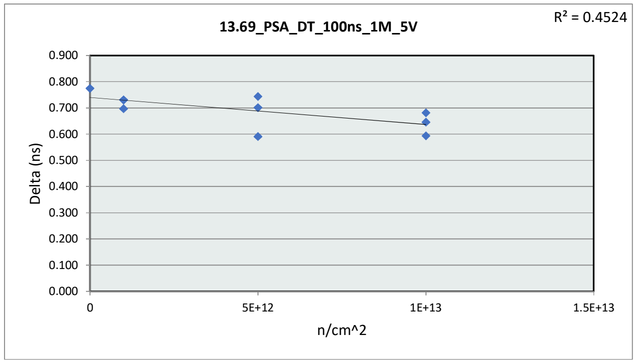


	13.68_SPB_DT_100ns_1M_4V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	102.761	98.731	99.948	98.480
Average	102.761	101.502	101.297	101.397
Max	102.761	103.140	102.414	103.005
UL	110.000	110.000	110.000	110.000

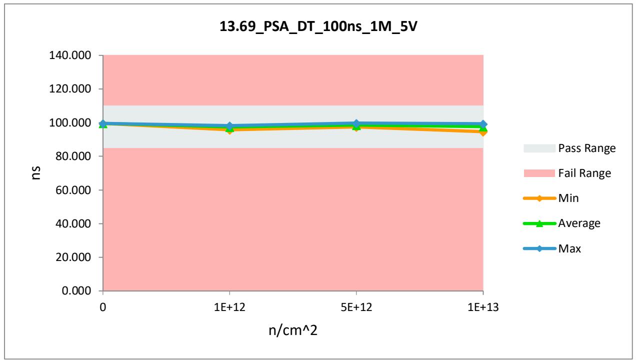


NDD Characterization Report
TPS7H5005-SEP

		13.69_PSA_DT_100ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	98.838	99.614	0.776
1E+12	1	97.407	98.139	0.732
1E+12	2	97.571	98.269	0.698
1E+12	3	95.043	95.775	0.732
5E+12	4	97.928	98.673	0.745
5E+12	5	96.641	97.344	0.703
5E+12	6	99.088	99.680	0.592
1E+13	7	98.206	98.889	0.683
1E+13	8	98.667	99.314	0.647
1E+13	9	94.018	94.613	0.595
	Max	99.088	99.680	0.776
	Average	97.341	98.031	0.690
	Min	94.018	94.613	0.592
	Std Dev	1.667	1.678	0.062

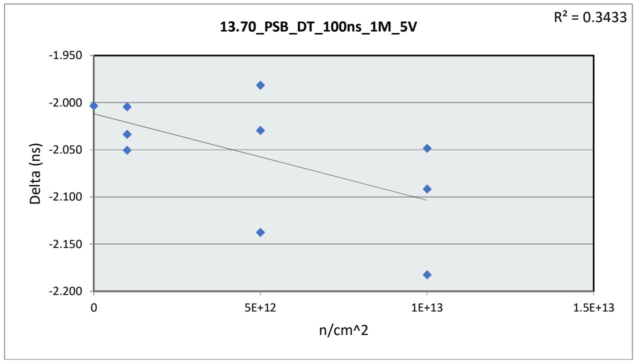


	13.69_PSA_DT_100ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	99.614	95.775	97.344	94.613
Average	99.614	97.394	98.566	97.605
Max	99.614	98.269	99.680	99.314
UL	110.000	110.000	110.000	110.000

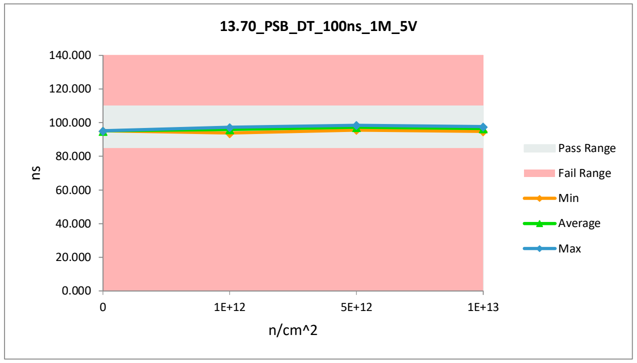


NDD Characterization Report
TPS7H5005-SEP

		13.70_PSB_DT_100ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	97.135	95.132	-2.003
1E+12	1	99.295	97.262	-2.033
1E+12	2	99.074	97.024	-2.050
1E+12	3	95.802	93.798	-2.004
5E+12	4	99.800	97.771	-2.029
5E+12	5	97.621	95.640	-1.981
5E+12	6	100.653	98.516	-2.137
1E+13	7	99.656	97.608	-2.048
1E+13	8	99.346	97.255	-2.091
1E+13	9	97.031	94.849	-2.182
	Max	100.653	98.516	-1.981
	Average	98.541	96.486	-2.056
	Min	95.802	93.798	-2.182
	Std Dev	1.542	1.526	0.063



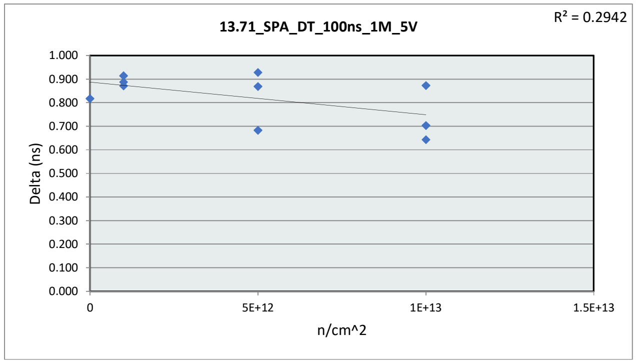
	13.70_PSB_DT_100ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	95.132	93.798	95.640	94.849
Average	95.132	96.028	97.309	96.571
Max	95.132	97.262	98.516	97.608
UL	110.000	110.000	110.000	110.000



NDD Characterization Report
TPS7H5005-SEP

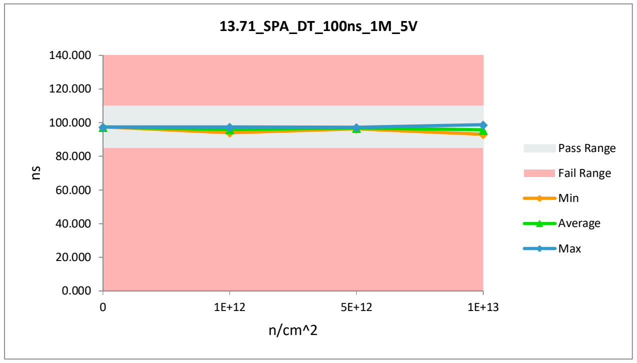
	13.71_SPA_DT_100ns_1M_5V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	110	110
Min Limit	85	85

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	96.583	97.402	0.819
1E+12	1	95.605	96.521	0.916
1E+12	2	96.644	97.533	0.889
1E+12	3	93.239	94.112	0.873
5E+12	4	96.382	97.252	0.870
5E+12	5	96.079	97.009	0.930
5E+12	6	95.637	96.322	0.685
1E+13	7	94.549	95.194	0.645
1E+13	8	98.110	98.815	0.705
1E+13	9	92.248	93.122	0.874
	Max	98.110	98.815	0.930
	Average	95.508	96.328	0.821
	Min	92.248	93.122	0.645
	Std Dev	1.733	1.720	0.103



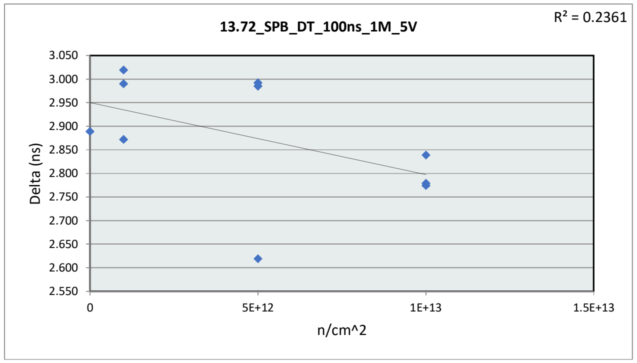
	13.71_SPA_DT_100ns_1M_5V	
Test Site		
Tester		
Test Number		
Max Limit	110	ns
Min Limit	85	ns

n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	97.402	94.112	96.322	93.122
Average	97.402	96.055	96.861	95.710
Max	97.402	97.533	97.252	98.815
UL	110.000	110.000	110.000	110.000

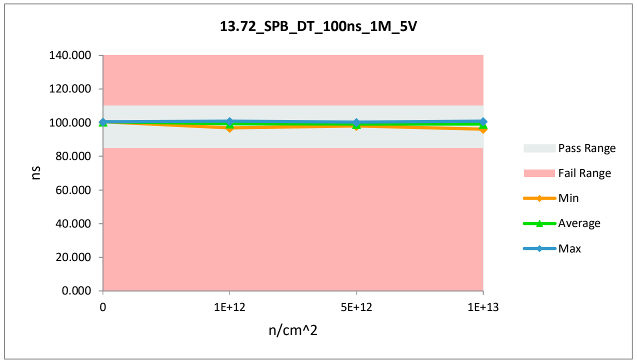


NDD Characterization Report
TPS7H5005-SEP

		13.72_SPB_DT_100ns_1M_5V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	97.679	100.569	2.890
1E+12	1	97.968	100.988	3.020
1E+12	2	97.423	100.296	2.873
1E+12	3	93.821	96.812	2.991
5E+12	4	97.393	100.379	2.986
5E+12	5	96.504	99.497	2.993
5E+12	6	95.300	97.920	2.620
1E+13	7	97.720	100.500	2.780
1E+13	8	98.061	100.836	2.775
1E+13	9	93.381	96.221	2.840
	Max	98.061	100.988	3.020
	Average	96.525	99.402	2.877
	Min	93.381	96.221	2.620
	Std Dev	1.747	1.761	0.127



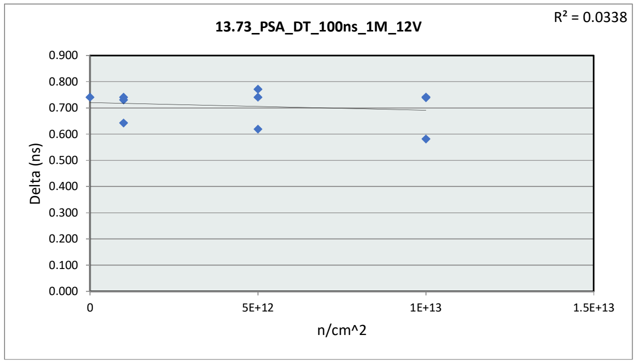
	13.72_SPB_DT_100ns_1M_5V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	100.569	96.812	97.920	96.221
Average	100.569	99.365	99.265	99.186
Max	100.569	100.988	100.379	100.836
UL	110.000	110.000	110.000	110.000



NDD Characterization Report
TPS7H5005-SEP

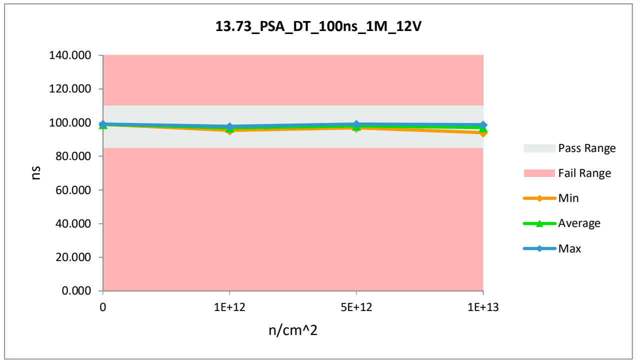
	13.73_PSA_DT_100ns_1M_12V	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	110	110
Min Limit	85	85

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	98.360	99.102	0.742
1E+12	1	96.976	97.718	0.742
1E+12	2	97.199	97.843	0.644
1E+12	3	94.580	95.312	0.732
5E+12	4	97.428	98.170	0.742
5E+12	5	96.179	96.952	0.773
5E+12	6	98.552	99.173	0.621
1E+13	7	97.725	98.466	0.741
1E+13	8	98.172	98.915	0.743
1E+13	9	93.542	94.125	0.583
	Max	98.552	99.173	0.773
	Average	96.871	97.578	0.706
	Min	93.542	94.125	0.583
	Std Dev	1.657	1.678	0.065



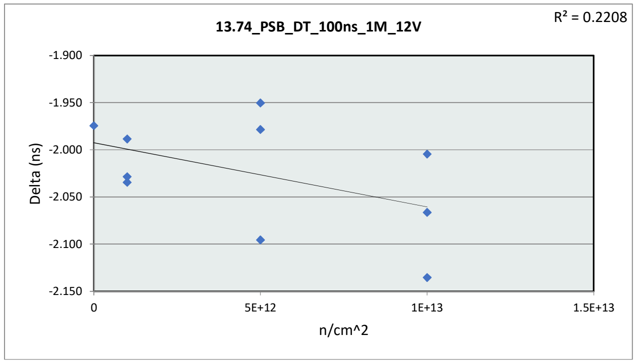
	13.73_PSA_DT_100ns_1M_12	
Test Site		
Tester		
Test Number		
Max Limit	110	ns
Min Limit	85	ns

n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	99.102	95.312	96.952	94.125
Average	99.102	96.958	98.098	97.169
Max	99.102	97.843	99.173	98.915
UL	110.000	110.000	110.000	110.000

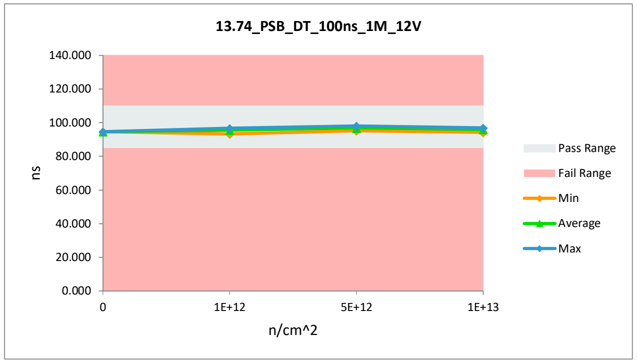


NDD Characterization Report
TPS7H5005-SEP

		13.74_PSB_DT_100ns_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	96.605	94.631	-1.974
1E+12	1	98.728	96.700	-2.028
1E+12	2	98.637	96.649	-1.988
1E+12	3	95.325	93.291	-2.034
5E+12	4	99.254	97.304	-1.950
5E+12	5	97.177	95.199	-1.978
5E+12	6	100.125	98.030	-2.095
1E+13	7	98.994	96.990	-2.004
1E+13	8	98.850	96.784	-2.066
1E+13	9	96.345	94.210	-2.135
	Max	100.125	98.030	-1.950
	Average	98.004	95.979	-2.025
	Min	95.325	93.291	-2.135
	Std Dev	1.537	1.541	0.059

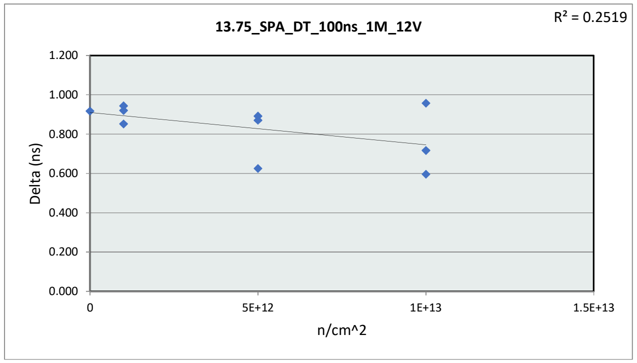


	13.74_PSB_DT_100ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	94.631	93.291	95.199	94.210
Average	94.631	95.547	96.844	95.995
Max	94.631	96.700	98.030	96.990
UL	110.000	110.000	110.000	110.000

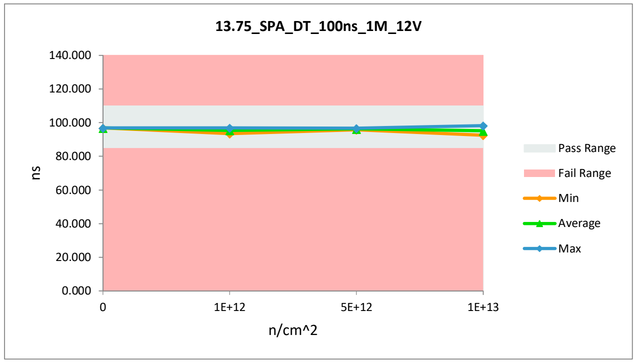


NDD Characterization Report
TPS7H5005-SEP

		13.75_SPA_DT_100ns_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	95.959	96.878	0.919
1E+12	1	95.045	95.991	0.946
1E+12	2	96.060	96.982	0.922
1E+12	3	92.713	93.567	0.854
5E+12	4	95.809	96.681	0.872
5E+12	5	95.593	96.487	0.894
5E+12	6	95.131	95.758	0.627
1E+13	7	93.996	94.594	0.598
1E+13	8	97.559	98.278	0.719
1E+13	9	91.590	92.549	0.959
	Max	97.559	98.278	0.959
	Average	94.945	95.777	0.831
	Min	91.590	92.549	0.598
	Std Dev	1.747	1.732	0.133

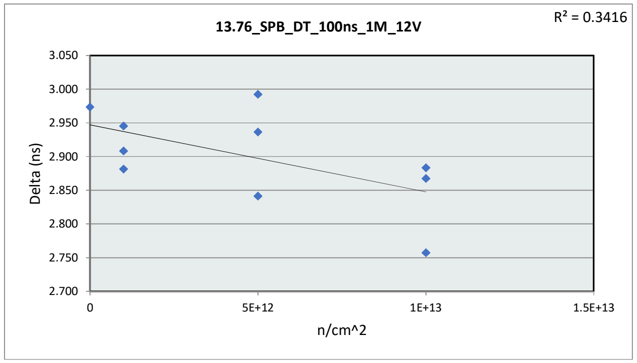


	13.75_SPA_DT_100ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	96.878	93.567	95.758	92.549
Average	96.878	95.513	96.309	95.140
Max	96.878	96.982	96.681	98.278
UL	110.000	110.000	110.000	110.000

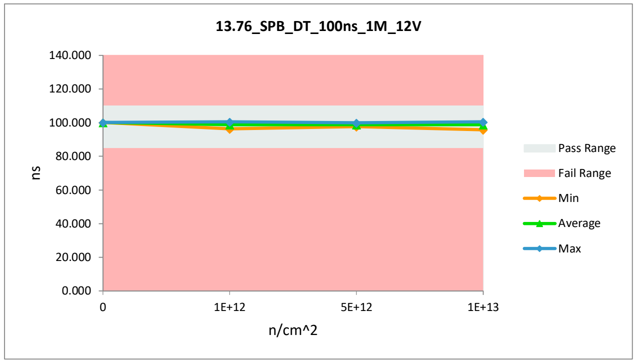


NDD Characterization Report
TPS7H5005-SEP

		13.76_SPB_DT_100ns_1M_12V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	97.149	100.123	2.974
1E+12	1	97.542	100.488	2.946
1E+12	2	96.980	99.889	2.909
1E+12	3	93.428	96.310	2.882
5E+12	4	96.929	99.866	2.937
5E+12	5	96.086	99.079	2.993
5E+12	6	94.757	97.599	2.842
1E+13	7	97.220	99.978	2.758
1E+13	8	97.588	100.456	2.868
1E+13	9	92.908	95.792	2.884
	Max	97.588	100.488	2.993
	Average	96.059	98.958	2.899
	Min	92.908	95.792	2.758
	Std Dev	1.739	1.750	0.069

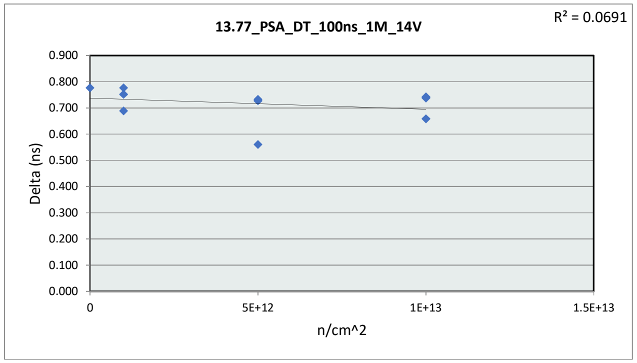


	13.76_SPB_DT_100ns_1M_12V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	100.123	96.310	97.599	95.792
Average	100.123	98.896	98.848	98.742
Max	100.123	100.488	99.866	100.456
UL	110.000	110.000	110.000	110.000

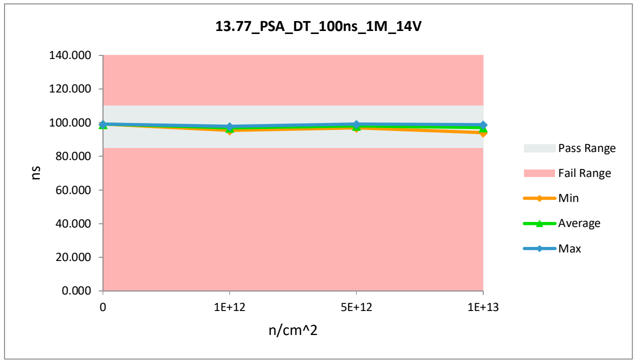


NDD Characterization Report
TPS7H5005-SEP

		13.77_PSA_DT_100ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	98.364	99.142	0.778
1E+12	1	96.990	97.743	0.753
1E+12	2	97.161	97.851	0.690
1E+12	3	94.534	95.312	0.778
5E+12	4	97.411	98.140	0.729
5E+12	5	96.173	96.907	0.734
5E+12	6	98.554	99.116	0.562
1E+13	7	97.723	98.462	0.739
1E+13	8	98.166	98.910	0.744
1E+13	9	93.476	94.136	0.660
	Max	98.554	99.142	0.778
	Average	96.855	97.572	0.717
	Min	93.476	94.136	0.562
	Std Dev	1.678	1.674	0.065

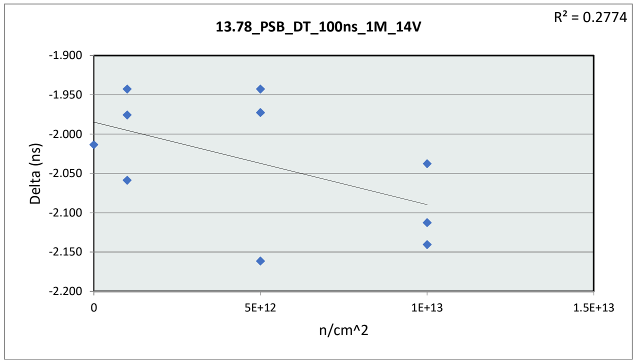


	13.77_PSA_DT_100ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	99.142	95.312	96.907	94.136
Average	99.142	96.969	98.054	97.169
Max	99.142	97.851	99.116	98.910
UL	110.000	110.000	110.000	110.000

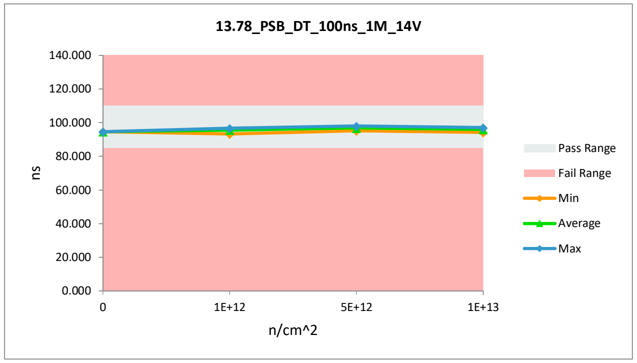


NDD Characterization Report
TPS7H5005-SEP

		13.78_PSB_DT_100ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	96.698	94.685	-2.013
1E+12	1	98.783	96.725	-2.058
1E+12	2	98.570	96.628	-1.942
1E+12	3	95.277	93.302	-1.975
5E+12	4	99.239	97.297	-1.942
5E+12	5	97.214	95.242	-1.972
5E+12	6	100.125	97.964	-2.161
1E+13	7	99.101	97.064	-2.037
1E+13	8	98.855	96.743	-2.112
1E+13	9	96.339	94.199	-2.140
	Max	100.125	97.964	-1.942
	Average	98.020	95.985	-2.035
	Min	95.277	93.302	-2.161
	Std Dev	1.543	1.526	0.081

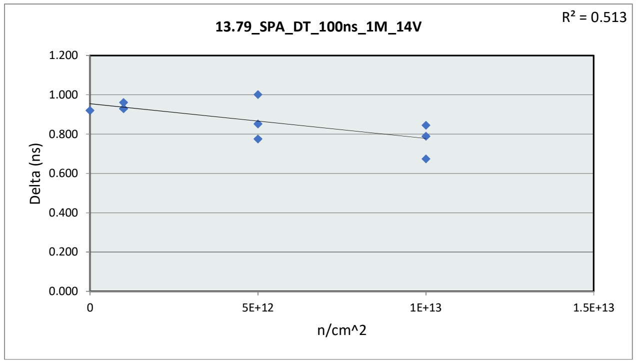


	13.78_PSB_DT_100ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	94.685	93.302	95.242	94.199
Average	94.685	95.552	96.834	96.002
Max	94.685	96.725	97.964	97.064
UL	110.000	110.000	110.000	110.000

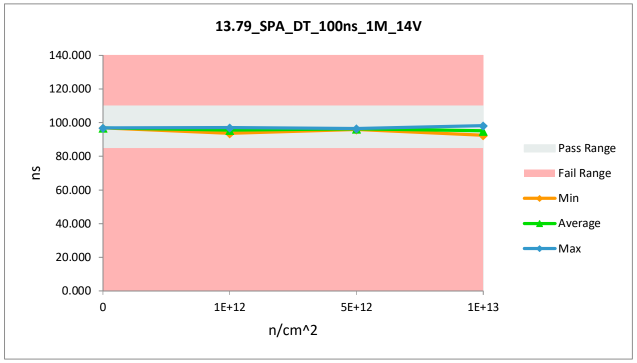


NDD Characterization Report
TPS7H5005-SEP

		13.79_SPA_DT_100ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	95.999	96.921	0.922
1E+12	1	95.049	95.980	0.931
1E+12	2	96.078	97.041	0.963
1E+12	3	92.684	93.617	0.933
5E+12	4	95.776	96.630	0.854
5E+12	5	95.532	96.535	1.003
5E+12	6	95.116	95.894	0.778
1E+13	7	93.976	94.652	0.676
1E+13	8	97.515	98.306	0.791
1E+13	9	91.684	92.531	0.847
	Max	97.515	98.306	1.003
	Average	94.941	95.811	0.870
	Min	91.684	92.531	0.676
	Std Dev	1.724	1.736	0.100

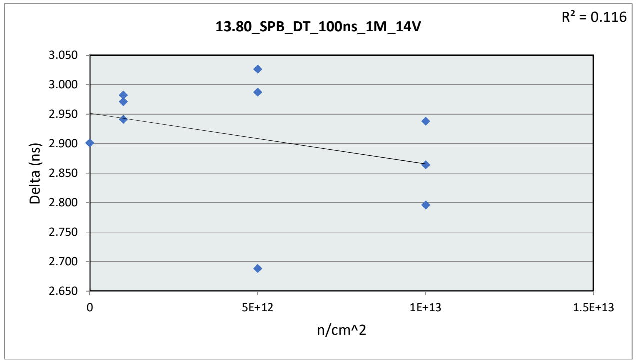


	13.79_SPA_DT_100ns_1M_14			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	96.921	93.617	95.894	92.531
Average	96.921	95.546	96.353	95.163
Max	96.921	97.041	96.630	98.306
UL	110.000	110.000	110.000	110.000

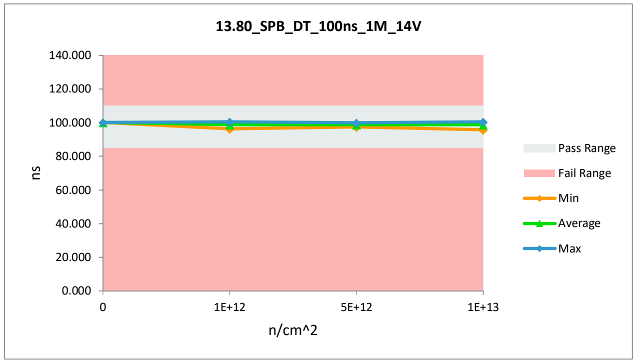


NDD Characterization Report
TPS7H5005-SEP

		13.80_SPB_DT_100ns_1M_14V		
	Test Site			
	Tester			
	Test Number			
	Unit	ns	ns	
	Max Limit	110	110	
	Min Limit	85	85	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	97.186	100.088	2.902
1E+12	1	97.544	100.516	2.972
1E+12	2	96.997	99.980	2.983
1E+12	3	93.338	96.280	2.942
5E+12	4	96.895	99.922	3.027
5E+12	5	96.083	99.071	2.988
5E+12	6	94.784	97.473	2.689
1E+13	7	97.176	99.973	2.797
1E+13	8	97.512	100.451	2.939
1E+13	9	92.900	95.765	2.865
	Max	97.544	100.516	3.027
	Average	96.041	98.952	2.910
	Min	92.900	95.765	2.689
	Std Dev	1.745	1.780	0.102



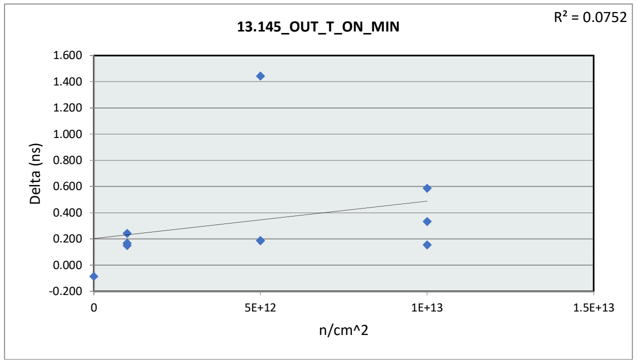
	13.80_SPB_DT_100ns_1M_14V			
Test Site				
Tester				
Test Number				
Max Limit	110	ns		
Min Limit	85	ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL	85.000	85.000	85.000	85.000
Min	100.088	96.280	97.473	95.765
Average	100.088	98.925	98.822	98.730
Max	100.088	100.516	99.922	100.451
UL	110.000	110.000	110.000	110.000



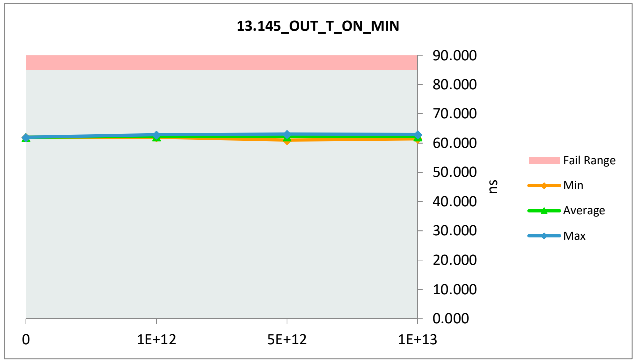
NDD Characterization Report
TPS7H5005-SEP

	13.145_OUT_T_ON_MIN	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	85	85
Min Limit		

n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	62.086	62.003	-0.083
1E+12	1	61.797	61.968	0.171
1E+12	2	62.601	62.846	0.245
1E+12	3	61.962	62.116	0.154
5E+12	4	62.457	62.648	0.191
5E+12	5	60.794	60.984	0.190
5E+12	6	61.642	63.088	1.446
1E+13	7	62.586	62.923	0.337
1E+13	8	61.797	62.387	0.590
1E+13	9	61.305	61.462	0.157
	Max	62.601	63.088	1.446
	Average	61.903	62.243	0.340
	Min	60.794	60.984	-0.083
	Std Dev	0.575	0.672	0.424

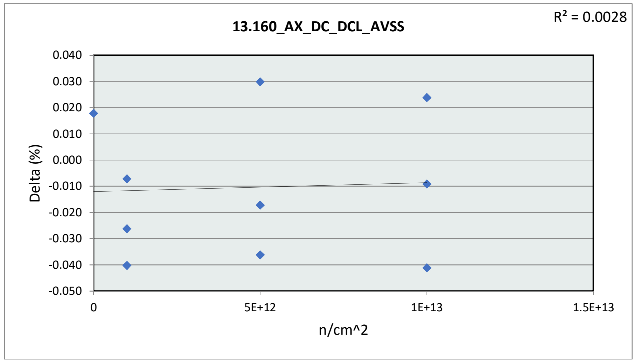


	13.145_OUT_T_ON_MIN			
Test Site				
Tester				
Test Number				
Max Limit	85	ns		
Min Limit		ns		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	62.003	61.968	60.984	61.462
Average	62.003	62.310	62.240	62.257
Max	62.003	62.846	63.088	62.923
UL	85.000	85.000	85.000	85.000

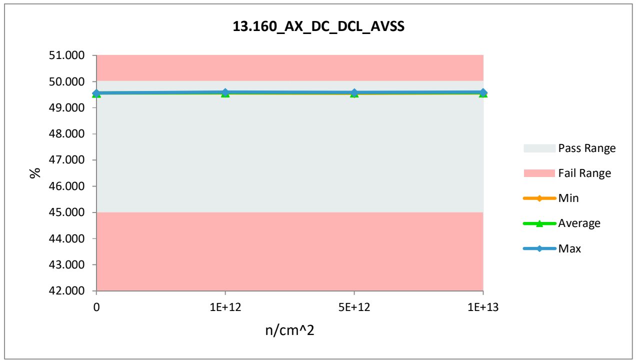


NDD Characterization Report
TPS7H5005-SEP

		13.160_AX_DC_DCL_AVSS		
	Test Site			
	Tester			
	Test Number			
	Unit	%	%	
	Max Limit	50	50	
	Min Limit	45	45	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	49.549	49.567	0.018
1E+12	1	49.591	49.565	-0.026
1E+12	2	49.609	49.569	-0.040
1E+12	3	49.611	49.604	-0.007
5E+12	4	49.552	49.582	0.030
5E+12	5	49.592	49.556	-0.036
5E+12	6	49.606	49.589	-0.017
1E+13	7	49.608	49.567	-0.041
1E+13	8	49.570	49.561	-0.009
1E+13	9	49.573	49.597	0.024
	Max	49.611	49.604	0.030
	Average	49.586	49.576	-0.010
	Min	49.549	49.556	-0.041
	Std Dev	0.024	0.016	0.027

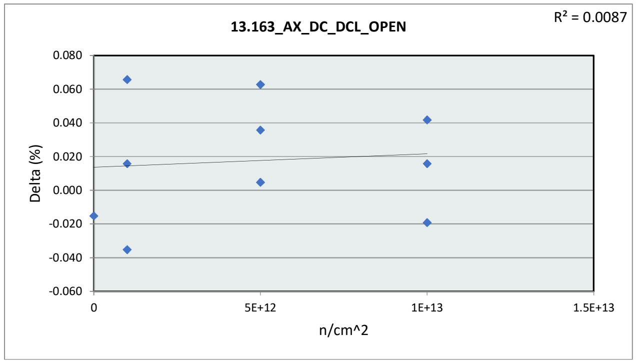


	13.160_AX_DC_DCL_AVSS			
Test Site				
Tester				
Test Number				
Max Limit	50	%		
Min Limit	45	%		
n/cm^2	0	1E+12	5E+12	1E+13
LL	45.000	45.000	45.000	45.000
Min	49.567	49.565	49.556	49.561
Average	49.567	49.579	49.576	49.575
Max	49.567	49.604	49.589	49.597
UL	50.000	50.000	50.000	50.000

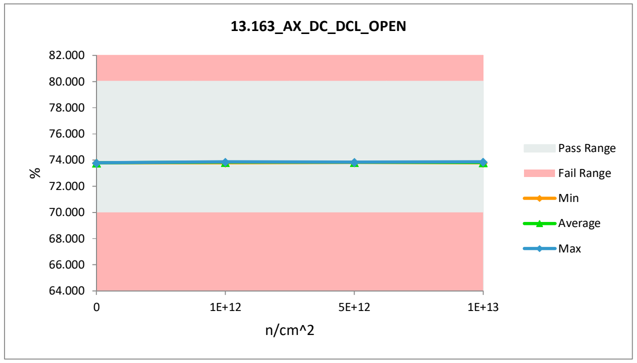


NDD Characterization Report
TPS7H5005-SEP

		13.163_AX_DC_DCL_OPEN		
Test Site				
Tester				
Test Number				
Unit		%	%	
Max Limit		80	80	
Min Limit		70	70	
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	73.808	73.793	-0.015
1E+12	1	73.789	73.855	0.066
1E+12	2	73.826	73.791	-0.035
1E+12	3	73.849	73.865	0.016
5E+12	4	73.843	73.848	0.005
5E+12	5	73.763	73.826	0.063
5E+12	6	73.813	73.849	0.036
1E+13	7	73.824	73.866	0.042
1E+13	8	73.807	73.788	-0.019
1E+13	9	73.815	73.831	0.016
	Max	73.849	73.866	0.066
	Average	73.814	73.831	0.017
	Min	73.763	73.788	-0.035
	Std Dev	0.025	0.031	0.034

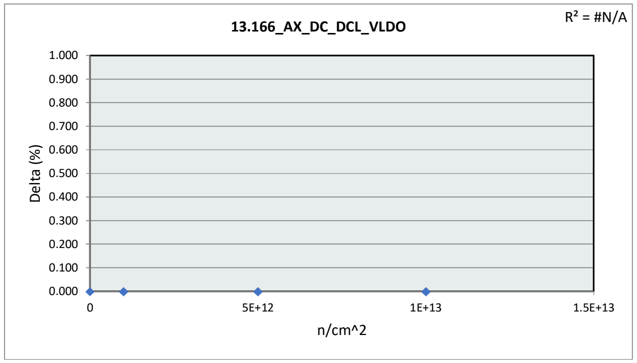


	13.163_AX_DC_DCL_OPEN			
Test Site				
Tester				
Test Number				
Max Limit	80	%		
Min Limit	70	%		
n/cm^2	0	1E+12	5E+12	1E+13
LL	70.000	70.000	70.000	70.000
Min	73.793	73.791	73.826	73.788
Average	73.793	73.837	73.841	73.828
Max	73.793	73.865	73.849	73.866
UL	80.000	80.000	80.000	80.000

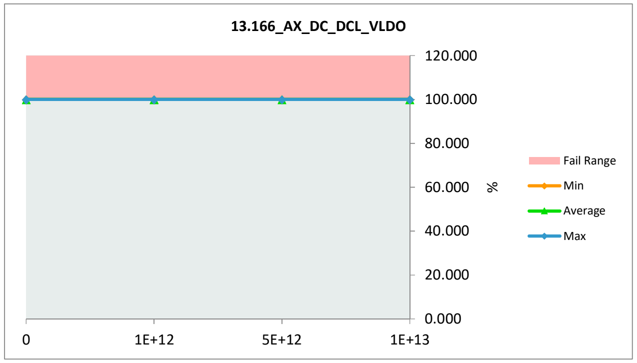


NDD Characterization Report
TPS7H5005-SEP

		13.166_AX_DC_DCL_VLDO		
	Test Site			
	Tester			
	Test Number			
	Unit	%	%	
	Max Limit	100	100	
	Min Limit			
n/cm^2	Serial #	Pre_NDD_5005-SEP	Post_NDD_5005-SEP	Delta
0	10	100.000	100.000	0.000
1E+12	1	100.000	100.000	0.000
1E+12	2	100.000	100.000	0.000
1E+12	3	100.000	100.000	0.000
5E+12	4	100.000	100.000	0.000
5E+12	5	100.000	100.000	0.000
5E+12	6	100.000	100.000	0.000
1E+13	7	100.000	100.000	0.000
1E+13	8	100.000	100.000	0.000
1E+13	9	100.000	100.000	0.000
	Max	100.000	100.000	0.000
	Average	100.000	100.000	0.000
	Min	100.000	100.000	0.000
	Std Dev	0.000	0.000	0.000



	13.166_AX_DC_DCL_VLDO			
Test Site				
Tester				
Test Number				
Max Limit	100	%		
Min Limit		%		
n/cm^2	0	1E+12	5E+12	1E+13
LL				
Min	100.000	100.000	100.000	100.000
Average	100.000	100.000	100.000	100.000
Max	100.000	100.000	100.000	100.000
UL	100.000	100.000	100.000	100.000



6 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision * (August 2022) to Revision A (August 2024) **Page**

- Updated document title..1
- Updated document to include information for TPS7H5001-SP QMLP...1

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